

Batch Wafer Quality Report

Report Generated: 2025-12-27 12:46:07

Simulation Date: 2025-12-27

Batch Summary

Total wafers: 236

Date Range: 2025-12-27 (Single Day)

PASS: 164 | FAIL: 72

PASS rate: 69.49%

Top 5 Highest Defect Percentages

- Thermal_THERM_01_W0022 (Thermal): 94.31% [Near-Full]
- Thermal_THERM_02_W0003 (Thermal): 91.72% [Near-Full]
- Thermal_THERM_02_W0026 (Thermal): 91.11% [Near-Full]
- Mechanical_MECH_02_W0029 (Mechanical): 89.73% [Near-Full]
- Electrical_ELEC_02_W0032 (Electrical): 86.14% [Random]

Distribution by Machine Type

- Electrical: 94 wafers
- Mechanical: 81 wafers
- Thermal: 61 wafers

Distribution by Defect Class

- Normal: 163 wafers
- Random: 13 wafers
- Donut: 13 wafers
- Edge-Ring: 12 wafers
- Edge-Loc: 10 wafers
- Local: 10 wafers
- Center: 6 wafers
- Scratch: 5 wafers
- Near-Full: 4 wafers

AI-Enhanced Engineering Summary

The batch yield is currently at 69.49%, with 72 out of 236 wafers failing. The highest defect concentrations are observed in the Thermal machine type, predominantly with Near-Full defect class wafers exhibiting over 90% defect coverage. Mechanical and Electrical machines also contribute to failures, with notable Random and Near-Full defects. The defect distribution suggests systemic issues in Thermal processing and sporadic defects in other machines.

Estimated batch yield impact: High

Key Risks

- High Near-Full defect rates in Thermal machine wafers

- Significant number of Random defects in Electrical machine wafers
- Potential systemic process issues in Thermal processing
- Mechanical machine also showing high Near-Full defect wafers

Recommended Actions

- Conduct detailed root cause analysis on Thermal machine processes
- Review and optimize process controls for Mechanical and Electrical machines
- Implement additional inline monitoring for early defect detection
- Increase wafer-level inspection frequency to identify defect trends

Per-Wafer Decisions

Wafer 1 Inspection Decision

Wafer ID: Mechanical_MECH_01_W0001

Decision: PASS

Machine Type: Mechanical

Machine ID: MECH_01

Timestamp: 2025-12-27T12:04:46.220967

Simulation Date: 2025-12-27

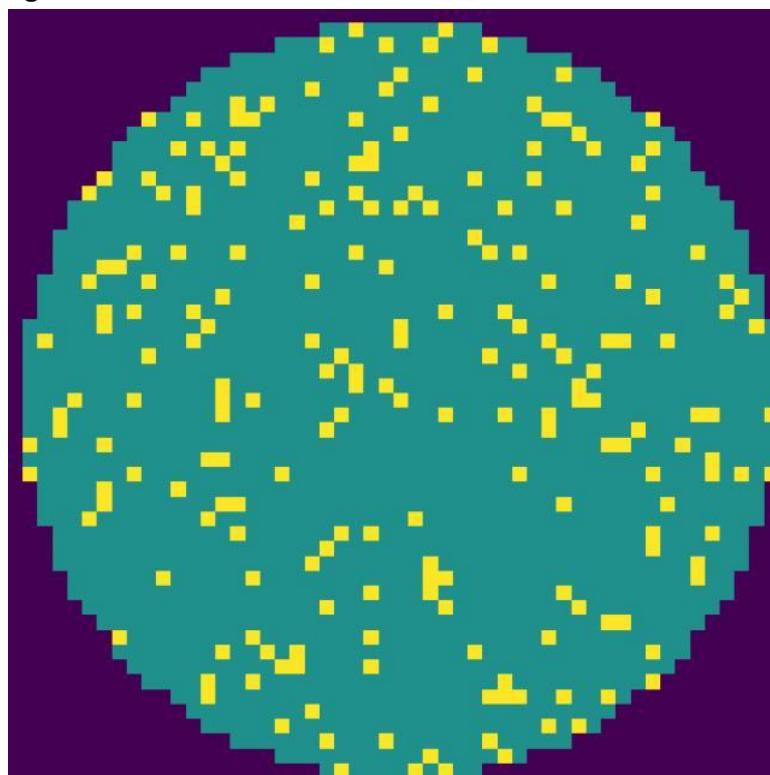
Defect Class: Normal

Confidence Score: 0.9997

Defect Percentage: 35.74%

Reason: Defect Percentage: 35.74% (<=40% threshold), Defect Class: Normal, Confidence: 99.97%

Wafer Defect Image:



Wafer 2 Inspection Decision

Wafer ID: Mechanical_MECH_02_W0001

Decision: PASS

Machine Type: Mechanical

Machine ID: MECH_02

Timestamp: 2025-12-27T12:04:46.221975

Simulation Date: 2025-12-27

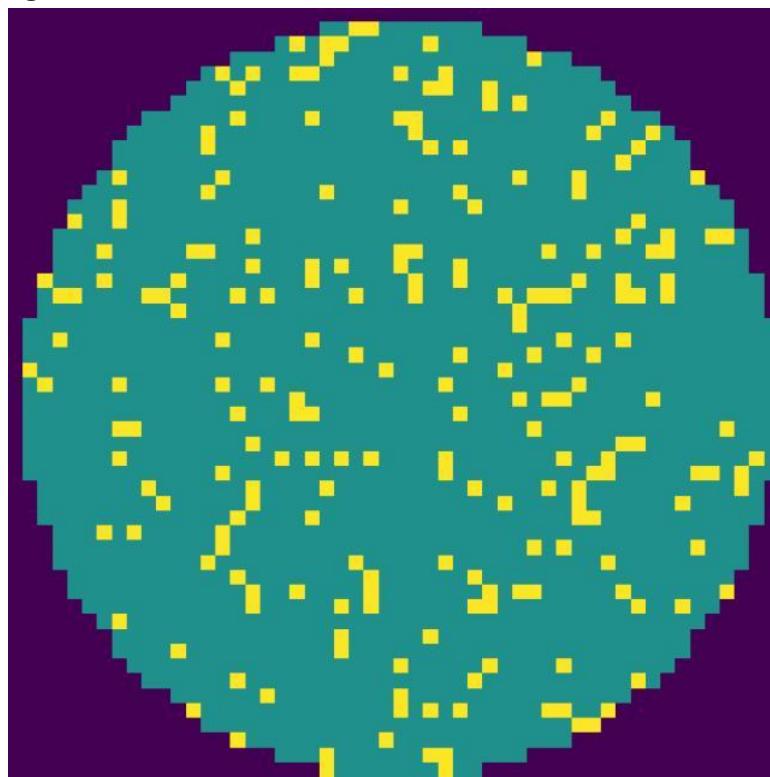
Defect Class: Normal

Confidence Score: 0.9998

Defect Percentage: 38.39%

Reason: Defect Percentage: 38.39% (<=40% threshold), Defect Class: Normal, Confidence: 99.98%

Wafer Defect Image:



Wafer 3 Inspection Decision

Wafer ID: Electrical_ELEC_02_W0001

Decision: FAIL

Machine Type: Electrical

Machine ID: ELEC_02

Timestamp: 2025-12-27T12:04:46.223318

Simulation Date: 2025-12-27

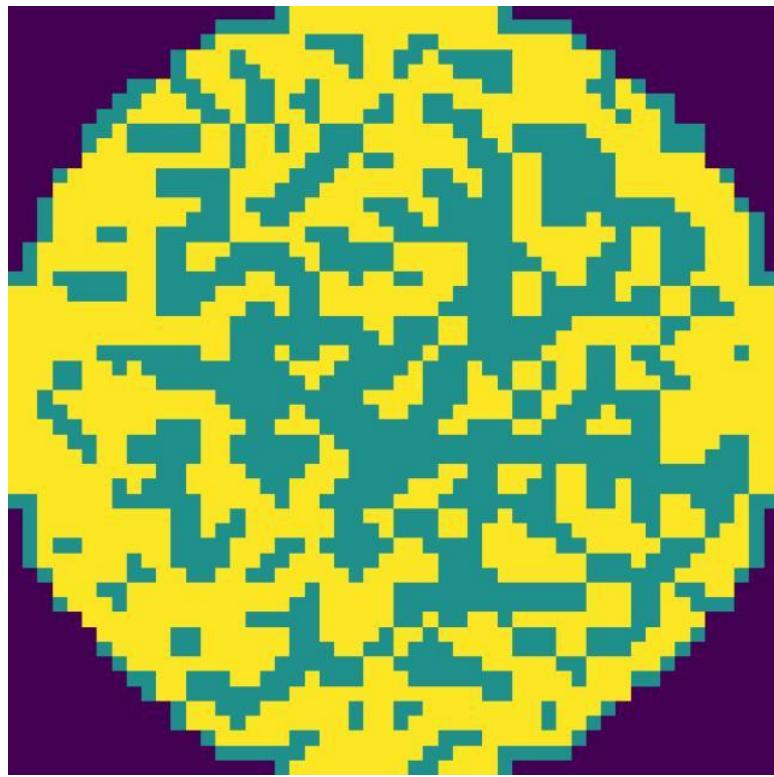
Defect Class: Random

Confidence Score: 0.9997

Defect Percentage: 76.97%

Reason: Defect Percentage: 76.97% (>40% threshold), Defect Class: Random, Confidence: 99.97%

Wafer Defect Image:



Wafer 4 Inspection Decision

Wafer ID: Electrical_ELEC_01_W0001

Decision: FAIL

Machine Type: Electrical

Machine ID: ELEC_01

Timestamp: 2025-12-27T12:04:46.223318

Simulation Date: 2025-12-27

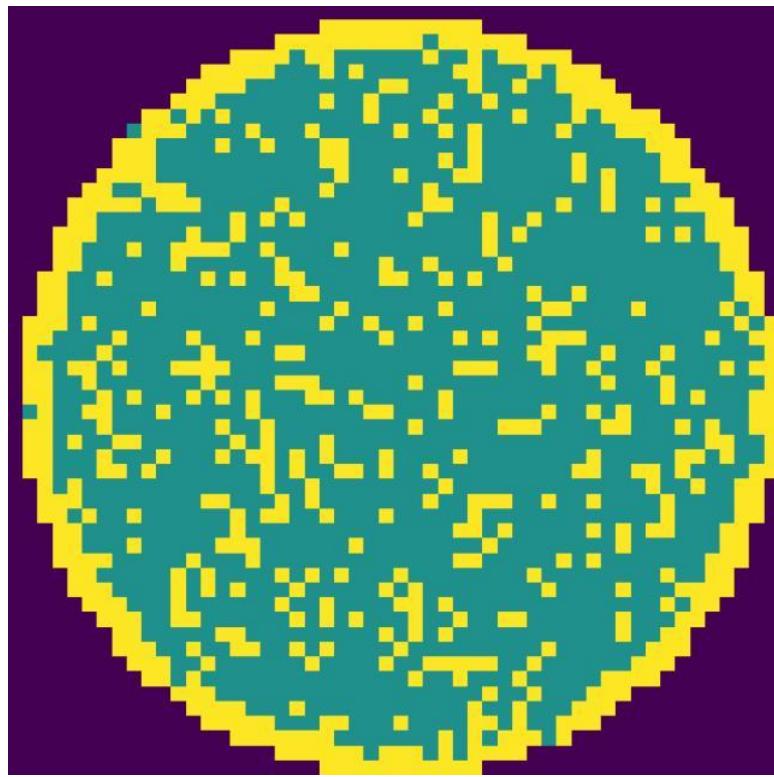
Defect Class: Edge-Ring

Confidence Score: 0.9954

Defect Percentage: 58.04%

Reason: Defect Percentage: 58.04% (>40% threshold), Defect Class: Edge-Ring, Confidence: 99.54%

Wafer Defect Image:



Wafer 5 Inspection Decision

Wafer ID: Thermal_THERM_02_W0001

Decision: PASS

Machine Type: Thermal

Machine ID: THERM_02

Timestamp: 2025-12-27T12:04:46.223823

Simulation Date: 2025-12-27

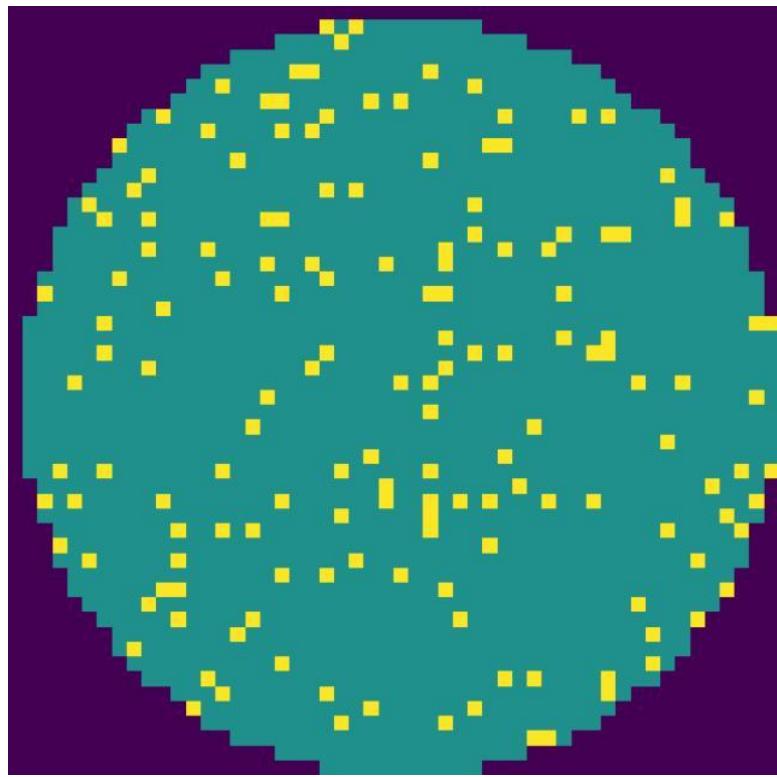
Defect Class: Normal

Confidence Score: 0.9996

Defect Percentage: 34.12%

Reason: Defect Percentage: 34.12% (<=40% threshold), Defect Class: Normal, Confidence: 99.96%

Wafer Defect Image:



Wafer 6 Inspection Decision

Wafer ID: Thermal_THERM_01_W0001

Decision: PASS

Machine Type: Thermal

Machine ID: THERM_01

Timestamp: 2025-12-27T12:04:46.223823

Simulation Date: 2025-12-27

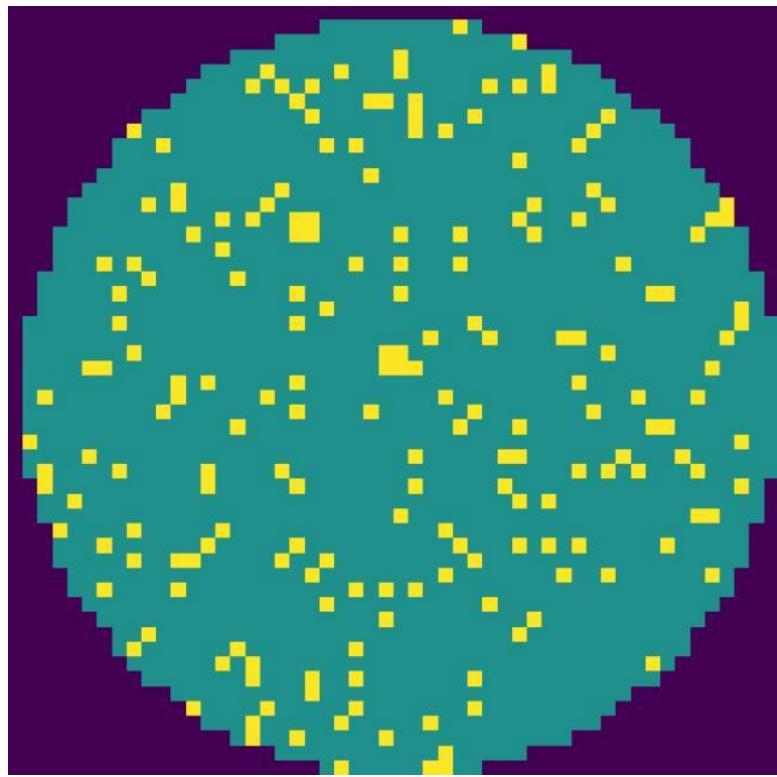
Defect Class: Normal

Confidence Score: 0.9997

Defect Percentage: 36.26%

Reason: Defect Percentage: 36.26% (<=40% threshold), Defect Class: Normal, Confidence: 99.97%

Wafer Defect Image:



Wafer 7 Inspection Decision

Wafer ID: Electrical_ELEC_02_W0002

Decision: PASS

Machine Type: Electrical

Machine ID: ELEC_02

Timestamp: 2025-12-27T12:04:51.707457

Simulation Date: 2025-12-27

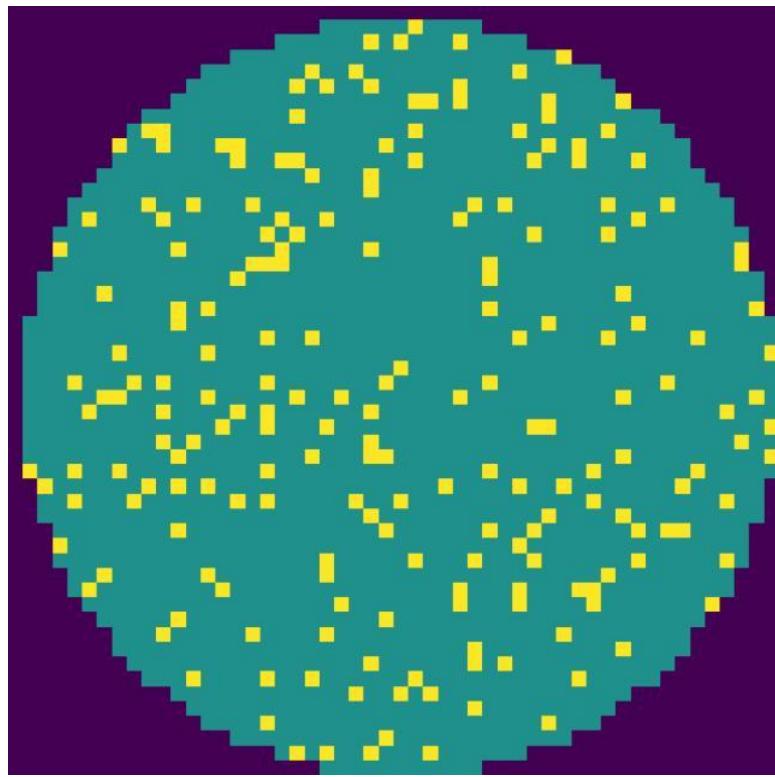
Defect Class: Normal

Confidence Score: 0.9998

Defect Percentage: 34.97%

Reason: Defect Percentage: 34.97% (<=40% threshold), Defect Class: Normal, Confidence: 99.98%

Wafer Defect Image:



Wafer 8 Inspection Decision

Wafer ID: Thermal_THERM_01_W0002

Decision: PASS

Machine Type: Thermal

Machine ID: THERM_01

Timestamp: 2025-12-27T12:04:51.786085

Simulation Date: 2025-12-27

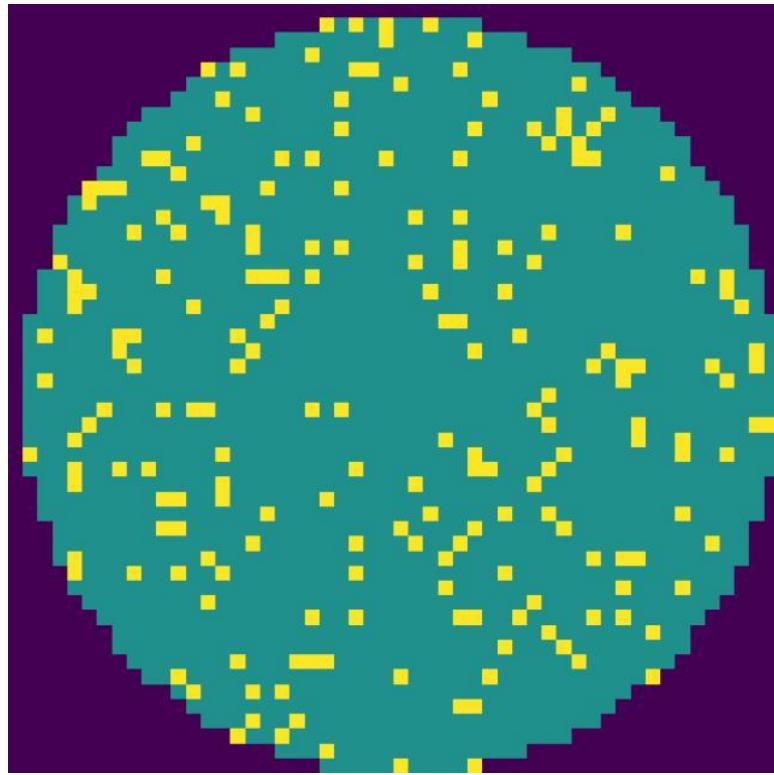
Defect Class: Normal

Confidence Score: 0.9993

Defect Percentage: 36.47%

Reason: Defect Percentage: 36.47% (<=40% threshold), Defect Class: Normal, Confidence: 99.93%

Wafer Defect Image:



Wafer 9 Inspection Decision

Wafer ID: Electrical_ELEC_01_W0002

Decision: FAIL

Machine Type: Electrical

Machine ID: ELEC_01

Timestamp: 2025-12-27T12:04:52.264065

Simulation Date: 2025-12-27

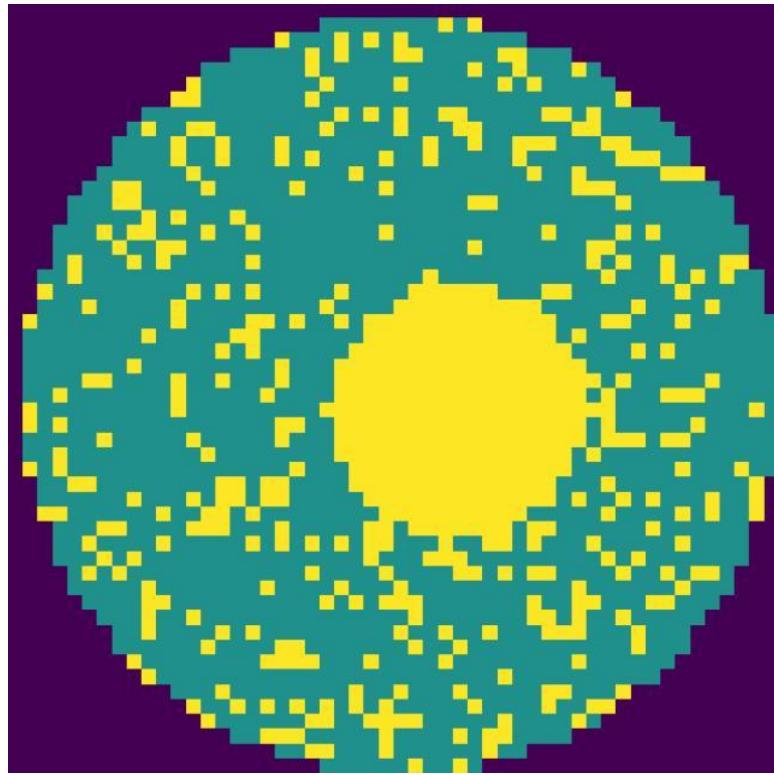
Defect Class: Center

Confidence Score: 0.9999

Defect Percentage: 59.07%

Reason: Defect Percentage: 59.07% (>40% threshold), Defect Class: Center, Confidence: 99.99%

Wafer Defect Image:



Wafer 10 Inspection Decision

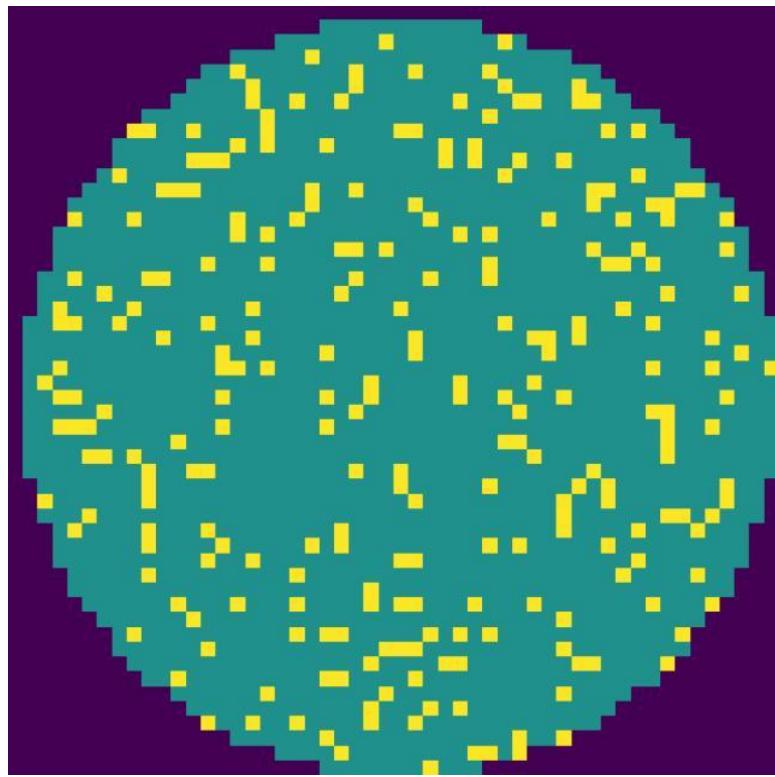
Wafer ID: Mechanical_MECH_02_W0002
Decision: PASS

Machine Type: Mechanical
Machine ID: MECH_02
Timestamp: 2025-12-27T12:04:52.603979
Simulation Date: 2025-12-27

Defect Class: Normal
Confidence Score: 0.9998
Defect Percentage: 38.11%

Reason: Defect Percentage: 38.11% (<=40% threshold), Defect Class: Normal, Confidence: 99.98%

Wafer Defect Image:



Wafer 11 Inspection Decision

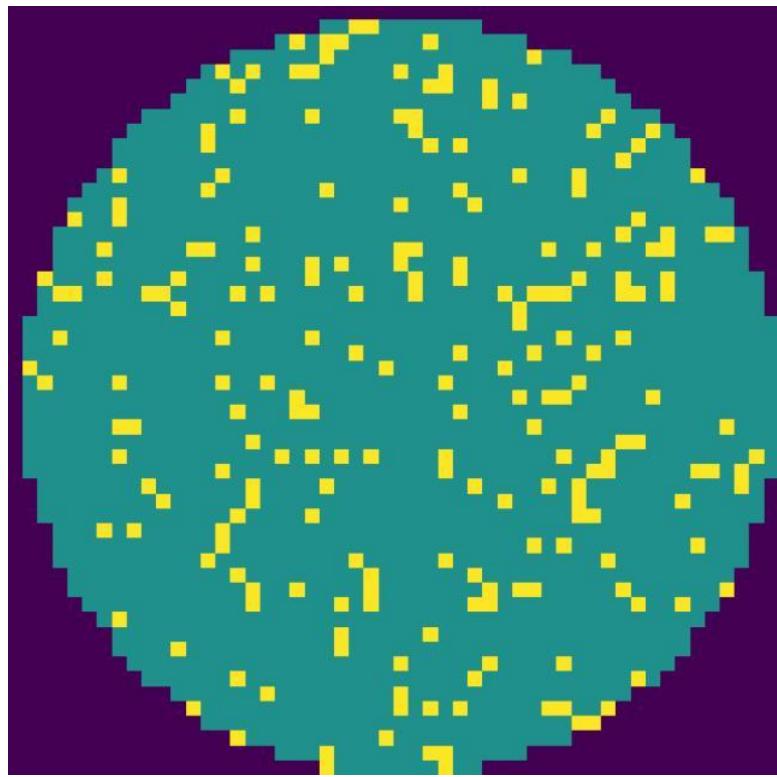
Wafer ID: Mechanical_MECH_01_W0002
Decision: PASS

Machine Type: Mechanical
Machine ID: MECH_01
Timestamp: 2025-12-27T12:04:52.690484
Simulation Date: 2025-12-27

Defect Class: Normal
Confidence Score: 0.9998
Defect Percentage: 38.39%

Reason: Defect Percentage: 38.39% (<=40% threshold), Defect Class: Normal, Confidence: 99.98%

Wafer Defect Image:



Wafer 12 Inspection Decision

Wafer ID: Thermal_THERM_02_W0002

Decision: FAIL

Machine Type: Thermal

Machine ID: THERM_02

Timestamp: 2025-12-27T12:04:55.370718

Simulation Date: 2025-12-27

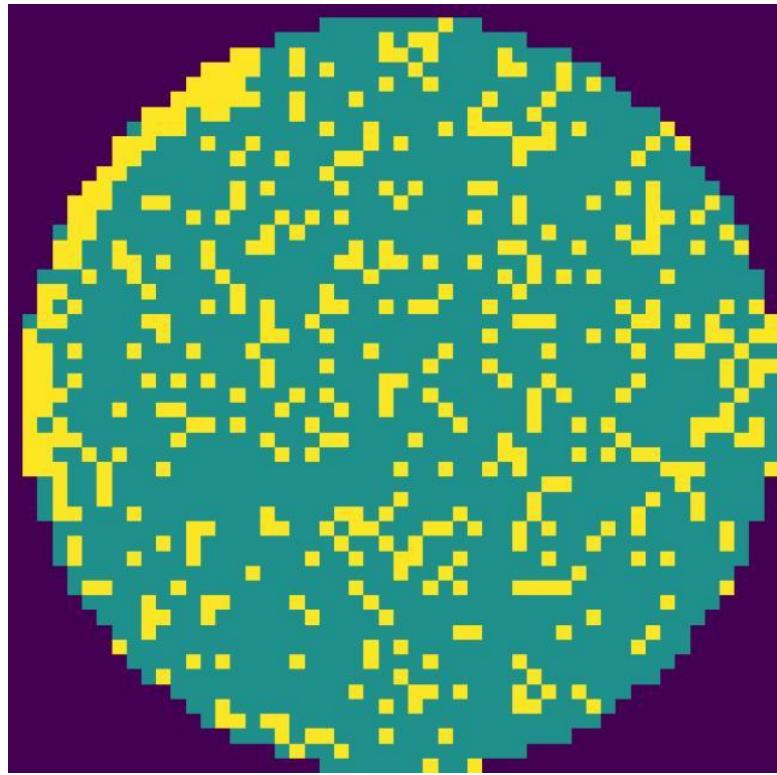
Defect Class: Edge-Loc

Confidence Score: 0.9531

Defect Percentage: 45.25%

Reason: Defect Percentage: 45.25% (>40% threshold), Defect Class: Edge-Loc, Confidence: 95.31%

Wafer Defect Image:



Wafer 13 Inspection Decision

Wafer ID: Electrical_ELEC_02_W0003

Decision: PASS

Machine Type: Electrical

Machine ID: ELEC_02

Timestamp: 2025-12-27T12:04:57.634761

Simulation Date: 2025-12-27

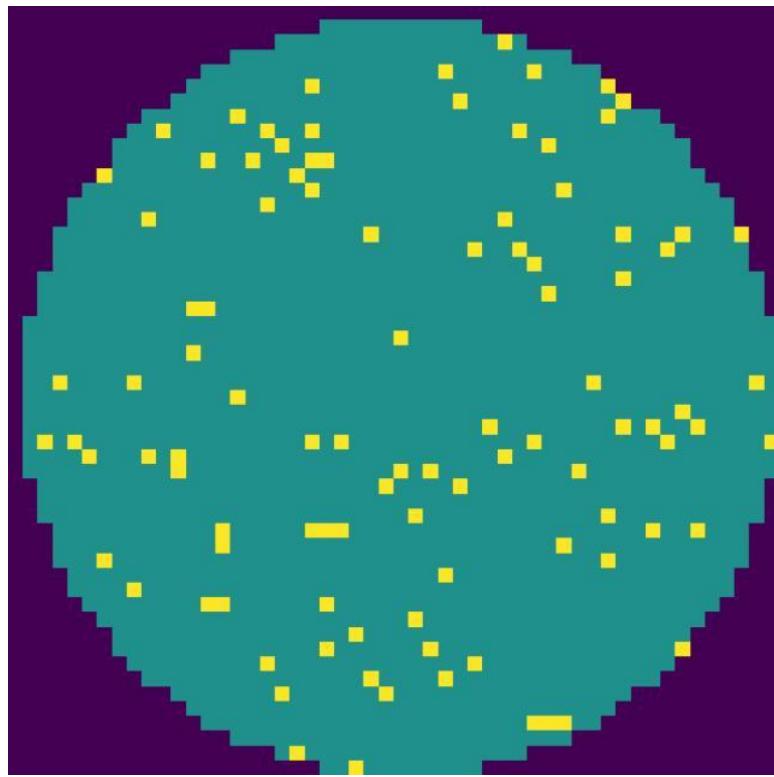
Defect Class: Normal

Confidence Score: 0.9998

Defect Percentage: 33.38%

Reason: Defect Percentage: 33.38% (<=40% threshold), Defect Class: Normal, Confidence: 99.98%

Wafer Defect Image:



Wafer 14 Inspection Decision

Wafer ID: Electrical_ELEC_01_W0003

Decision: PASS

Machine Type: Electrical

Machine ID: ELEC_01

Timestamp: 2025-12-27T12:04:58.043874

Simulation Date: 2025-12-27

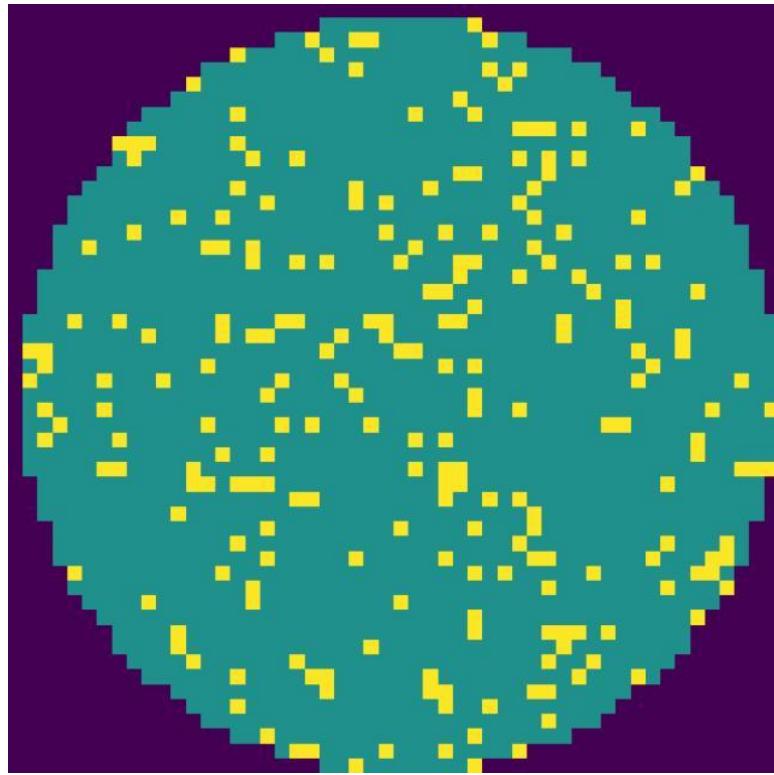
Defect Class: Normal

Confidence Score: 1.0000

Defect Percentage: 38.90%

Reason: Defect Percentage: 38.9% (<=40% threshold), Defect Class: Normal, Confidence: 100.00%

Wafer Defect Image:



Wafer 15 Inspection Decision

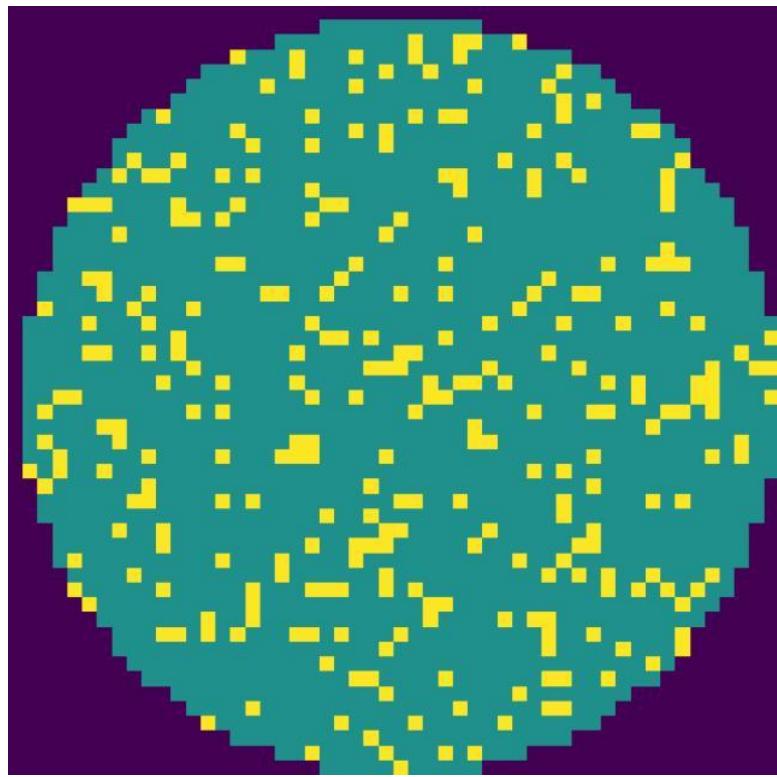
Wafer ID: Mechanical_MECH_02_W0003
Decision: PASS

Machine Type: Mechanical
Machine ID: MECH_02
Timestamp: 2025-12-27T12:04:58.826203
Simulation Date: 2025-12-27

Defect Class: Normal
Confidence Score: 0.9995
Defect Percentage: 39.51%

Reason: Defect Percentage: 39.51% (<=40% threshold), Defect Class: Normal, Confidence: 99.95%

Wafer Defect Image:



Wafer 16 Inspection Decision

Wafer ID: Thermal_THERM_01_W0003

Decision: PASS

Machine Type: Thermal

Machine ID: THERM_01

Timestamp: 2025-12-27T12:04:59.142516

Simulation Date: 2025-12-27

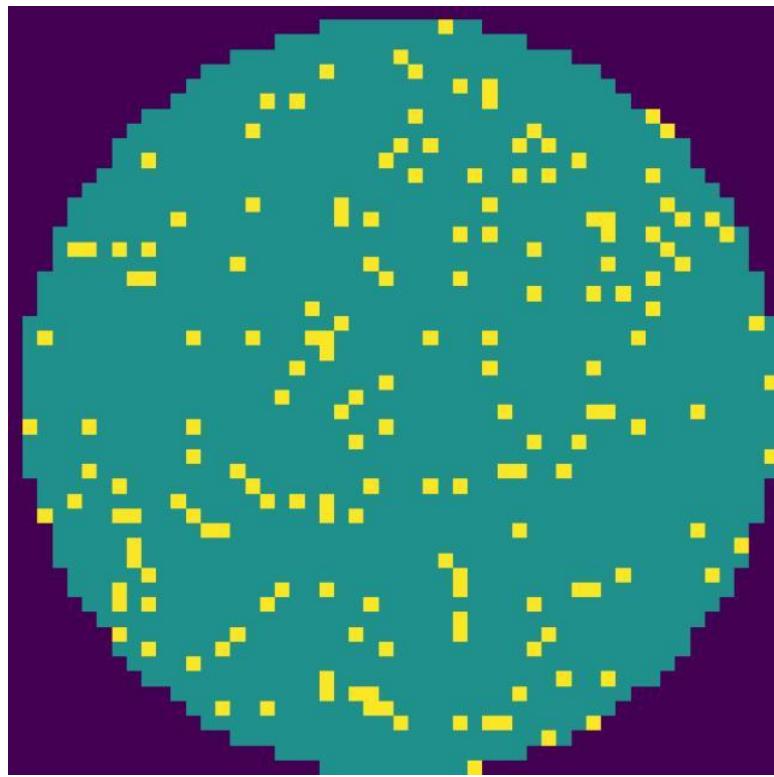
Defect Class: Normal

Confidence Score: 0.9997

Defect Percentage: 35.20%

Reason: Defect Percentage: 35.2% (<=40% threshold), Defect Class: Normal, Confidence: 99.97%

Wafer Defect Image:



Wafer 17 Inspection Decision

Wafer ID: Mechanical_MECH_01_W0003

Decision: PASS

Machine Type: Mechanical

Machine ID: MECH_01

Timestamp: 2025-12-27T12:04:59.606736

Simulation Date: 2025-12-27

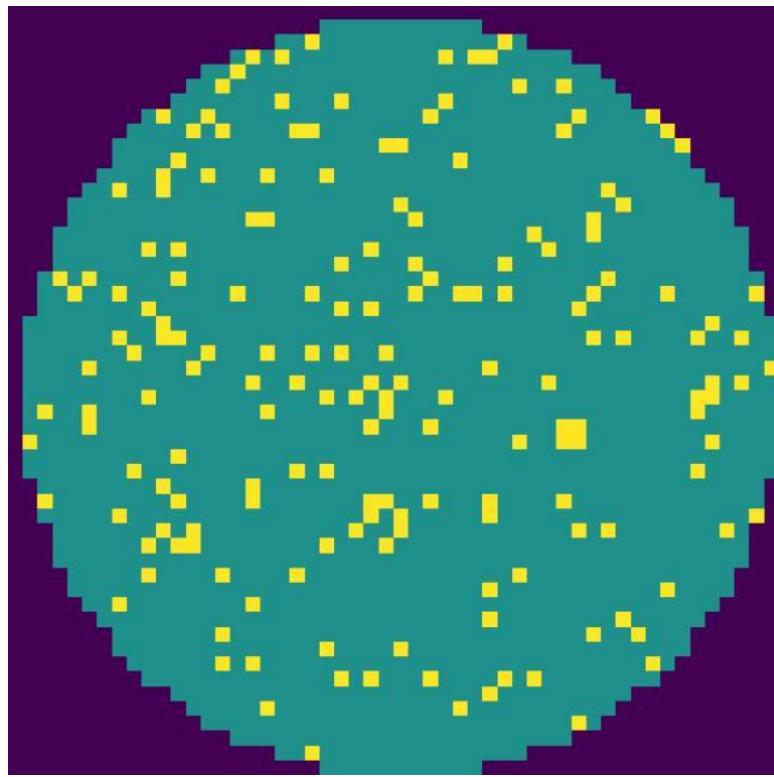
Defect Class: Normal

Confidence Score: 0.9999

Defect Percentage: 34.89%

Reason: Defect Percentage: 34.89% (<=40% threshold), Defect Class: Normal, Confidence: 99.99%

Wafer Defect Image:



Wafer 18 Inspection Decision

Wafer ID: Electrical_ELEC_02_W0004

Decision: FAIL

Machine Type: Electrical

Machine ID: ELEC_02

Timestamp: 2025-12-27T12:05:03.060846

Simulation Date: 2025-12-27

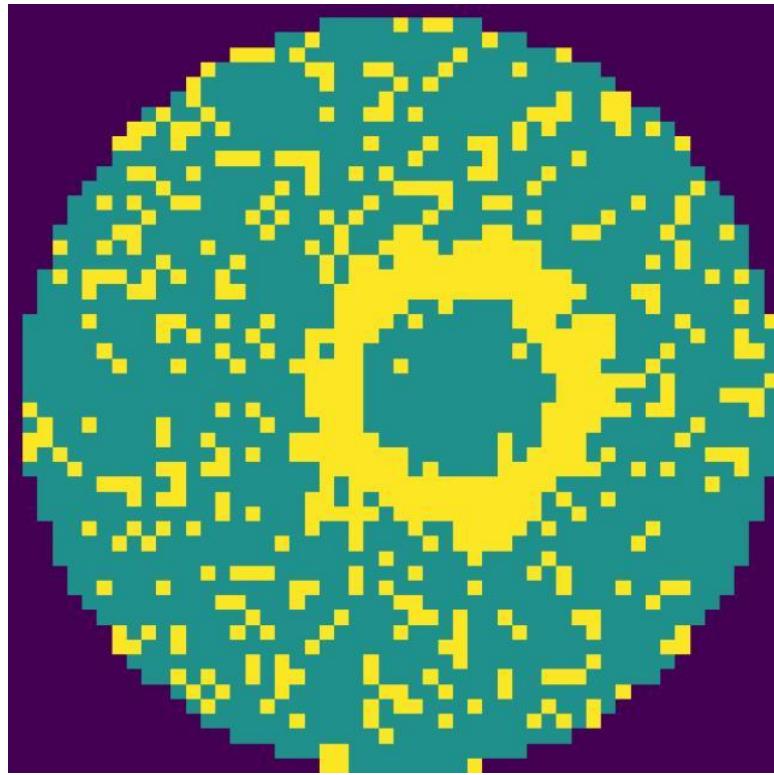
Defect Class: Donut

Confidence Score: 1.0000

Defect Percentage: 55.45%

Reason: Defect Percentage: 55.45% (>40% threshold), Defect Class: Donut, Confidence: 100.00%

Wafer Defect Image:



Wafer 19 Inspection Decision

Wafer ID: Electrical_ELEC_01_W0004

Decision: FAIL

Machine Type: Electrical

Machine ID: ELEC_01

Timestamp: 2025-12-27T12:05:03.455798

Simulation Date: 2025-12-27

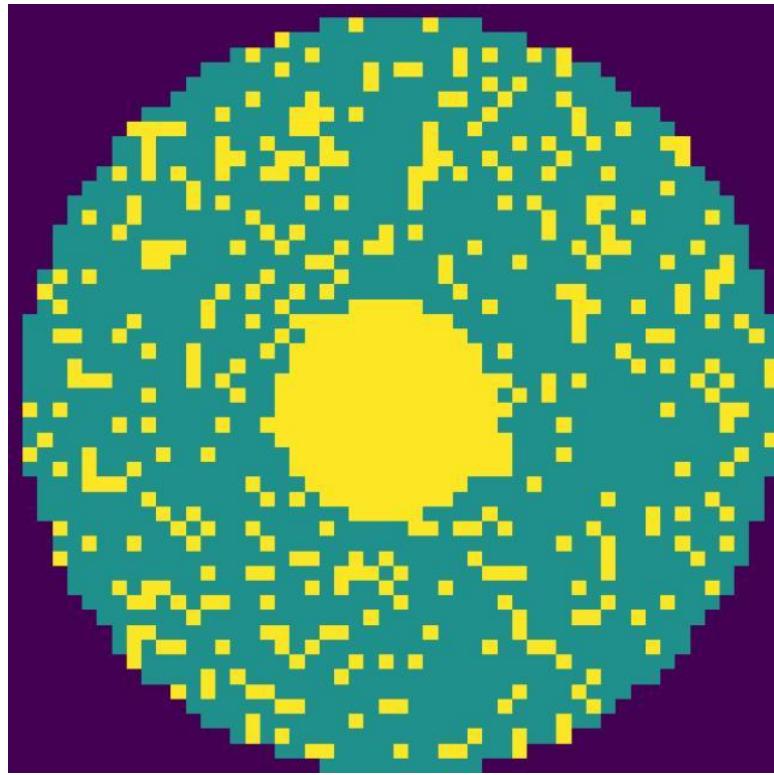
Defect Class: Center

Confidence Score: 1.0000

Defect Percentage: 53.65%

Reason: Defect Percentage: 53.65% (>40% threshold), Defect Class: Center, Confidence: 100.00%

Wafer Defect Image:



Wafer 20 Inspection Decision

Wafer ID: Thermal_THERM_01_W0004

Decision: FAIL

Machine Type: Thermal

Machine ID: THERM_01

Timestamp: 2025-12-27T12:05:04.929362

Simulation Date: 2025-12-27

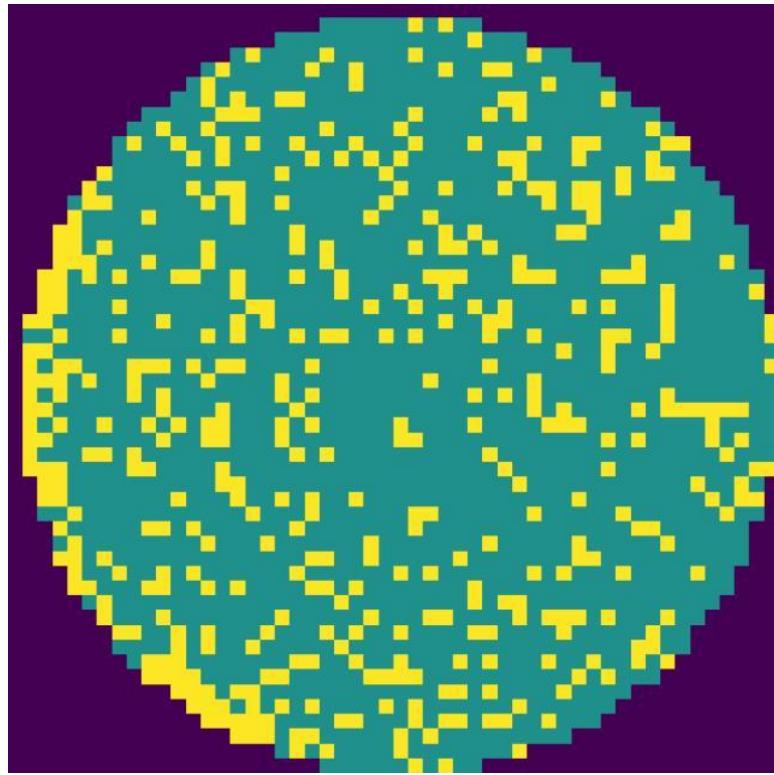
Defect Class: Edge-Loc

Confidence Score: 0.9990

Defect Percentage: 45.65%

Reason: Defect Percentage: 45.65% (>40% threshold), Defect Class: Edge-Loc, Confidence: 99.90%

Wafer Defect Image:



Wafer 21 Inspection Decision

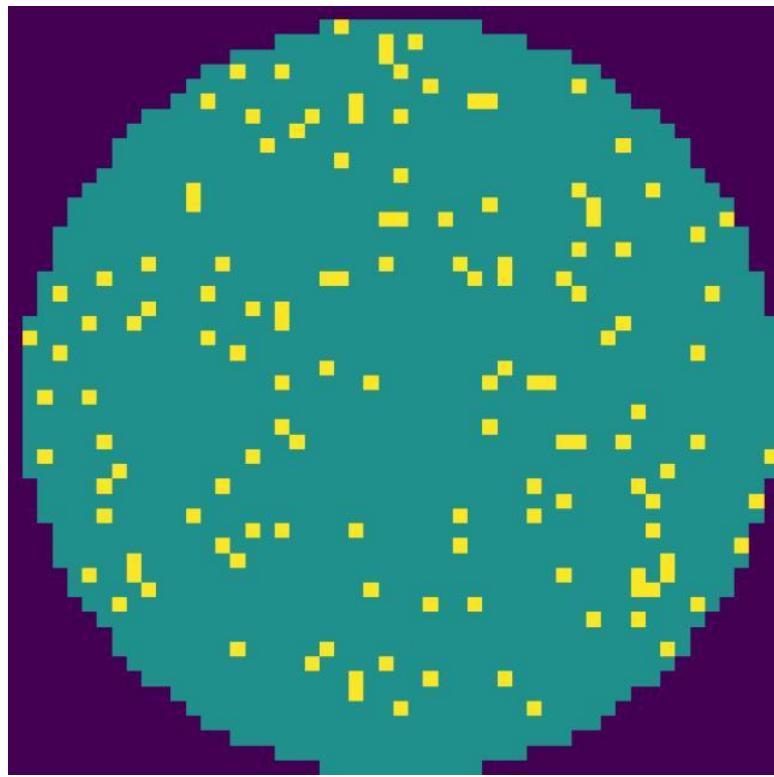
Wafer ID: Mechanical_MECH_02_W0004
Decision: PASS

Machine Type: Mechanical
Machine ID: MECH_02
Timestamp: 2025-12-27T12:05:05.520309
Simulation Date: 2025-12-27

Defect Class: Normal
Confidence Score: 0.9998
Defect Percentage: 34.03%

Reason: Defect Percentage: 34.03% (<=40% threshold), Defect Class: Normal, Confidence: 99.98%

Wafer Defect Image:



Wafer 22 Inspection Decision

Wafer ID: Thermal_THERM_02_W0003

Decision: FAIL

Machine Type: Thermal

Machine ID: THERM_02

Timestamp: 2025-12-27T12:05:07.149710

Simulation Date: 2025-12-27

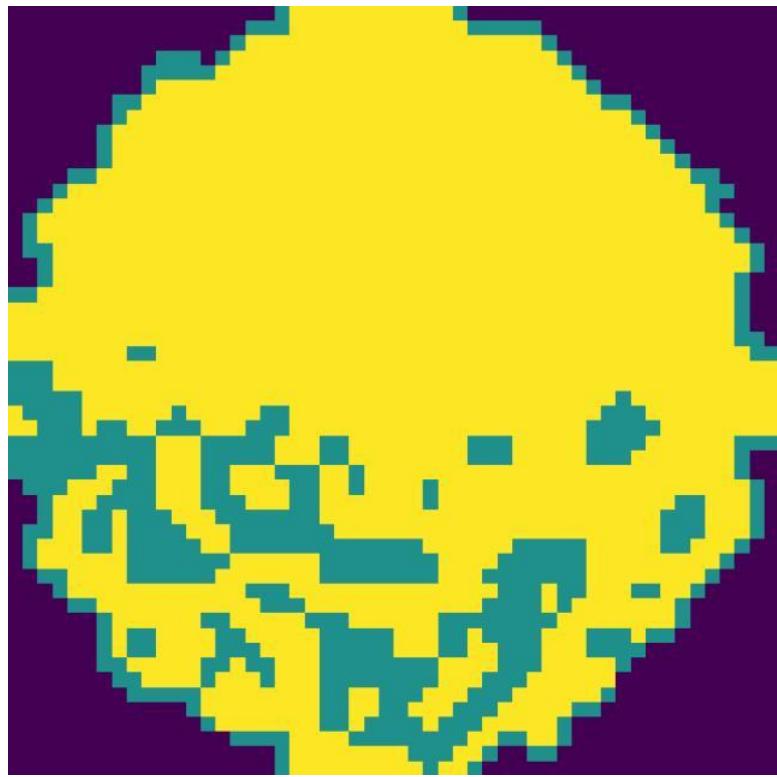
Defect Class: Near-Full

Confidence Score: 0.9999

Defect Percentage: 91.72%

Reason: Defect Percentage: 91.72% (>40% threshold), Defect Class: Near-Full, Confidence: 99.99%

Wafer Defect Image:



Wafer 23 Inspection Decision

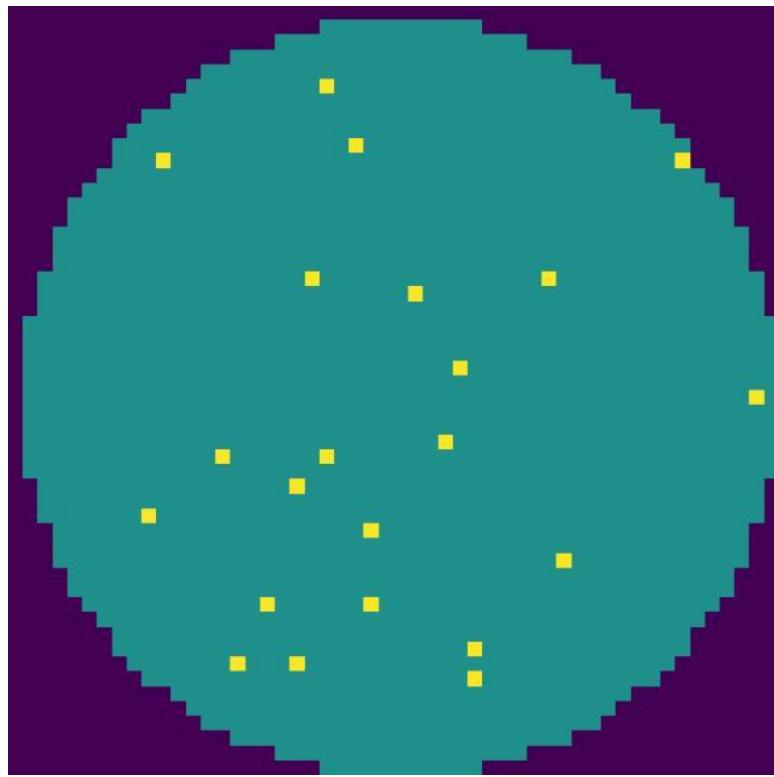
Wafer ID: Mechanical_MECH_01_W0004
Decision: PASS

Machine Type: Mechanical
Machine ID: MECH_01
Timestamp: 2025-12-27T12:05:07.445990
Simulation Date: 2025-12-27

Defect Class: Normal
Confidence Score: 0.9997
Defect Percentage: 29.05%

Reason: Defect Percentage: 29.05% (<=40% threshold), Defect Class: Normal, Confidence: 99.97%

Wafer Defect Image:



Wafer 24 Inspection Decision

Wafer ID: Electrical_ELEC_02_W0005

Decision: PASS

Machine Type: Electrical

Machine ID: ELEC_02

Timestamp: 2025-12-27T12:05:08.524111

Simulation Date: 2025-12-27

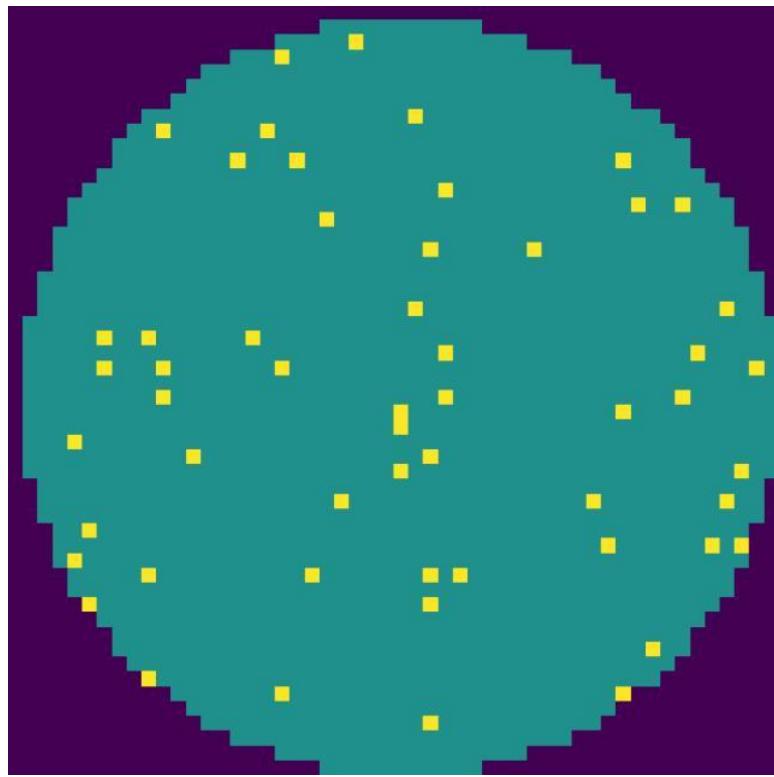
Defect Class: Normal

Confidence Score: 0.9998

Defect Percentage: 30.86%

Reason: Defect Percentage: 30.86% (<=40% threshold), Defect Class: Normal, Confidence: 99.98%

Wafer Defect Image:



Wafer 25 Inspection Decision

Wafer ID: Electrical_ELEC_01_W0005

Decision: FAIL

Machine Type: Electrical

Machine ID: ELEC_01

Timestamp: 2025-12-27T12:05:09.327225

Simulation Date: 2025-12-27

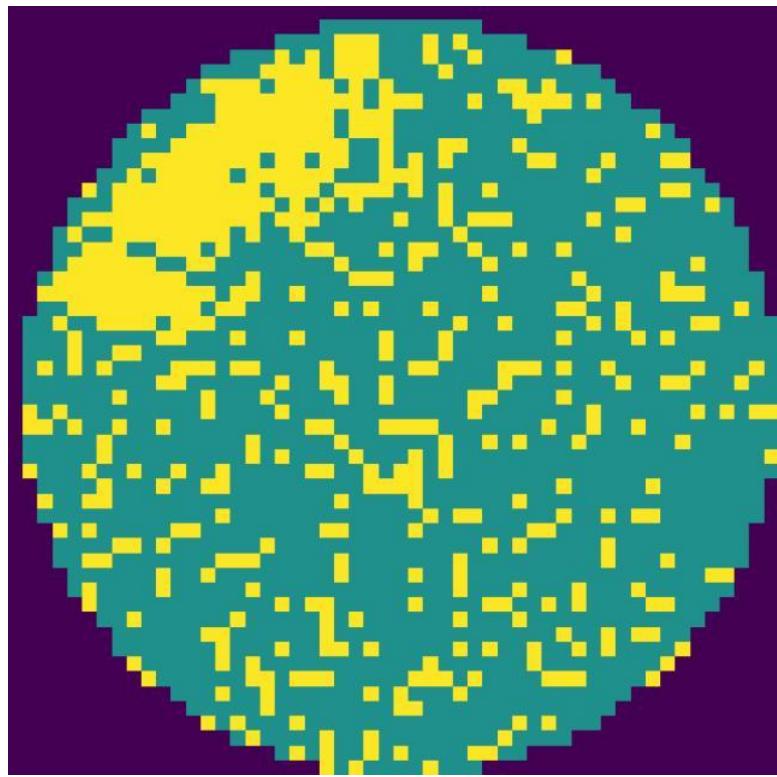
Defect Class: Local

Confidence Score: 1.0000

Defect Percentage: 53.72%

Reason: Defect Percentage: 53.72% (>40% threshold), Defect Class: Local, Confidence: 100.00%

Wafer Defect Image:



Wafer 26 Inspection Decision

Wafer ID: Thermal_THERM_01_W0005

Decision: PASS

Machine Type: Thermal

Machine ID: THERM_01

Timestamp: 2025-12-27T12:05:10.881489

Simulation Date: 2025-12-27

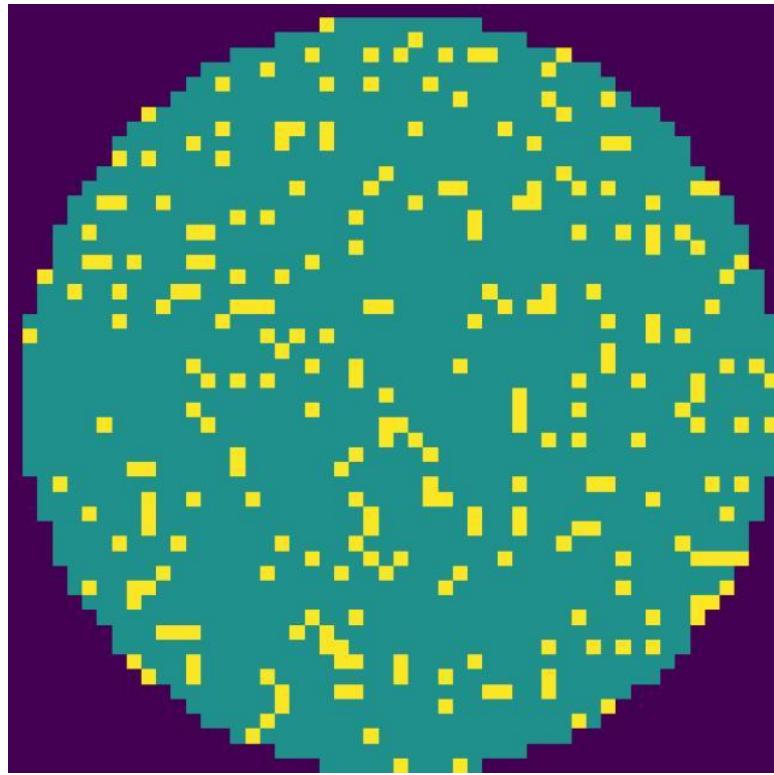
Defect Class: Normal

Confidence Score: 0.9998

Defect Percentage: 37.71%

Reason: Defect Percentage: 37.71% (<=40% threshold), Defect Class: Normal, Confidence: 99.98%

Wafer Defect Image:



Wafer 27 Inspection Decision

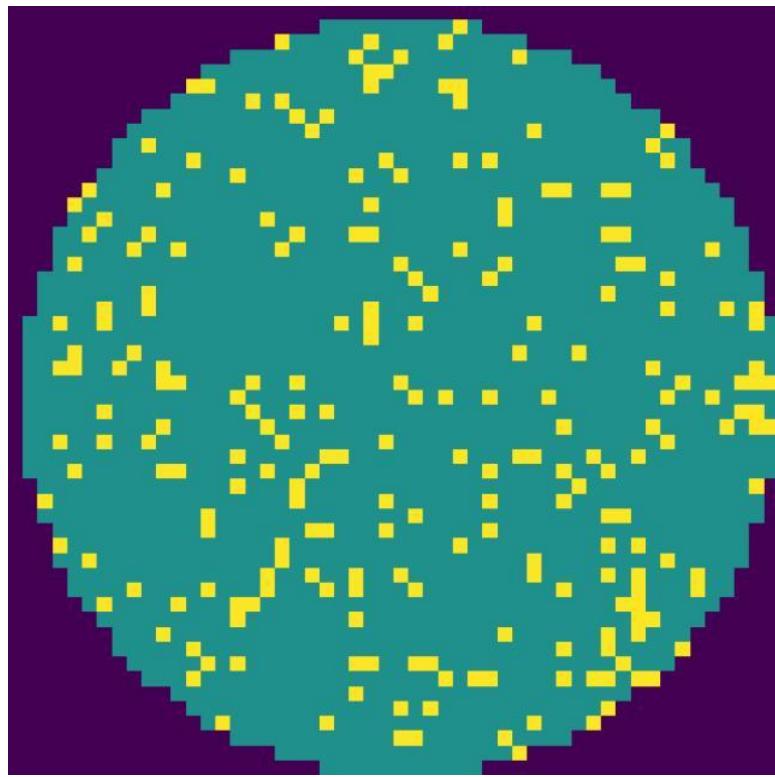
Wafer ID: Mechanical_MECH_02_W0005
Decision: PASS

Machine Type: Mechanical
Machine ID: MECH_02
Timestamp: 2025-12-27T12:05:12.360378
Simulation Date: 2025-12-27

Defect Class: Normal
Confidence Score: 0.9996
Defect Percentage: 37.60%

Reason: Defect Percentage: 37.6% (<=40% threshold), Defect Class: Normal, Confidence: 99.96%

Wafer Defect Image:



Wafer 28 Inspection Decision

Wafer ID: Electrical_ELEC_02_W0006

Decision: FAIL

Machine Type: Electrical

Machine ID: ELEC_02

Timestamp: 2025-12-27T12:05:14.161093

Simulation Date: 2025-12-27

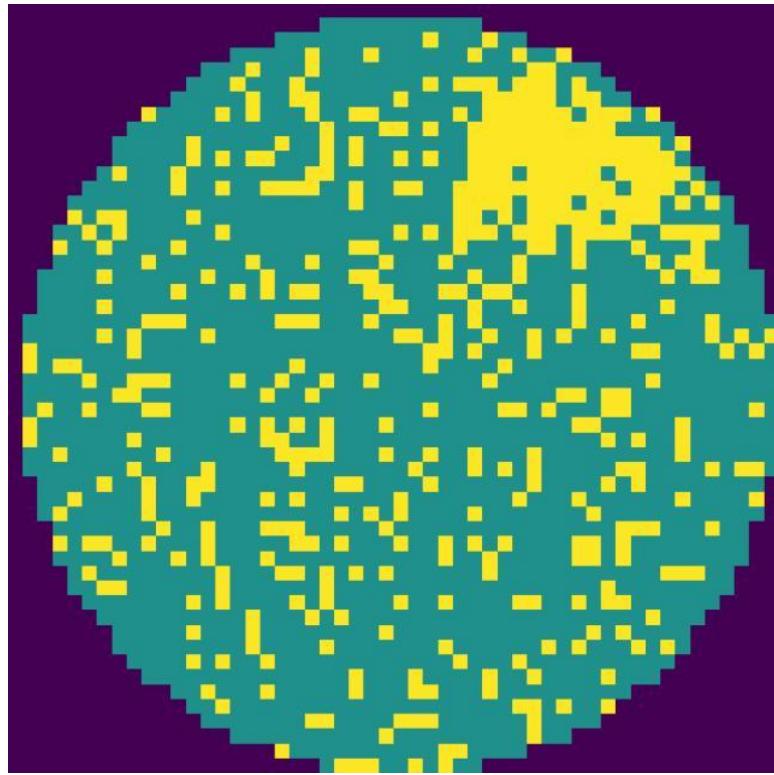
Defect Class: Local

Confidence Score: 1.0000

Defect Percentage: 49.60%

Reason: Defect Percentage: 49.6% (>40% threshold), Defect Class: Local, Confidence: 100.00%

Wafer Defect Image:



Wafer 29 Inspection Decision

Wafer ID: Electrical_ELEC_01_W0006

Decision: PASS

Machine Type: Electrical

Machine ID: ELEC_01

Timestamp: 2025-12-27T12:05:14.563979

Simulation Date: 2025-12-27

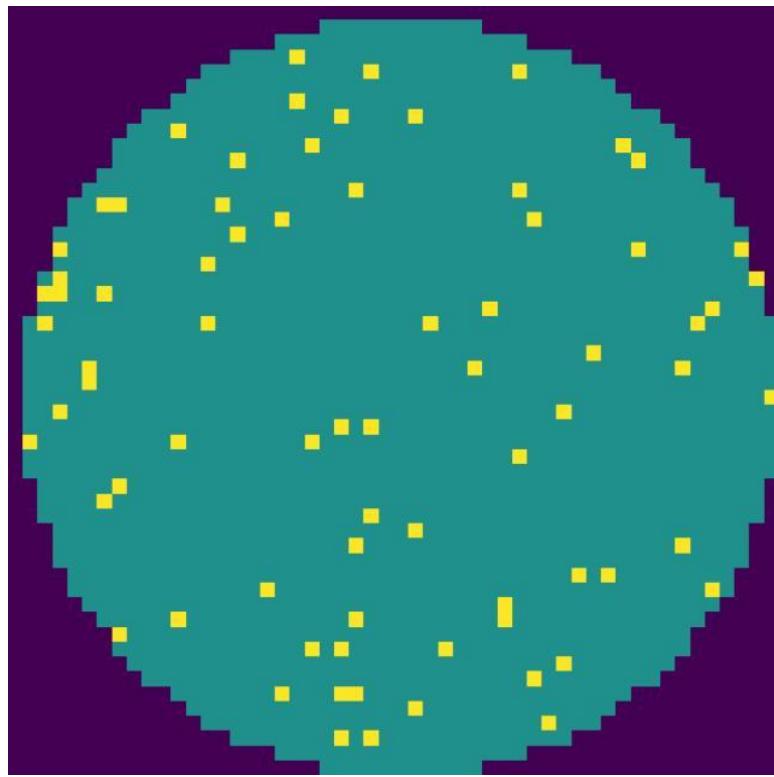
Defect Class: Normal

Confidence Score: 0.9998

Defect Percentage: 32.88%

Reason: Defect Percentage: 32.88% (<=40% threshold), Defect Class: Normal, Confidence: 99.98%

Wafer Defect Image:



Wafer 30 Inspection Decision

Wafer ID: Mechanical_MECH_01_W0005

Decision: PASS

Machine Type: Mechanical

Machine ID: MECH_01

Timestamp: 2025-12-27T12:05:15.316036

Simulation Date: 2025-12-27

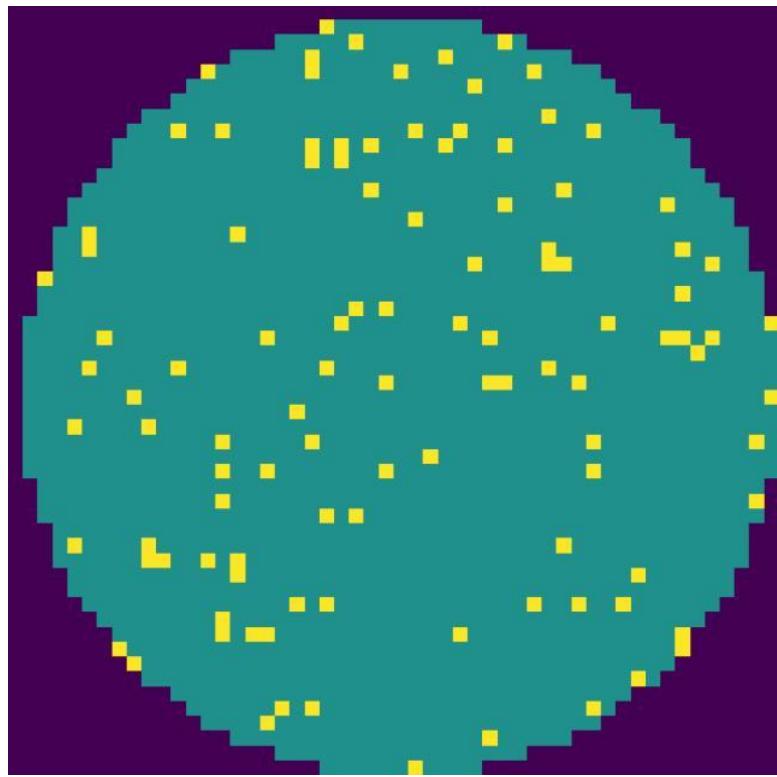
Defect Class: Normal

Confidence Score: 0.9997

Defect Percentage: 35.66%

Reason: Defect Percentage: 35.66% (<=40% threshold), Defect Class: Normal, Confidence: 99.97%

Wafer Defect Image:



Wafer 31 Inspection Decision

Wafer ID: Thermal_THERM_01_W0006

Decision: FAIL

Machine Type: Thermal

Machine ID: THERM_01

Timestamp: 2025-12-27T12:05:17.279825

Simulation Date: 2025-12-27

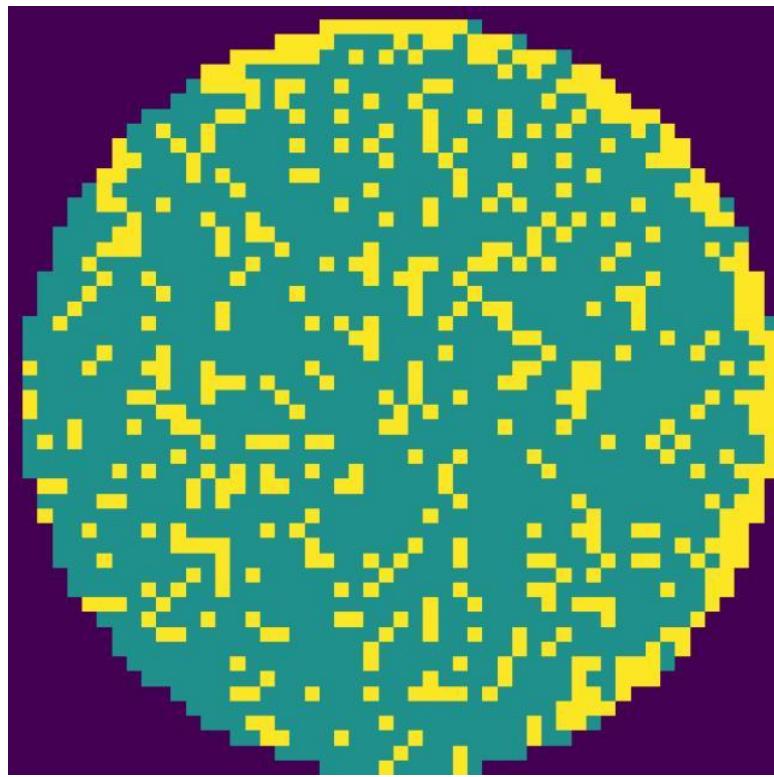
Defect Class: Edge-Loc

Confidence Score: 0.9999

Defect Percentage: 48.70%

Reason: Defect Percentage: 48.7% (>40% threshold), Defect Class: Edge-Loc, Confidence: 99.99%

Wafer Defect Image:



Wafer 32 Inspection Decision

Wafer ID: Thermal_THERM_02_W0004

Decision: PASS

Machine Type: Thermal

Machine ID: THERM_02

Timestamp: 2025-12-27T12:05:17.282335

Simulation Date: 2025-12-27

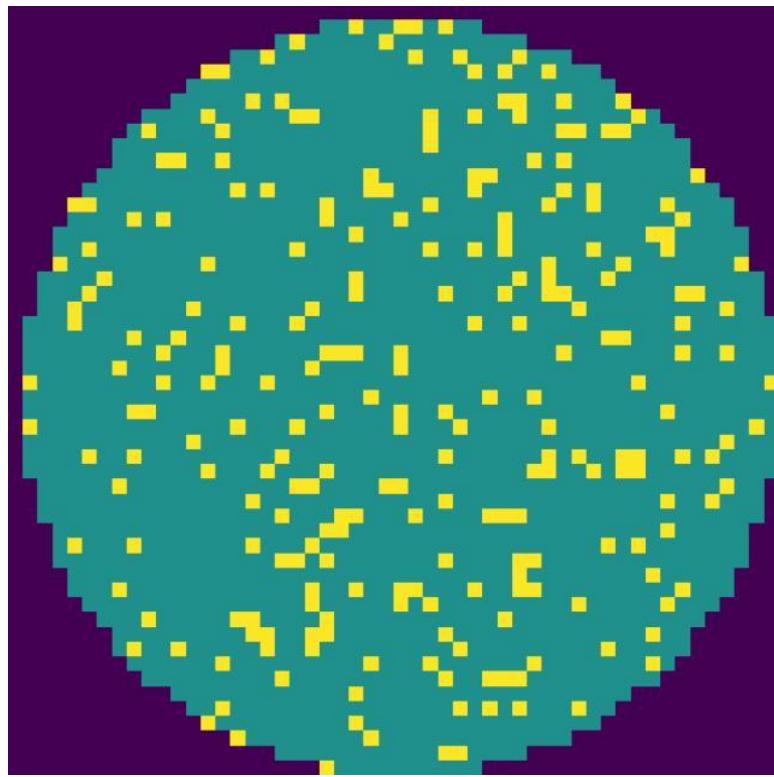
Defect Class: Normal

Confidence Score: 0.9999

Defect Percentage: 38.54%

Reason: Defect Percentage: 38.54% (<=40% threshold), Defect Class: Normal, Confidence: 99.99%

Wafer Defect Image:



Wafer 33 Inspection Decision

Wafer ID: Mechanical_MECH_02_W0006

Decision: FAIL

Machine Type: Mechanical

Machine ID: MECH_02

Timestamp: 2025-12-27T12:05:18.053274

Simulation Date: 2025-12-27

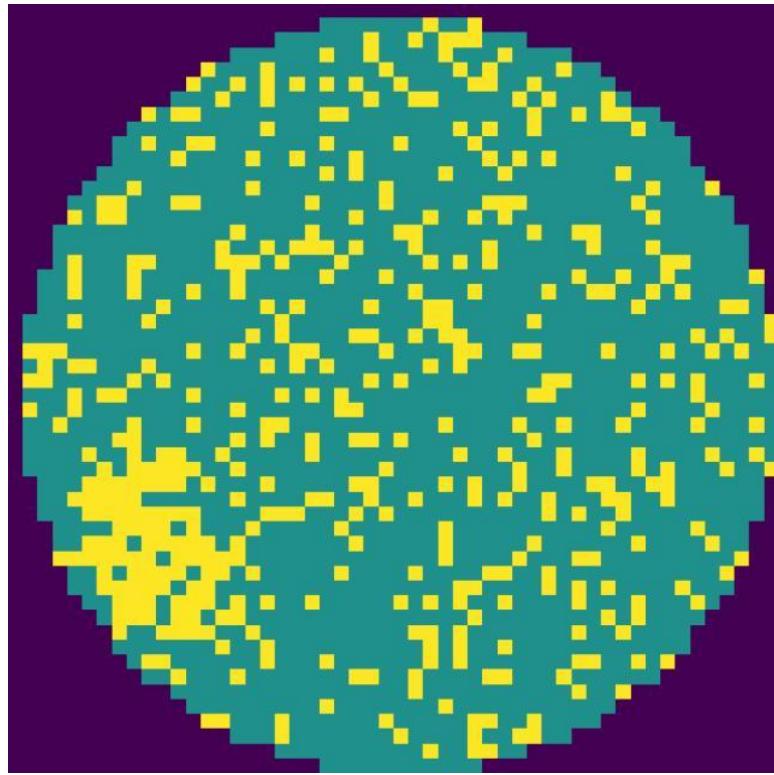
Defect Class: Local

Confidence Score: 1.0000

Defect Percentage: 45.35%

Reason: Defect Percentage: 45.35% (>40% threshold), Defect Class: Local, Confidence: 100.00%

Wafer Defect Image:



Wafer 34 Inspection Decision

Wafer ID: Electrical_ELEC_02_W0007

Decision: FAIL

Machine Type: Electrical

Machine ID: ELEC_02

Timestamp: 2025-12-27T12:05:19.803333

Simulation Date: 2025-12-27

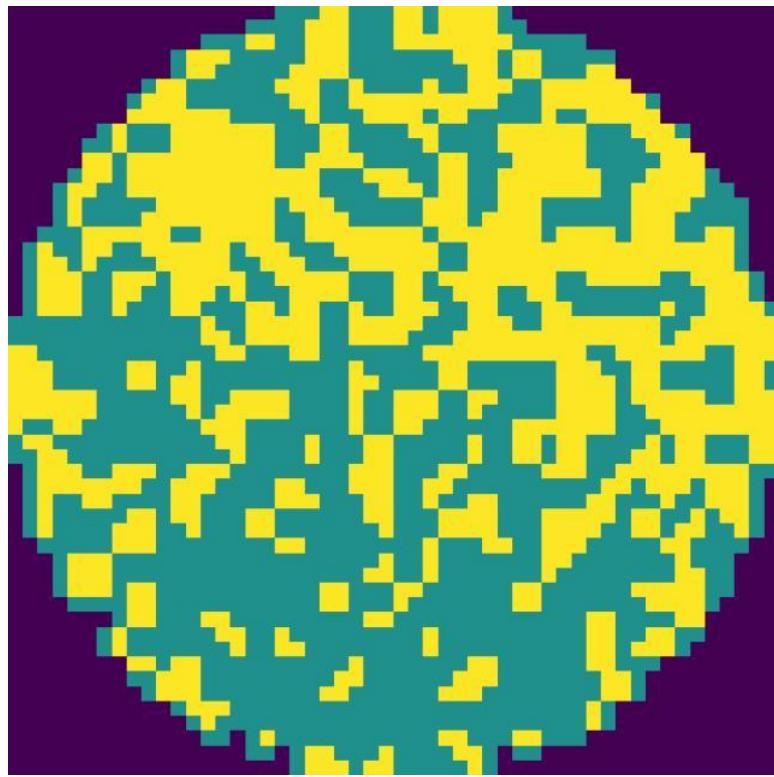
Defect Class: Random

Confidence Score: 0.9999

Defect Percentage: 73.27%

Reason: Defect Percentage: 73.27% (>40% threshold), Defect Class: Random, Confidence: 99.99%

Wafer Defect Image:



Wafer 35 Inspection Decision

Wafer ID: Mechanical_MECH_01_W0006

Decision: FAIL

Machine Type: Mechanical

Machine ID: MECH_01

Timestamp: 2025-12-27T12:05:20.402885

Simulation Date: 2025-12-27

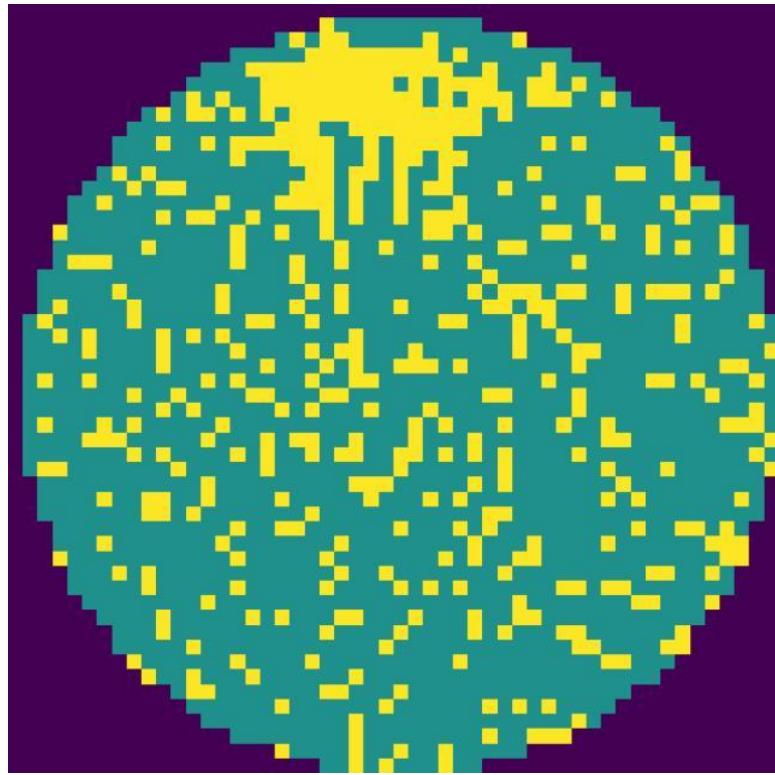
Defect Class: Local

Confidence Score: 1.0000

Defect Percentage: 48.94%

Reason: Defect Percentage: 48.94% (>40% threshold), Defect Class: Local, Confidence: 100.00%

Wafer Defect Image:



Wafer 36 Inspection Decision

Wafer ID: Electrical_ELEC_01_W0007

Decision: PASS

Machine Type: Electrical

Machine ID: ELEC_01

Timestamp: 2025-12-27T12:05:20.435388

Simulation Date: 2025-12-27

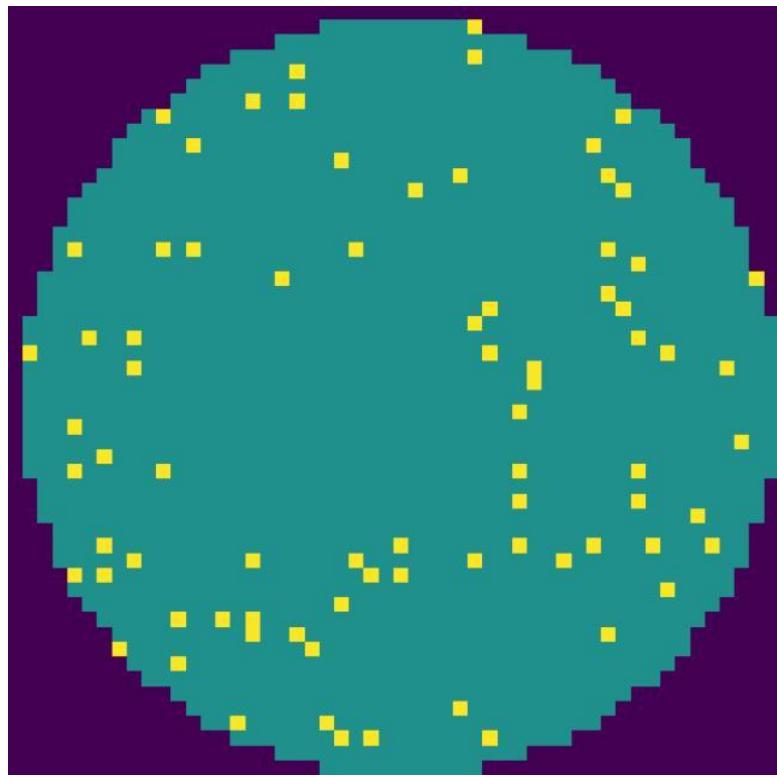
Defect Class: Normal

Confidence Score: 0.9998

Defect Percentage: 31.81%

Reason: Defect Percentage: 31.81% (<=40% threshold), Defect Class: Normal, Confidence: 99.98%

Wafer Defect Image:



Wafer 37 Inspection Decision

Wafer ID: Thermal_THERM_01_W0007

Decision: PASS

Machine Type: Thermal

Machine ID: THERM_01

Timestamp: 2025-12-27T12:05:23.681753

Simulation Date: 2025-12-27

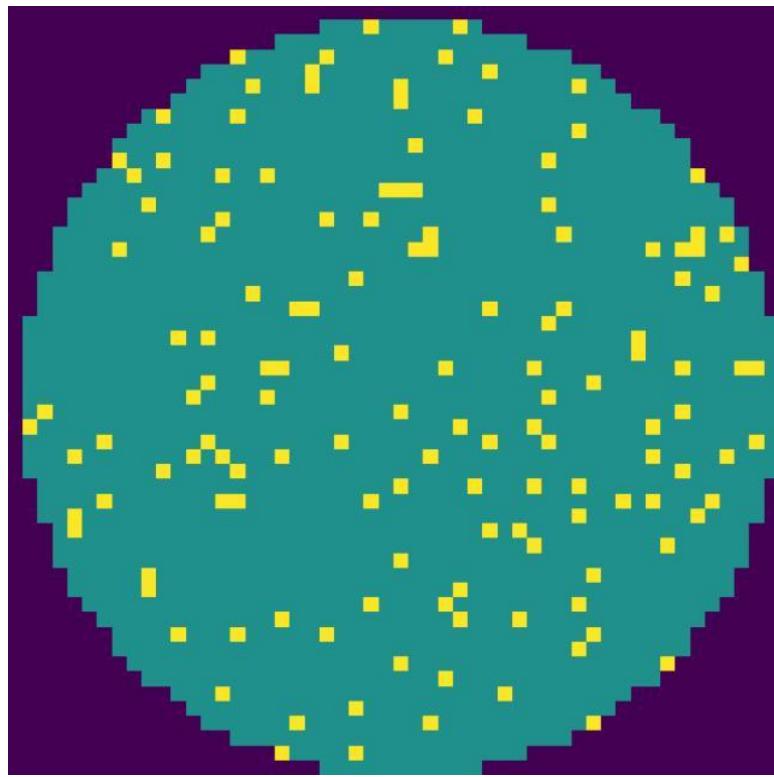
Defect Class: Normal

Confidence Score: 0.9999

Defect Percentage: 33.69%

Reason: Defect Percentage: 33.69% (<=40% threshold), Defect Class: Normal, Confidence: 99.99%

Wafer Defect Image:



Wafer 38 Inspection Decision

Wafer ID: Mechanical_MECH_02_W0007

Decision: FAIL

Machine Type: Mechanical

Machine ID: MECH_02

Timestamp: 2025-12-27T12:05:23.952339

Simulation Date: 2025-12-27

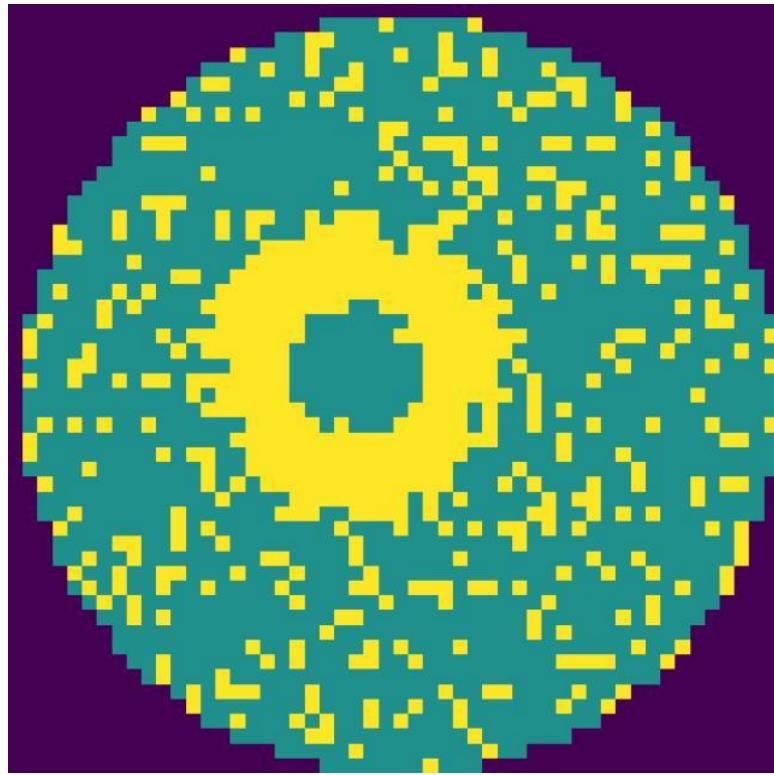
Defect Class: Donut

Confidence Score: 0.9997

Defect Percentage: 57.79%

Reason: Defect Percentage: 57.79% (>40% threshold), Defect Class: Donut, Confidence: 99.97%

Wafer Defect Image:



Wafer 39 Inspection Decision

Wafer ID: Electrical_ELEC_02_W0008

Decision: PASS

Machine Type: Electrical

Machine ID: ELEC_02

Timestamp: 2025-12-27T12:05:25.065850

Simulation Date: 2025-12-27

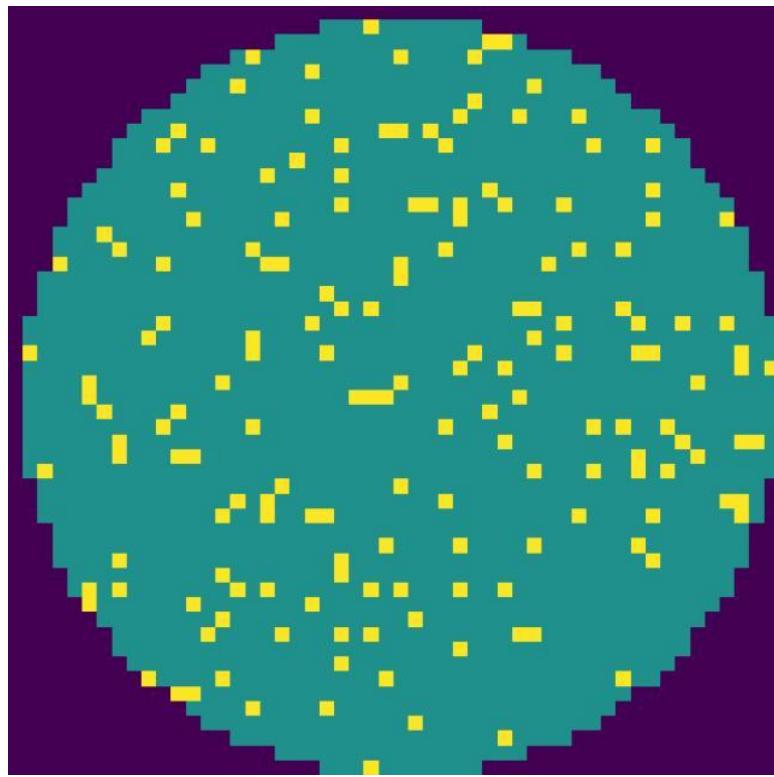
Defect Class: Normal

Confidence Score: 0.9999

Defect Percentage: 35.60%

Reason: Defect Percentage: 35.6% (<=40% threshold), Defect Class: Normal, Confidence: 99.99%

Wafer Defect Image:



Wafer 40 Inspection Decision

Wafer ID: Electrical_ELEC_01_W0008

Decision: FAIL

Machine Type: Electrical

Machine ID: ELEC_01

Timestamp: 2025-12-27T12:05:25.674798

Simulation Date: 2025-12-27

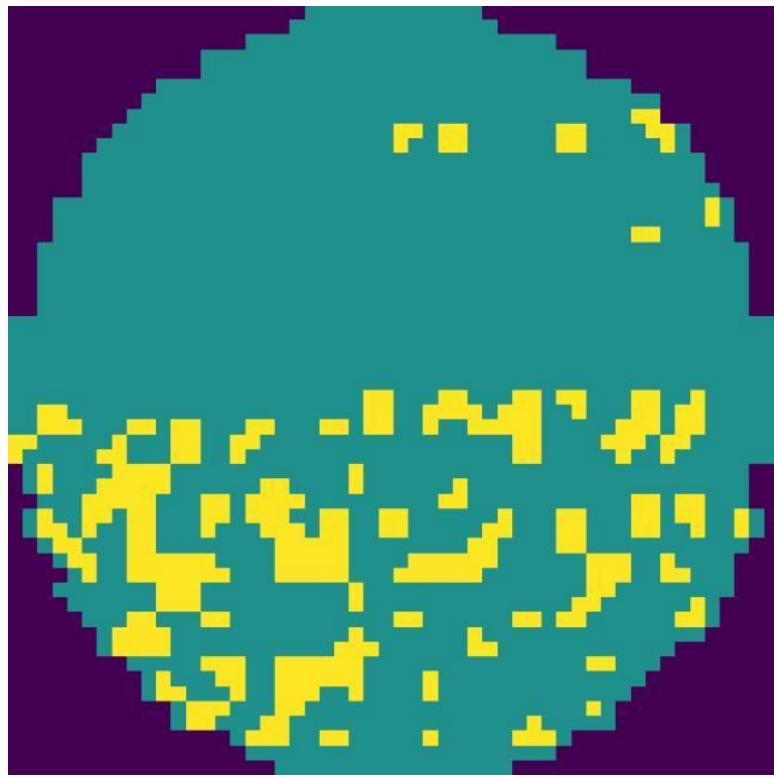
Defect Class: Random

Confidence Score: 0.9808

Defect Percentage: 62.73%

Reason: Defect Percentage: 62.73% (>40% threshold), Defect Class: Random, Confidence: 98.08%

Wafer Defect Image:



Wafer 41 Inspection Decision

Wafer ID: Mechanical_MECH_01_W0007

Decision: FAIL

Machine Type: Mechanical

Machine ID: MECH_01

Timestamp: 2025-12-27T12:05:27.352415

Simulation Date: 2025-12-27

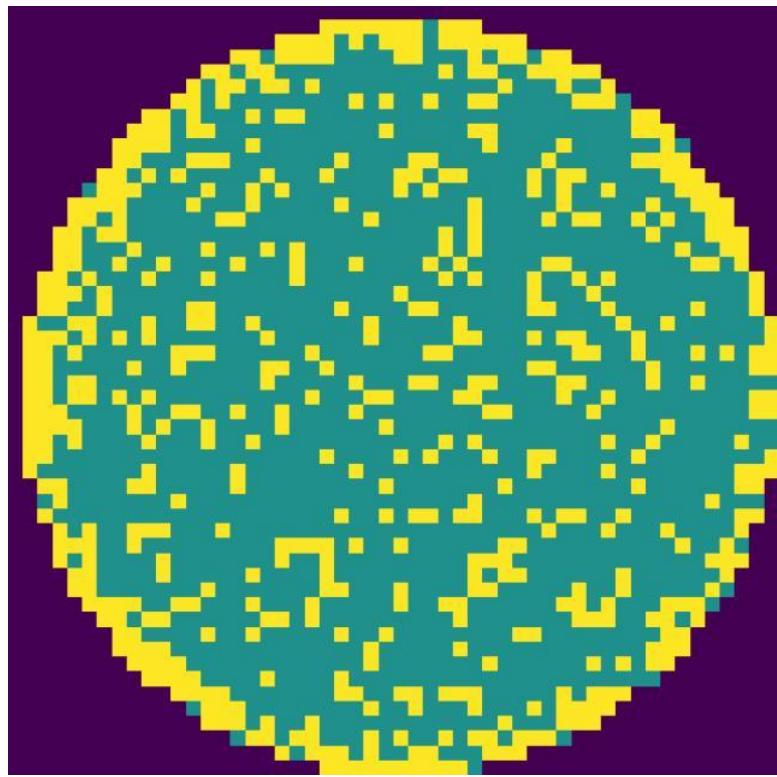
Defect Class: Edge-Ring

Confidence Score: 0.9940

Defect Percentage: 54.68%

Reason: Defect Percentage: 54.68% (>40% threshold), Defect Class: Edge-Ring, Confidence: 99.40%

Wafer Defect Image:



Wafer 42 Inspection Decision

Wafer ID: Thermal_THERM_02_W0005

Decision: PASS

Machine Type: Thermal

Machine ID: THERM_02

Timestamp: 2025-12-27T12:05:28.720322

Simulation Date: 2025-12-27

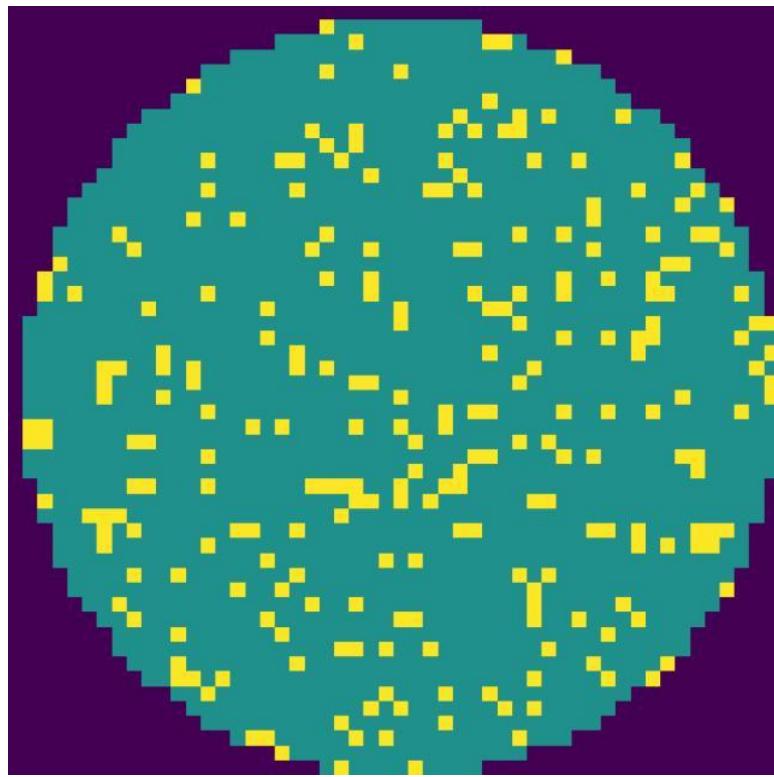
Defect Class: Normal

Confidence Score: 0.9999

Defect Percentage: 39.60%

Reason: Defect Percentage: 39.6% (<=40% threshold), Defect Class: Normal, Confidence: 99.99%

Wafer Defect Image:



Wafer 43 Inspection Decision

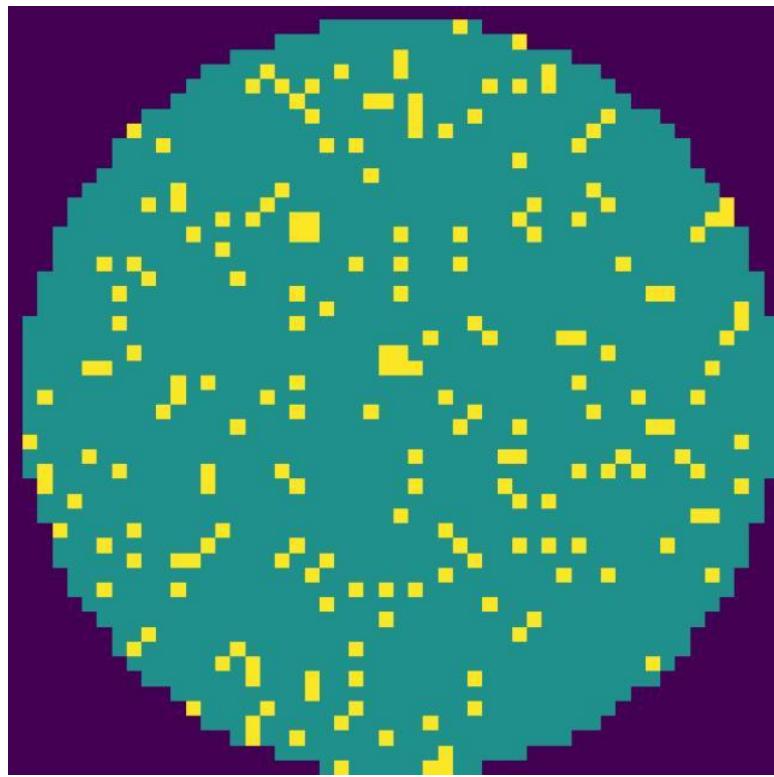
Wafer ID: Mechanical_MECH_02_W0008
Decision: PASS

Machine Type: Mechanical
Machine ID: MECH_02
Timestamp: 2025-12-27T12:05:30.062679
Simulation Date: 2025-12-27

Defect Class: Normal
Confidence Score: 0.9997
Defect Percentage: 36.26%

Reason: Defect Percentage: 36.26% (<=40% threshold), Defect Class: Normal, Confidence: 99.97%

Wafer Defect Image:



Wafer 44 Inspection Decision

Wafer ID: Electrical_ELEC_02_W0009

Decision: PASS

Machine Type: Electrical

Machine ID: ELEC_02

Timestamp: 2025-12-27T12:05:30.618248

Simulation Date: 2025-12-27

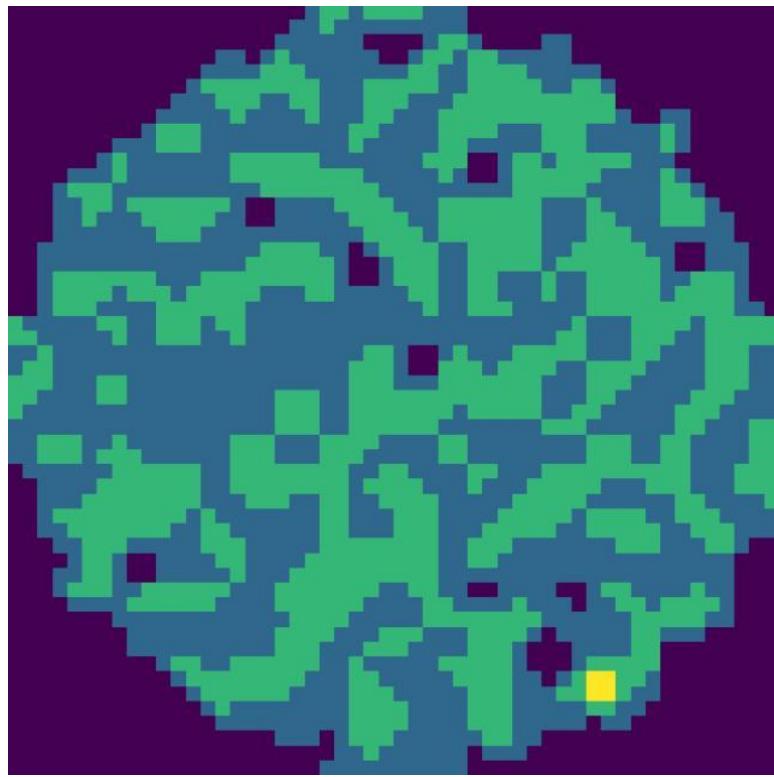
Defect Class: Random

Confidence Score: 0.9999

Defect Percentage: 0.36%

Reason: Defect Percentage: 0.36% (<=40% threshold), Defect Class: Random, Confidence: 99.99%

Wafer Defect Image:



Wafer 45 Inspection Decision

Wafer ID: Electrical_ELEC_01_W0009

Decision: PASS

Machine Type: Electrical

Machine ID: ELEC_01

Timestamp: 2025-12-27T12:05:30.853988

Simulation Date: 2025-12-27

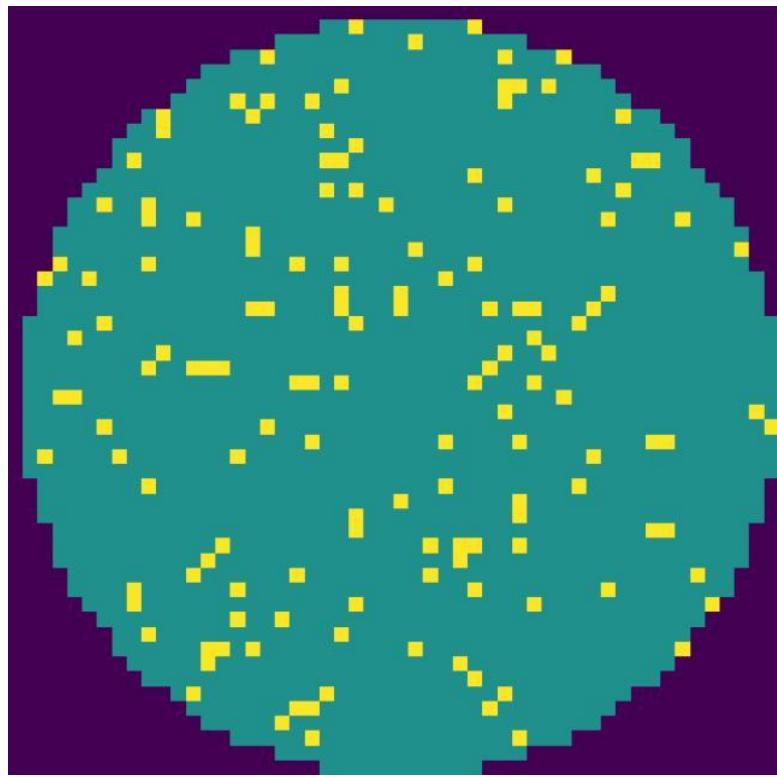
Defect Class: Normal

Confidence Score: 0.9998

Defect Percentage: 35.77%

Reason: Defect Percentage: 35.77% (<=40% threshold), Defect Class: Normal, Confidence: 99.98%

Wafer Defect Image:



Wafer 46 Inspection Decision

Wafer ID: Thermal_THERM_01_W0008

Decision: PASS

Machine Type: Thermal

Machine ID: THERM_01

Timestamp: 2025-12-27T12:05:33.978257

Simulation Date: 2025-12-27

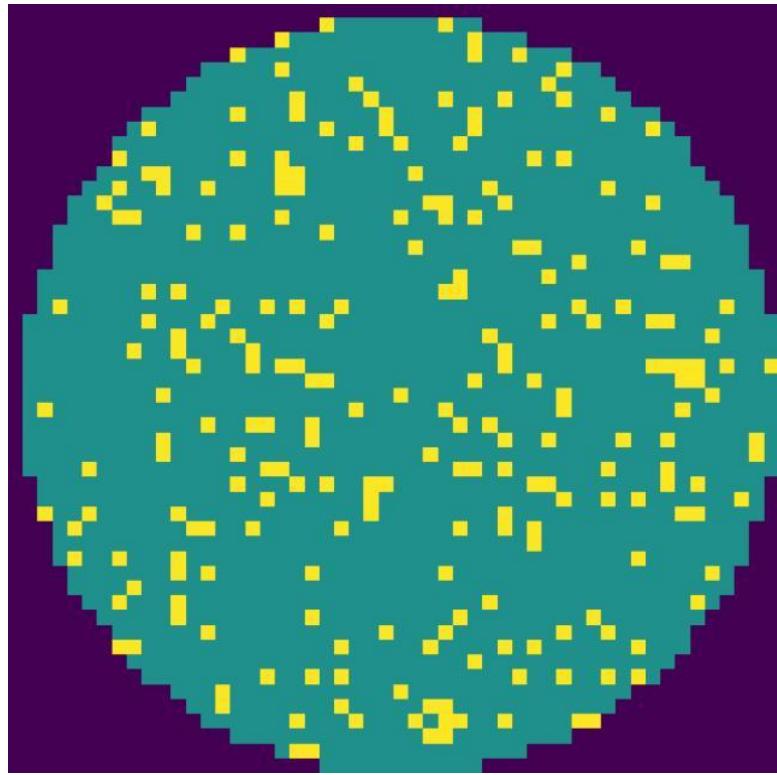
Defect Class: Normal

Confidence Score: 0.9999

Defect Percentage: 37.45%

Reason: Defect Percentage: 37.45% (<=40% threshold), Defect Class: Normal, Confidence: 99.99%

Wafer Defect Image:



Wafer 47 Inspection Decision

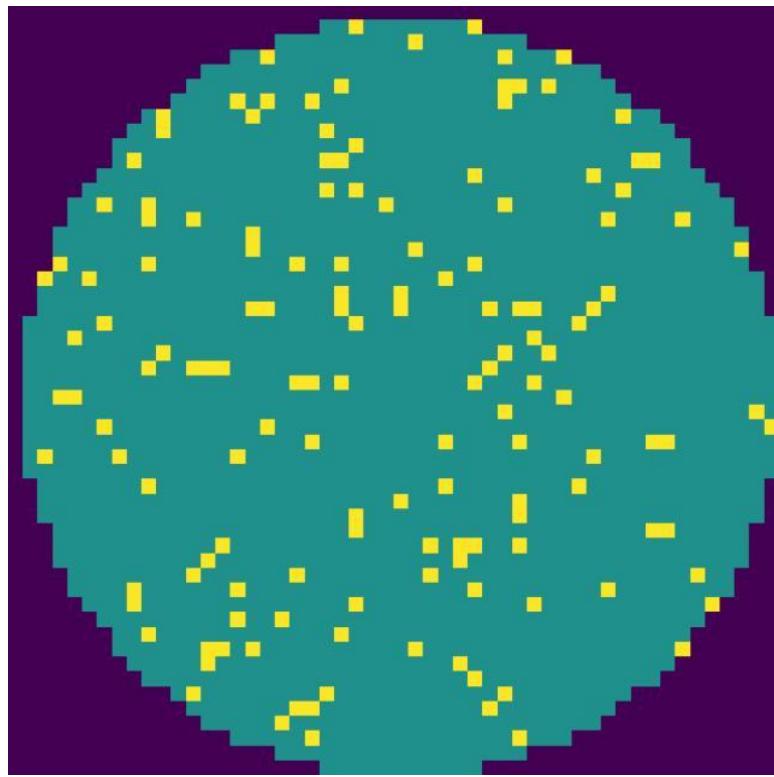
Wafer ID: Mechanical_MECH_01_W0008
Decision: PASS

Machine Type: Mechanical
Machine ID: MECH_01
Timestamp: 2025-12-27T12:05:34.252295
Simulation Date: 2025-12-27

Defect Class: Normal
Confidence Score: 0.9998
Defect Percentage: 35.77%

Reason: Defect Percentage: 35.77% (<=40% threshold), Defect Class: Normal, Confidence: 99.98%

Wafer Defect Image:



Wafer 48 Inspection Decision

Wafer ID: Thermal_THERM_02_W0006

Decision: FAIL

Machine Type: Thermal

Machine ID: THERM_02

Timestamp: 2025-12-27T12:05:36.119961

Simulation Date: 2025-12-27

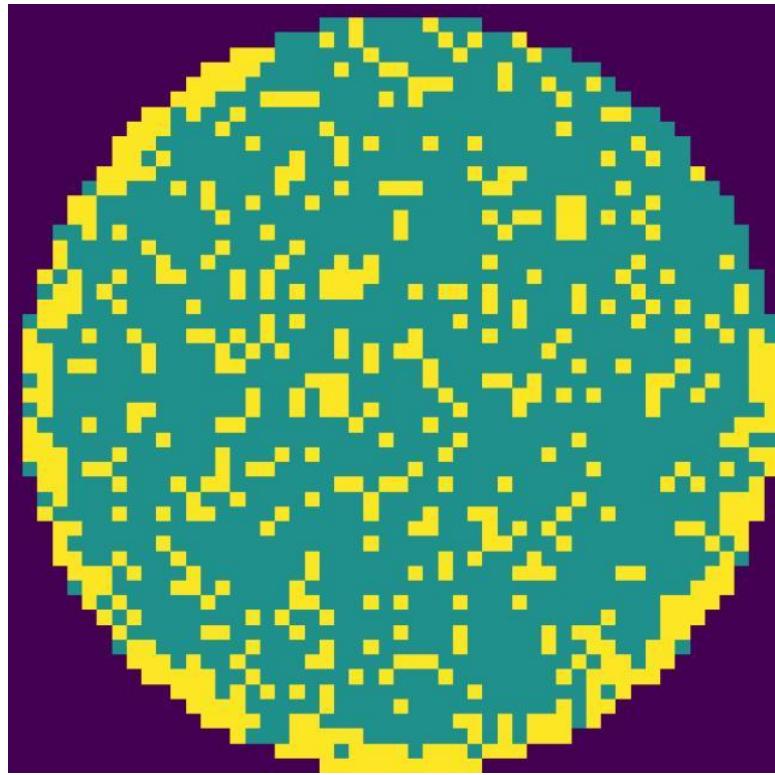
Defect Class: Edge-Loc

Confidence Score: 0.9933

Defect Percentage: 51.32%

Reason: Defect Percentage: 51.32% (>40% threshold), Defect Class: Edge-Loc, Confidence: 99.33%

Wafer Defect Image:



Wafer 49 Inspection Decision

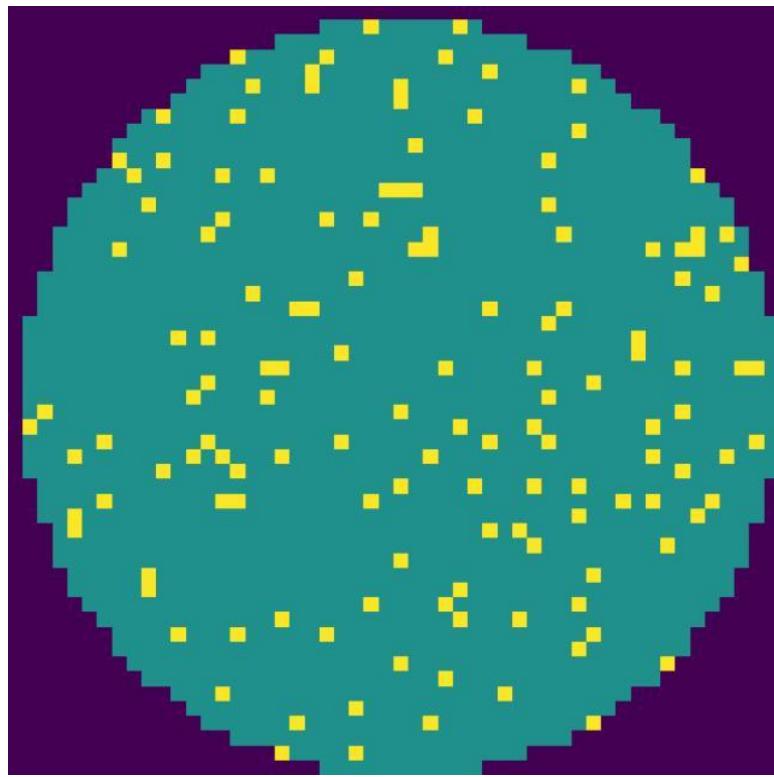
Wafer ID: Mechanical_MECH_02_W0009
Decision: PASS

Machine Type: Mechanical
Machine ID: MECH_02
Timestamp: 2025-12-27T12:05:36.230835
Simulation Date: 2025-12-27

Defect Class: Normal
Confidence Score: 0.9999
Defect Percentage: 33.69%

Reason: Defect Percentage: 33.69% (<=40% threshold), Defect Class: Normal, Confidence: 99.99%

Wafer Defect Image:



Wafer 50 Inspection Decision

Wafer ID: Electrical_ELEC_01_W0010

Decision: FAIL

Machine Type: Electrical

Machine ID: ELEC_01

Timestamp: 2025-12-27T12:05:36.529291

Simulation Date: 2025-12-27

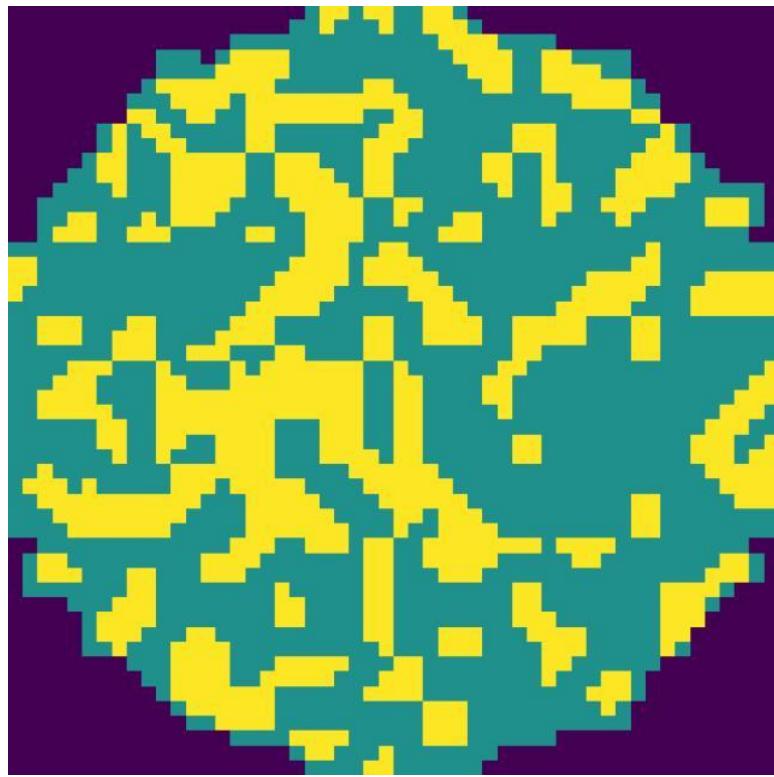
Defect Class: Random

Confidence Score: 0.9999

Defect Percentage: 73.10%

Reason: Defect Percentage: 73.1% (>40% threshold), Defect Class: Random, Confidence: 99.99%

Wafer Defect Image:



Wafer 51 Inspection Decision

Wafer ID: Electrical_ELEC_02_W0010

Decision: PASS

Machine Type: Electrical

Machine ID: ELEC_02

Timestamp: 2025-12-27T12:05:36.546121

Simulation Date: 2025-12-27

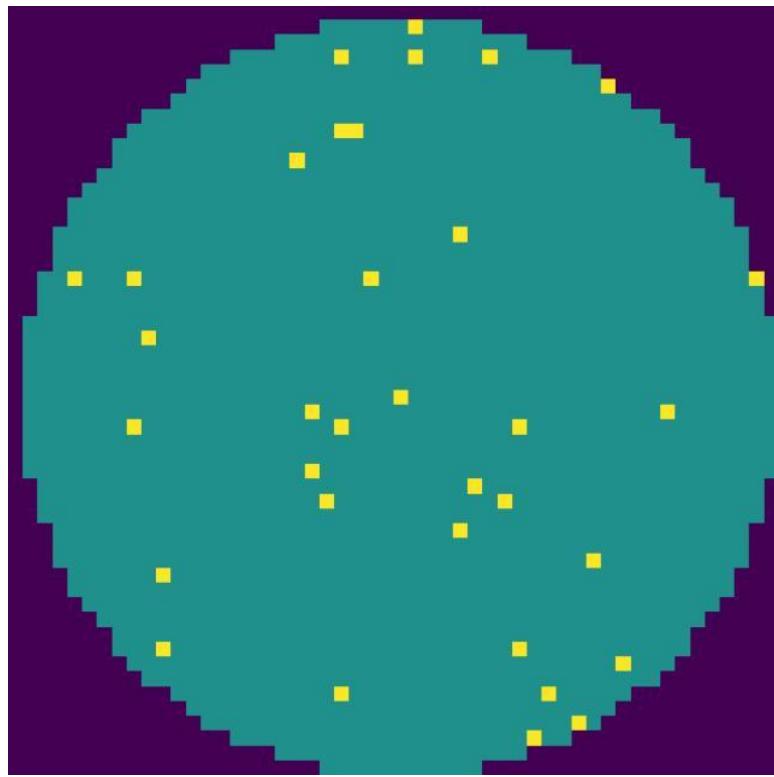
Defect Class: Normal

Confidence Score: 0.9999

Defect Percentage: 33.22%

Reason: Defect Percentage: 33.22% (<=40% threshold), Defect Class: Normal, Confidence: 99.99%

Wafer Defect Image:



Wafer 52 Inspection Decision

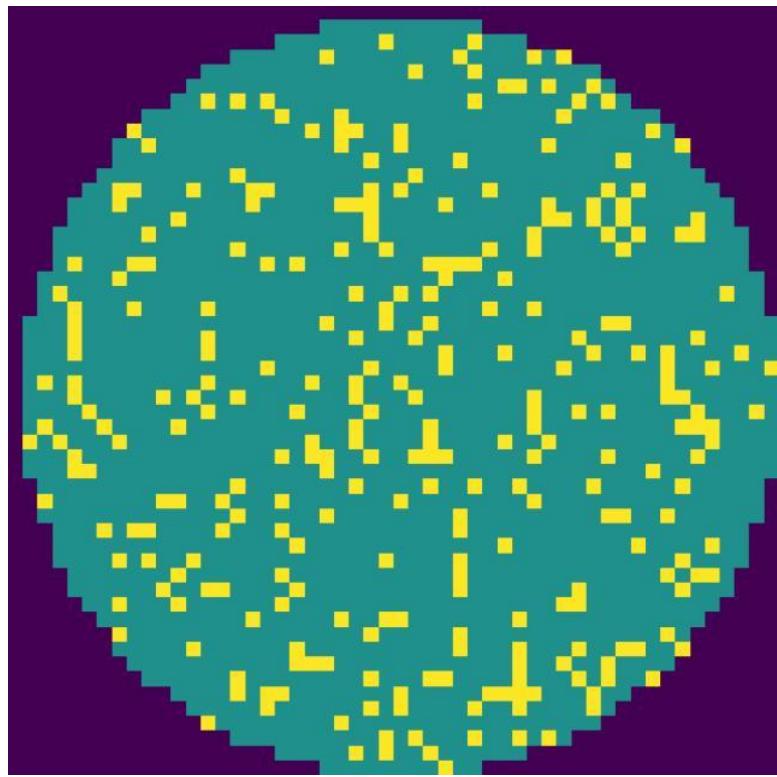
Wafer ID: Mechanical_MECH_01_W0009
Decision: PASS

Machine Type: Mechanical
Machine ID: MECH_01
Timestamp: 2025-12-27T12:05:41.435925
Simulation Date: 2025-12-27

Defect Class: Normal
Confidence Score: 0.9991
Defect Percentage: 38.98%

Reason: Defect Percentage: 38.98% (<=40% threshold), Defect Class: Normal, Confidence: 99.91%

Wafer Defect Image:



Wafer 53 Inspection Decision

Wafer ID: Thermal_THERM_01_W0009

Decision: PASS

Machine Type: Thermal

Machine ID: THERM_01

Timestamp: 2025-12-27T12:05:41.758738

Simulation Date: 2025-12-27

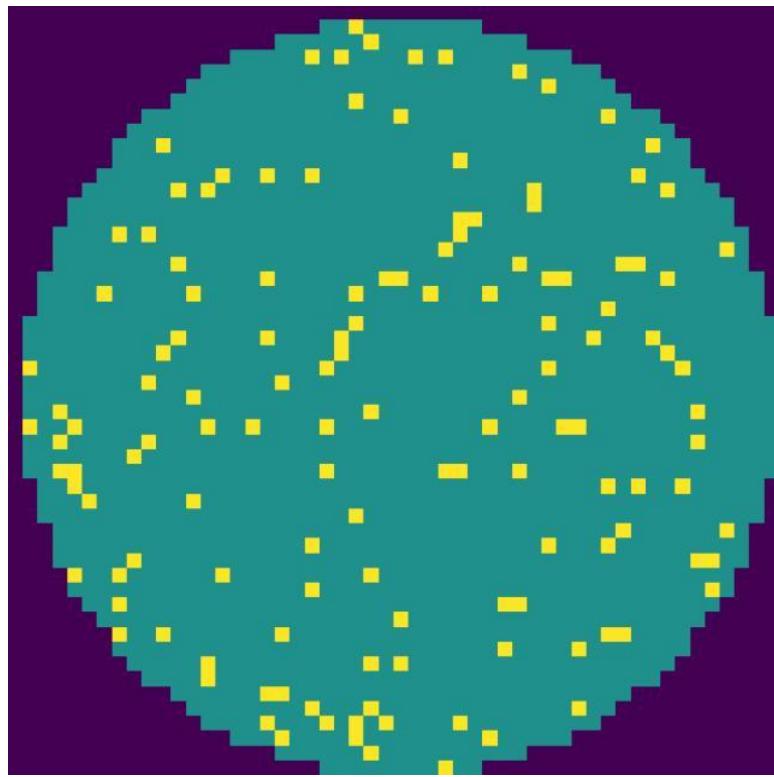
Defect Class: Normal

Confidence Score: 0.9996

Defect Percentage: 33.89%

Reason: Defect Percentage: 33.89% (<=40% threshold), Defect Class: Normal, Confidence: 99.96%

Wafer Defect Image:



Wafer 54 Inspection Decision

Wafer ID: Electrical_ELEC_01_W0011

Decision: PASS

Machine Type: Electrical

Machine ID: ELEC_01

Timestamp: 2025-12-27T12:05:41.793896

Simulation Date: 2025-12-27

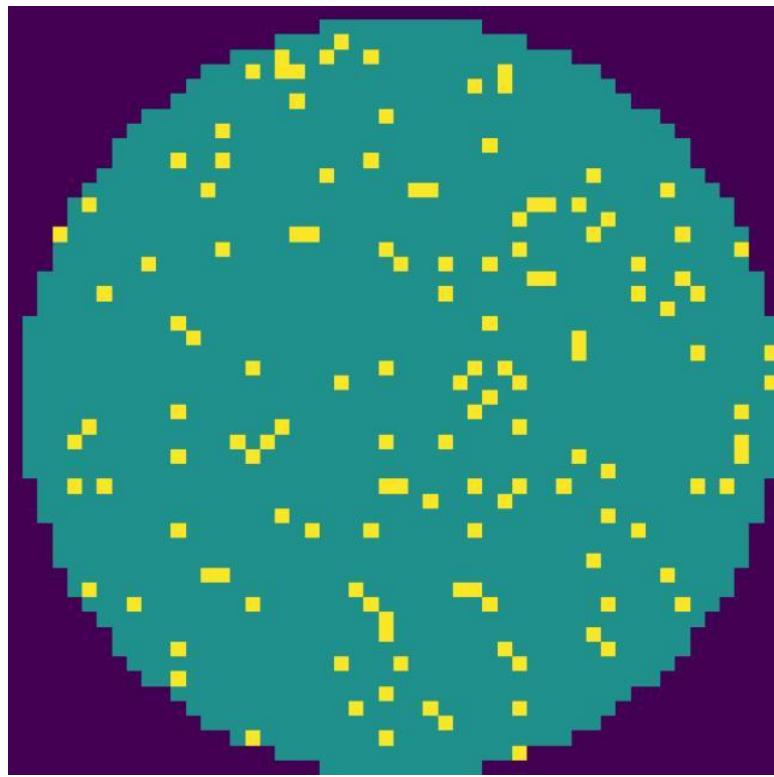
Defect Class: Normal

Confidence Score: 0.9998

Defect Percentage: 33.52%

Reason: Defect Percentage: 33.52% (<=40% threshold), Defect Class: Normal, Confidence: 99.98%

Wafer Defect Image:



Wafer 55 Inspection Decision

Wafer ID: Electrical_ELEC_02_W0011

Decision: PASS

Machine Type: Electrical

Machine ID: ELEC_02

Timestamp: 2025-12-27T12:05:42.370591

Simulation Date: 2025-12-27

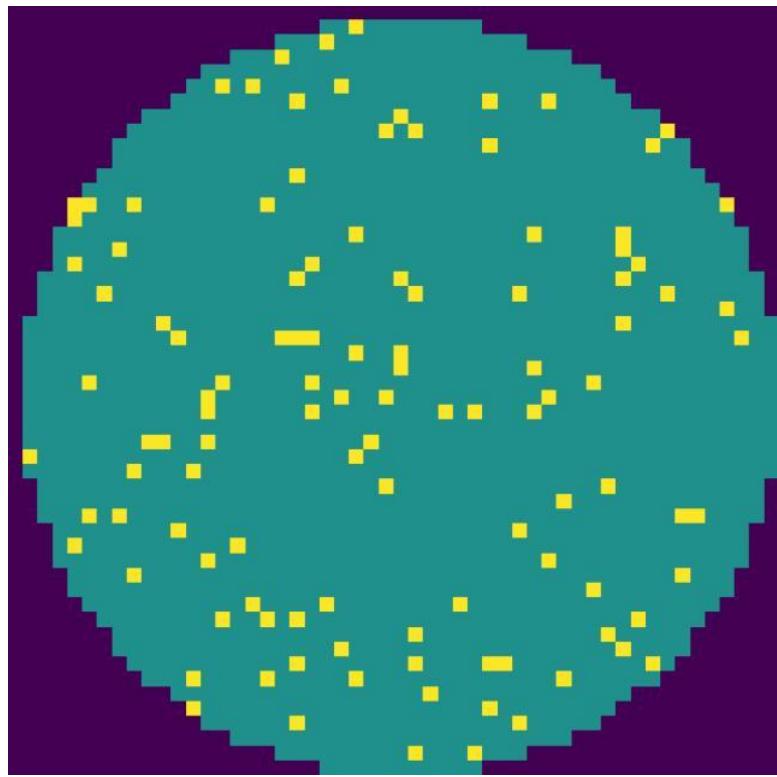
Defect Class: Normal

Confidence Score: 0.9998

Defect Percentage: 33.44%

Reason: Defect Percentage: 33.44% (<=40% threshold), Defect Class: Normal, Confidence: 99.98%

Wafer Defect Image:



Wafer 56 Inspection Decision

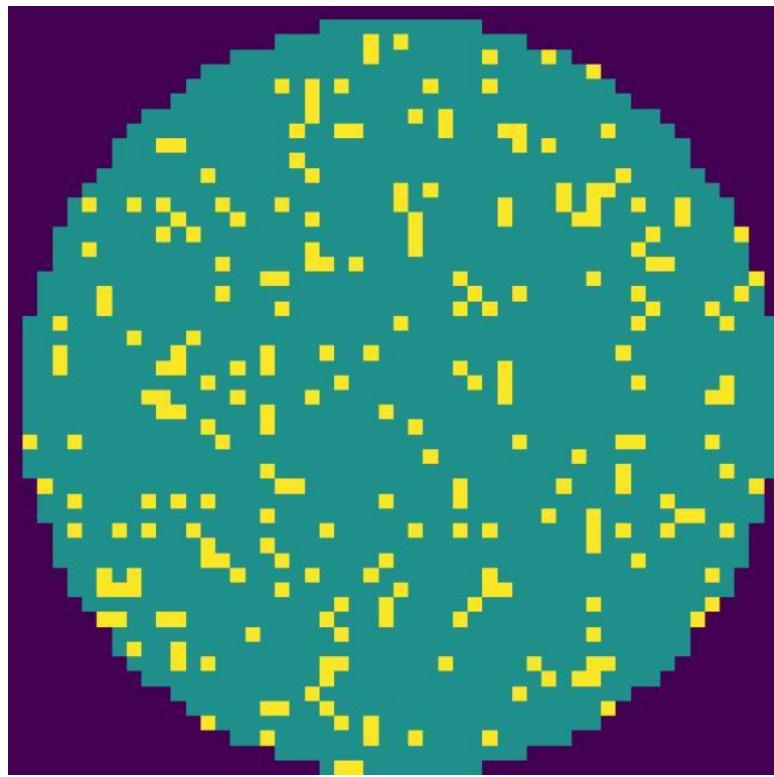
Wafer ID: Mechanical_MECH_02_W0010
Decision: PASS

Machine Type: Mechanical
Machine ID: MECH_02
Timestamp: 2025-12-27T12:05:43.938247
Simulation Date: 2025-12-27

Defect Class: Normal
Confidence Score: 0.9998
Defect Percentage: 38.44%

Reason: Defect Percentage: 38.44% (<=40% threshold), Defect Class: Normal, Confidence: 99.98%

Wafer Defect Image:



Wafer 57 Inspection Decision

Wafer ID: Thermal_THERM_02_W0007

Decision: FAIL

Machine Type: Thermal

Machine ID: THERM_02

Timestamp: 2025-12-27T12:05:45.940390

Simulation Date: 2025-12-27

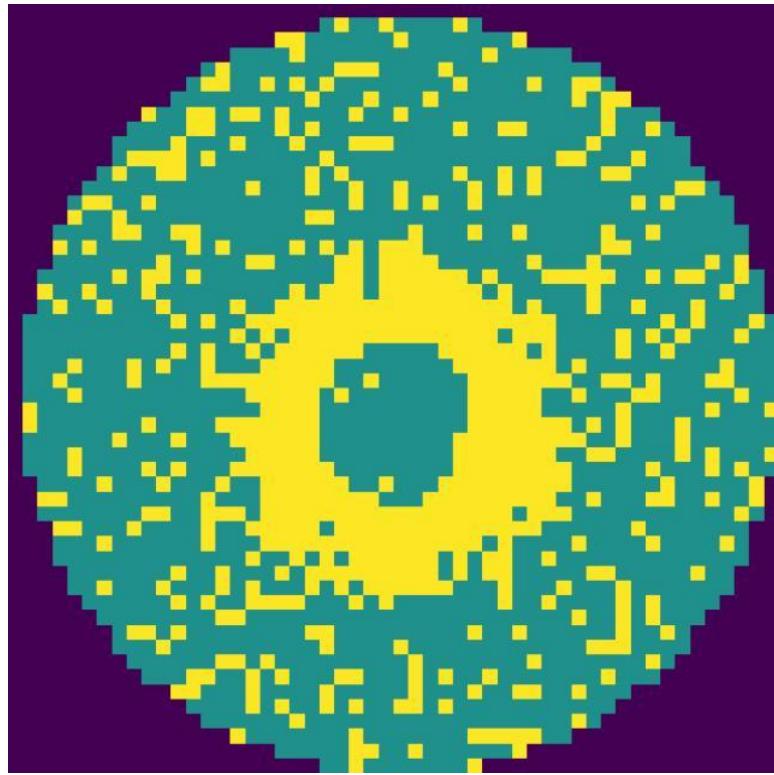
Defect Class: Donut

Confidence Score: 1.0000

Defect Percentage: 59.76%

Reason: Defect Percentage: 59.76% (>40% threshold), Defect Class: Donut, Confidence: 100.00%

Wafer Defect Image:



Wafer 58 Inspection Decision

Wafer ID: Electrical_ELEC_01_W0012

Decision: FAIL

Machine Type: Electrical

Machine ID: ELEC_01

Timestamp: 2025-12-27T12:05:46.897439

Simulation Date: 2025-12-27

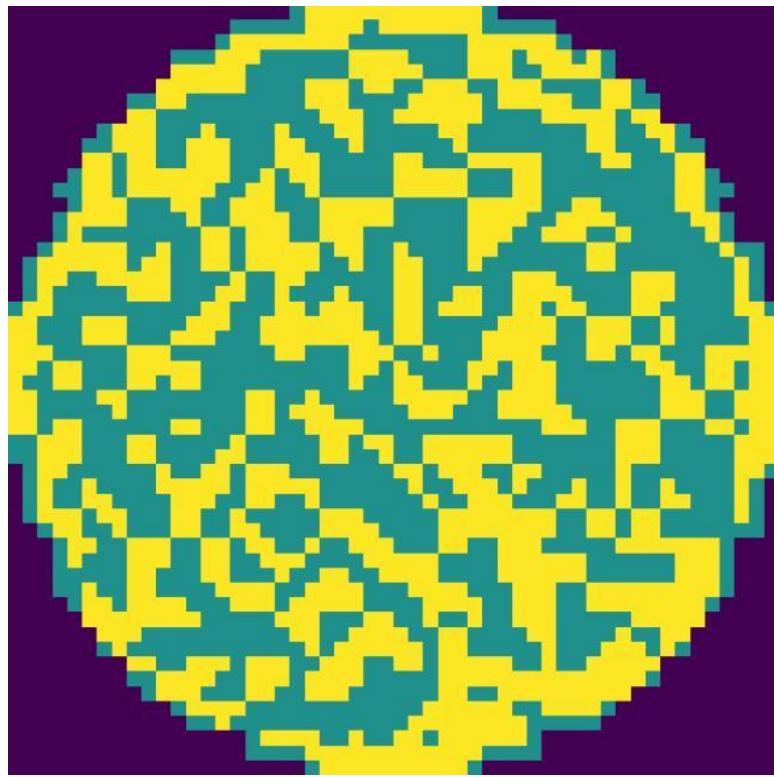
Defect Class: Random

Confidence Score: 0.9998

Defect Percentage: 71.30%

Reason: Defect Percentage: 71.3% (>40% threshold), Defect Class: Random, Confidence: 99.98%

Wafer Defect Image:



Wafer 59 Inspection Decision

Wafer ID: Electrical_ELEC_02_W0012

Decision: PASS

Machine Type: Electrical

Machine ID: ELEC_02

Timestamp: 2025-12-27T12:05:47.599214

Simulation Date: 2025-12-27

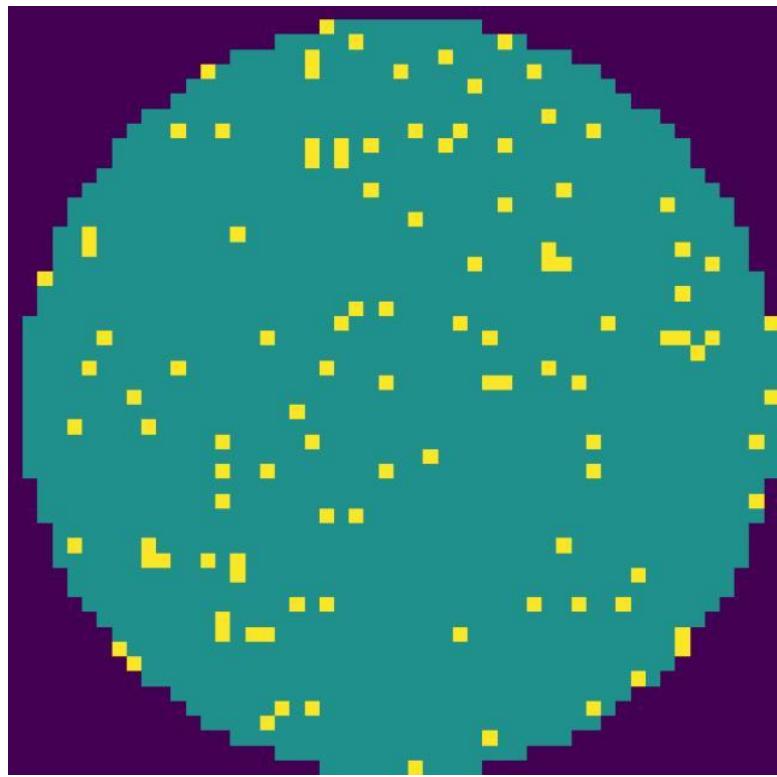
Defect Class: Normal

Confidence Score: 0.9997

Defect Percentage: 35.66%

Reason: Defect Percentage: 35.66% (<=40% threshold), Defect Class: Normal, Confidence: 99.97%

Wafer Defect Image:



Wafer 60 Inspection Decision

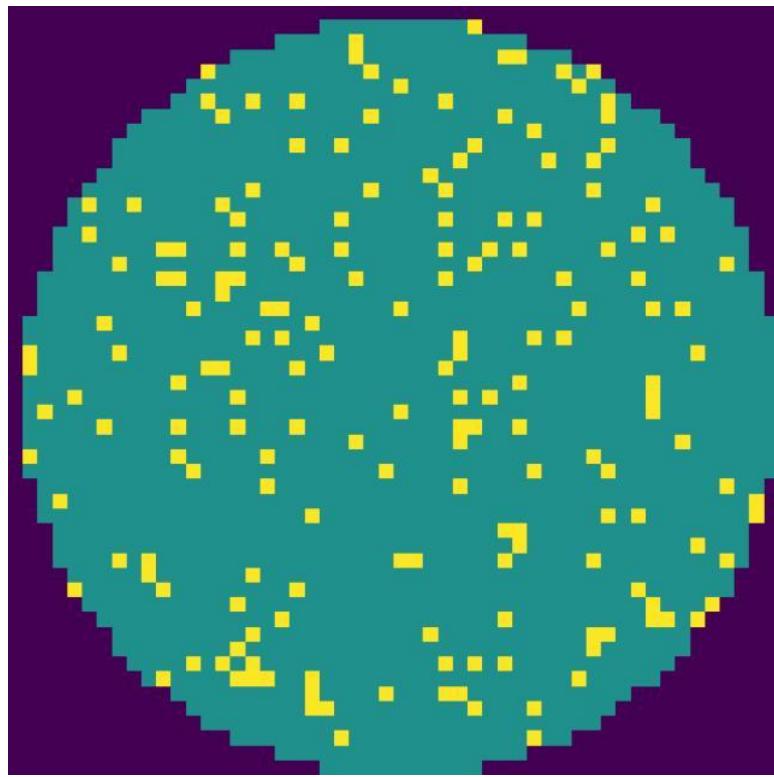
Wafer ID: Mechanical_MECH_01_W0010
Decision: PASS

Machine Type: Mechanical
Machine ID: MECH_01
Timestamp: 2025-12-27T12:05:49.114666
Simulation Date: 2025-12-27

Defect Class: Normal
Confidence Score: 0.9998
Defect Percentage: 35.70%

Reason: Defect Percentage: 35.7% (<=40% threshold), Defect Class: Normal, Confidence: 99.98%

Wafer Defect Image:



Wafer 61 Inspection Decision

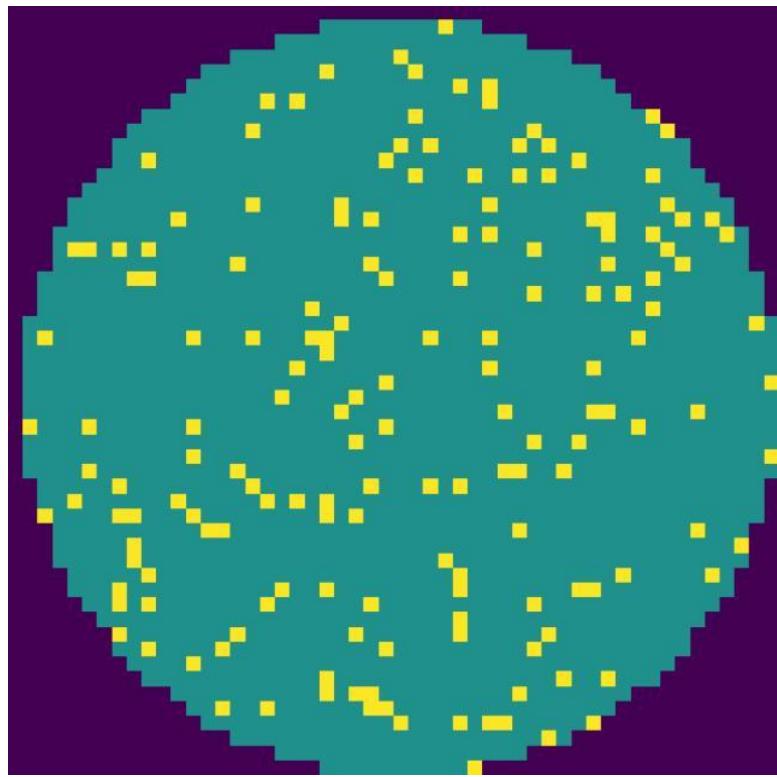
Wafer ID: Mechanical_MECH_02_W0011
Decision: PASS

Machine Type: Mechanical
Machine ID: MECH_02
Timestamp: 2025-12-27T12:05:51.328704
Simulation Date: 2025-12-27

Defect Class: Normal
Confidence Score: 0.9997
Defect Percentage: 35.20%

Reason: Defect Percentage: 35.2% (<=40% threshold), Defect Class: Normal, Confidence: 99.97%

Wafer Defect Image:



Wafer 62 Inspection Decision

Wafer ID: Thermal_THERM_01_W0010

Decision: PASS

Machine Type: Thermal

Machine ID: THERM_01

Timestamp: 2025-12-27T12:05:51.433861

Simulation Date: 2025-12-27

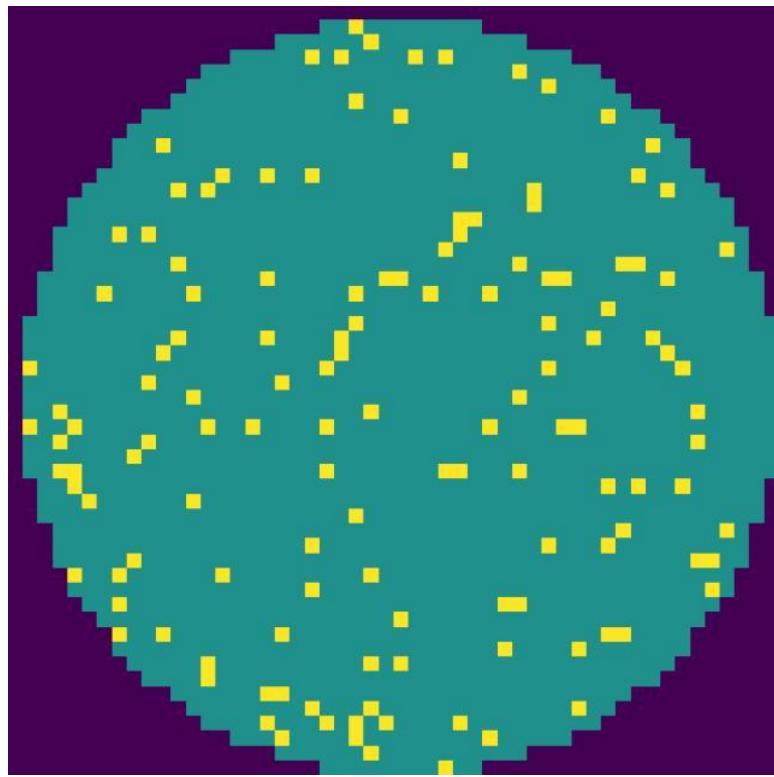
Defect Class: Normal

Confidence Score: 0.9996

Defect Percentage: 33.89%

Reason: Defect Percentage: 33.89% (<=40% threshold), Defect Class: Normal, Confidence: 99.96%

Wafer Defect Image:



Wafer 63 Inspection Decision

Wafer ID: Electrical_ELEC_01_W0013

Decision: PASS

Machine Type: Electrical

Machine ID: ELEC_01

Timestamp: 2025-12-27T12:05:51.978675

Simulation Date: 2025-12-27

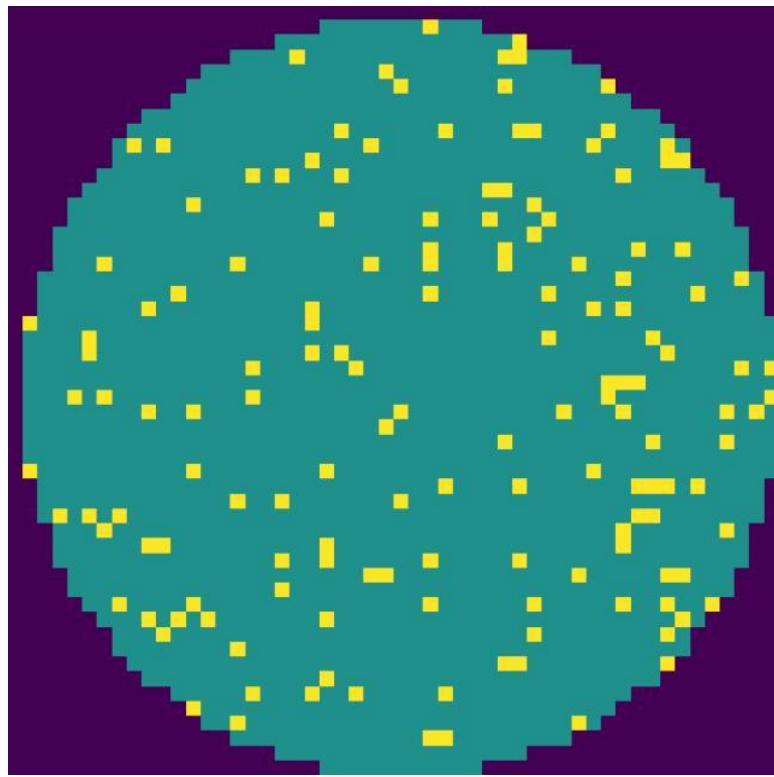
Defect Class: Normal

Confidence Score: 0.9997

Defect Percentage: 35.54%

Reason: Defect Percentage: 35.54% (<=40% threshold), Defect Class: Normal, Confidence: 99.97%

Wafer Defect Image:



Wafer 64 Inspection Decision

Wafer ID: Electrical_ELEC_02_W0013

Decision: PASS

Machine Type: Electrical

Machine ID: ELEC_02

Timestamp: 2025-12-27T12:05:53.053750

Simulation Date: 2025-12-27

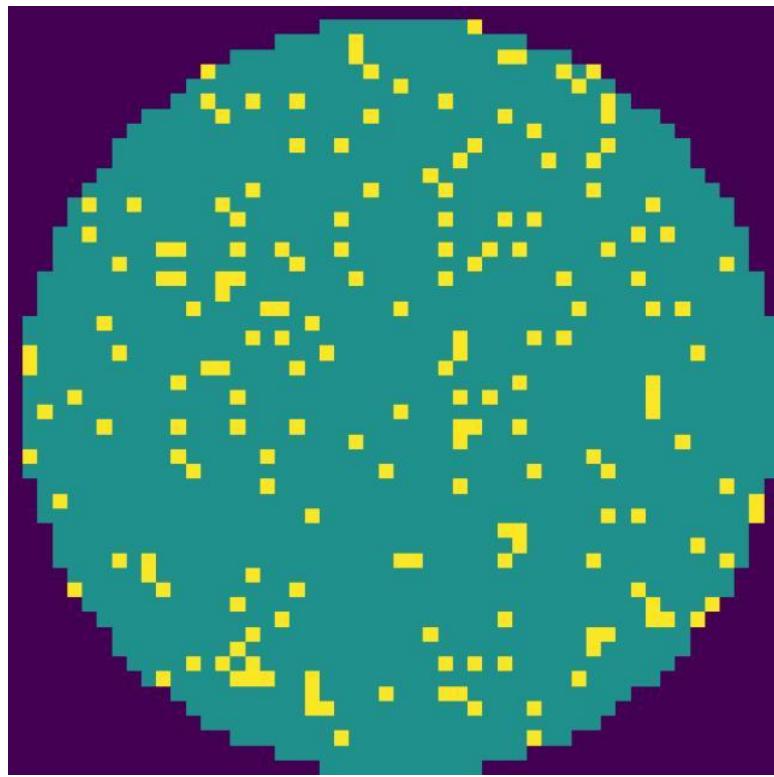
Defect Class: Normal

Confidence Score: 0.9998

Defect Percentage: 35.70%

Reason: Defect Percentage: 35.7% (<=40% threshold), Defect Class: Normal, Confidence: 99.98%

Wafer Defect Image:



Wafer 65 Inspection Decision

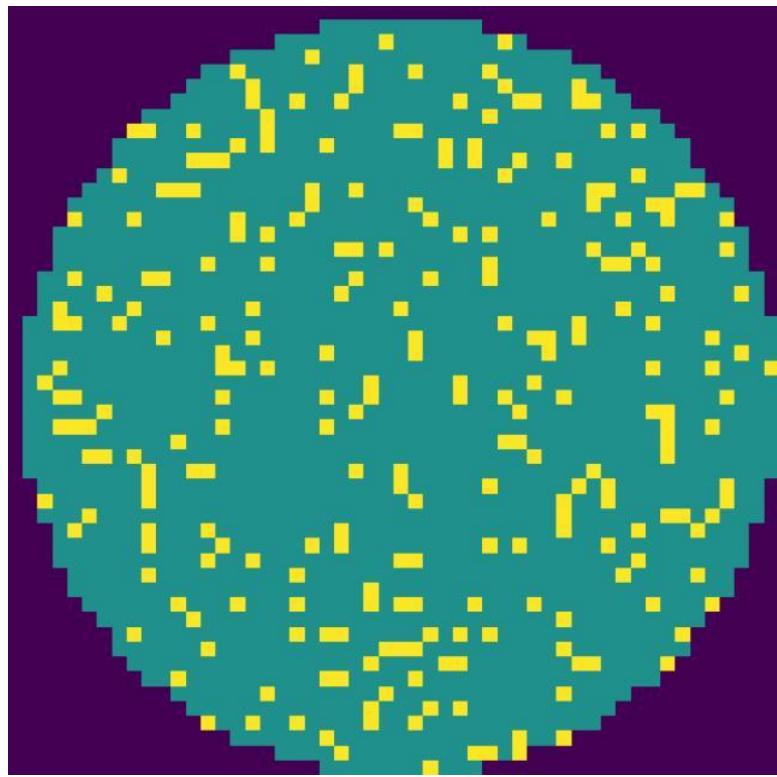
Wafer ID: Mechanical_MECH_01_W0011
Decision: PASS

Machine Type: Mechanical
Machine ID: MECH_01
Timestamp: 2025-12-27T12:05:56.313130
Simulation Date: 2025-12-27

Defect Class: Normal
Confidence Score: 0.9998
Defect Percentage: 38.11%

Reason: Defect Percentage: 38.11% (<=40% threshold), Defect Class: Normal, Confidence: 99.98%

Wafer Defect Image:



Wafer 66 Inspection Decision

Wafer ID: Thermal_THERM_02_W0008

Decision: FAIL

Machine Type: Thermal

Machine ID: THERM_02

Timestamp: 2025-12-27T12:05:57.418650

Simulation Date: 2025-12-27

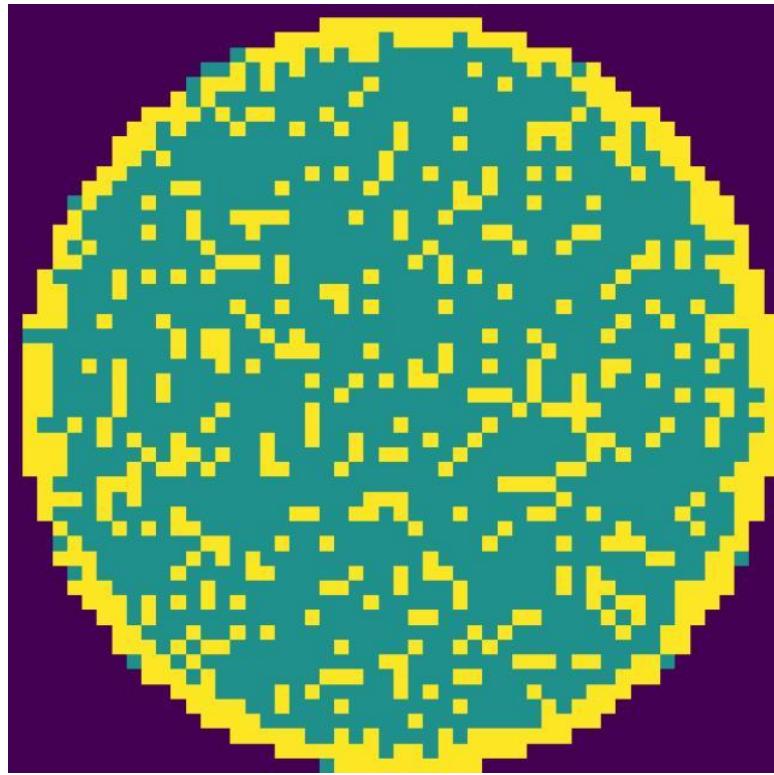
Defect Class: Edge-Ring

Confidence Score: 0.9923

Defect Percentage: 55.67%

Reason: Defect Percentage: 55.67% (>40% threshold), Defect Class: Edge-Ring, Confidence: 99.23%

Wafer Defect Image:



Wafer 67 Inspection Decision

Wafer ID: Electrical_ELEC_01_W0014

Decision: PASS

Machine Type: Electrical

Machine ID: ELEC_01

Timestamp: 2025-12-27T12:05:57.638565

Simulation Date: 2025-12-27

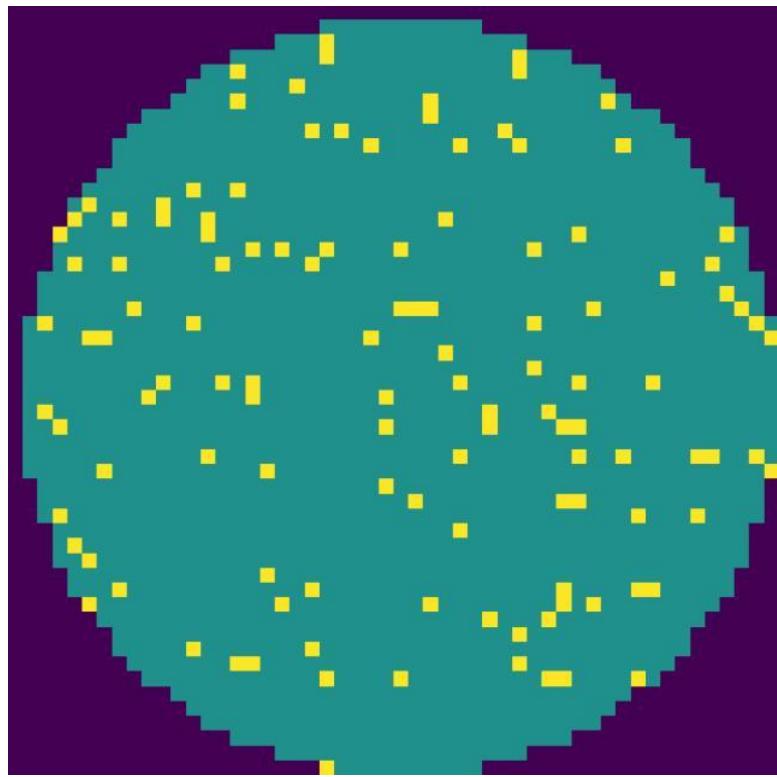
Defect Class: Normal

Confidence Score: 0.9996

Defect Percentage: 35.93%

Reason: Defect Percentage: 35.93% (<=40% threshold), Defect Class: Normal, Confidence: 99.96%

Wafer Defect Image:



Wafer 68 Inspection Decision

Wafer ID: Thermal_THERM_01_W0011

Decision: PASS

Machine Type: Thermal

Machine ID: THERM_01

Timestamp: 2025-12-27T12:05:57.671134

Simulation Date: 2025-12-27

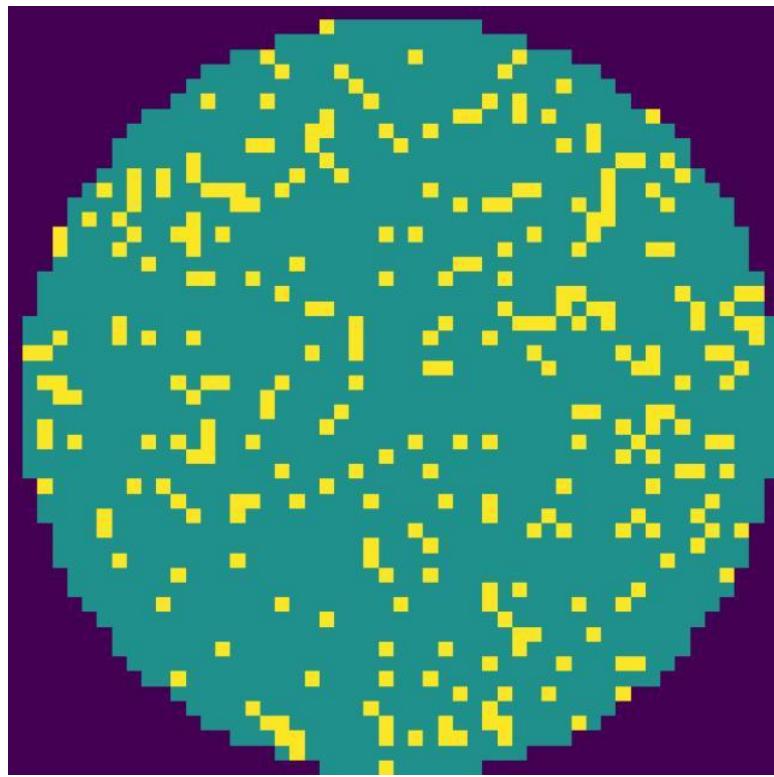
Defect Class: Normal

Confidence Score: 0.9999

Defect Percentage: 38.85%

Reason: Defect Percentage: 38.85% (<=40% threshold), Defect Class: Normal, Confidence: 99.99%

Wafer Defect Image:



Wafer 69 Inspection Decision

Wafer ID: Electrical_ELEC_02_W0014

Decision: PASS

Machine Type: Electrical

Machine ID: ELEC_02

Timestamp: 2025-12-27T12:05:58.388002

Simulation Date: 2025-12-27

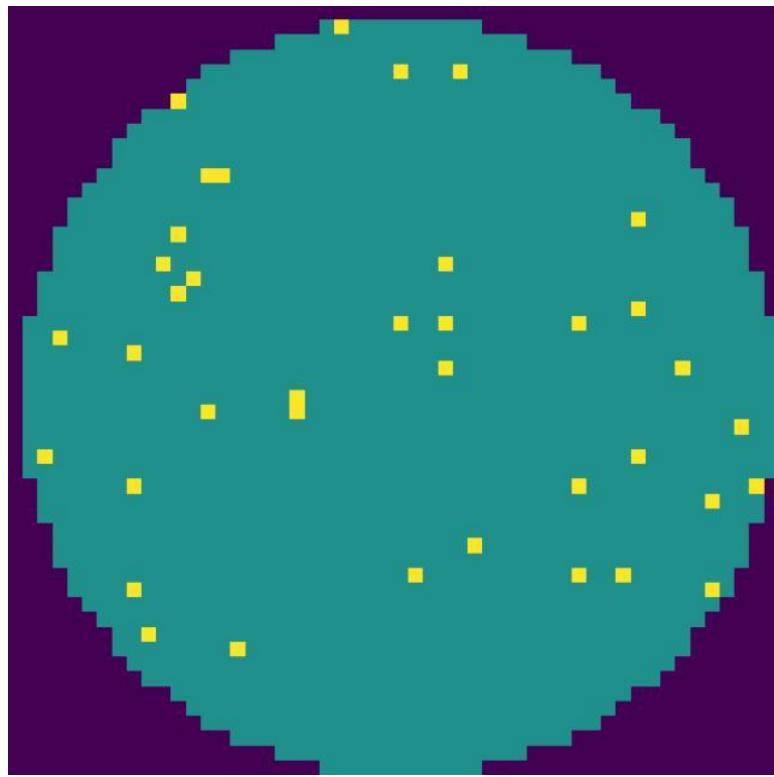
Defect Class: Normal

Confidence Score: 0.9999

Defect Percentage: 33.56%

Reason: Defect Percentage: 33.56% (<=40% threshold), Defect Class: Normal, Confidence: 99.99%

Wafer Defect Image:



Wafer 70 Inspection Decision

Wafer ID: Mechanical_MECH_02_W0012

Decision: FAIL

Machine Type: Mechanical

Machine ID: MECH_02

Timestamp: 2025-12-27T12:05:58.997624

Simulation Date: 2025-12-27

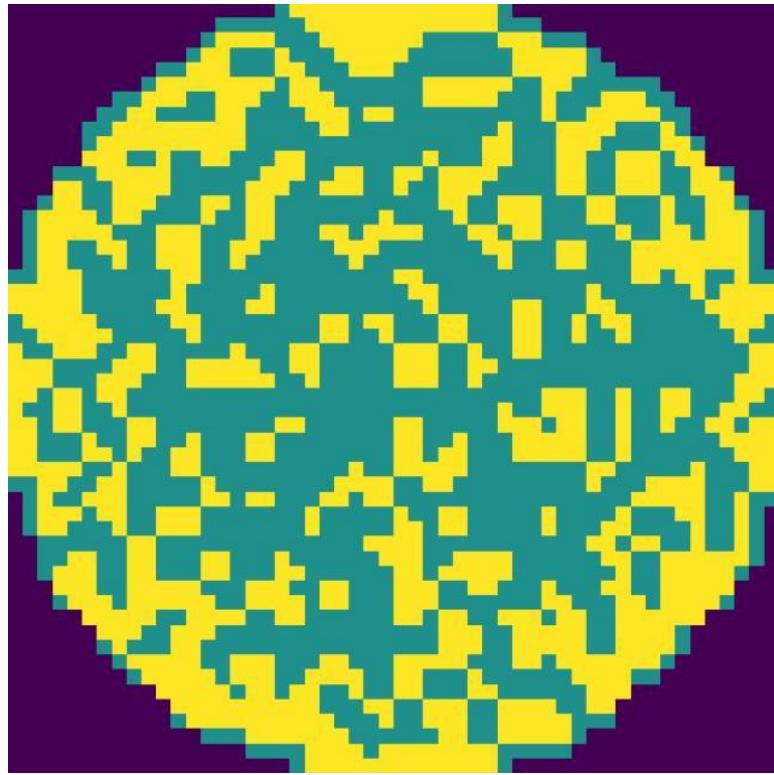
Defect Class: Random

Confidence Score: 0.9991

Defect Percentage: 70.29%

Reason: Defect Percentage: 70.29% (>40% threshold), Defect Class: Random, Confidence: 99.91%

Wafer Defect Image:



Wafer 71 Inspection Decision

Wafer ID: Electrical_ELEC_01_W0015

Decision: FAIL

Machine Type: Electrical

Machine ID: ELEC_01

Timestamp: 2025-12-27T12:06:02.921634

Simulation Date: 2025-12-27

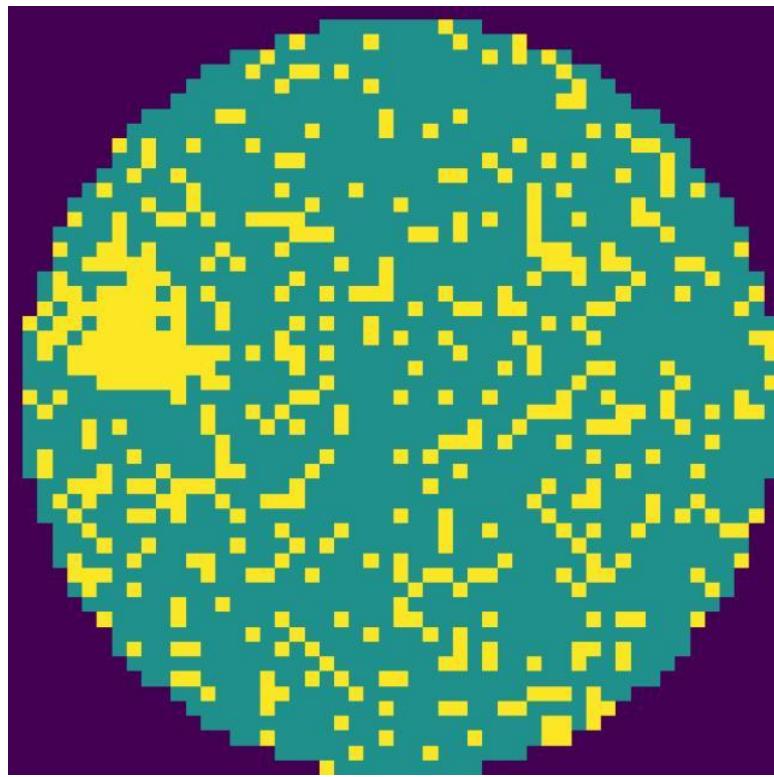
Defect Class: Local

Confidence Score: 1.0000

Defect Percentage: 45.66%

Reason: Defect Percentage: 45.66% (>40% threshold), Defect Class: Local, Confidence: 100.00%

Wafer Defect Image:



Wafer 72 Inspection Decision

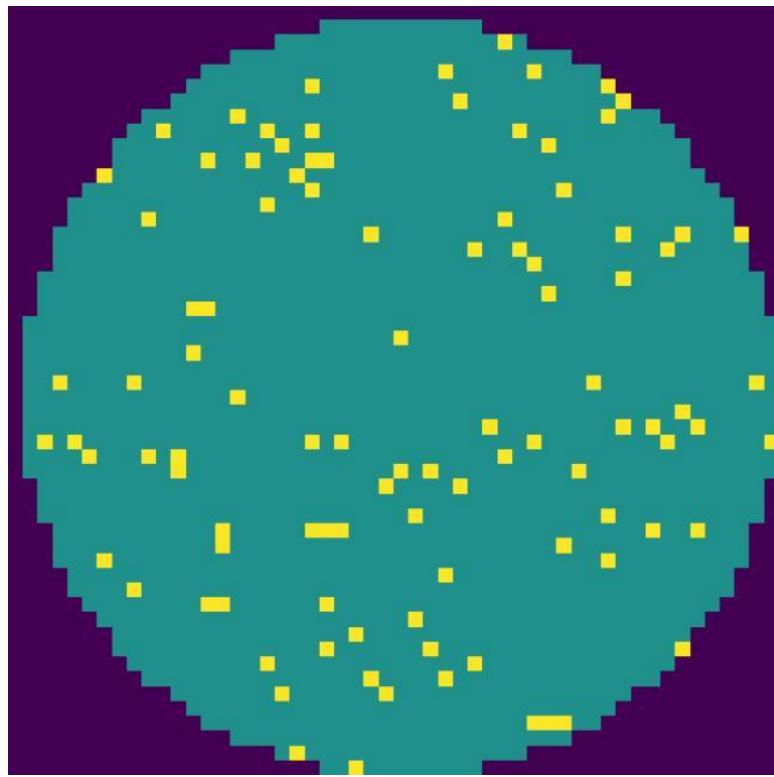
Wafer ID: Mechanical_MECH_01_W0012
Decision: PASS

Machine Type: Mechanical
Machine ID: MECH_01
Timestamp: 2025-12-27T12:06:03.301529
Simulation Date: 2025-12-27

Defect Class: Normal
Confidence Score: 0.9998
Defect Percentage: 33.38%

Reason: Defect Percentage: 33.38% (<=40% threshold), Defect Class: Normal, Confidence: 99.98%

Wafer Defect Image:



Wafer 73 Inspection Decision

Wafer ID: Electrical_ELEC_02_W0015

Decision: PASS

Machine Type: Electrical

Machine ID: ELEC_02

Timestamp: 2025-12-27T12:06:03.903929

Simulation Date: 2025-12-27

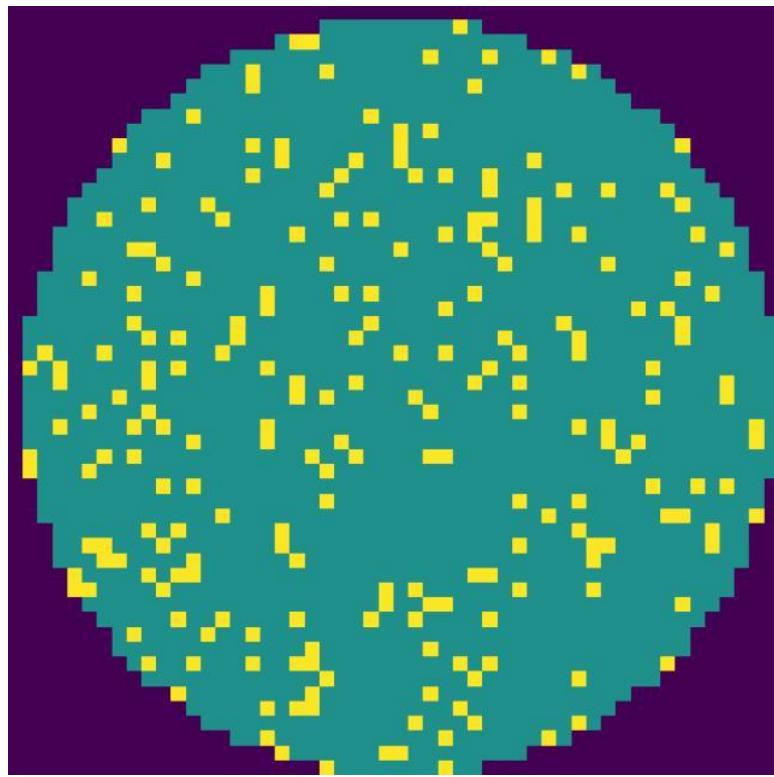
Defect Class: Normal

Confidence Score: 0.9999

Defect Percentage: 36.54%

Reason: Defect Percentage: 36.54% (<=40% threshold), Defect Class: Normal, Confidence: 99.99%

Wafer Defect Image:



Wafer 74 Inspection Decision

Wafer ID: Mechanical_MECH_02_W0013

Decision: FAIL

Machine Type: Mechanical

Machine ID: MECH_02

Timestamp: 2025-12-27T12:06:06.593978

Simulation Date: 2025-12-27

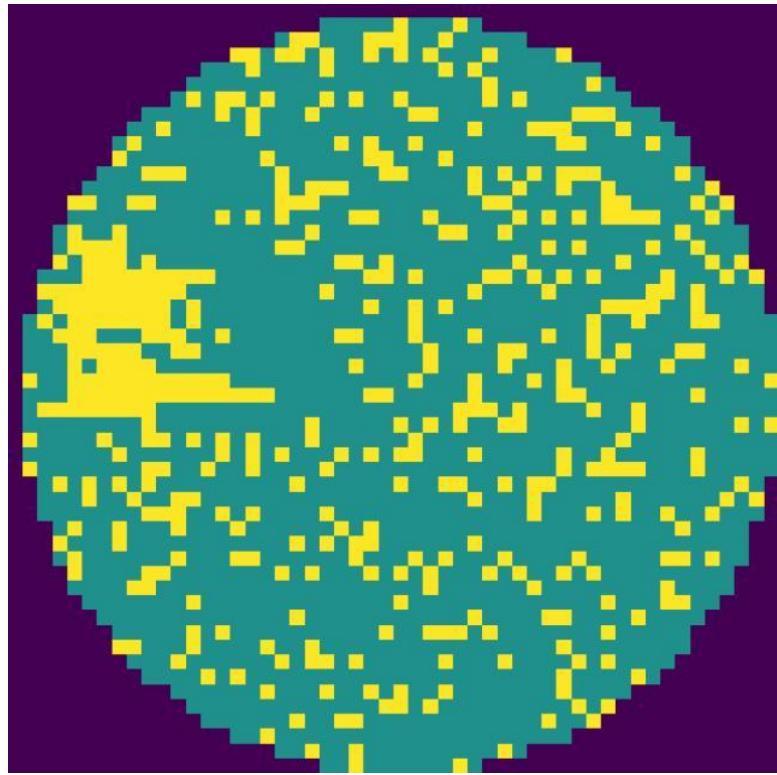
Defect Class: Local

Confidence Score: 1.0000

Defect Percentage: 47.13%

Reason: Defect Percentage: 47.13% (>40% threshold), Defect Class: Local, Confidence: 100.00%

Wafer Defect Image:



Wafer 75 Inspection Decision

Wafer ID: Thermal_THERM_02_W0009

Decision: PASS

Machine Type: Thermal

Machine ID: THERM_02

Timestamp: 2025-12-27T12:06:07.616231

Simulation Date: 2025-12-27

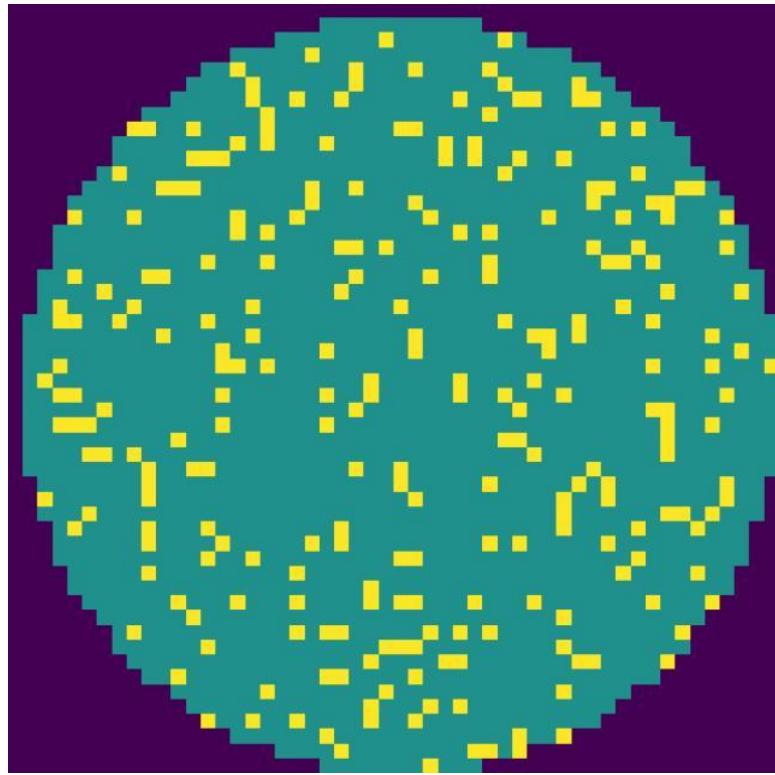
Defect Class: Normal

Confidence Score: 0.9998

Defect Percentage: 38.11%

Reason: Defect Percentage: 38.11% (<=40% threshold), Defect Class: Normal, Confidence: 99.98%

Wafer Defect Image:



Wafer 76 Inspection Decision

Wafer ID: Electrical_ELEC_01_W0016

Decision: PASS

Machine Type: Electrical

Machine ID: ELEC_01

Timestamp: 2025-12-27T12:06:08.548773

Simulation Date: 2025-12-27

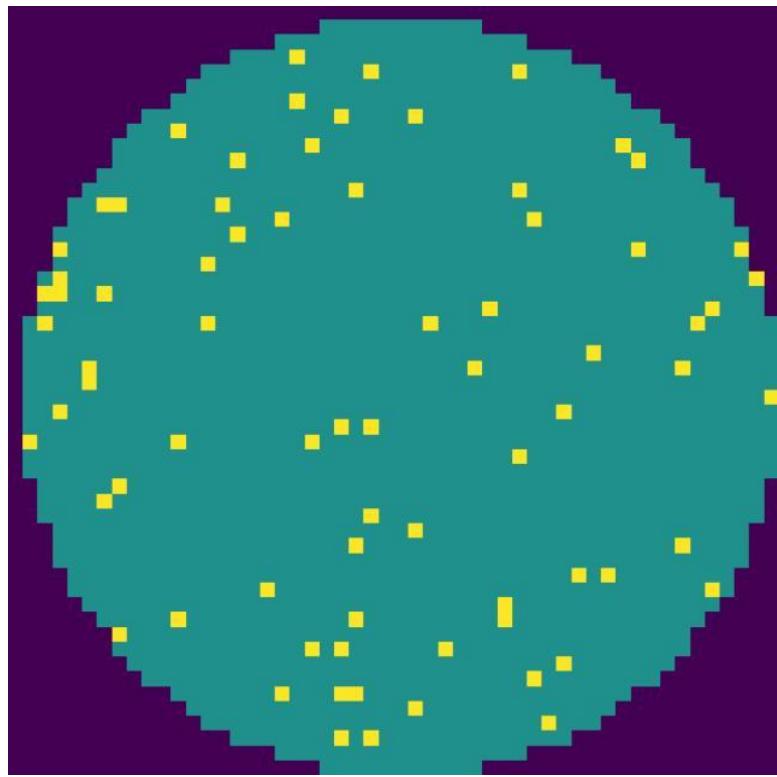
Defect Class: Normal

Confidence Score: 0.9998

Defect Percentage: 32.88%

Reason: Defect Percentage: 32.88% (<=40% threshold), Defect Class: Normal, Confidence: 99.98%

Wafer Defect Image:



Wafer 77 Inspection Decision

Wafer ID: Thermal_THERM_01_W0012

Decision: PASS

Machine Type: Thermal

Machine ID: THERM_01

Timestamp: 2025-12-27T12:06:08.867935

Simulation Date: 2025-12-27

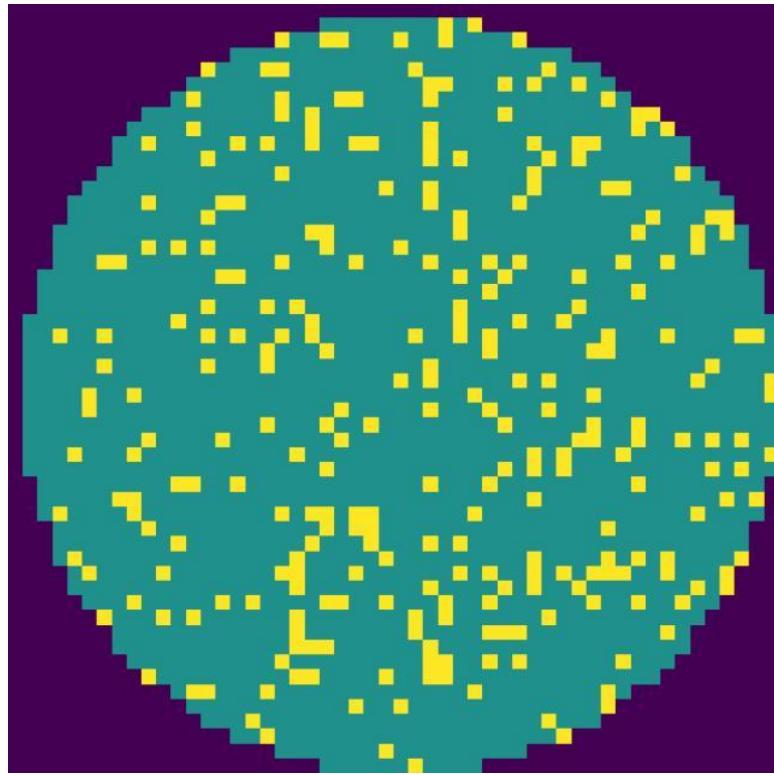
Defect Class: Normal

Confidence Score: 0.9998

Defect Percentage: 39.16%

Reason: Defect Percentage: 39.16% (<=40% threshold), Defect Class: Normal, Confidence: 99.98%

Wafer Defect Image:



Wafer 78 Inspection Decision

Wafer ID: Electrical_ELEC_02_W0016

Decision: PASS

Machine Type: Electrical

Machine ID: ELEC_02

Timestamp: 2025-12-27T12:06:08.950678

Simulation Date: 2025-12-27

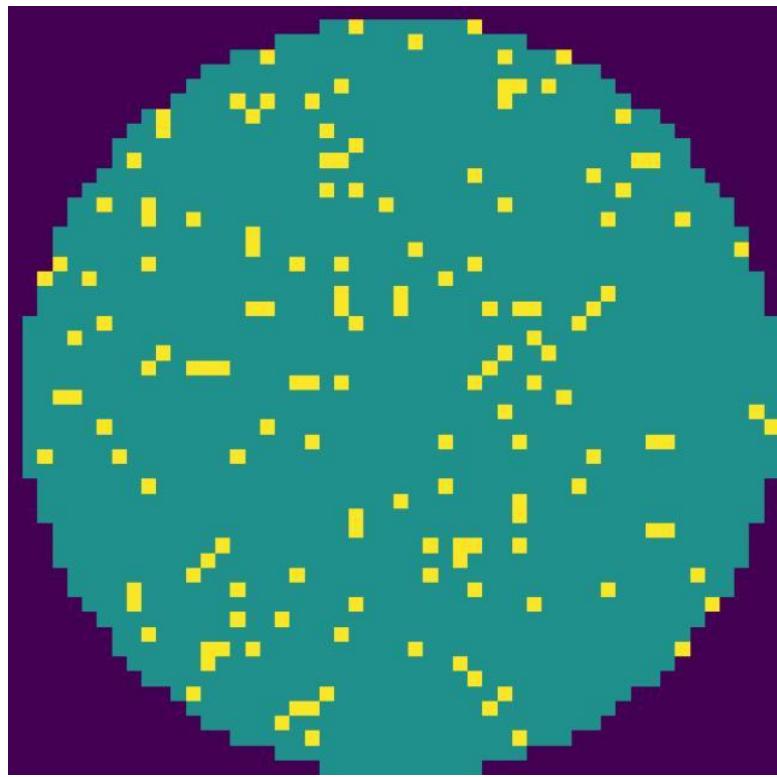
Defect Class: Normal

Confidence Score: 0.9998

Defect Percentage: 35.77%

Reason: Defect Percentage: 35.77% (<=40% threshold), Defect Class: Normal, Confidence: 99.98%

Wafer Defect Image:



Wafer 79 Inspection Decision

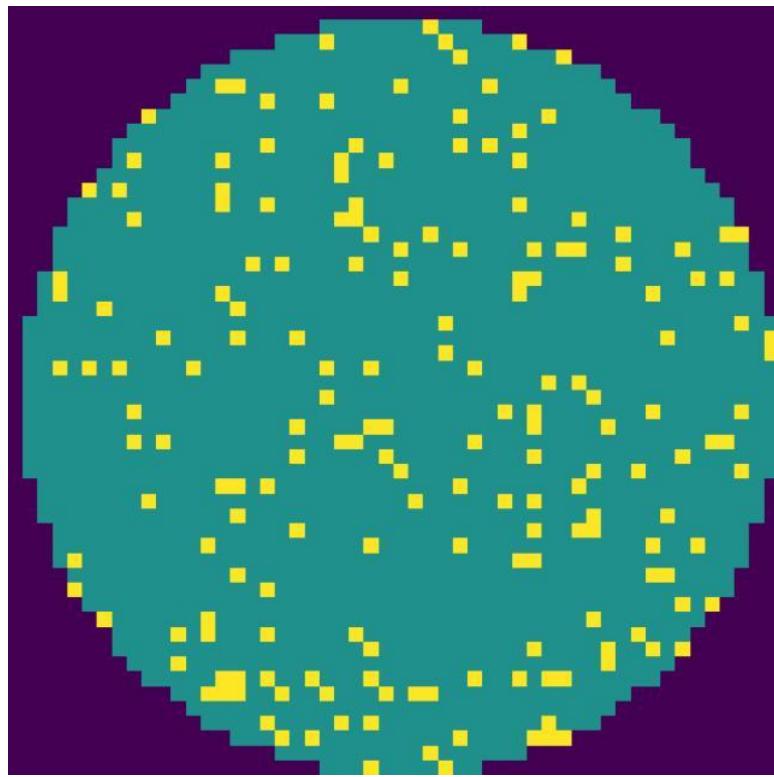
Wafer ID: Mechanical_MECH_01_W0013
Decision: PASS

Machine Type: Mechanical
Machine ID: MECH_01
Timestamp: 2025-12-27T12:06:09.962193
Simulation Date: 2025-12-27

Defect Class: Normal
Confidence Score: 0.9998
Defect Percentage: 36.69%

Reason: Defect Percentage: 36.69% (<=40% threshold), Defect Class: Normal, Confidence: 99.98%

Wafer Defect Image:



Wafer 80 Inspection Decision

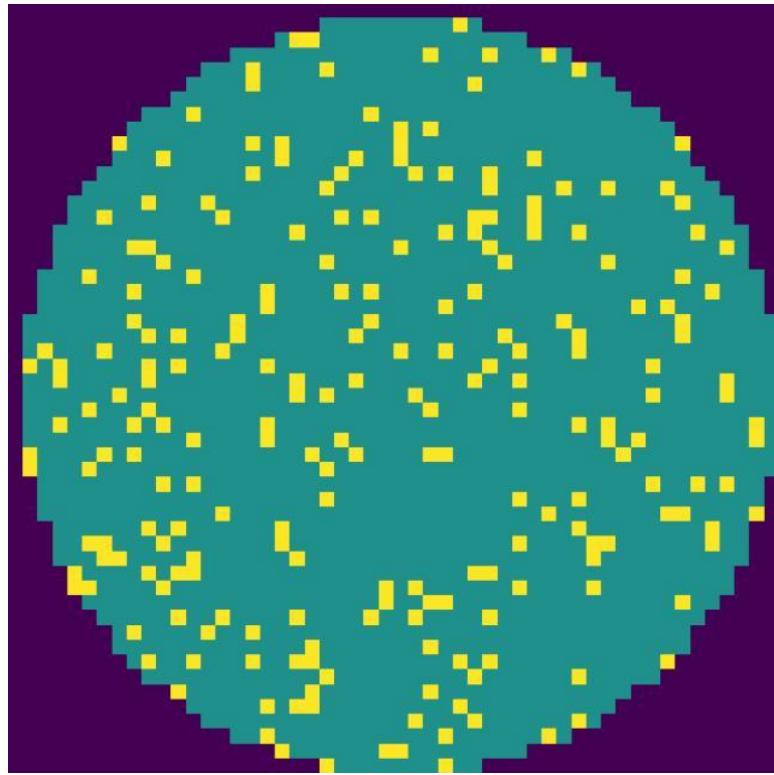
Wafer ID: Mechanical_MECH_02_W0014
Decision: PASS

Machine Type: Mechanical
Machine ID: MECH_02
Timestamp: 2025-12-27T12:06:11.734808
Simulation Date: 2025-12-27

Defect Class: Normal
Confidence Score: 0.9999
Defect Percentage: 36.54%

Reason: Defect Percentage: 36.54% (<=40% threshold), Defect Class: Normal, Confidence: 99.99%

Wafer Defect Image:



Wafer 81 Inspection Decision

Wafer ID: Electrical_ELEC_01_W0017

Decision: FAIL

Machine Type: Electrical

Machine ID: ELEC_01

Timestamp: 2025-12-27T12:06:13.715121

Simulation Date: 2025-12-27

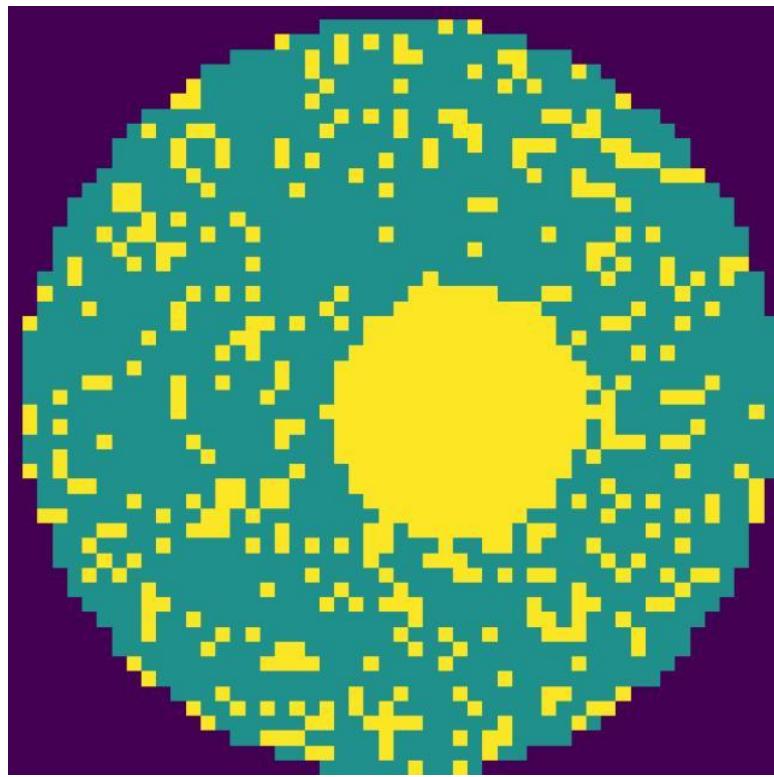
Defect Class: Center

Confidence Score: 0.9999

Defect Percentage: 59.07%

Reason: Defect Percentage: 59.07% (>40% threshold), Defect Class: Center, Confidence: 99.99%

Wafer Defect Image:



Wafer 82 Inspection Decision

Wafer ID: Thermal_THERM_01_W0013

Decision: PASS

Machine Type: Thermal

Machine ID: THERM_01

Timestamp: 2025-12-27T12:06:14.436573

Simulation Date: 2025-12-27

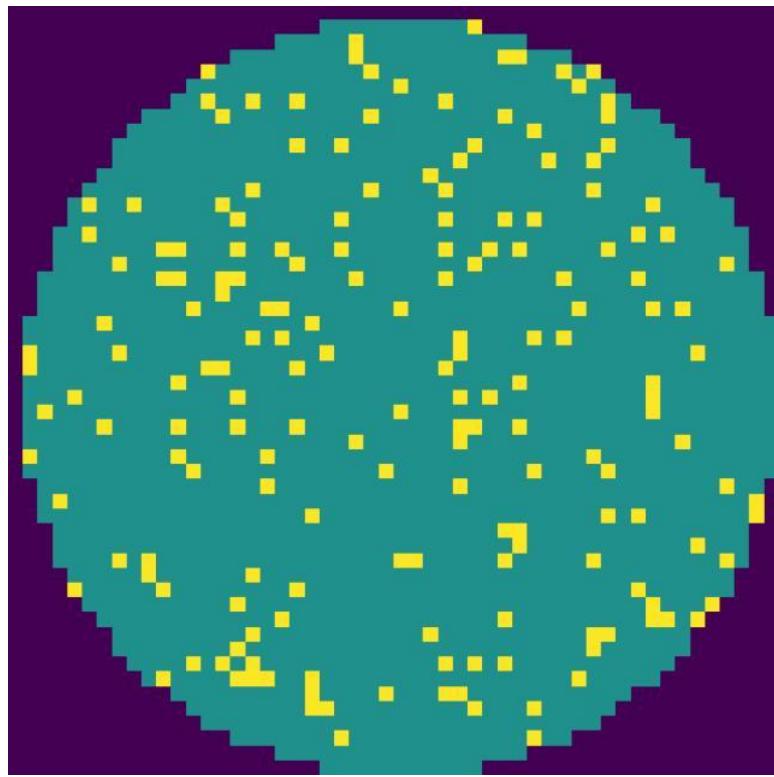
Defect Class: Normal

Confidence Score: 0.9998

Defect Percentage: 35.70%

Reason: Defect Percentage: 35.7% (<=40% threshold), Defect Class: Normal, Confidence: 99.98%

Wafer Defect Image:



Wafer 83 Inspection Decision

Wafer ID: Electrical_ELEC_02_W0017

Decision: FAIL

Machine Type: Electrical

Machine ID: ELEC_02

Timestamp: 2025-12-27T12:06:14.720768

Simulation Date: 2025-12-27

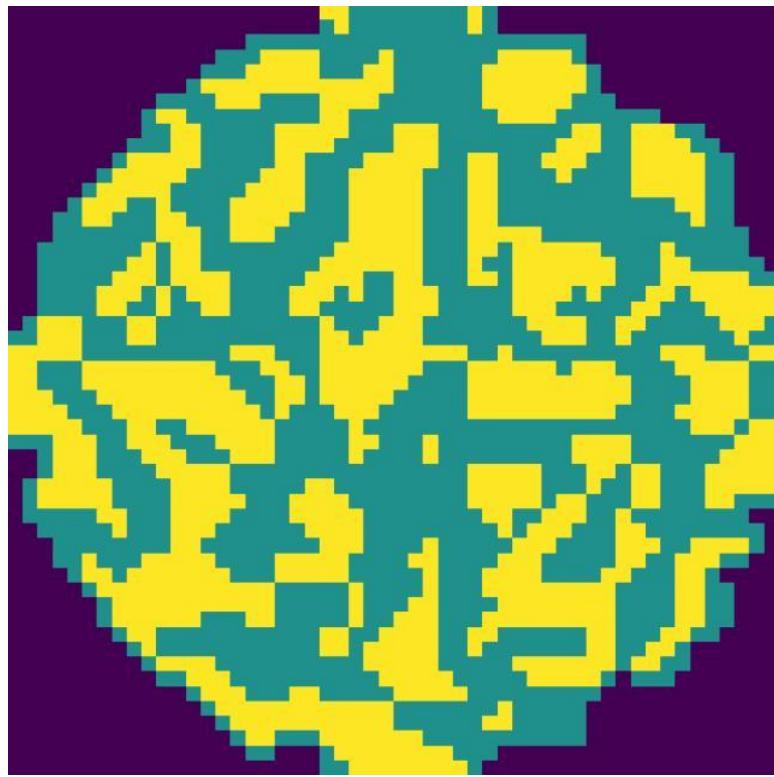
Defect Class: Random

Confidence Score: 1.0000

Defect Percentage: 75.51%

Reason: Defect Percentage: 75.51% (>40% threshold), Defect Class: Random, Confidence: 100.00%

Wafer Defect Image:



Wafer 84 Inspection Decision

Wafer ID: Thermal_THERM_02_W0010

Decision: PASS

Machine Type: Thermal

Machine ID: THERM_02

Timestamp: 2025-12-27T12:06:14.881292

Simulation Date: 2025-12-27

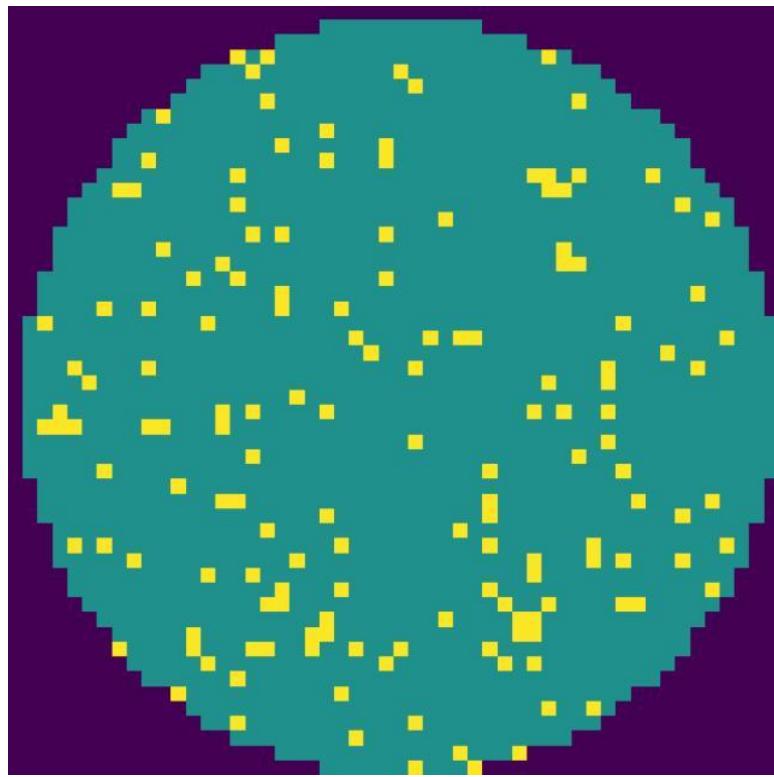
Defect Class: Normal

Confidence Score: 0.9998

Defect Percentage: 35.83%

Reason: Defect Percentage: 35.83% (<=40% threshold), Defect Class: Normal, Confidence: 99.98%

Wafer Defect Image:



Wafer 85 Inspection Decision

Wafer ID: Mechanical_MECH_01_W0014

Decision: FAIL

Machine Type: Mechanical

Machine ID: MECH_01

Timestamp: 2025-12-27T12:06:15.420153

Simulation Date: 2025-12-27

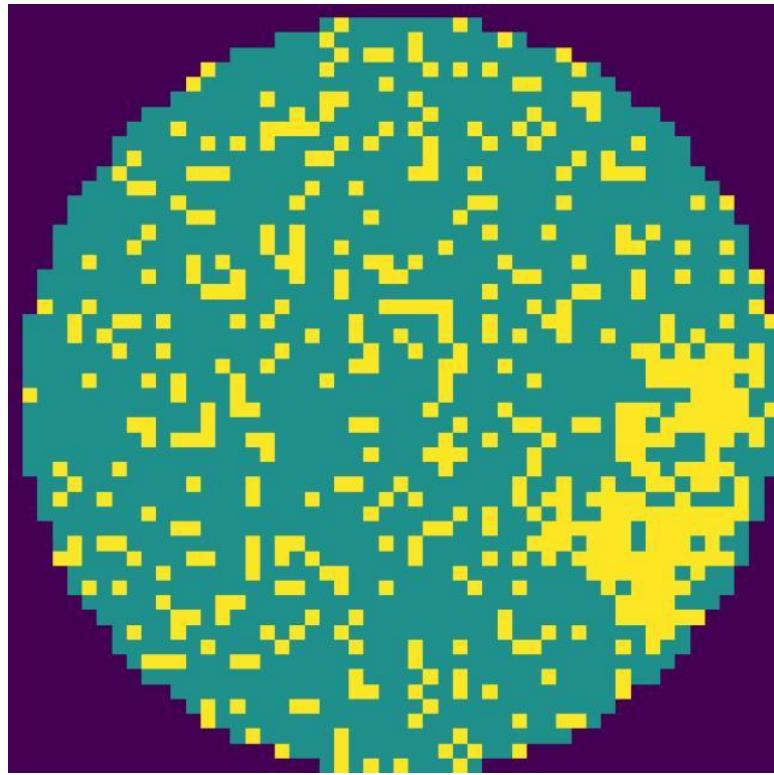
Defect Class: Local

Confidence Score: 0.9998

Defect Percentage: 48.65%

Reason: Defect Percentage: 48.65% (>40% threshold), Defect Class: Local, Confidence: 99.98%

Wafer Defect Image:



Wafer 86 Inspection Decision

Wafer ID: Mechanical_MECH_02_W0015

Decision: FAIL

Machine Type: Mechanical

Machine ID: MECH_02

Timestamp: 2025-12-27T12:06:17.576237

Simulation Date: 2025-12-27

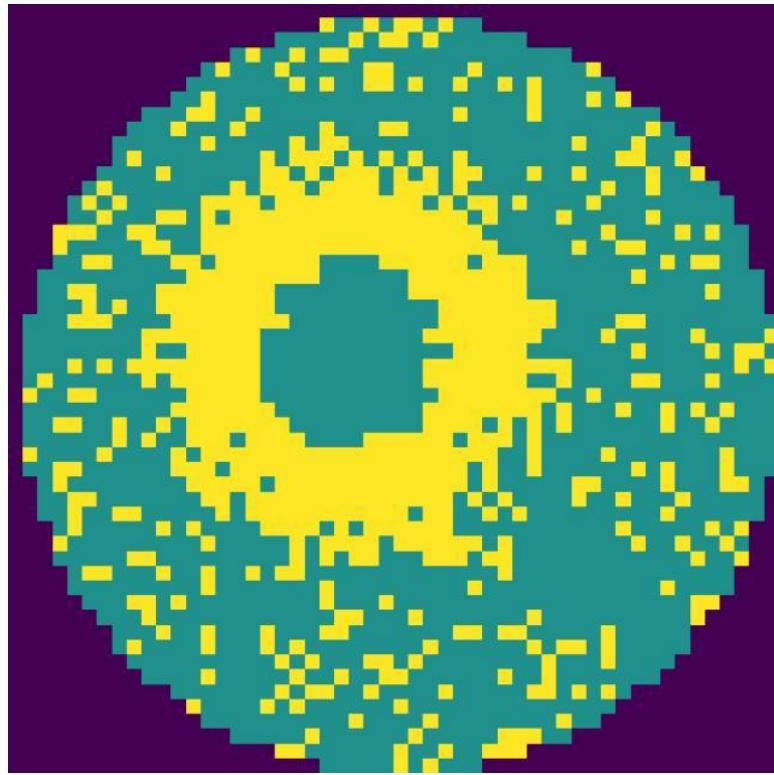
Defect Class: Donut

Confidence Score: 1.0000

Defect Percentage: 63.56%

Reason: Defect Percentage: 63.56% (>40% threshold), Defect Class: Donut, Confidence: 100.00%

Wafer Defect Image:



Wafer 87 Inspection Decision

Wafer ID: Electrical_ELEC_01_W0018

Decision: PASS

Machine Type: Electrical

Machine ID: ELEC_01

Timestamp: 2025-12-27T12:06:19.638251

Simulation Date: 2025-12-27

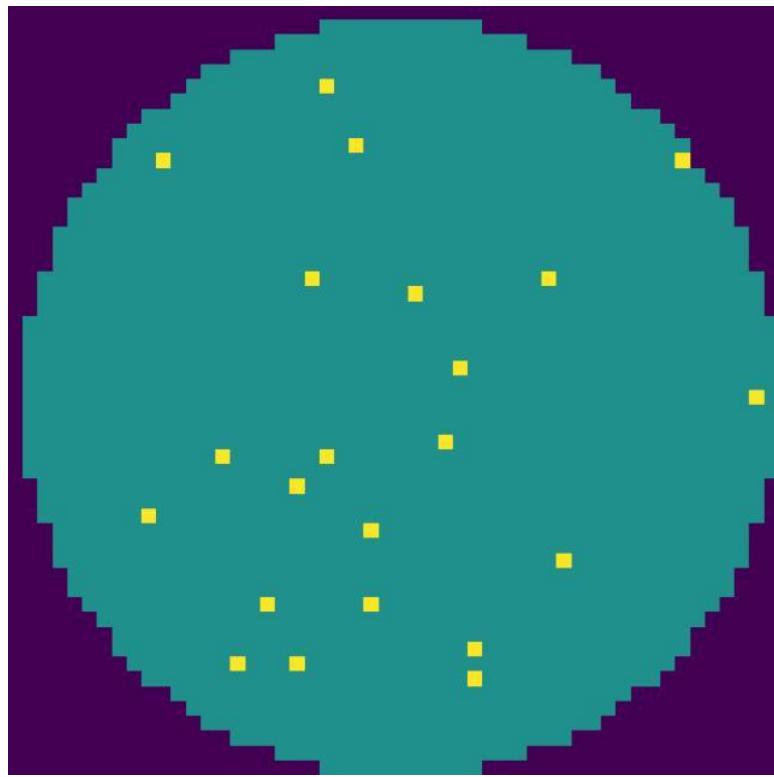
Defect Class: Normal

Confidence Score: 0.9997

Defect Percentage: 29.05%

Reason: Defect Percentage: 29.05% (<=40% threshold), Defect Class: Normal, Confidence: 99.97%

Wafer Defect Image:



Wafer 88 Inspection Decision

Wafer ID: Electrical_ELEC_02_W0018

Decision: FAIL

Machine Type: Electrical

Machine ID: ELEC_02

Timestamp: 2025-12-27T12:06:20.709268

Simulation Date: 2025-12-27

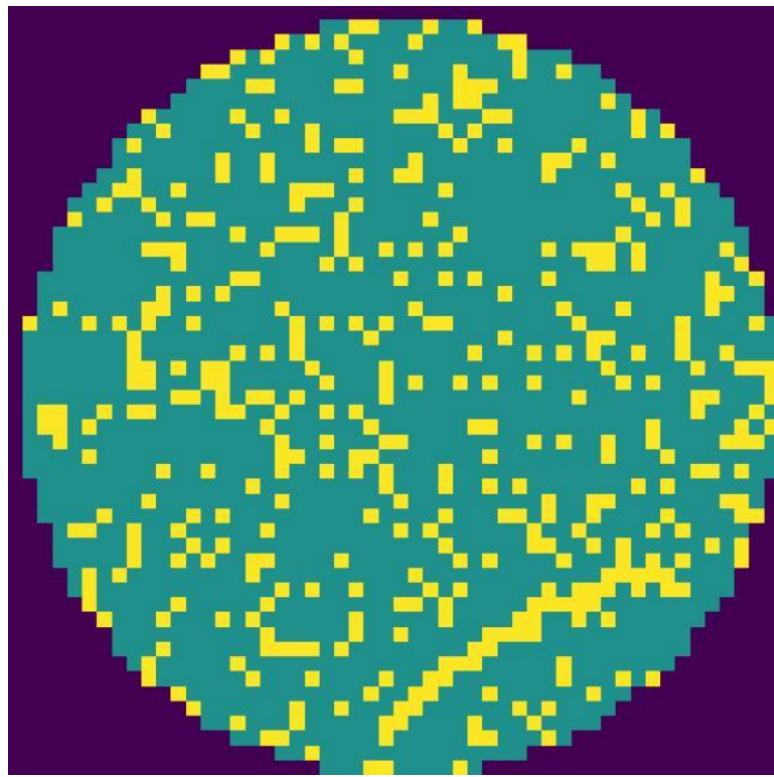
Defect Class: Scratch

Confidence Score: 1.0000

Defect Percentage: 43.34%

Reason: Defect Percentage: 43.34% (>40% threshold), Defect Class: Scratch, Confidence: 100.00%

Wafer Defect Image:



Wafer 89 Inspection Decision

Wafer ID: Mechanical_MECH_01_W0015

Decision: FAIL

Machine Type: Mechanical

Machine ID: MECH_01

Timestamp: 2025-12-27T12:06:21.109262

Simulation Date: 2025-12-27

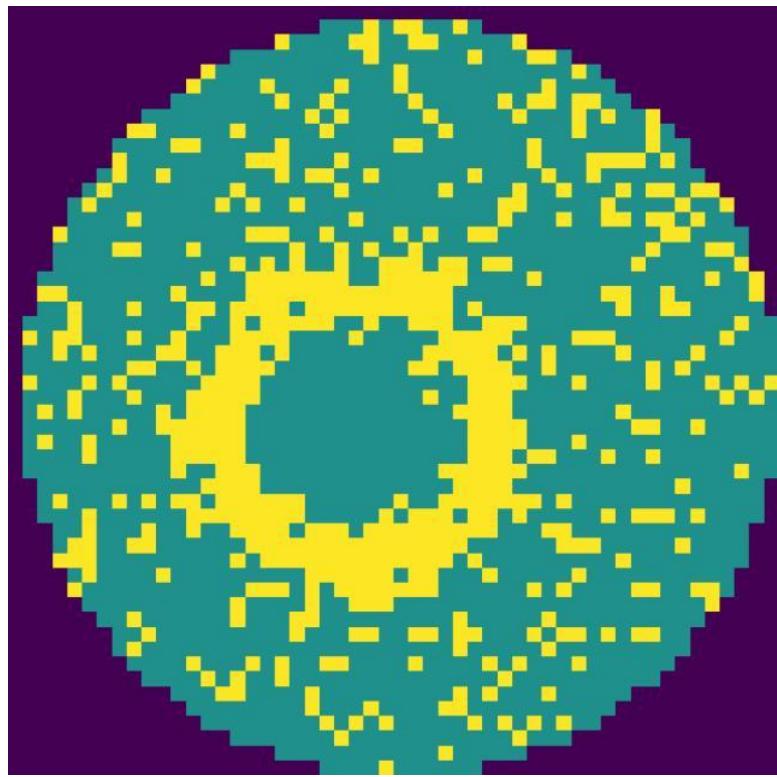
Defect Class: Donut

Confidence Score: 0.9999

Defect Percentage: 55.99%

Reason: Defect Percentage: 55.99% (>40% threshold), Defect Class: Donut, Confidence: 99.99%

Wafer Defect Image:



Wafer 90 Inspection Decision

Wafer ID: Thermal_THERM_02_W0011

Decision: PASS

Machine Type: Thermal

Machine ID: THERM_02

Timestamp: 2025-12-27T12:06:22.296010

Simulation Date: 2025-12-27

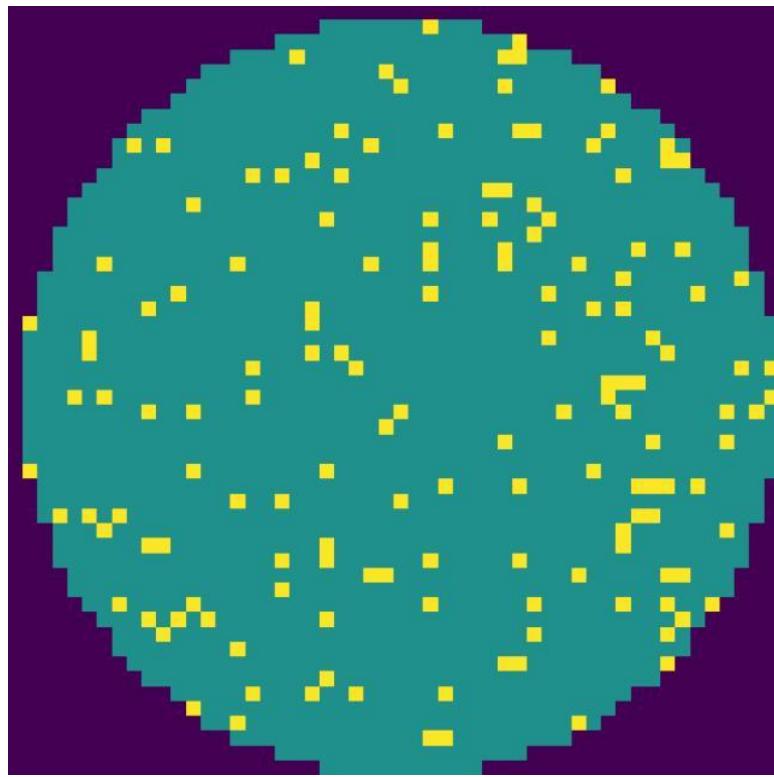
Defect Class: Normal

Confidence Score: 0.9997

Defect Percentage: 35.54%

Reason: Defect Percentage: 35.54% (<=40% threshold), Defect Class: Normal, Confidence: 99.97%

Wafer Defect Image:



Wafer 91 Inspection Decision

Wafer ID: Thermal_THERM_01_W0014

Decision: PASS

Machine Type: Thermal

Machine ID: THERM_01

Timestamp: 2025-12-27T12:06:24.251113

Simulation Date: 2025-12-27

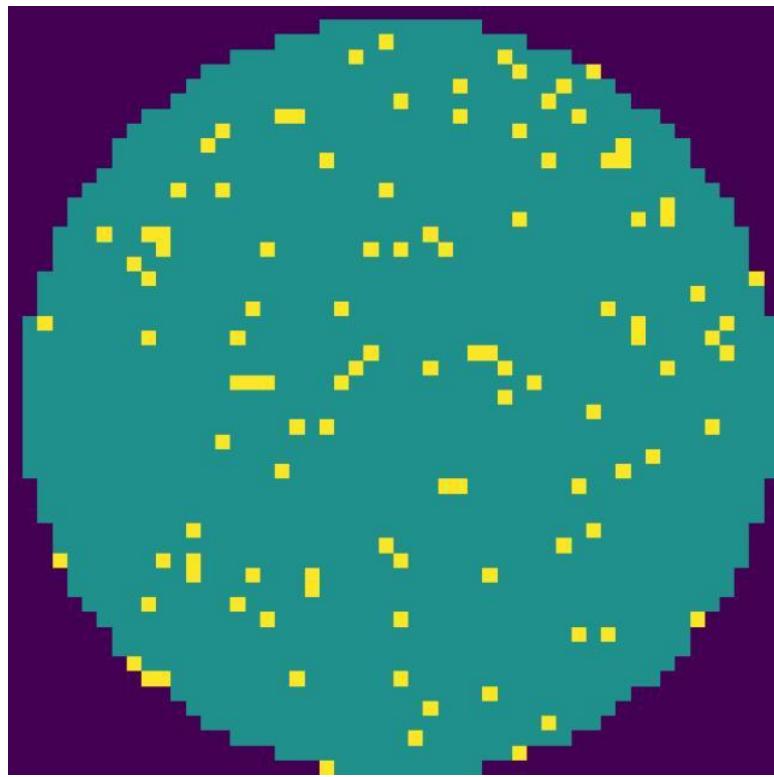
Defect Class: Normal

Confidence Score: 0.9996

Defect Percentage: 35.18%

Reason: Defect Percentage: 35.18% (<=40% threshold), Defect Class: Normal, Confidence: 99.96%

Wafer Defect Image:



Wafer 92 Inspection Decision

Wafer ID: Electrical_ELEC_01_W0019

Decision: PASS

Machine Type: Electrical

Machine ID: ELEC_01

Timestamp: 2025-12-27T12:06:24.761425

Simulation Date: 2025-12-27

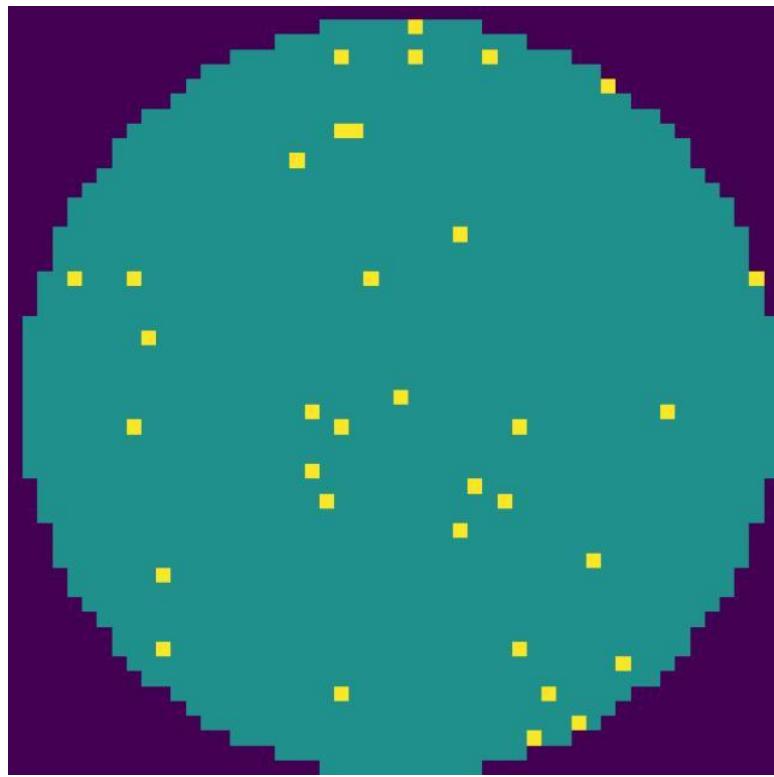
Defect Class: Normal

Confidence Score: 0.9999

Defect Percentage: 33.22%

Reason: Defect Percentage: 33.22% (<=40% threshold), Defect Class: Normal, Confidence: 99.99%

Wafer Defect Image:



Wafer 93 Inspection Decision

Wafer ID: Mechanical_MECH_02_W0016

Decision: FAIL

Machine Type: Mechanical

Machine ID: MECH_02

Timestamp: 2025-12-27T12:06:24.935151

Simulation Date: 2025-12-27

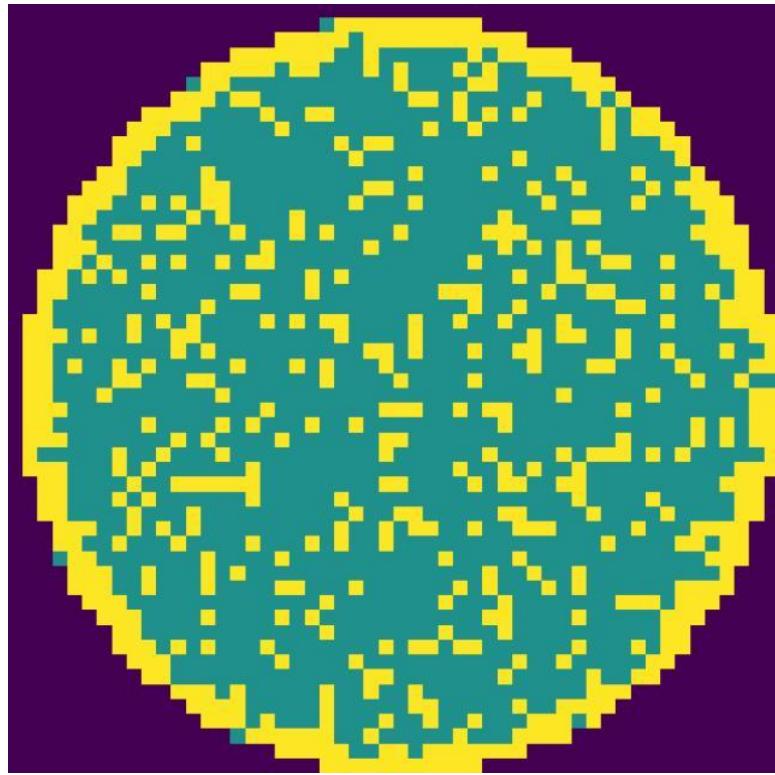
Defect Class: Edge-Ring

Confidence Score: 0.9917

Defect Percentage: 56.59%

Reason: Defect Percentage: 56.59% (>40% threshold), Defect Class: Edge-Ring, Confidence: 99.17%

Wafer Defect Image:



Wafer 94 Inspection Decision

Wafer ID: Electrical_ELEC_02_W0019

Decision: PASS

Machine Type: Electrical

Machine ID: ELEC_02

Timestamp: 2025-12-27T12:06:26.683602

Simulation Date: 2025-12-27

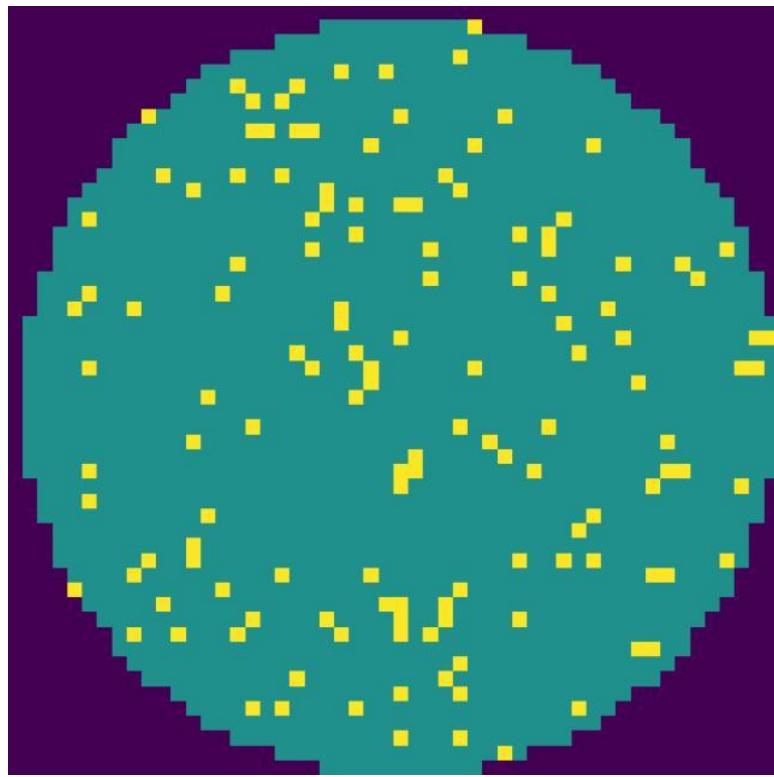
Defect Class: Normal

Confidence Score: 0.9997

Defect Percentage: 34.83%

Reason: Defect Percentage: 34.83% (<=40% threshold), Defect Class: Normal, Confidence: 99.97%

Wafer Defect Image:



Wafer 95 Inspection Decision

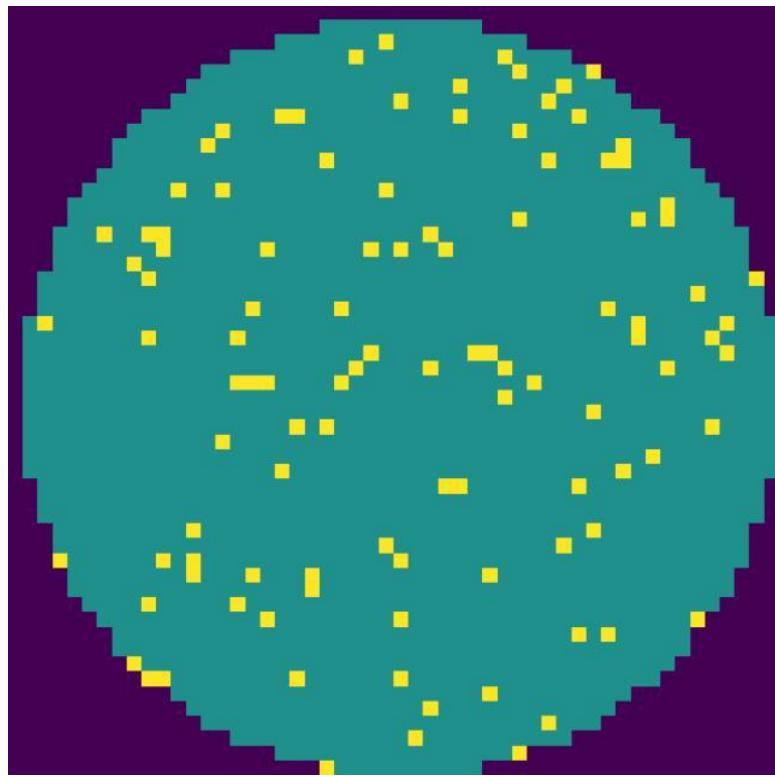
Wafer ID: Mechanical_MECH_01_W0016
Decision: PASS

Machine Type: Mechanical
Machine ID: MECH_01
Timestamp: 2025-12-27T12:06:27.800614
Simulation Date: 2025-12-27

Defect Class: Normal
Confidence Score: 0.9996
Defect Percentage: 35.18%

Reason: Defect Percentage: 35.18% (<=40% threshold), Defect Class: Normal, Confidence: 99.96%

Wafer Defect Image:



Wafer 96 Inspection Decision

Wafer ID: Electrical_ELEC_01_W0020

Decision: PASS

Machine Type: Electrical

Machine ID: ELEC_01

Timestamp: 2025-12-27T12:06:30.235885

Simulation Date: 2025-12-27

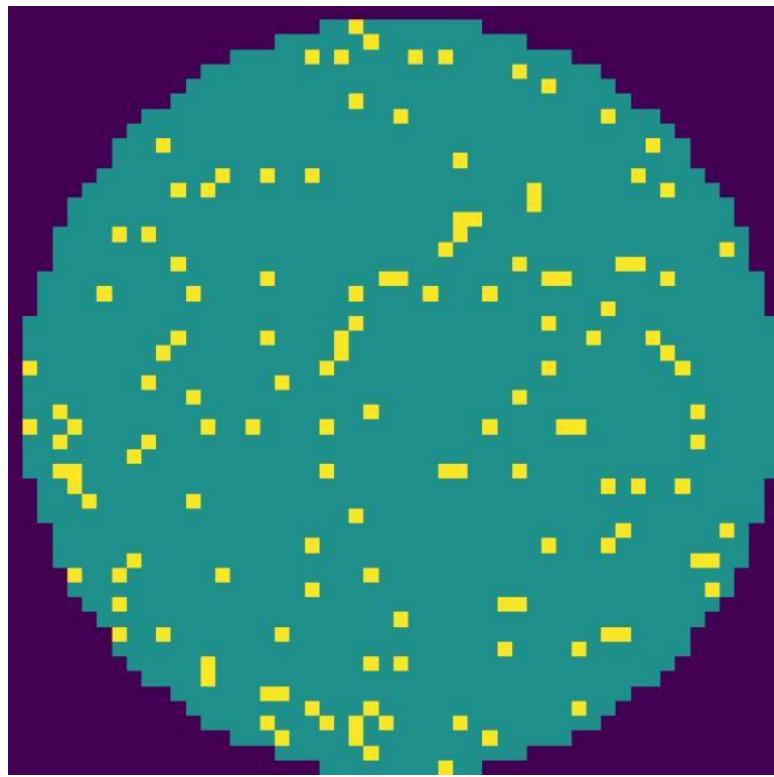
Defect Class: Normal

Confidence Score: 0.9996

Defect Percentage: 33.89%

Reason: Defect Percentage: 33.89% (<=40% threshold), Defect Class: Normal, Confidence: 99.96%

Wafer Defect Image:



Wafer 97 Inspection Decision

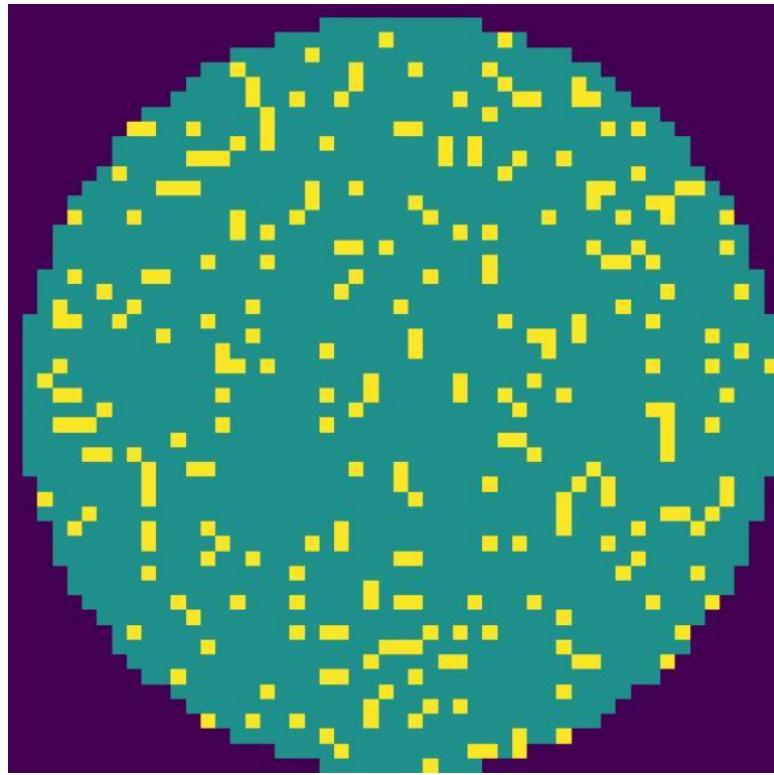
Wafer ID: Mechanical_MECH_02_W0017
Decision: PASS

Machine Type: Mechanical
Machine ID: MECH_02
Timestamp: 2025-12-27T12:06:31.531958
Simulation Date: 2025-12-27

Defect Class: Normal
Confidence Score: 0.9998
Defect Percentage: 38.11%

Reason: Defect Percentage: 38.11% (<=40% threshold), Defect Class: Normal, Confidence: 99.98%

Wafer Defect Image:



Wafer 98 Inspection Decision

Wafer ID: Electrical_ELEC_02_W0020

Decision: PASS

Machine Type: Electrical

Machine ID: ELEC_02

Timestamp: 2025-12-27T12:06:32.084824

Simulation Date: 2025-12-27

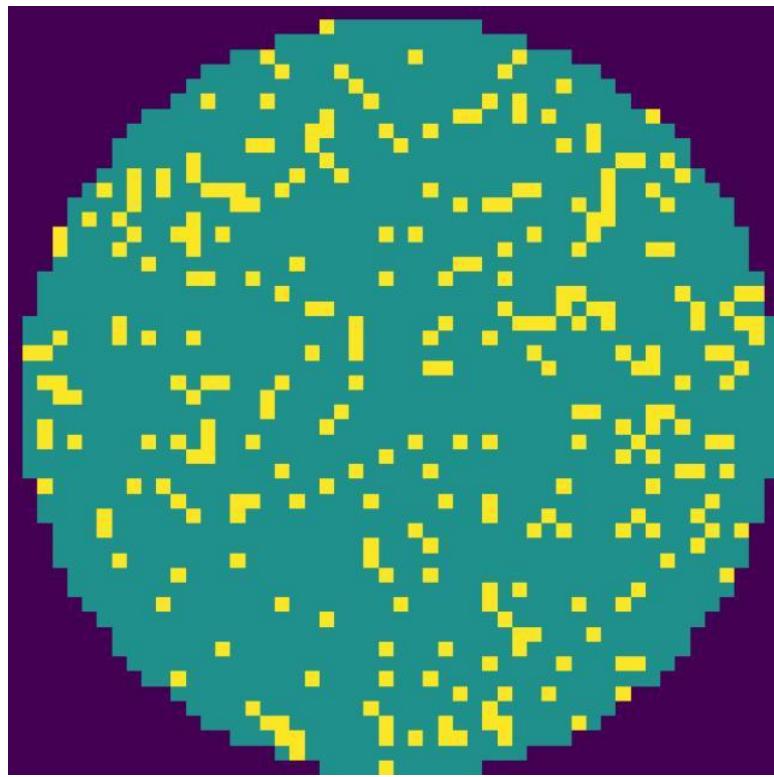
Defect Class: Normal

Confidence Score: 0.9999

Defect Percentage: 38.85%

Reason: Defect Percentage: 38.85% (<=40% threshold), Defect Class: Normal, Confidence: 99.99%

Wafer Defect Image:



Wafer 99 Inspection Decision

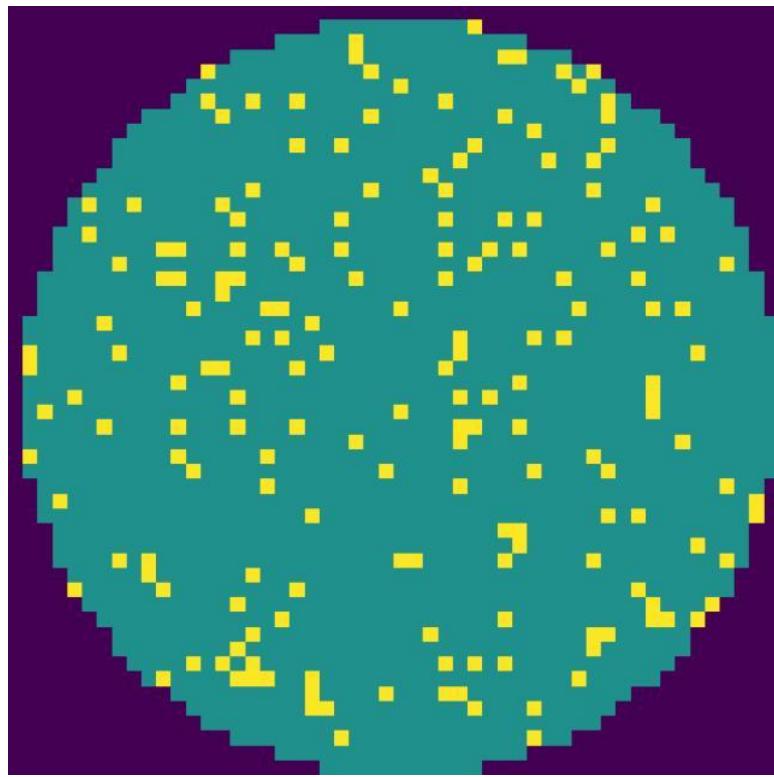
Wafer ID: Mechanical_MECH_01_W0017
Decision: PASS

Machine Type: Mechanical
Machine ID: MECH_01
Timestamp: 2025-12-27T12:06:33.736893
Simulation Date: 2025-12-27

Defect Class: Normal
Confidence Score: 0.9998
Defect Percentage: 35.70%

Reason: Defect Percentage: 35.7% (<=40% threshold), Defect Class: Normal, Confidence: 99.98%

Wafer Defect Image:



Wafer 100 Inspection Decision

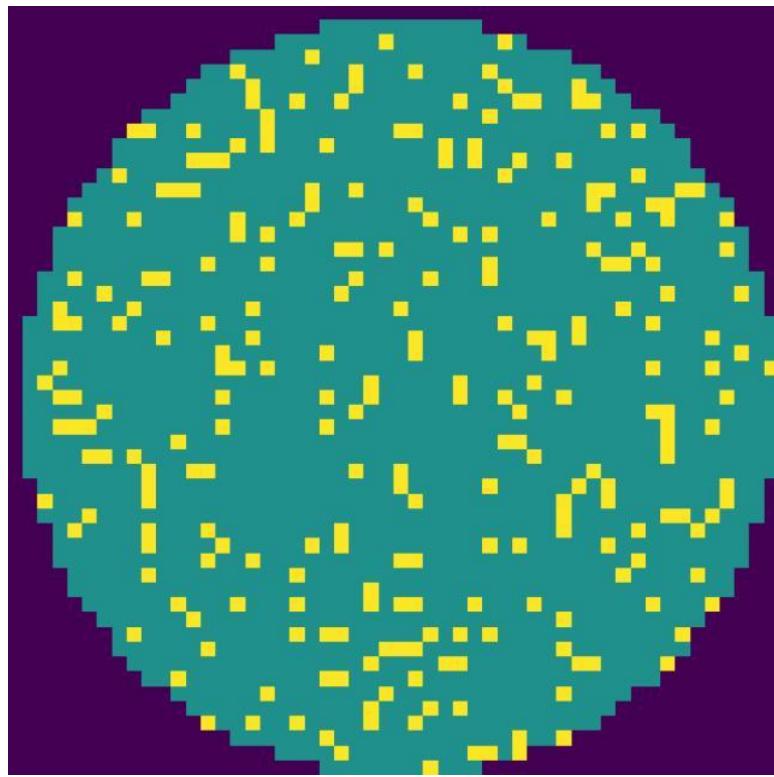
Wafer ID: Thermal_THERM_02_W0012
Decision: PASS

Machine Type: Thermal
Machine ID: THERM_02
Timestamp: 2025-12-27T12:06:33.984933
Simulation Date: 2025-12-27

Defect Class: Normal
Confidence Score: 0.9998
Defect Percentage: 38.11%

Reason: Defect Percentage: 38.11% (<=40% threshold), Defect Class: Normal, Confidence: 99.98%

Wafer Defect Image:



Wafer 101 Inspection Decision

Wafer ID: Thermal_THERM_01_W0015

Decision: FAIL

Machine Type: Thermal

Machine ID: THERM_01

Timestamp: 2025-12-27T12:06:34.020927

Simulation Date: 2025-12-27

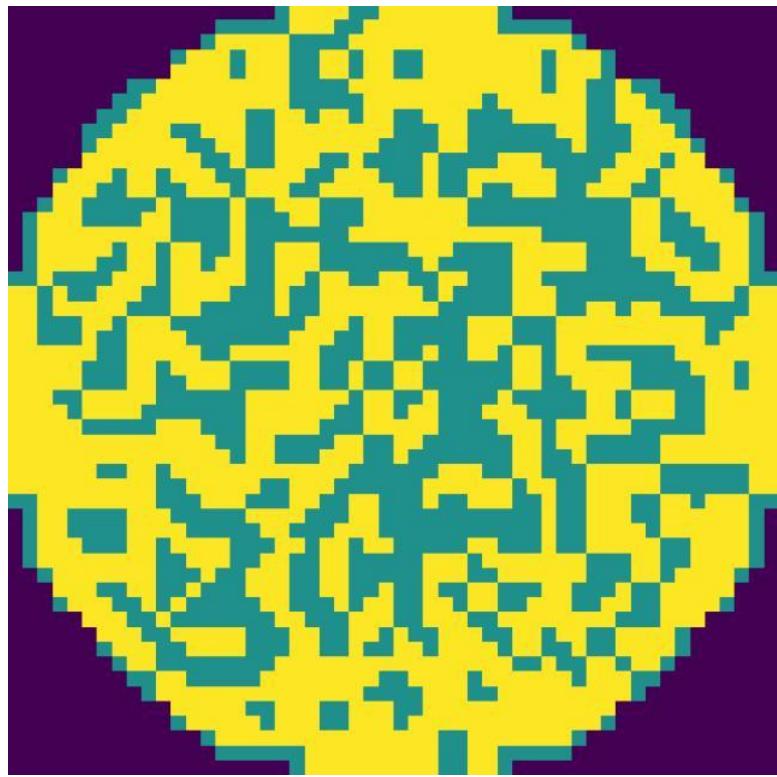
Defect Class: Random

Confidence Score: 0.9996

Defect Percentage: 77.21%

Reason: Defect Percentage: 77.21% (>40% threshold), Defect Class: Random, Confidence: 99.96%

Wafer Defect Image:



Wafer 102 Inspection Decision

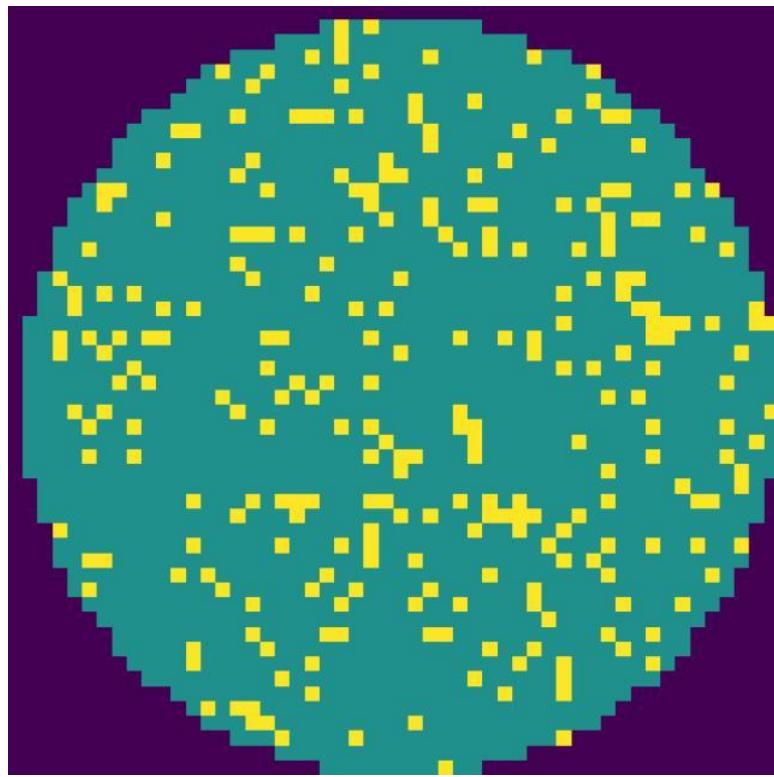
Wafer ID: Electrical_ELEC_01_W0021
Decision: PASS

Machine Type: Electrical
Machine ID: ELEC_01
Timestamp: 2025-12-27T12:06:35.993893
Simulation Date: 2025-12-27

Defect Class: Normal
Confidence Score: 0.9999
Defect Percentage: 37.90%

Reason: Defect Percentage: 37.9% (<=40% threshold), Defect Class: Normal, Confidence: 99.99%

Wafer Defect Image:



Wafer 103 Inspection Decision

Wafer ID: Mechanical_MECH_02_W0018

Decision: FAIL

Machine Type: Mechanical

Machine ID: MECH_02

Timestamp: 2025-12-27T12:06:36.738499

Simulation Date: 2025-12-27

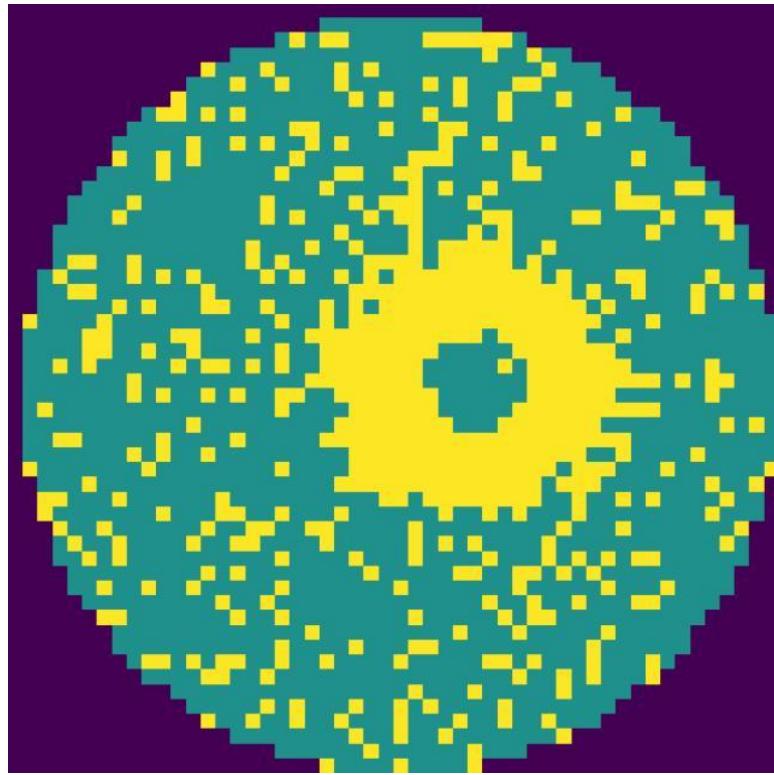
Defect Class: Donut

Confidence Score: 0.9997

Defect Percentage: 56.64%

Reason: Defect Percentage: 56.64% (>40% threshold), Defect Class: Donut, Confidence: 99.97%

Wafer Defect Image:



Wafer 104 Inspection Decision

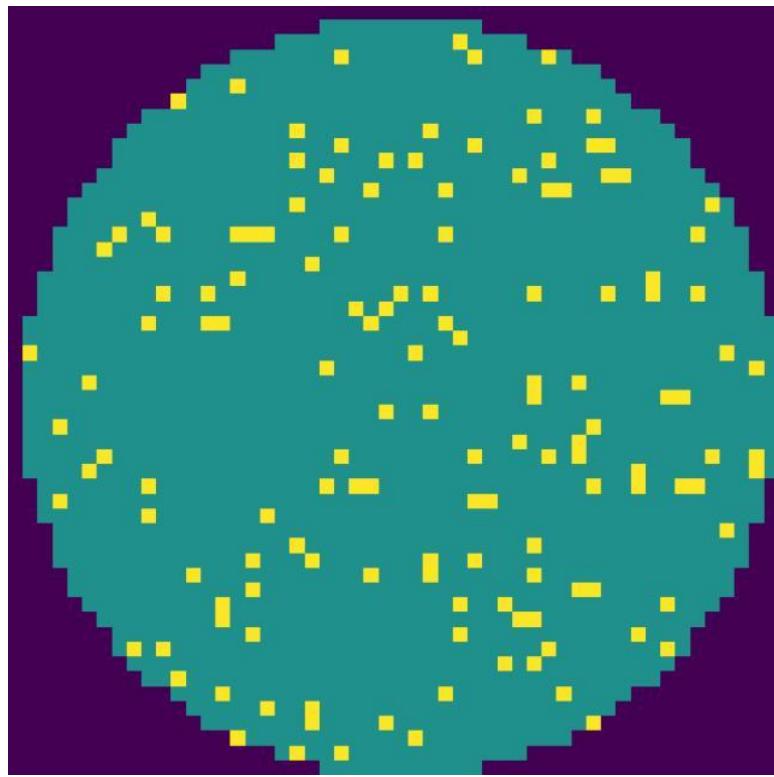
Wafer ID: Electrical_ELEC_02_W0021
Decision: PASS

Machine Type: Electrical
Machine ID: ELEC_02
Timestamp: 2025-12-27T12:06:37.392655
Simulation Date: 2025-12-27

Defect Class: Normal
Confidence Score: 0.9998
Defect Percentage: 34.76%

Reason: Defect Percentage: 34.76% (<=40% threshold), Defect Class: Normal, Confidence: 99.98%

Wafer Defect Image:



Wafer 105 Inspection Decision

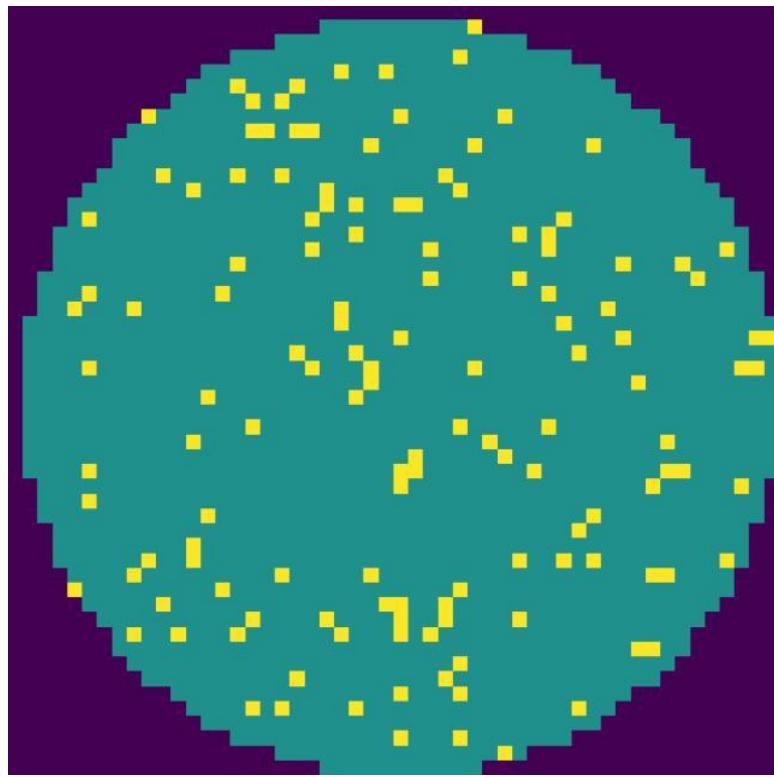
Wafer ID: Mechanical_MECH_01_W0018
Decision: PASS

Machine Type: Mechanical
Machine ID: MECH_01
Timestamp: 2025-12-27T12:06:40.009928
Simulation Date: 2025-12-27

Defect Class: Normal
Confidence Score: 0.9997
Defect Percentage: 34.83%

Reason: Defect Percentage: 34.83% (<=40% threshold), Defect Class: Normal, Confidence: 99.97%

Wafer Defect Image:



Wafer 106 Inspection Decision

Wafer ID: Electrical_ELEC_01_W0022

Decision: FAIL

Machine Type: Electrical

Machine ID: ELEC_01

Timestamp: 2025-12-27T12:06:41.972288

Simulation Date: 2025-12-27

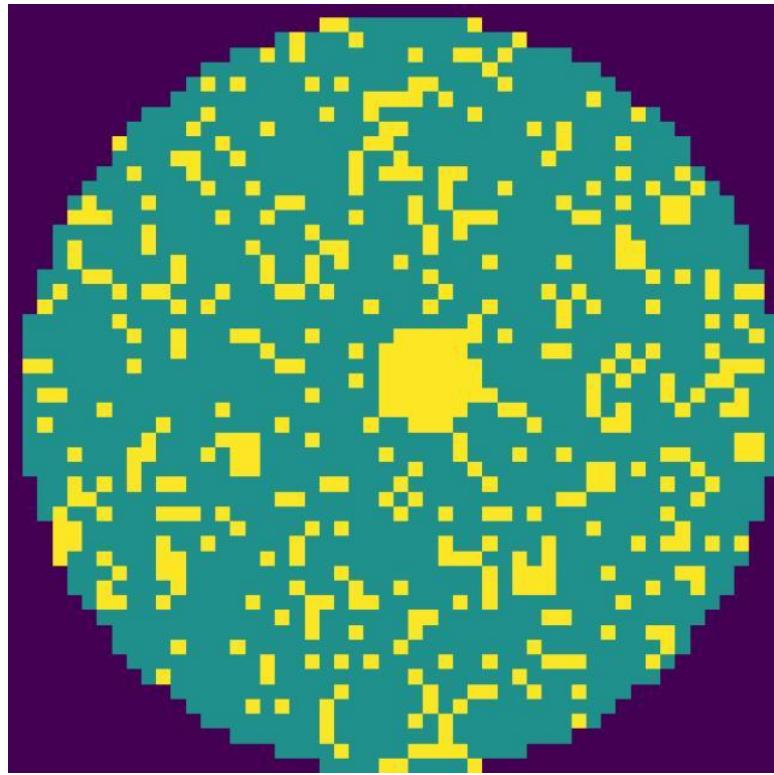
Defect Class: Center

Confidence Score: 0.9999

Defect Percentage: 45.54%

Reason: Defect Percentage: 45.54% (>40% threshold), Defect Class: Center, Confidence: 99.99%

Wafer Defect Image:



Wafer 107 Inspection Decision

Wafer ID: Thermal_THERM_01_W0016

Decision: FAIL

Machine Type: Thermal

Machine ID: THERM_01

Timestamp: 2025-12-27T12:06:42.572294

Simulation Date: 2025-12-27

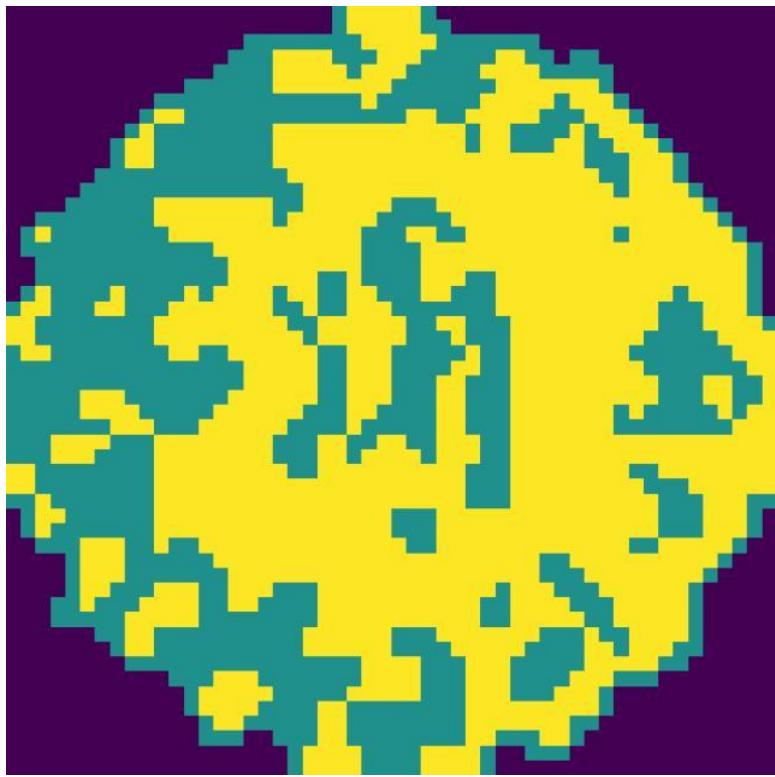
Defect Class: Random

Confidence Score: 0.9976

Defect Percentage: 84.62%

Reason: Defect Percentage: 84.62% (>40% threshold), Defect Class: Random, Confidence: 99.76%

Wafer Defect Image:



Wafer 108 Inspection Decision

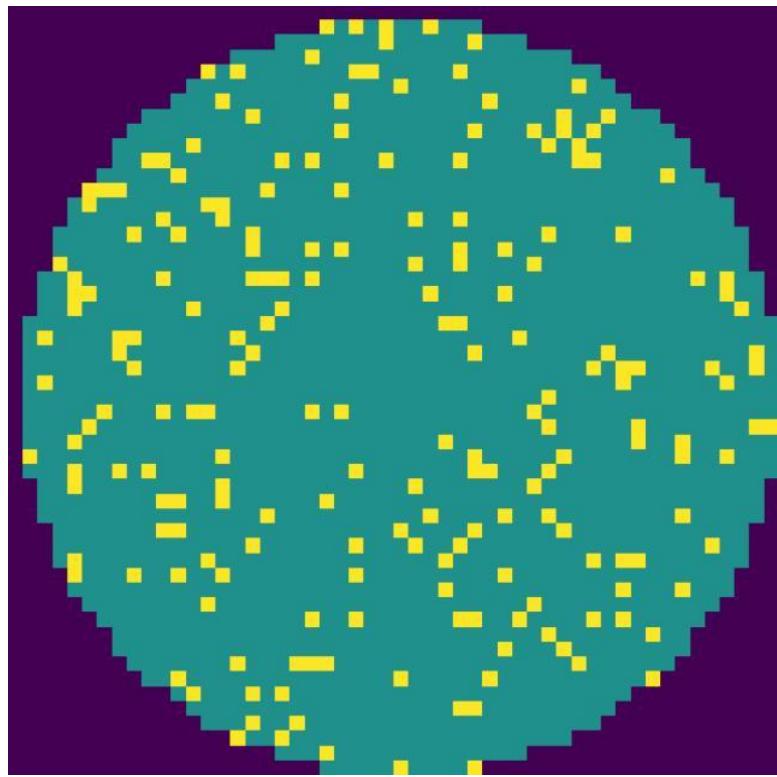
Wafer ID: Electrical_ELEC_02_W0022
Decision: PASS

Machine Type: Electrical
Machine ID: ELEC_02
Timestamp: 2025-12-27T12:06:43.270395
Simulation Date: 2025-12-27

Defect Class: Normal
Confidence Score: 0.9993
Defect Percentage: 36.47%

Reason: Defect Percentage: 36.47% (<=40% threshold), Defect Class: Normal, Confidence: 99.93%

Wafer Defect Image:



Wafer 109 Inspection Decision

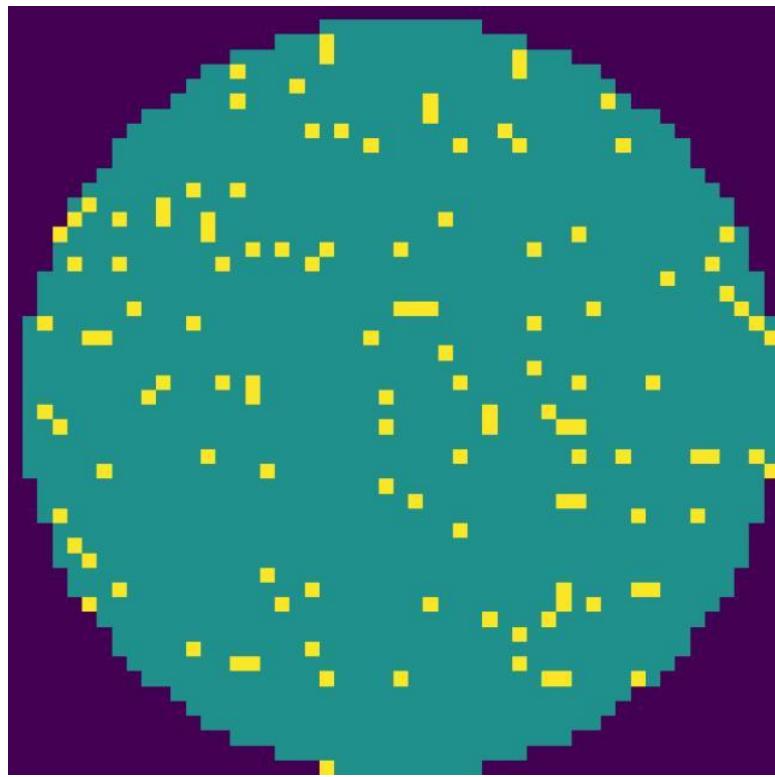
Wafer ID: Mechanical_MECH_02_W0019
Decision: PASS

Machine Type: Mechanical
Machine ID: MECH_02
Timestamp: 2025-12-27T12:06:43.495097
Simulation Date: 2025-12-27

Defect Class: Normal
Confidence Score: 0.9996
Defect Percentage: 35.93%

Reason: Defect Percentage: 35.93% (<=40% threshold), Defect Class: Normal, Confidence: 99.96%

Wafer Defect Image:



Wafer 110 Inspection Decision

Wafer ID: Thermal_THERM_02_W0013

Decision: PASS

Machine Type: Thermal

Machine ID: THERM_02

Timestamp: 2025-12-27T12:06:45.246058

Simulation Date: 2025-12-27

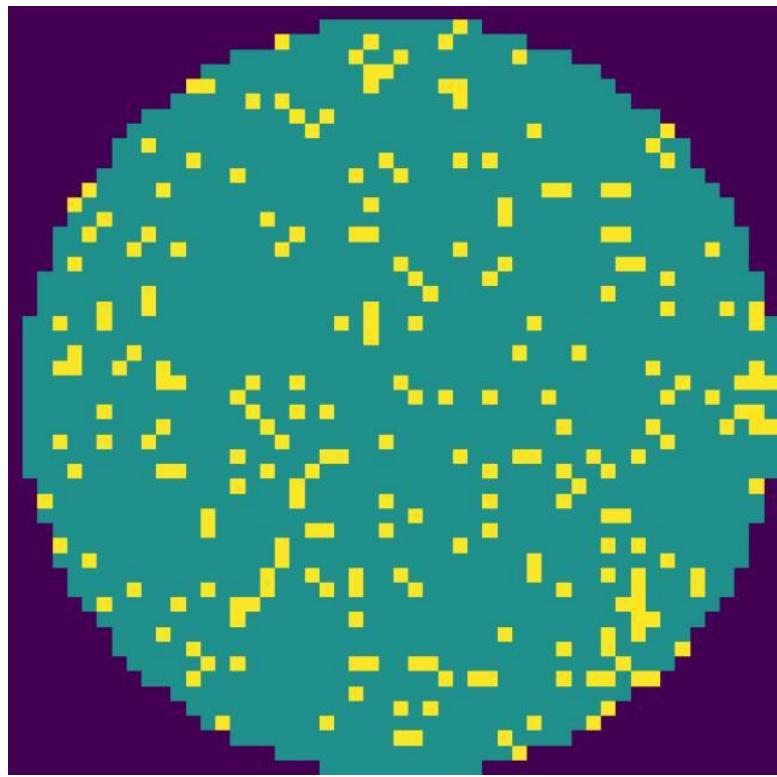
Defect Class: Normal

Confidence Score: 0.9996

Defect Percentage: 37.60%

Reason: Defect Percentage: 37.6% (<=40% threshold), Defect Class: Normal, Confidence: 99.96%

Wafer Defect Image:



Wafer 111 Inspection Decision

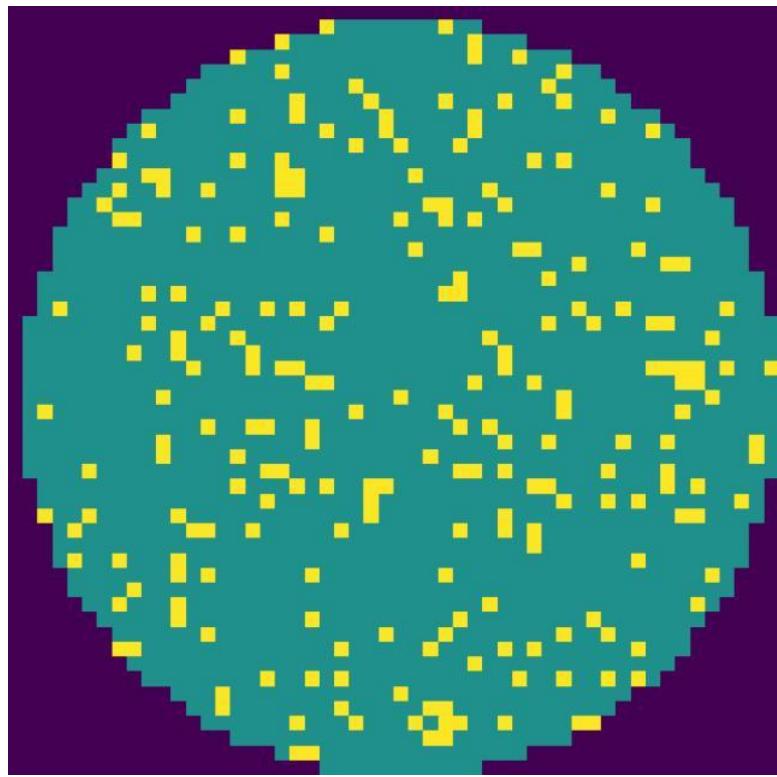
Wafer ID: Mechanical_MECH_01_W0019
Decision: PASS

Machine Type: Mechanical
Machine ID: MECH_01
Timestamp: 2025-12-27T12:06:46.654884
Simulation Date: 2025-12-27

Defect Class: Normal
Confidence Score: 0.9999
Defect Percentage: 37.45%

Reason: Defect Percentage: 37.45% (<=40% threshold), Defect Class: Normal, Confidence: 99.99%

Wafer Defect Image:



Wafer 112 Inspection Decision

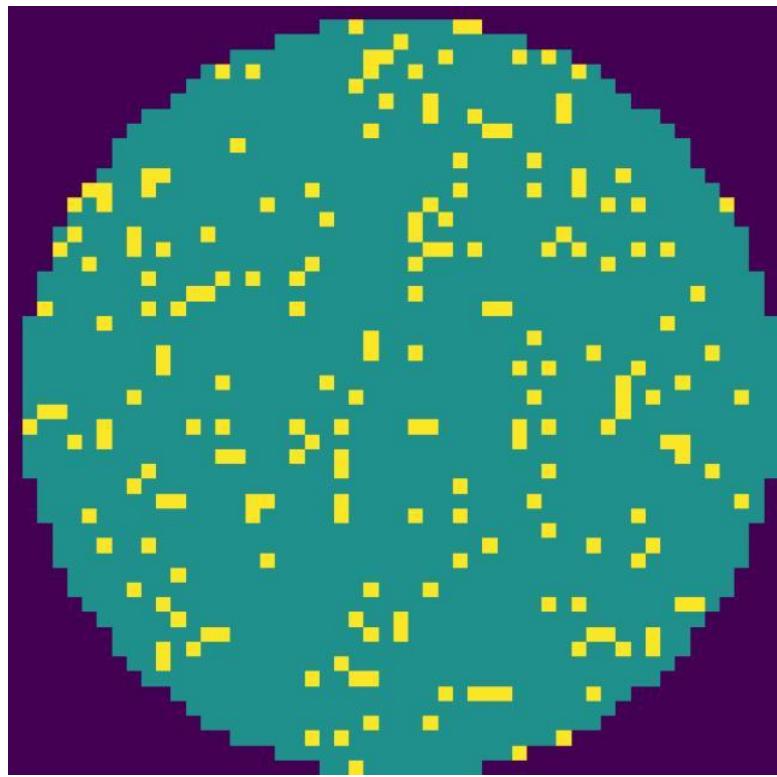
Wafer ID: Electrical_ELEC_01_W0023
Decision: PASS

Machine Type: Electrical
Machine ID: ELEC_01
Timestamp: 2025-12-27T12:06:47.800404
Simulation Date: 2025-12-27

Defect Class: Normal
Confidence Score: 0.9999
Defect Percentage: 36.68%

Reason: Defect Percentage: 36.68% (<=40% threshold), Defect Class: Normal, Confidence: 99.99%

Wafer Defect Image:



Wafer 113 Inspection Decision

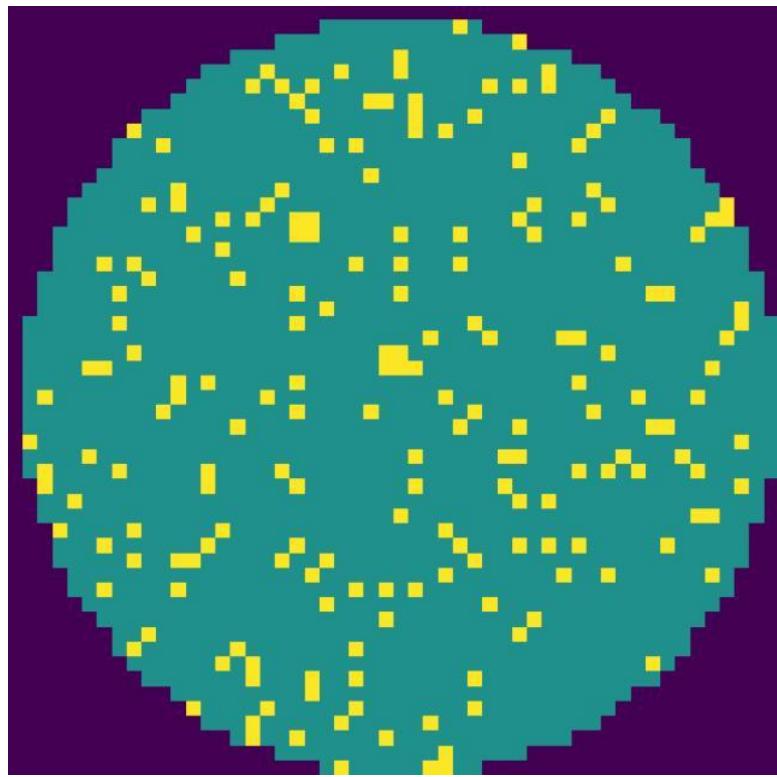
Wafer ID: Electrical_ELEC_02_W0023
Decision: PASS

Machine Type: Electrical
Machine ID: ELEC_02
Timestamp: 2025-12-27T12:06:48.979185
Simulation Date: 2025-12-27

Defect Class: Normal
Confidence Score: 0.9997
Defect Percentage: 36.26%

Reason: Defect Percentage: 36.26% (<=40% threshold), Defect Class: Normal, Confidence: 99.97%

Wafer Defect Image:



Wafer 114 Inspection Decision

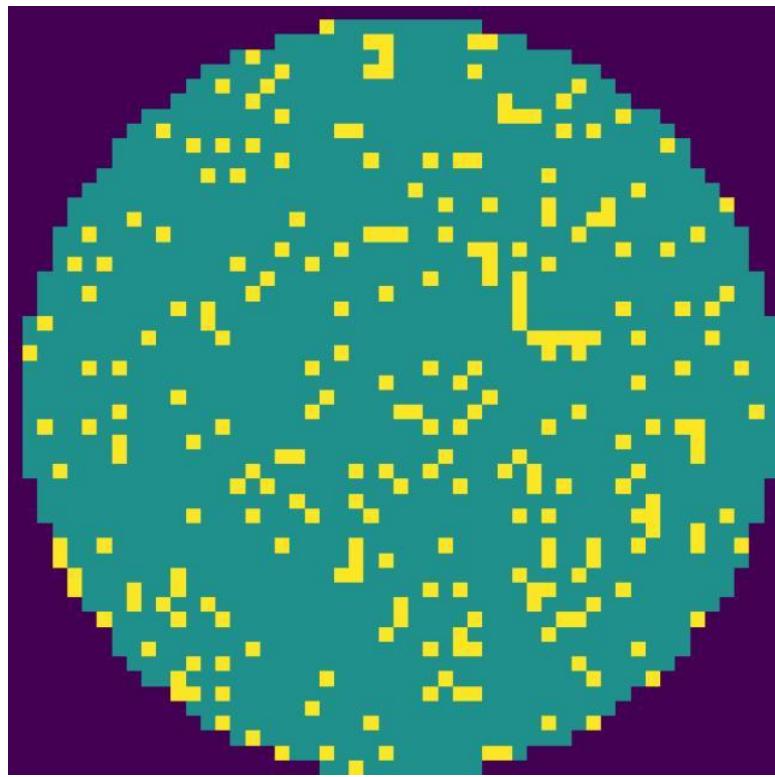
Wafer ID: Mechanical_MECH_02_W0020
Decision: PASS

Machine Type: Mechanical
Machine ID: MECH_02
Timestamp: 2025-12-27T12:06:49.957325
Simulation Date: 2025-12-27

Defect Class: Normal
Confidence Score: 0.9999
Defect Percentage: 37.49%

Reason: Defect Percentage: 37.49% (<=40% threshold), Defect Class: Normal, Confidence: 99.99%

Wafer Defect Image:



Wafer 115 Inspection Decision

Wafer ID: Thermal_THERM_01_W0017

Decision: FAIL

Machine Type: Thermal

Machine ID: THERM_01

Timestamp: 2025-12-27T12:06:50.750237

Simulation Date: 2025-12-27

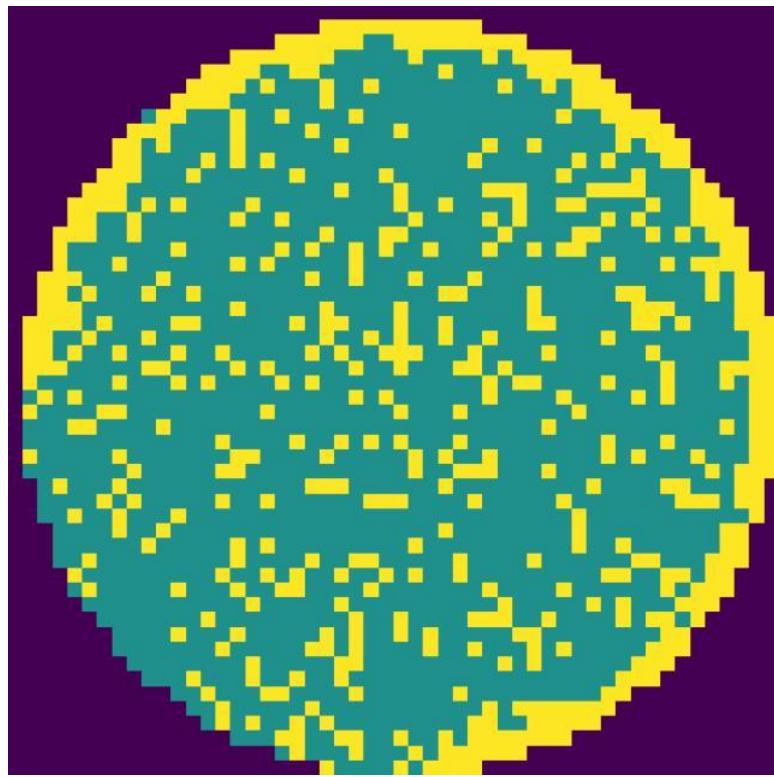
Defect Class: Edge-Loc

Confidence Score: 0.9987

Defect Percentage: 54.02%

Reason: Defect Percentage: 54.02% (>40% threshold), Defect Class: Edge-Loc, Confidence: 99.87%

Wafer Defect Image:



Wafer 116 Inspection Decision

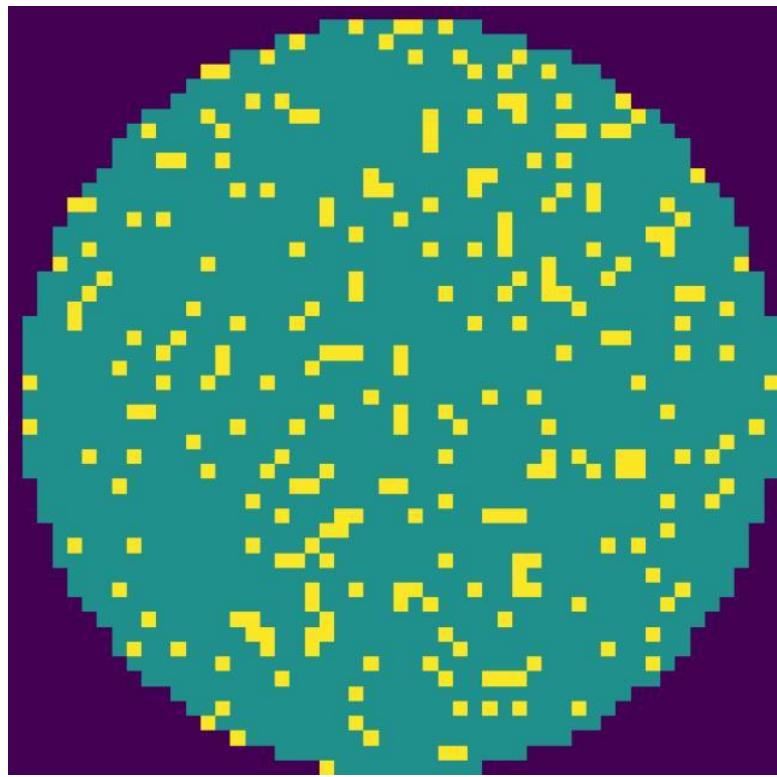
Wafer ID: Thermal_THERM_02_W0014
Decision: PASS

Machine Type: Thermal
Machine ID: THERM_02
Timestamp: 2025-12-27T12:06:52.298564
Simulation Date: 2025-12-27

Defect Class: Normal
Confidence Score: 0.9999
Defect Percentage: 38.54%

Reason: Defect Percentage: 38.54% (<=40% threshold), Defect Class: Normal, Confidence: 99.99%

Wafer Defect Image:



Wafer 117 Inspection Decision

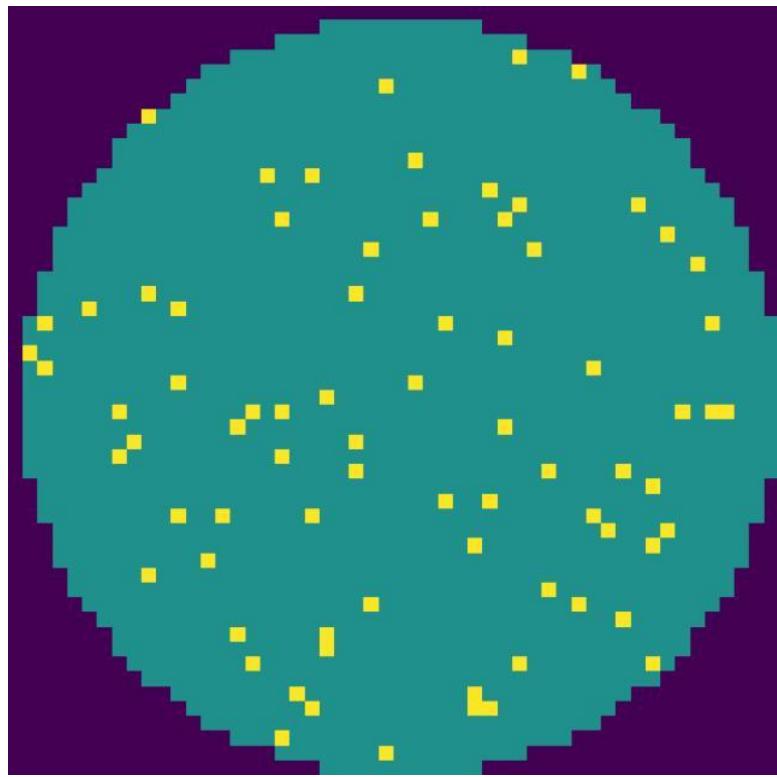
Wafer ID: Mechanical_MECH_01_W0020
Decision: PASS

Machine Type: Mechanical
Machine ID: MECH_01
Timestamp: 2025-12-27T12:06:52.726050
Simulation Date: 2025-12-27

Defect Class: Normal
Confidence Score: 0.9999
Defect Percentage: 32.13%

Reason: Defect Percentage: 32.13% (<=40% threshold), Defect Class: Normal, Confidence: 99.99%

Wafer Defect Image:



Wafer 118 Inspection Decision

Wafer ID: Electrical_ELEC_01_W0024

Decision: FAIL

Machine Type: Electrical

Machine ID: ELEC_01

Timestamp: 2025-12-27T12:06:53.166136

Simulation Date: 2025-12-27

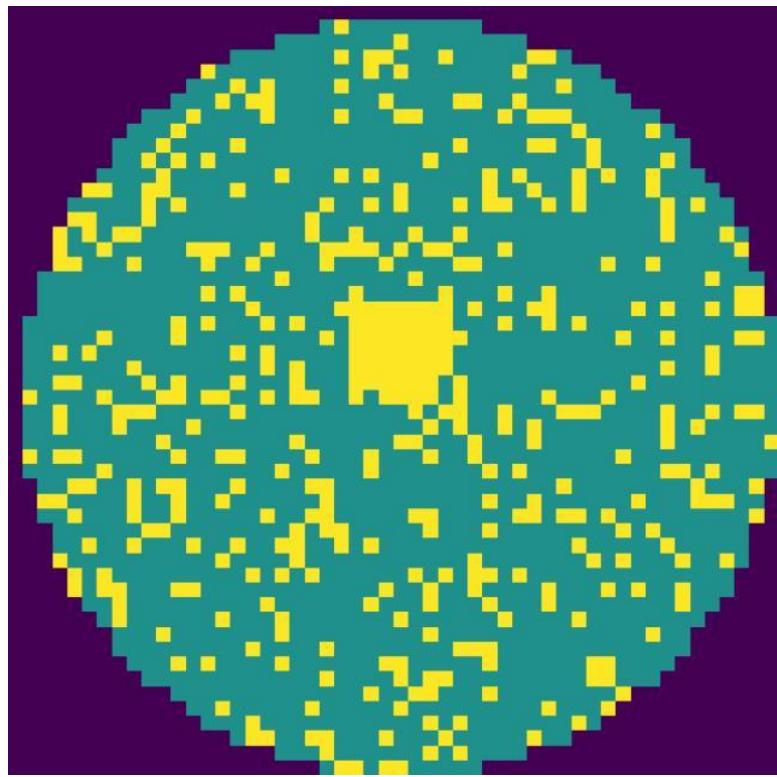
Defect Class: Center

Confidence Score: 0.9996

Defect Percentage: 45.15%

Reason: Defect Percentage: 45.15% (>40% threshold), Defect Class: Center, Confidence: 99.96%

Wafer Defect Image:



Wafer 119 Inspection Decision

Wafer ID: Electrical_ELEC_02_W0024

Decision: FAIL

Machine Type: Electrical

Machine ID: ELEC_02

Timestamp: 2025-12-27T12:06:54.687358

Simulation Date: 2025-12-27

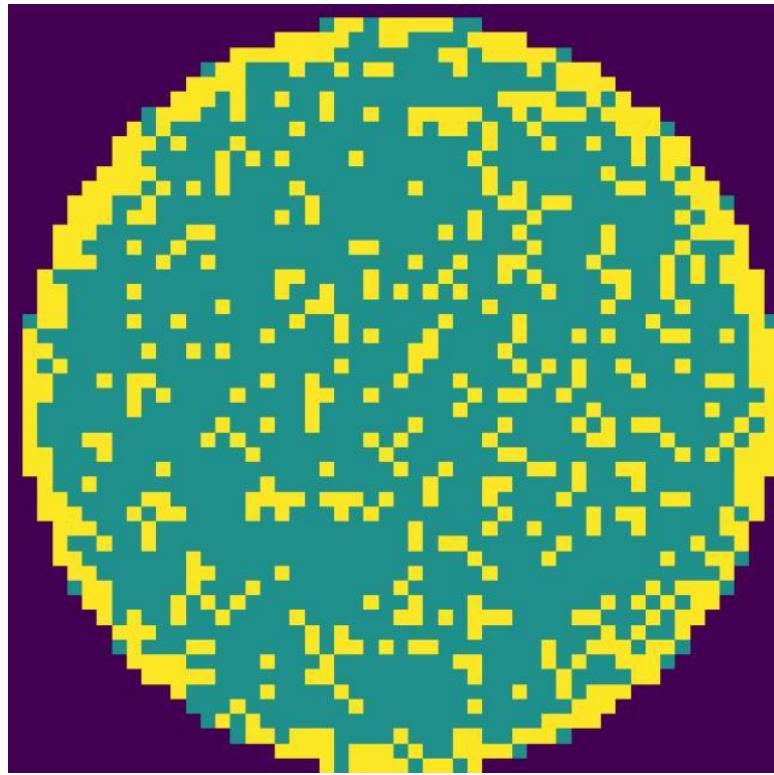
Defect Class: Edge-Ring

Confidence Score: 0.9893

Defect Percentage: 53.70%

Reason: Defect Percentage: 53.7% (>40% threshold), Defect Class: Edge-Ring, Confidence: 98.93%

Wafer Defect Image:



Wafer 120 Inspection Decision

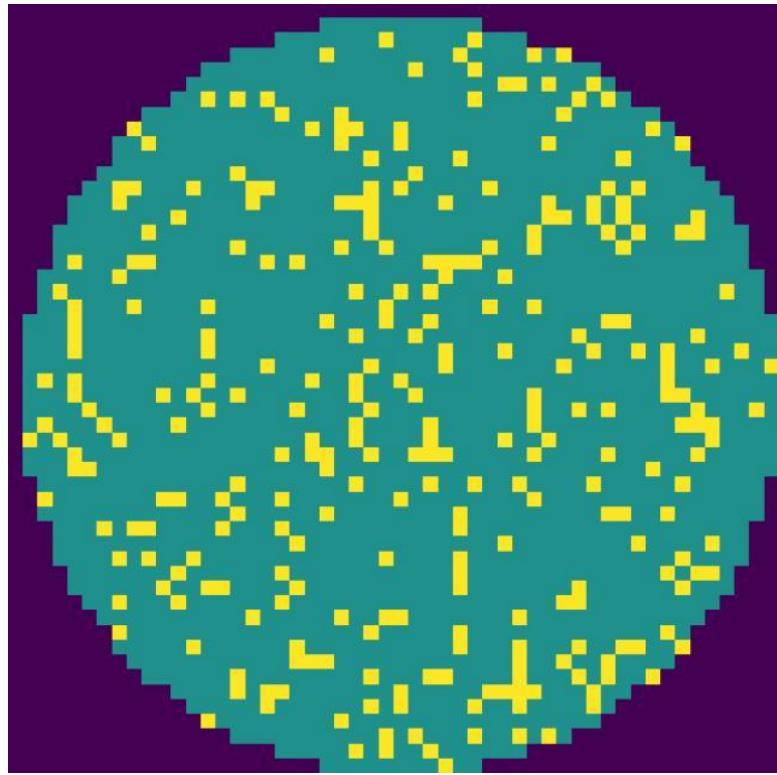
Wafer ID: Thermal_THERM_01_W0018
Decision: PASS

Machine Type: Thermal
Machine ID: THERM_01
Timestamp: 2025-12-27T12:06:55.859420
Simulation Date: 2025-12-27

Defect Class: Normal
Confidence Score: 0.9991
Defect Percentage: 38.98%

Reason: Defect Percentage: 38.98% (<=40% threshold), Defect Class: Normal, Confidence: 99.91%

Wafer Defect Image:



Wafer 121 Inspection Decision

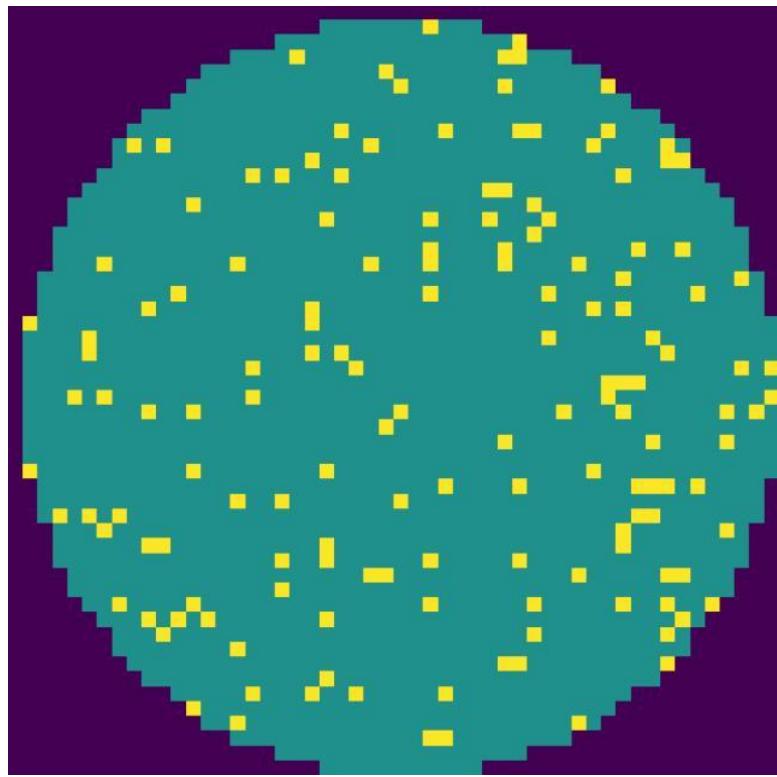
Wafer ID: Mechanical_MECH_02_W0021
Decision: PASS

Machine Type: Mechanical
Machine ID: MECH_02
Timestamp: 2025-12-27T12:06:56.749327
Simulation Date: 2025-12-27

Defect Class: Normal
Confidence Score: 0.9997
Defect Percentage: 35.54%

Reason: Defect Percentage: 35.54% (<=40% threshold), Defect Class: Normal, Confidence: 99.97%

Wafer Defect Image:



Wafer 122 Inspection Decision

Wafer ID: Electrical_ELEC_01_W0025

Decision: PASS

Machine Type: Electrical

Machine ID: ELEC_01

Timestamp: 2025-12-27T12:06:59.057905

Simulation Date: 2025-12-27

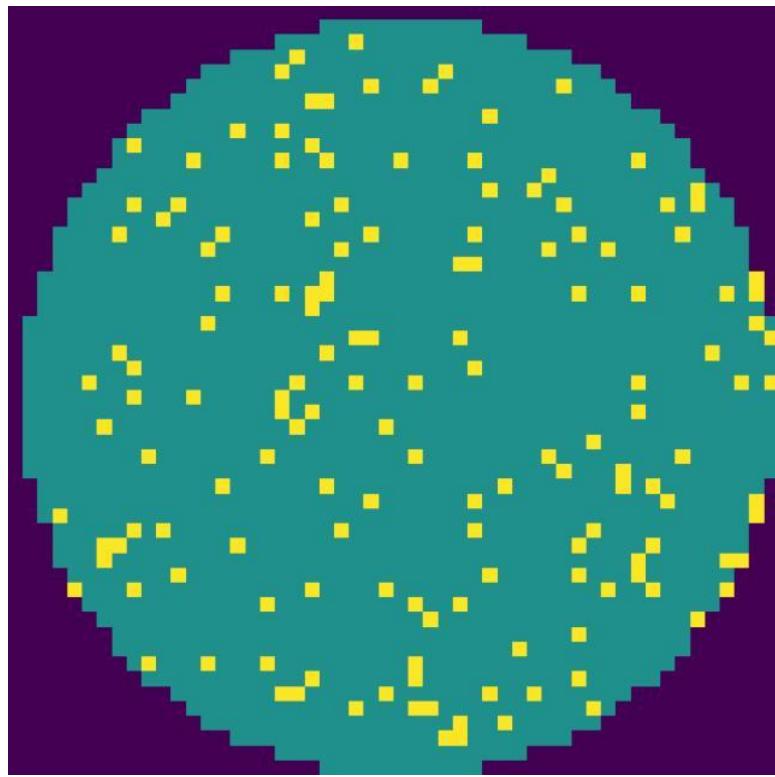
Defect Class: Normal

Confidence Score: 0.9997

Defect Percentage: 34.55%

Reason: Defect Percentage: 34.55% (<=40% threshold), Defect Class: Normal, Confidence: 99.97%

Wafer Defect Image:



Wafer 123 Inspection Decision

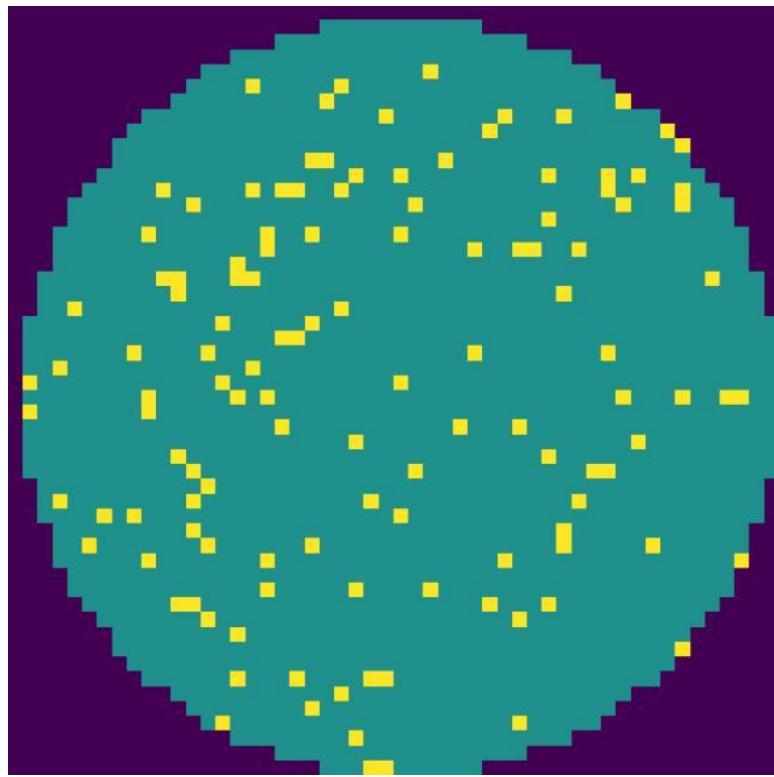
Wafer ID: Mechanical_MECH_01_W0021
Decision: PASS

Machine Type: Mechanical
Machine ID: MECH_01
Timestamp: 2025-12-27T12:06:59.968110
Simulation Date: 2025-12-27

Defect Class: Normal
Confidence Score: 0.9998
Defect Percentage: 34.89%

Reason: Defect Percentage: 34.89% (<=40% threshold), Defect Class: Normal, Confidence: 99.98%

Wafer Defect Image:



Wafer 124 Inspection Decision

Wafer ID: Electrical_ELEC_02_W0025

Decision: PASS

Machine Type: Electrical

Machine ID: ELEC_02

Timestamp: 2025-12-27T12:07:00.672033

Simulation Date: 2025-12-27

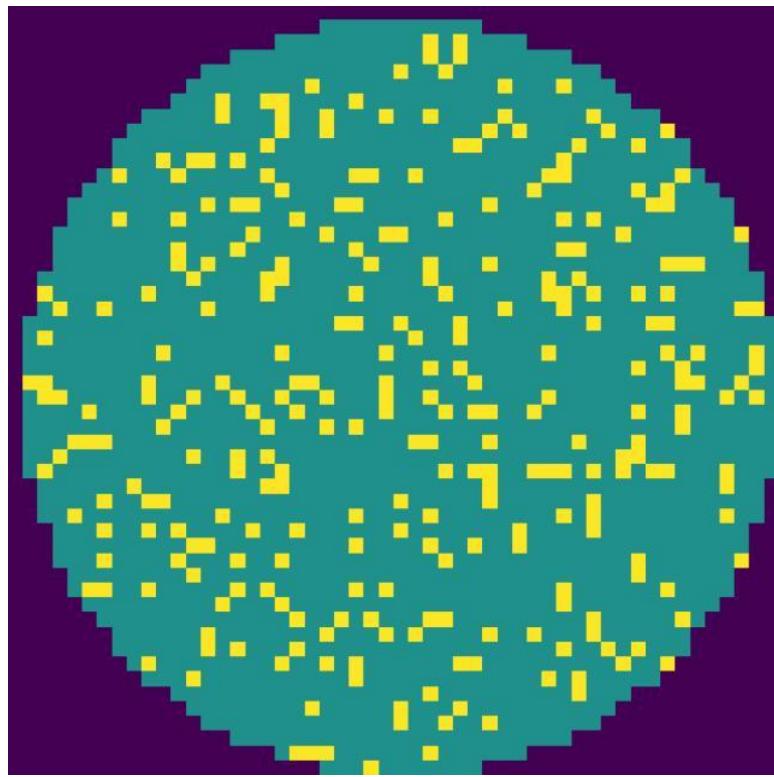
Defect Class: Normal

Confidence Score: 0.9976

Defect Percentage: 37.70%

Reason: Defect Percentage: 37.7% (<=40% threshold), Defect Class: Normal, Confidence: 99.76%

Wafer Defect Image:



Wafer 125 Inspection Decision

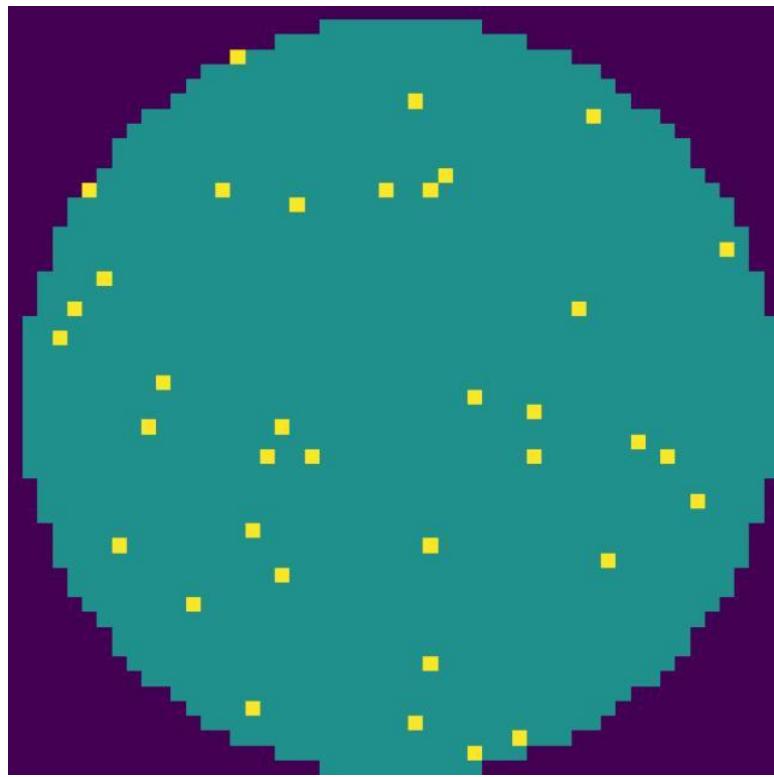
Wafer ID: Thermal_THERM_01_W0019
Decision: PASS

Machine Type: Thermal
Machine ID: THERM_01
Timestamp: 2025-12-27T12:07:01.498254
Simulation Date: 2025-12-27

Defect Class: Normal
Confidence Score: 0.9999
Defect Percentage: 31.11%

Reason: Defect Percentage: 31.11% (<=40% threshold), Defect Class: Normal, Confidence: 99.99%

Wafer Defect Image:



Wafer 126 Inspection Decision

Wafer ID: Thermal_THERM_02_W0015

Decision: FAIL

Machine Type: Thermal

Machine ID: THERM_02

Timestamp: 2025-12-27T12:07:02.734960

Simulation Date: 2025-12-27

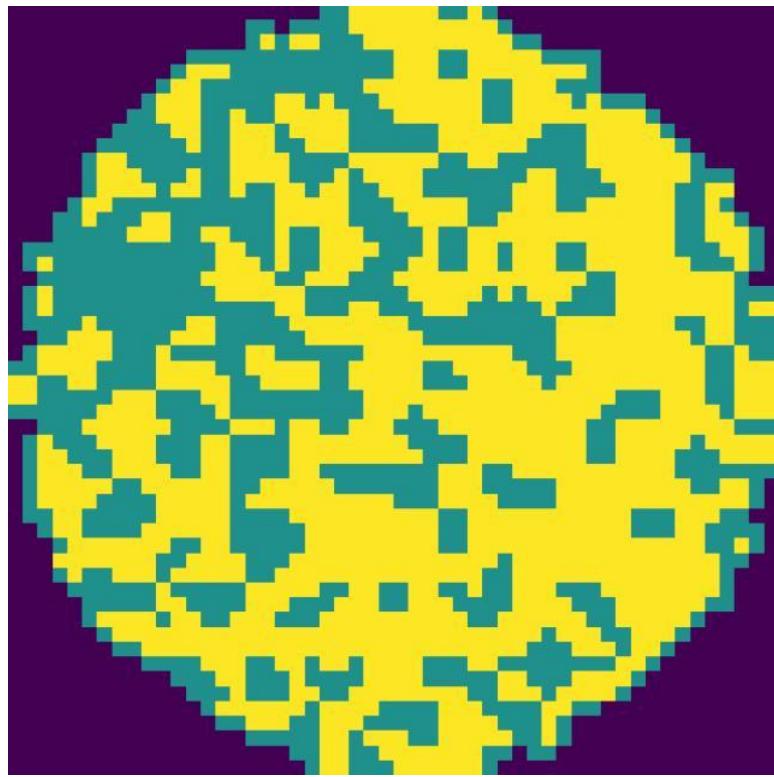
Defect Class: Random

Confidence Score: 0.9999

Defect Percentage: 79.42%

Reason: Defect Percentage: 79.42% (>40% threshold), Defect Class: Random, Confidence: 99.99%

Wafer Defect Image:



Wafer 127 Inspection Decision

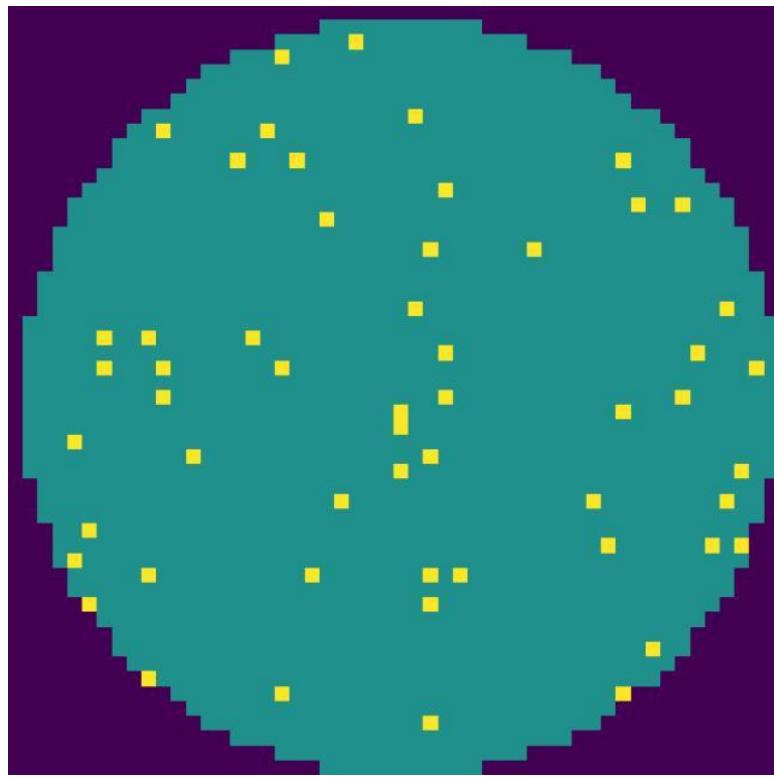
Wafer ID: Mechanical_MECH_02_W0022
Decision: PASS

Machine Type: Mechanical
Machine ID: MECH_02
Timestamp: 2025-12-27T12:07:03.106505
Simulation Date: 2025-12-27

Defect Class: Normal
Confidence Score: 0.9998
Defect Percentage: 30.86%

Reason: Defect Percentage: 30.86% (<=40% threshold), Defect Class: Normal, Confidence: 99.98%

Wafer Defect Image:



Wafer 128 Inspection Decision

Wafer ID: Electrical_ELEC_01_W0026

Decision: FAIL

Machine Type: Electrical

Machine ID: ELEC_01

Timestamp: 2025-12-27T12:07:04.430468

Simulation Date: 2025-12-27

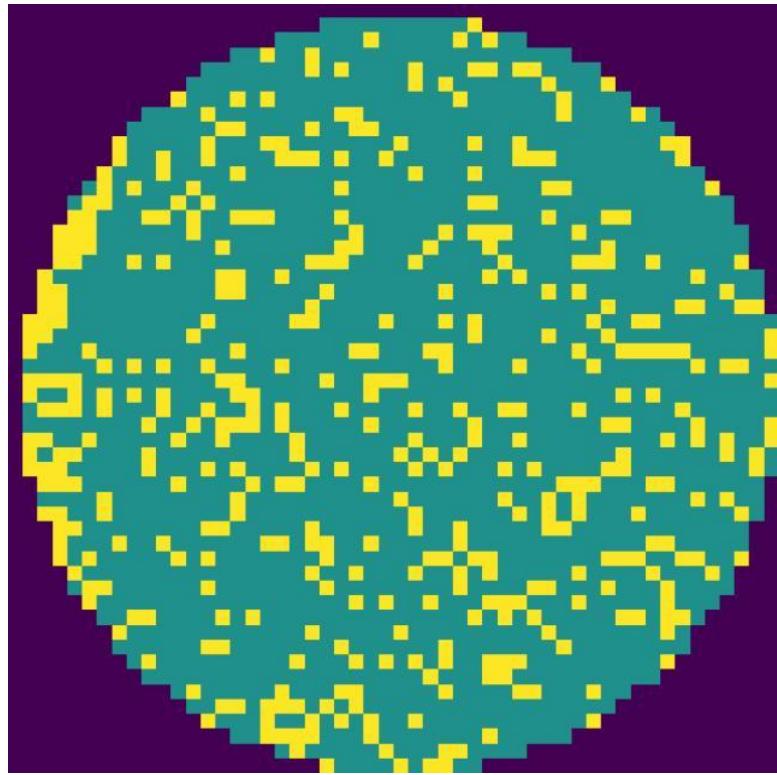
Defect Class: Edge-Loc

Confidence Score: 0.9893

Defect Percentage: 44.78%

Reason: Defect Percentage: 44.78% (>40% threshold), Defect Class: Edge-Loc, Confidence: 98.93%

Wafer Defect Image:



Wafer 129 Inspection Decision

Wafer ID: Electrical_ELEC_02_W0026

Decision: PASS

Machine Type: Electrical

Machine ID: ELEC_02

Timestamp: 2025-12-27T12:07:05.717798

Simulation Date: 2025-12-27

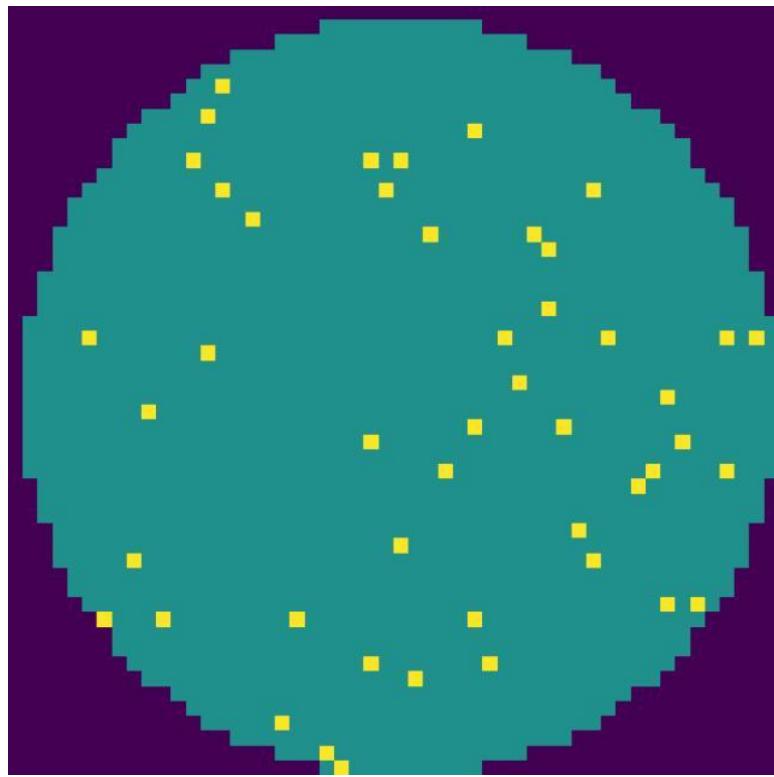
Defect Class: Normal

Confidence Score: 0.9998

Defect Percentage: 30.04%

Reason: Defect Percentage: 30.04% (<=40% threshold), Defect Class: Normal, Confidence: 99.98%

Wafer Defect Image:



Wafer 130 Inspection Decision

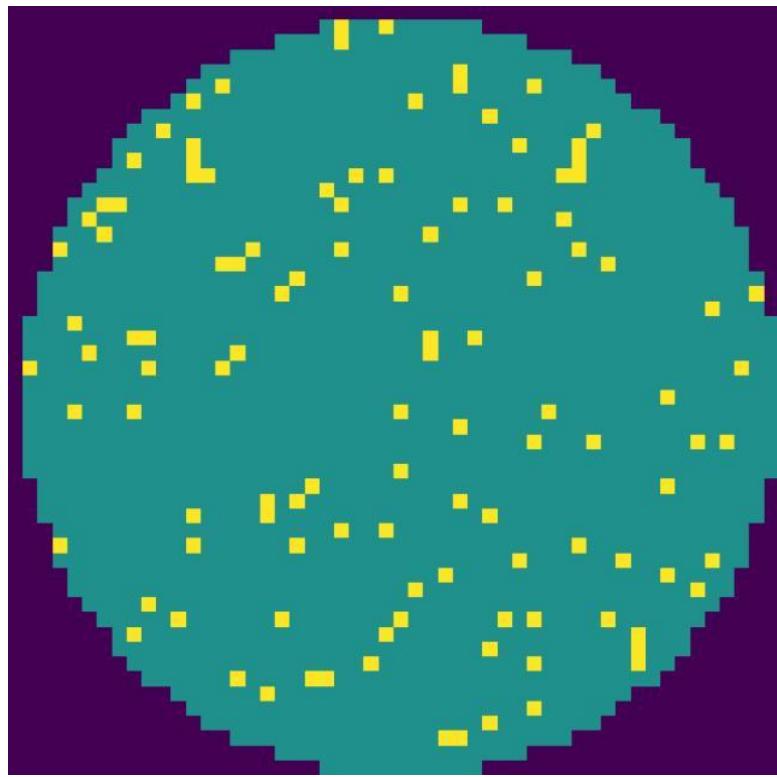
Wafer ID: Mechanical_MECH_01_W0022
Decision: PASS

Machine Type: Mechanical
Machine ID: MECH_01
Timestamp: 2025-12-27T12:07:06.873197
Simulation Date: 2025-12-27

Defect Class: Normal
Confidence Score: 0.9997
Defect Percentage: 34.20%

Reason: Defect Percentage: 34.2% (<=40% threshold), Defect Class: Normal, Confidence: 99.97%

Wafer Defect Image:



Wafer 131 Inspection Decision

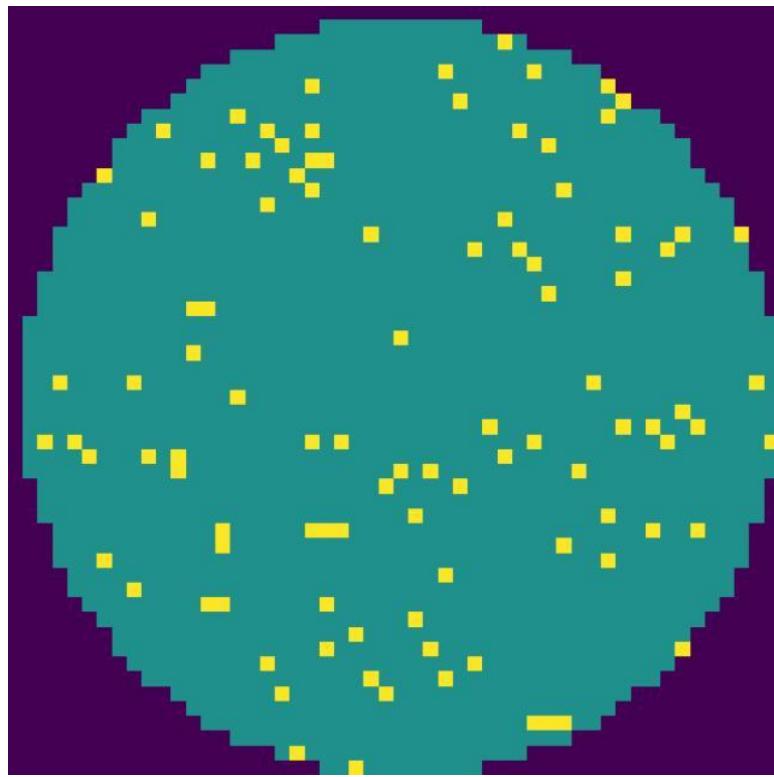
Wafer ID: Mechanical_MECH_02_W0023
Decision: PASS

Machine Type: Mechanical
Machine ID: MECH_02
Timestamp: 2025-12-27T12:07:09.854951
Simulation Date: 2025-12-27

Defect Class: Normal
Confidence Score: 0.9998
Defect Percentage: 33.38%

Reason: Defect Percentage: 33.38% (<=40% threshold), Defect Class: Normal, Confidence: 99.98%

Wafer Defect Image:



Wafer 132 Inspection Decision

Wafer ID: Electrical_ELEC_01_W0027

Decision: PASS

Machine Type: Electrical

Machine ID: ELEC_01

Timestamp: 2025-12-27T12:07:10.288258

Simulation Date: 2025-12-27

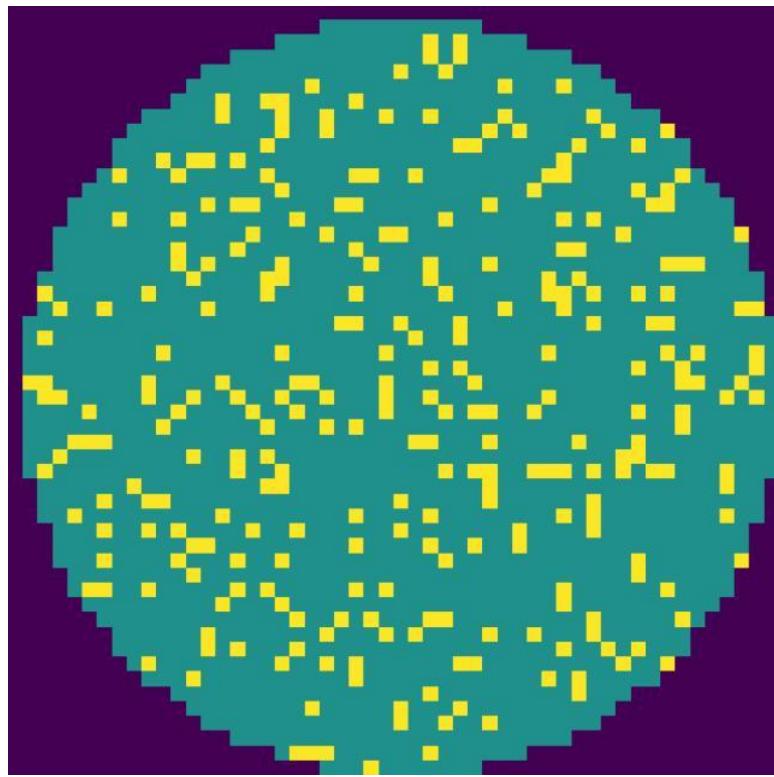
Defect Class: Normal

Confidence Score: 0.9976

Defect Percentage: 37.70%

Reason: Defect Percentage: 37.7% (<=40% threshold), Defect Class: Normal, Confidence: 99.76%

Wafer Defect Image:



Wafer 133 Inspection Decision

Wafer ID: Electrical_ELEC_02_W0027

Decision: PASS

Machine Type: Electrical

Machine ID: ELEC_02

Timestamp: 2025-12-27T12:07:10.797005

Simulation Date: 2025-12-27

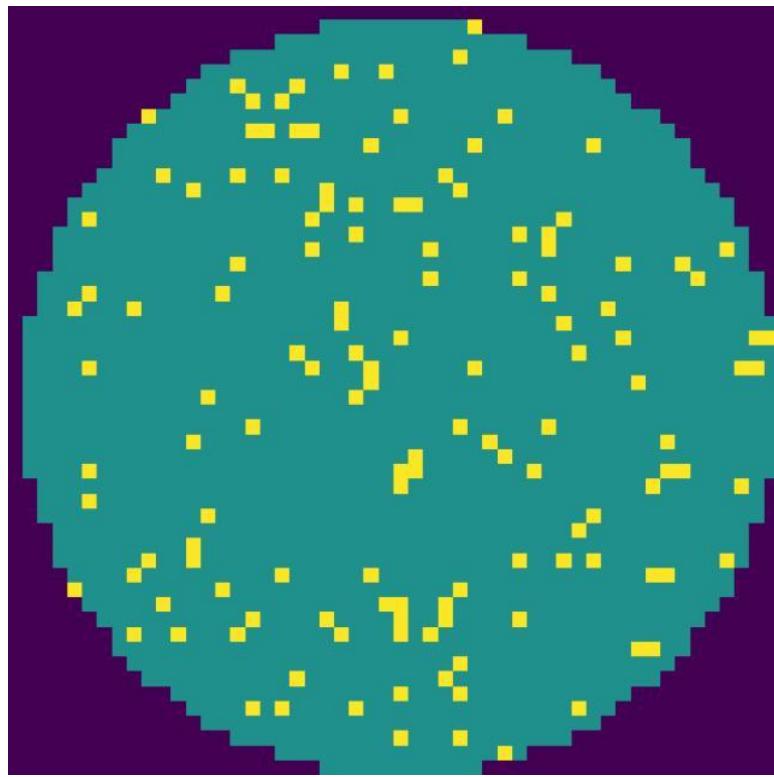
Defect Class: Normal

Confidence Score: 0.9997

Defect Percentage: 34.83%

Reason: Defect Percentage: 34.83% (<=40% threshold), Defect Class: Normal, Confidence: 99.97%

Wafer Defect Image:



Wafer 134 Inspection Decision

Wafer ID: Thermal_THERM_01_W0020

Decision: PASS

Machine Type: Thermal

Machine ID: THERM_01

Timestamp: 2025-12-27T12:07:12.096002

Simulation Date: 2025-12-27

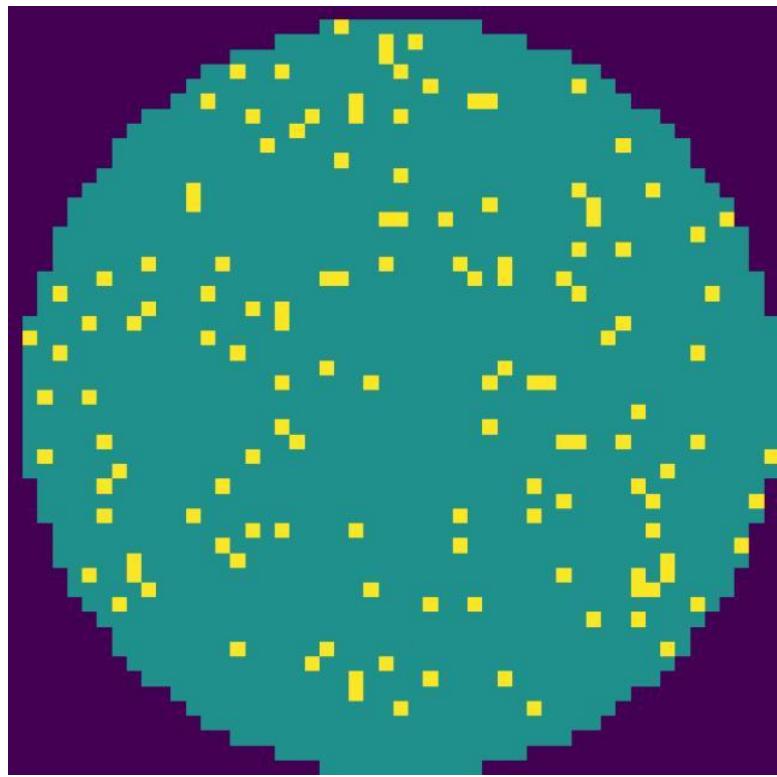
Defect Class: Normal

Confidence Score: 0.9998

Defect Percentage: 34.03%

Reason: Defect Percentage: 34.03% (<=40% threshold), Defect Class: Normal, Confidence: 99.98%

Wafer Defect Image:



Wafer 135 Inspection Decision

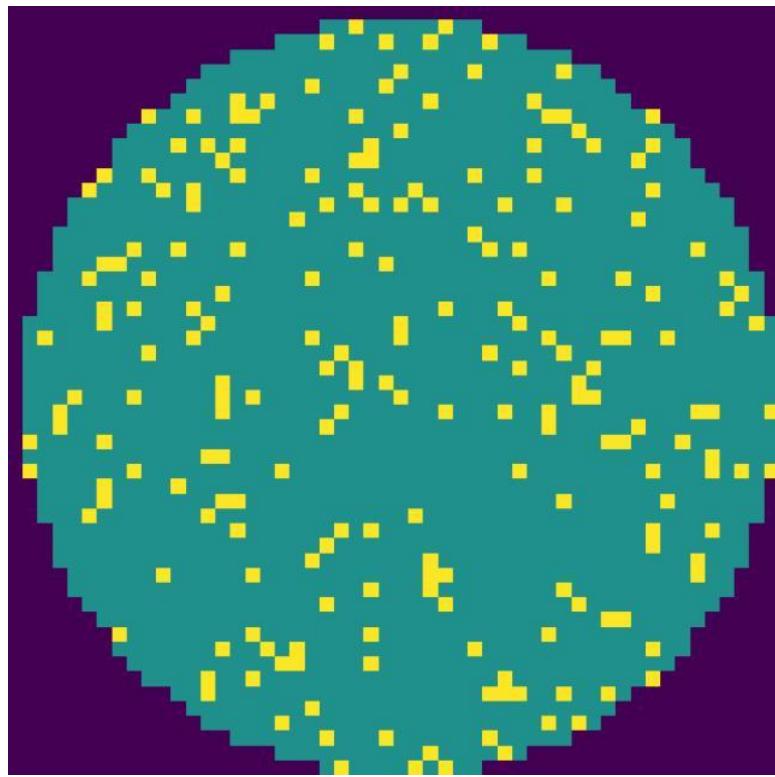
Wafer ID: Mechanical_MECH_01_W0023
Decision: PASS

Machine Type: Mechanical
Machine ID: MECH_01
Timestamp: 2025-12-27T12:07:13.152086
Simulation Date: 2025-12-27

Defect Class: Normal
Confidence Score: 0.9997
Defect Percentage: 35.74%

Reason: Defect Percentage: 35.74% (<=40% threshold), Defect Class: Normal, Confidence: 99.97%

Wafer Defect Image:



Wafer 136 Inspection Decision

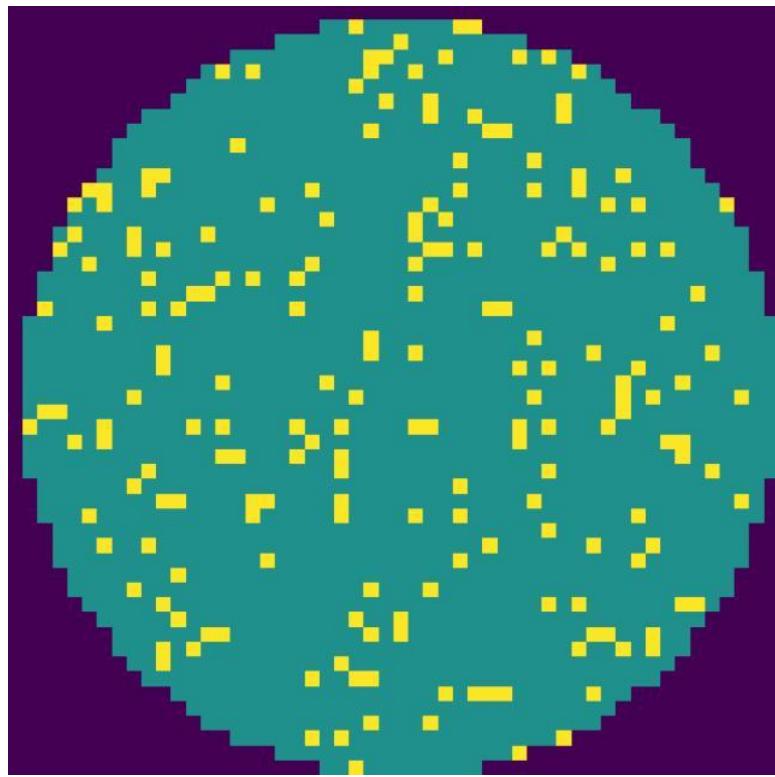
Wafer ID: Thermal_THERM_02_W0016
Decision: PASS

Machine Type: Thermal
Machine ID: THERM_02
Timestamp: 2025-12-27T12:07:13.822573
Simulation Date: 2025-12-27

Defect Class: Normal
Confidence Score: 0.9999
Defect Percentage: 36.68%

Reason: Defect Percentage: 36.68% (<=40% threshold), Defect Class: Normal, Confidence: 99.99%

Wafer Defect Image:



Wafer 137 Inspection Decision

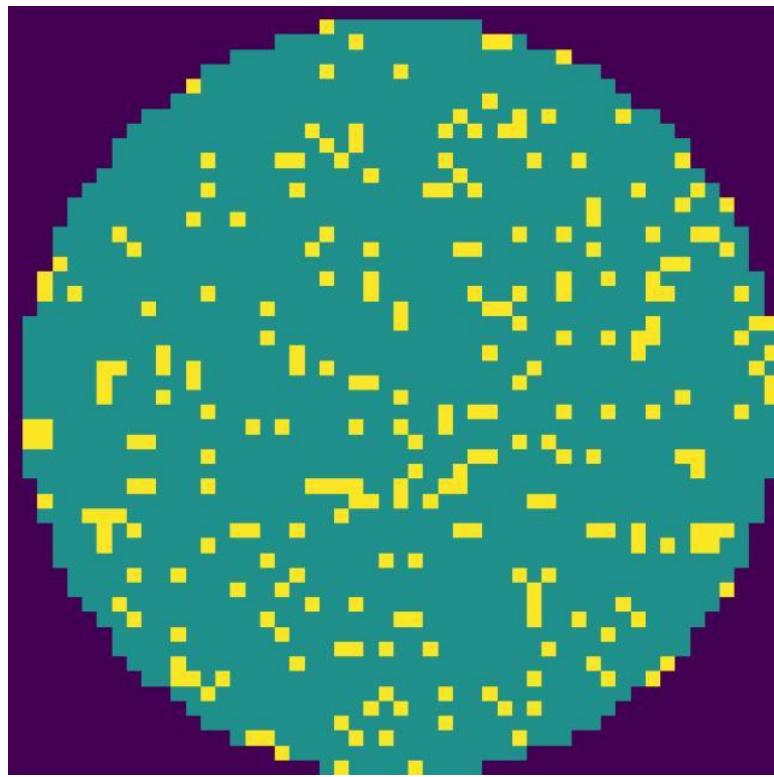
Wafer ID: Mechanical_MECH_02_W0024
Decision: PASS

Machine Type: Mechanical
Machine ID: MECH_02
Timestamp: 2025-12-27T12:07:15.997936
Simulation Date: 2025-12-27

Defect Class: Normal
Confidence Score: 0.9999
Defect Percentage: 39.60%

Reason: Defect Percentage: 39.6% (<=40% threshold), Defect Class: Normal, Confidence: 99.99%

Wafer Defect Image:



Wafer 138 Inspection Decision

Wafer ID: Electrical_ELEC_01_W0028

Decision: FAIL

Machine Type: Electrical

Machine ID: ELEC_01

Timestamp: 2025-12-27T12:07:15.997936

Simulation Date: 2025-12-27

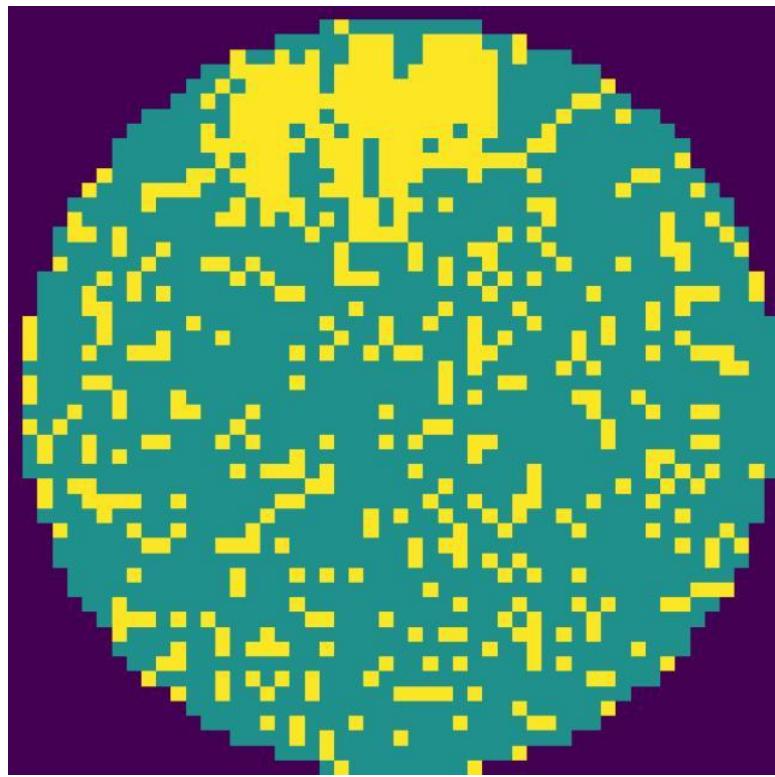
Defect Class: Local

Confidence Score: 1.0000

Defect Percentage: 51.96%

Reason: Defect Percentage: 51.96% (>40% threshold), Defect Class: Local, Confidence: 100.00%

Wafer Defect Image:



Wafer 139 Inspection Decision

Wafer ID: Electrical_ELEC_02_W0028

Decision: PASS

Machine Type: Electrical

Machine ID: ELEC_02

Timestamp: 2025-12-27T12:07:16.215188

Simulation Date: 2025-12-27

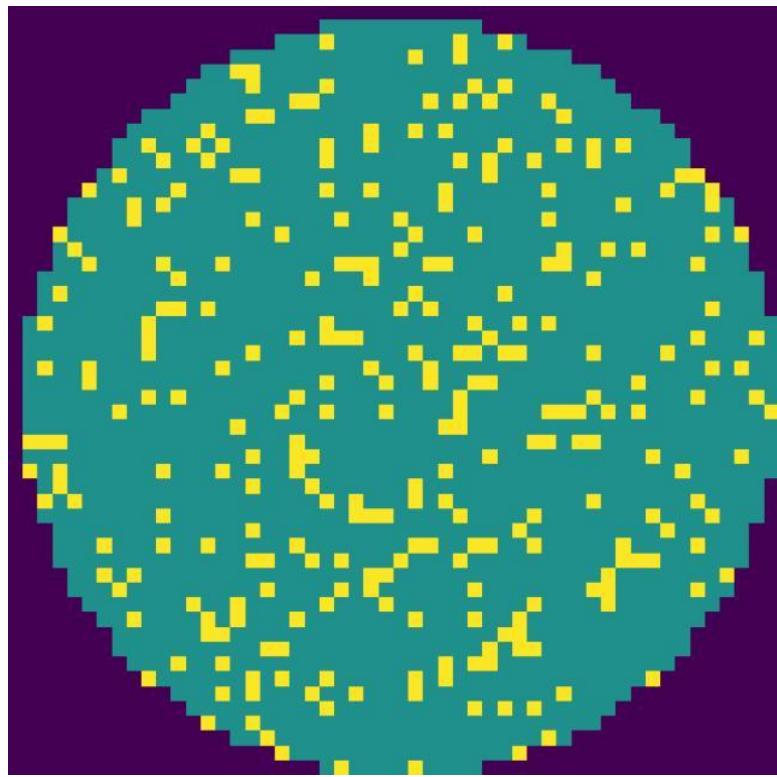
Defect Class: Normal

Confidence Score: 0.9999

Defect Percentage: 38.27%

Reason: Defect Percentage: 38.27% (<=40% threshold), Defect Class: Normal, Confidence: 99.99%

Wafer Defect Image:



Wafer 140 Inspection Decision

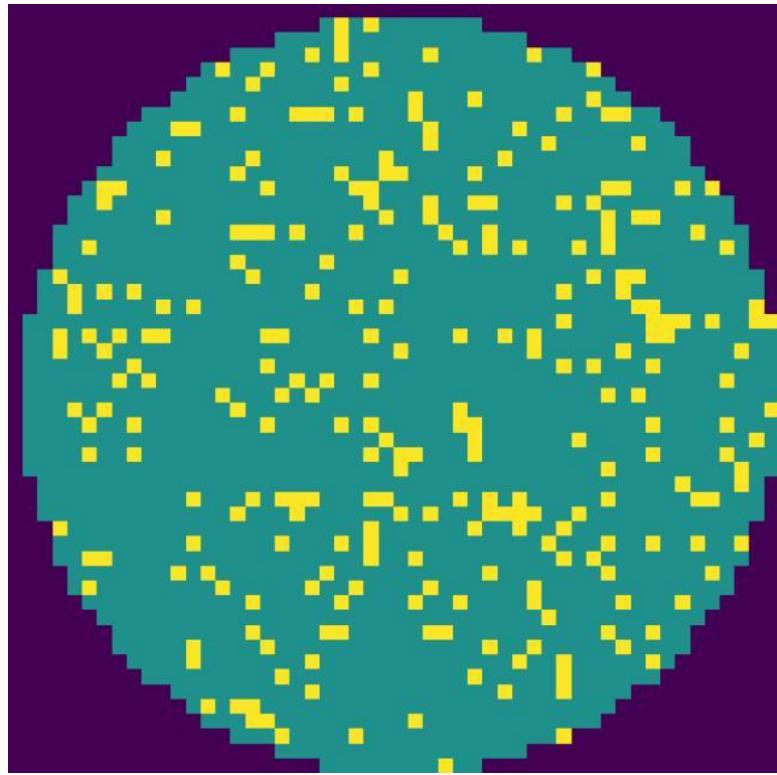
Wafer ID: Mechanical_MECH_01_W0024
Decision: PASS

Machine Type: Mechanical
Machine ID: MECH_01
Timestamp: 2025-12-27T12:07:20.761128
Simulation Date: 2025-12-27

Defect Class: Normal
Confidence Score: 0.9999
Defect Percentage: 37.90%

Reason: Defect Percentage: 37.9% (<=40% threshold), Defect Class: Normal, Confidence: 99.99%

Wafer Defect Image:



Wafer 141 Inspection Decision

Wafer ID: Electrical_ELEC_02_W0029

Decision: PASS

Machine Type: Electrical

Machine ID: ELEC_02

Timestamp: 2025-12-27T12:07:21.762754

Simulation Date: 2025-12-27

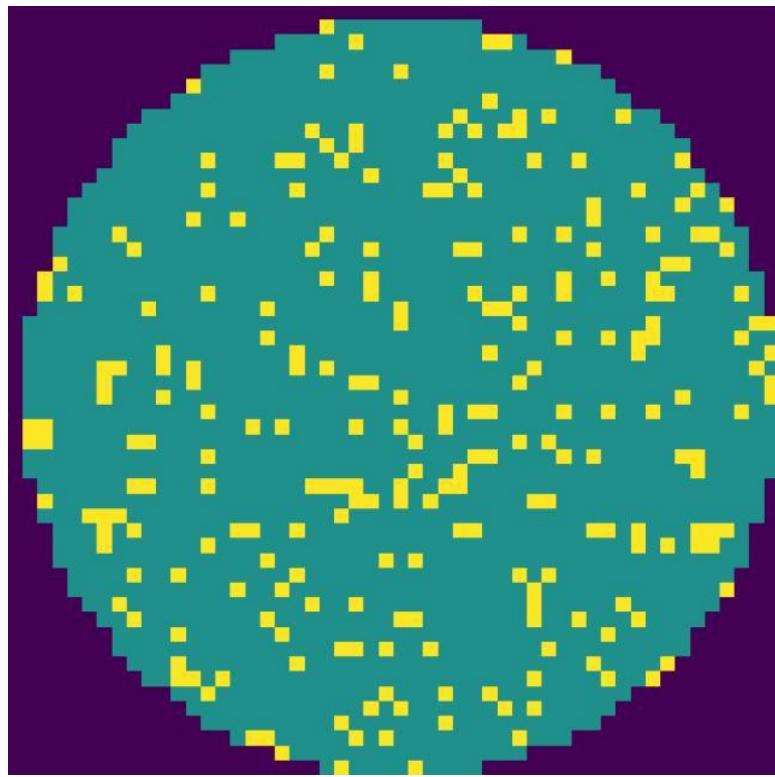
Defect Class: Normal

Confidence Score: 0.9999

Defect Percentage: 39.60%

Reason: Defect Percentage: 39.6% (<=40% threshold), Defect Class: Normal, Confidence: 99.99%

Wafer Defect Image:



Wafer 142 Inspection Decision

Wafer ID: Thermal_THERM_01_W0021

Decision: FAIL

Machine Type: Thermal

Machine ID: THERM_01

Timestamp: 2025-12-27T12:07:21.774080

Simulation Date: 2025-12-27

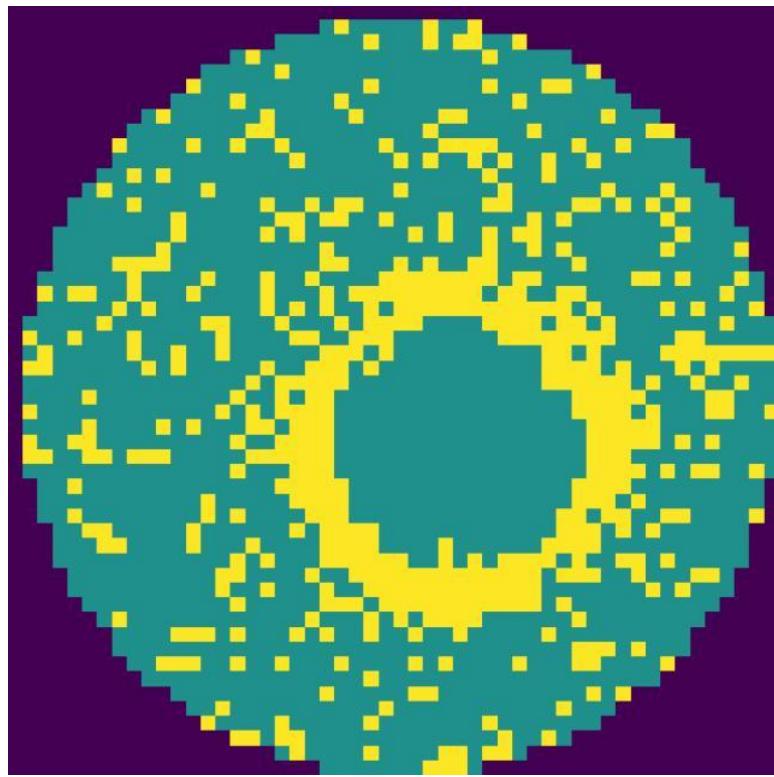
Defect Class: Donut

Confidence Score: 0.9982

Defect Percentage: 55.10%

Reason: Defect Percentage: 55.1% (>40% threshold), Defect Class: Donut, Confidence: 99.82%

Wafer Defect Image:



Wafer 143 Inspection Decision

Wafer ID: Electrical_ELEC_01_W0029

Decision: PASS

Machine Type: Electrical

Machine ID: ELEC_01

Timestamp: 2025-12-27T12:07:21.972610

Simulation Date: 2025-12-27

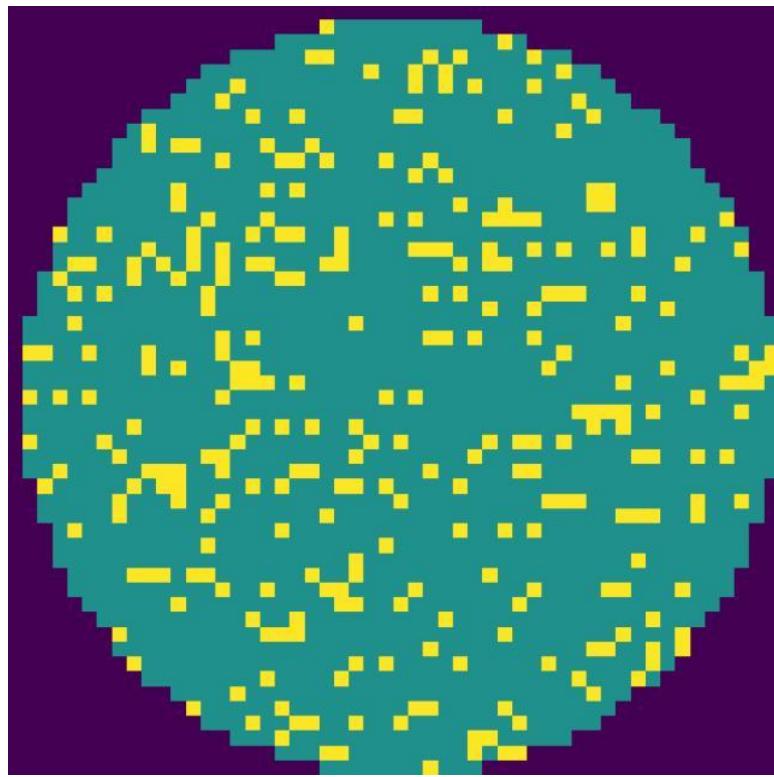
Defect Class: Normal

Confidence Score: 0.9995

Defect Percentage: 39.46%

Reason: Defect Percentage: 39.46% (<=40% threshold), Defect Class: Normal, Confidence: 99.95%

Wafer Defect Image:



Wafer 144 Inspection Decision

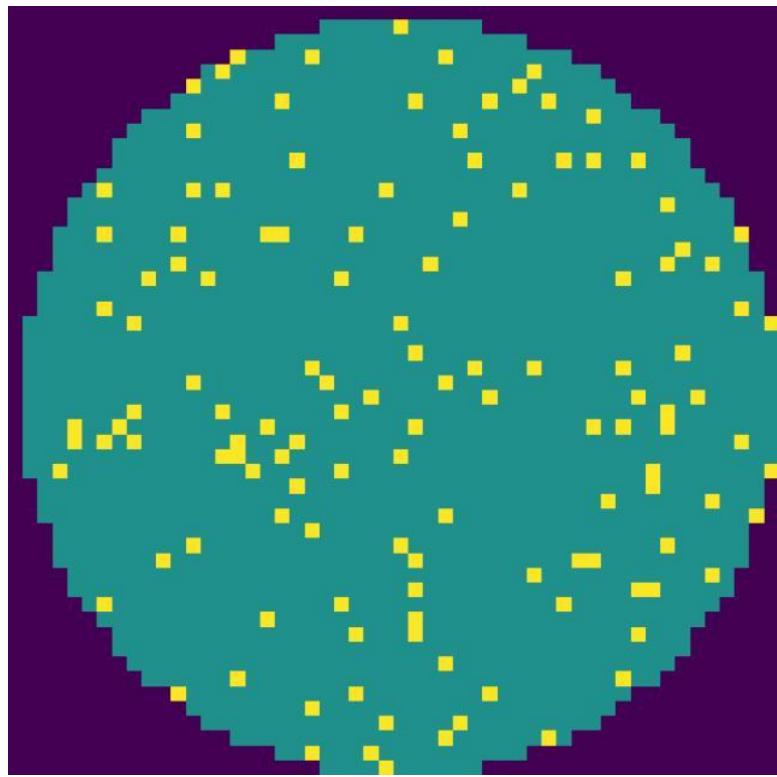
Wafer ID: Mechanical_MECH_02_W0025
Decision: PASS

Machine Type: Mechanical
Machine ID: MECH_02
Timestamp: 2025-12-27T12:07:22.316698
Simulation Date: 2025-12-27

Defect Class: Normal
Confidence Score: 0.9998
Defect Percentage: 33.33%

Reason: Defect Percentage: 33.33% (<=40% threshold), Defect Class: Normal, Confidence: 99.98%

Wafer Defect Image:



Wafer 145 Inspection Decision

Wafer ID: Thermal_THERM_02_W0017

Decision: PASS

Machine Type: Thermal

Machine ID: THERM_02

Timestamp: 2025-12-27T12:07:23.586239

Simulation Date: 2025-12-27

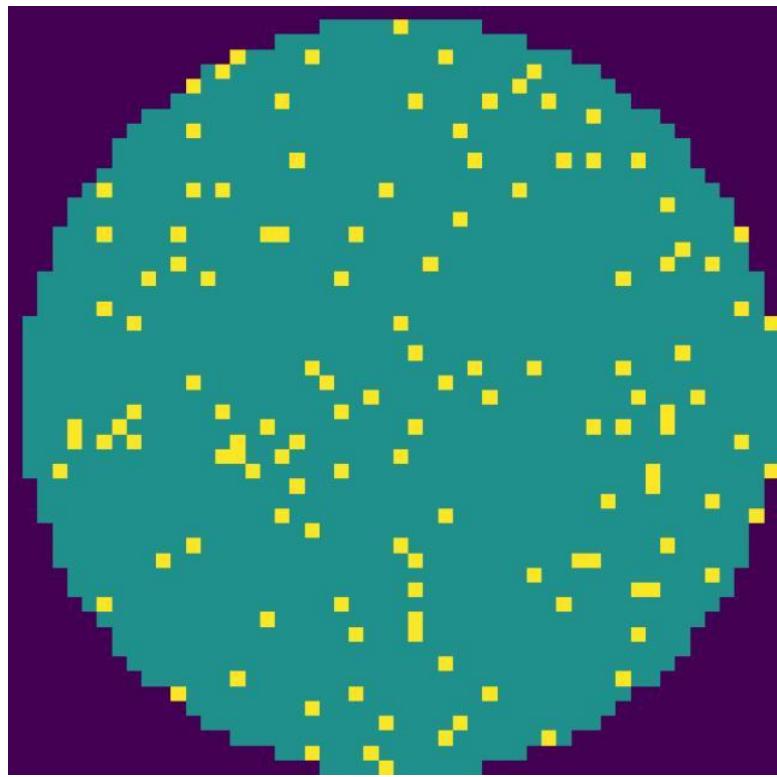
Defect Class: Normal

Confidence Score: 0.9998

Defect Percentage: 33.33%

Reason: Defect Percentage: 33.33% (<=40% threshold), Defect Class: Normal, Confidence: 99.98%

Wafer Defect Image:



Wafer 146 Inspection Decision

Wafer ID: Mechanical_MECH_01_W0025

Decision: FAIL

Machine Type: Mechanical

Machine ID: MECH_01

Timestamp: 2025-12-27T12:07:25.964321

Simulation Date: 2025-12-27

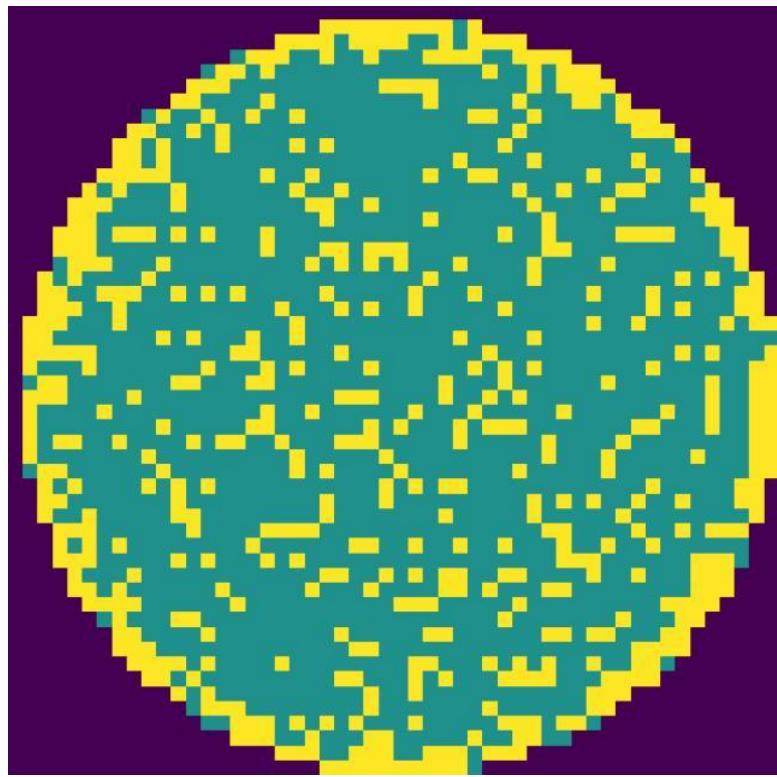
Defect Class: Edge-Ring

Confidence Score: 0.9951

Defect Percentage: 53.62%

Reason: Defect Percentage: 53.62% (>40% threshold), Defect Class: Edge-Ring, Confidence: 99.51%

Wafer Defect Image:



Wafer 147 Inspection Decision

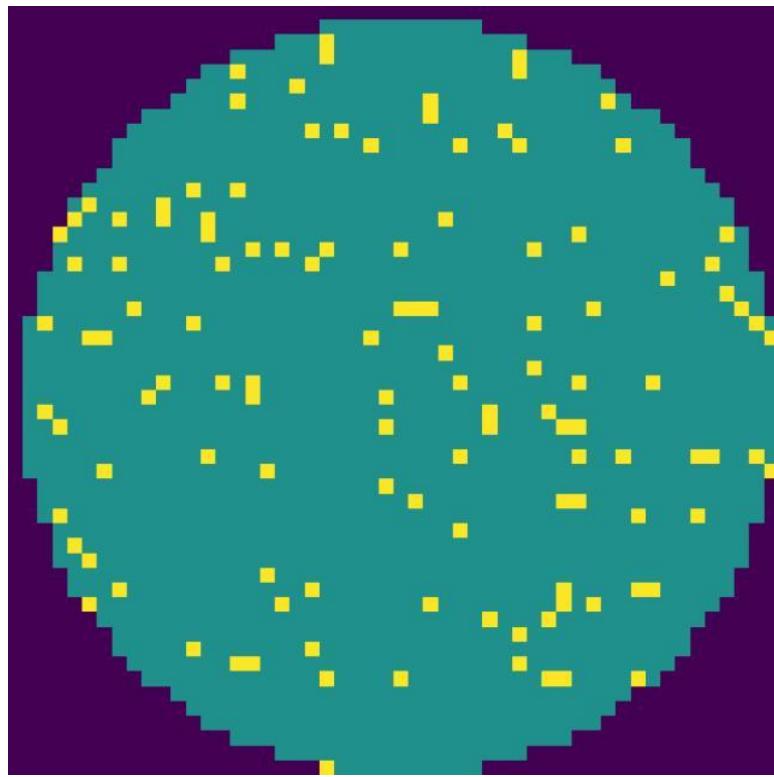
Wafer ID: Electrical_ELEC_02_W0030
Decision: PASS

Machine Type: Electrical
Machine ID: ELEC_02
Timestamp: 2025-12-27T12:07:27.403453
Simulation Date: 2025-12-27

Defect Class: Normal
Confidence Score: 0.9996
Defect Percentage: 35.93%

Reason: Defect Percentage: 35.93% (<=40% threshold), Defect Class: Normal, Confidence: 99.96%

Wafer Defect Image:



Wafer 148 Inspection Decision

Wafer ID: Electrical_ELEC_01_W0030

Decision: FAIL

Machine Type: Electrical

Machine ID: ELEC_01

Timestamp: 2025-12-27T12:07:27.700614

Simulation Date: 2025-12-27

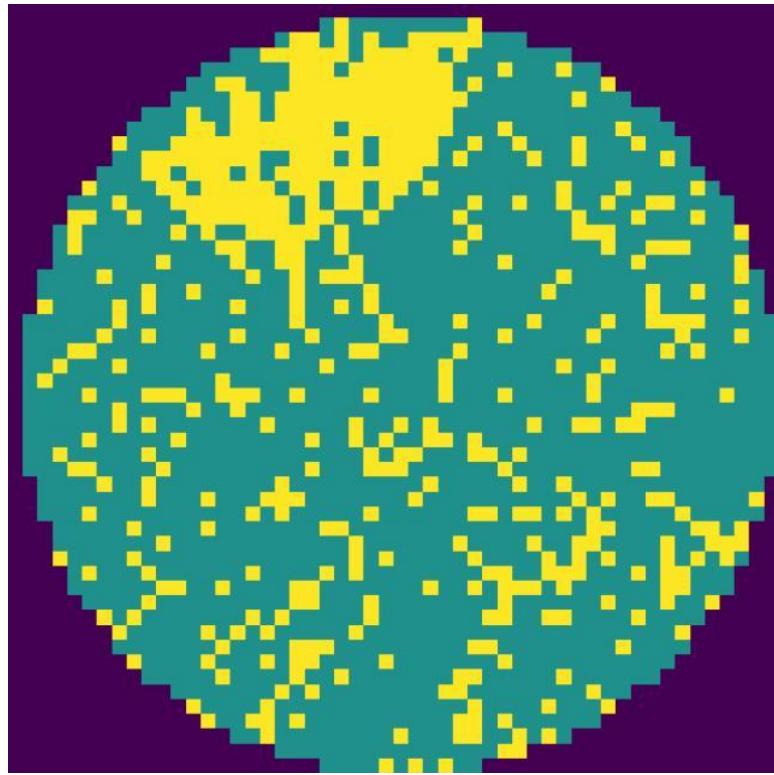
Defect Class: Local

Confidence Score: 0.9999

Defect Percentage: 53.16%

Reason: Defect Percentage: 53.16% (>40% threshold), Defect Class: Local, Confidence: 99.99%

Wafer Defect Image:



Wafer 149 Inspection Decision

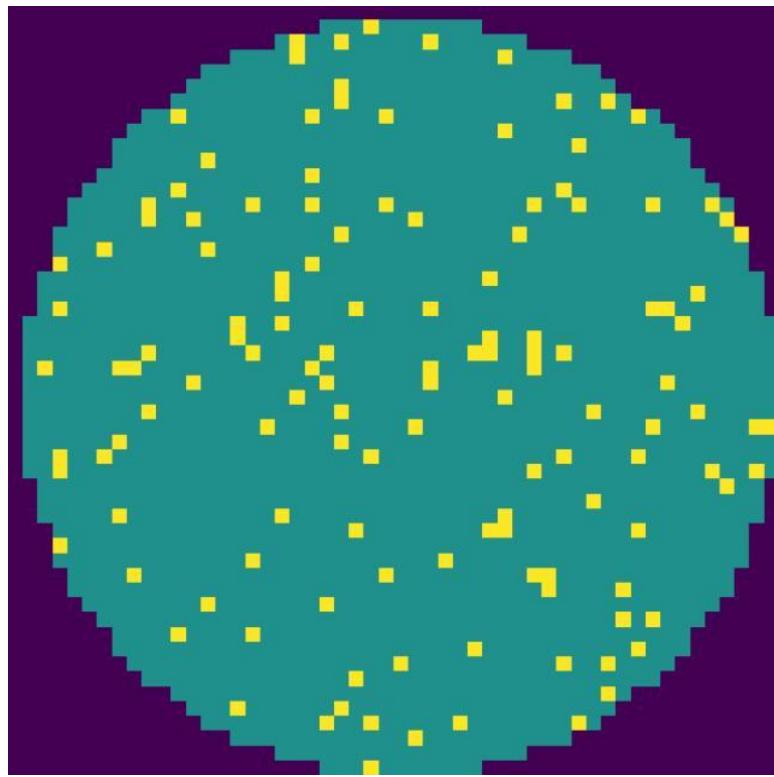
Wafer ID: Mechanical_MECH_02_W0026
Decision: PASS

Machine Type: Mechanical
Machine ID: MECH_02
Timestamp: 2025-12-27T12:07:27.706340
Simulation Date: 2025-12-27

Defect Class: Normal
Confidence Score: 0.9998
Defect Percentage: 34.28%

Reason: Defect Percentage: 34.28% (<=40% threshold), Defect Class: Normal, Confidence: 99.98%

Wafer Defect Image:



Wafer 150 Inspection Decision

Wafer ID: Thermal_THERM_01_W0022

Decision: FAIL

Machine Type: Thermal

Machine ID: THERM_01

Timestamp: 2025-12-27T12:07:29.093285

Simulation Date: 2025-12-27

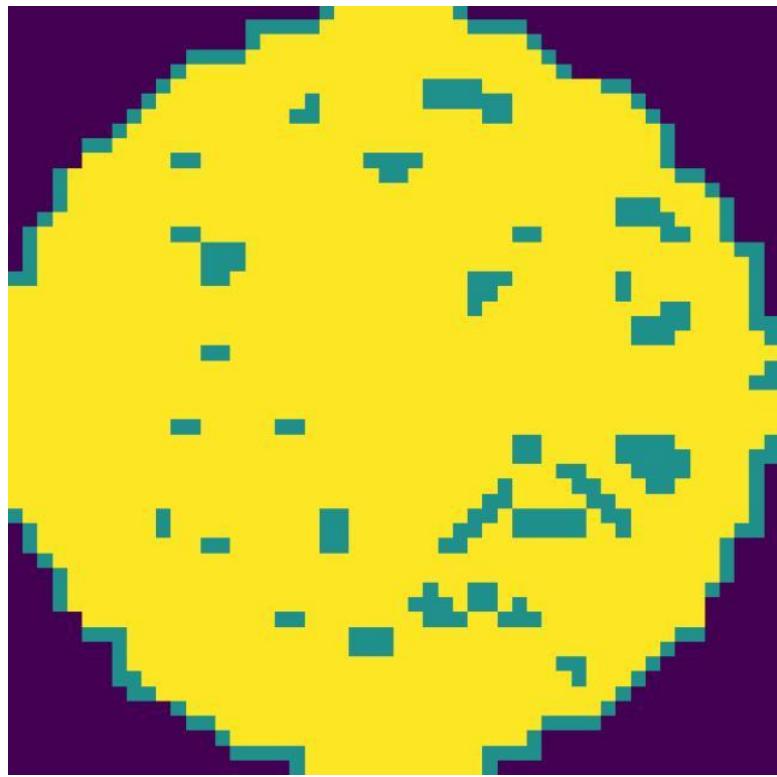
Defect Class: Near-Full

Confidence Score: 1.0000

Defect Percentage: 94.31%

Reason: Defect Percentage: 94.31% (>40% threshold), Defect Class: Near-Full, Confidence: 100.00%

Wafer Defect Image:



Wafer 151 Inspection Decision

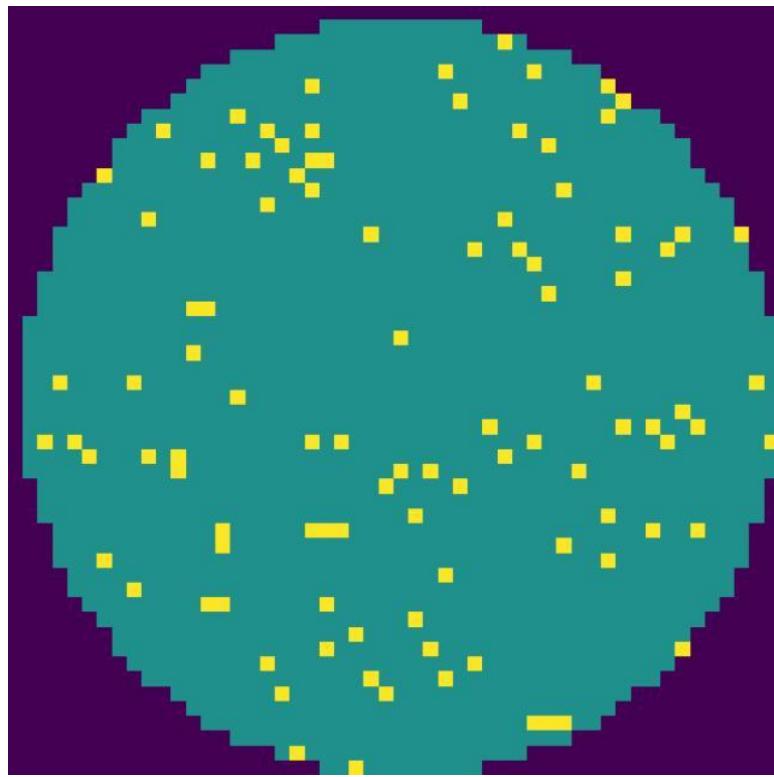
Wafer ID: Mechanical_MECH_01_W0026
Decision: PASS

Machine Type: Mechanical
Machine ID: MECH_01
Timestamp: 2025-12-27T12:07:32.222126
Simulation Date: 2025-12-27

Defect Class: Normal
Confidence Score: 0.9998
Defect Percentage: 33.38%

Reason: Defect Percentage: 33.38% (<=40% threshold), Defect Class: Normal, Confidence: 99.98%

Wafer Defect Image:



Wafer 152 Inspection Decision

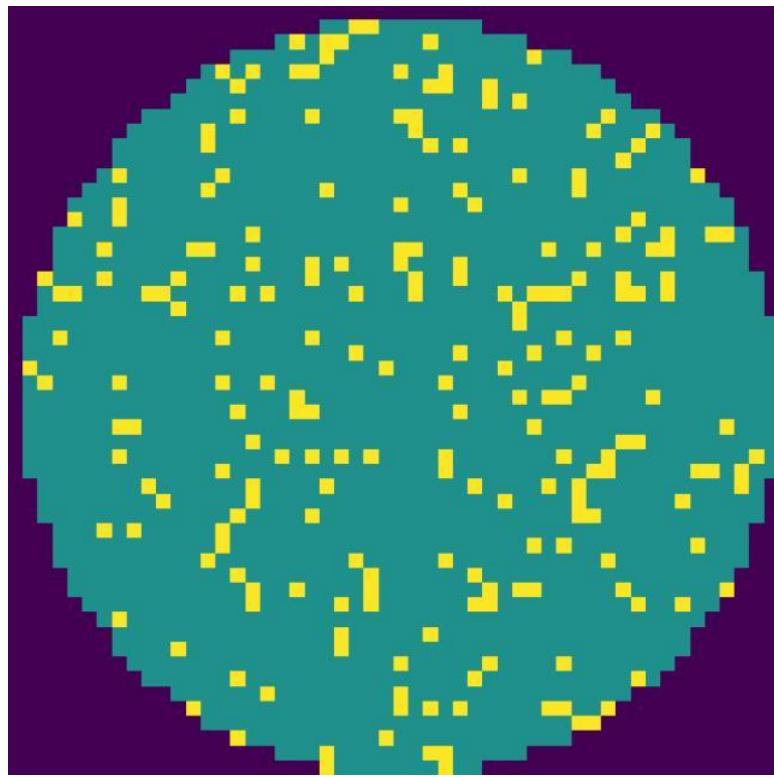
Wafer ID: Electrical_ELEC_02_W0031
Decision: PASS

Machine Type: Electrical
Machine ID: ELEC_02
Timestamp: 2025-12-27T12:07:32.527610
Simulation Date: 2025-12-27

Defect Class: Normal
Confidence Score: 0.9998
Defect Percentage: 38.39%

Reason: Defect Percentage: 38.39% (<=40% threshold), Defect Class: Normal, Confidence: 99.98%

Wafer Defect Image:



Wafer 153 Inspection Decision

Wafer ID: Electrical_ELEC_01_W0031

Decision: PASS

Machine Type: Electrical

Machine ID: ELEC_01

Timestamp: 2025-12-27T12:07:32.928420

Simulation Date: 2025-12-27

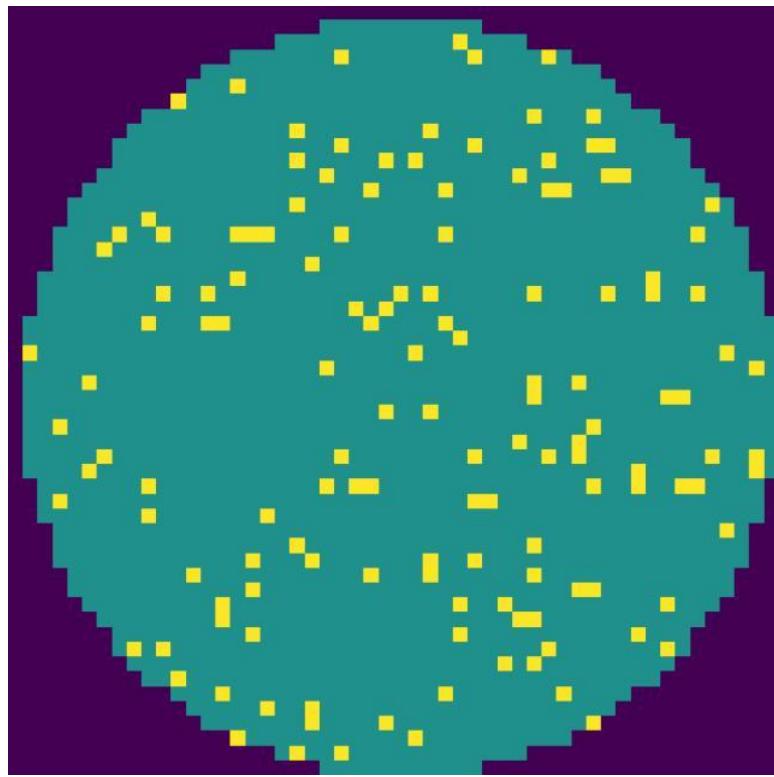
Defect Class: Normal

Confidence Score: 0.9998

Defect Percentage: 34.76%

Reason: Defect Percentage: 34.76% (<=40% threshold), Defect Class: Normal, Confidence: 99.98%

Wafer Defect Image:



Wafer 154 Inspection Decision

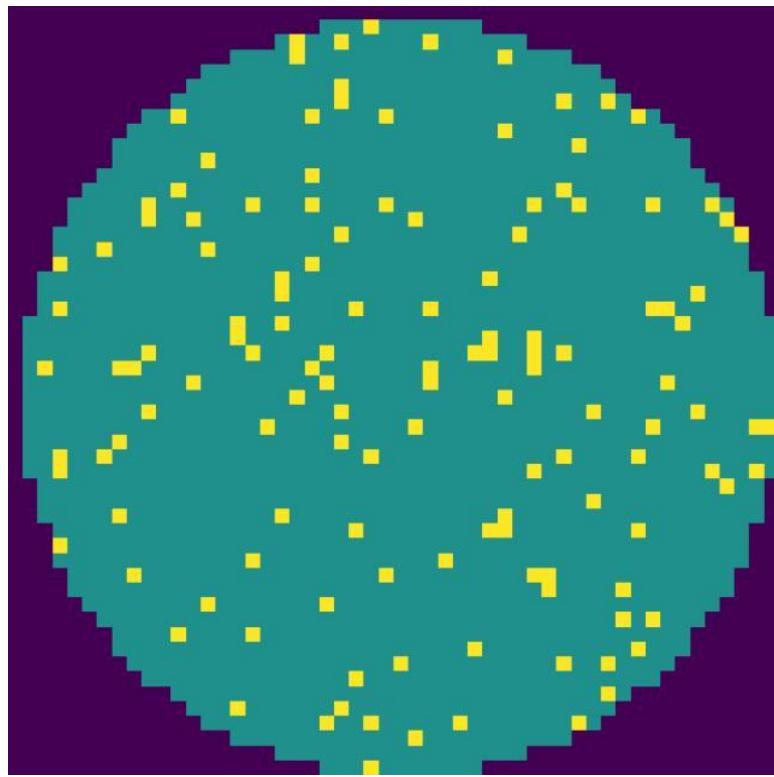
Wafer ID: Thermal_THERM_02_W0018
Decision: PASS

Machine Type: Thermal
Machine ID: THERM_02
Timestamp: 2025-12-27T12:07:33.363221
Simulation Date: 2025-12-27

Defect Class: Normal
Confidence Score: 0.9998
Defect Percentage: 34.28%

Reason: Defect Percentage: 34.28% (<=40% threshold), Defect Class: Normal, Confidence: 99.98%

Wafer Defect Image:



Wafer 155 Inspection Decision

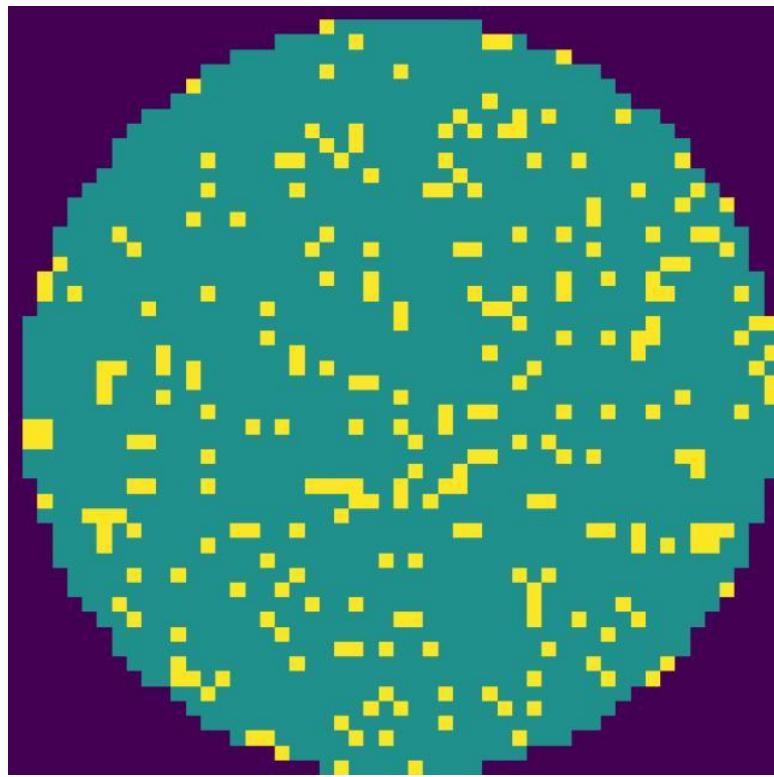
Wafer ID: Mechanical_MECH_02_W0027
Decision: PASS

Machine Type: Mechanical
Machine ID: MECH_02
Timestamp: 2025-12-27T12:07:34.455162
Simulation Date: 2025-12-27

Defect Class: Normal
Confidence Score: 0.9999
Defect Percentage: 39.60%

Reason: Defect Percentage: 39.6% (<=40% threshold), Defect Class: Normal, Confidence: 99.99%

Wafer Defect Image:



Wafer 156 Inspection Decision

Wafer ID: Thermal_THERM_01_W0023

Decision: FAIL

Machine Type: Thermal

Machine ID: THERM_01

Timestamp: 2025-12-27T12:07:37.156033

Simulation Date: 2025-12-27

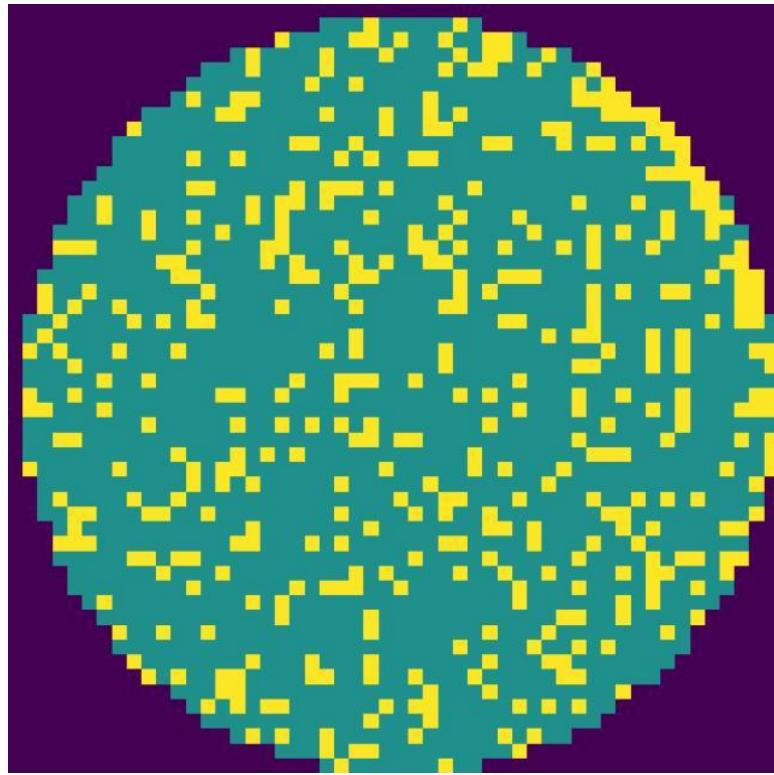
Defect Class: Edge-Loc

Confidence Score: 0.9996

Defect Percentage: 44.30%

Reason: Defect Percentage: 44.3% (>40% threshold), Defect Class: Edge-Loc, Confidence: 99.96%

Wafer Defect Image:



Wafer 157 Inspection Decision

Wafer ID: Electrical_ELEC_02_W0032

Decision: FAIL

Machine Type: Electrical

Machine ID: ELEC_02

Timestamp: 2025-12-27T12:07:38.018935

Simulation Date: 2025-12-27

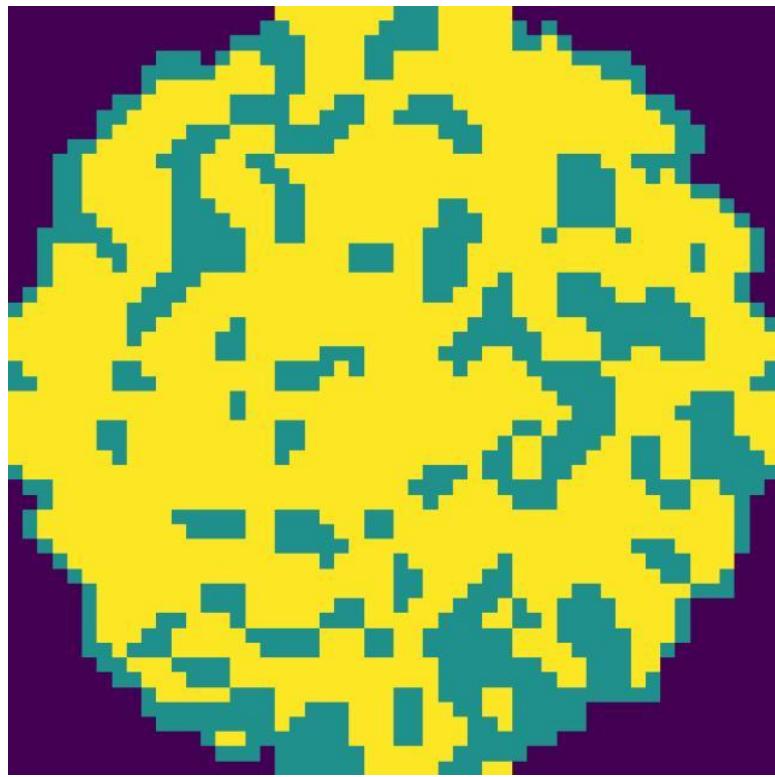
Defect Class: Random

Confidence Score: 0.5003

Defect Percentage: 86.14%

Reason: Defect Percentage: 86.14% (>40% threshold), Defect Class: Random, Confidence: 50.03%

Wafer Defect Image:



Wafer 158 Inspection Decision

Wafer ID: Electrical_ELEC_01_W0032

Decision: PASS

Machine Type: Electrical

Machine ID: ELEC_01

Timestamp: 2025-12-27T12:07:38.618548

Simulation Date: 2025-12-27

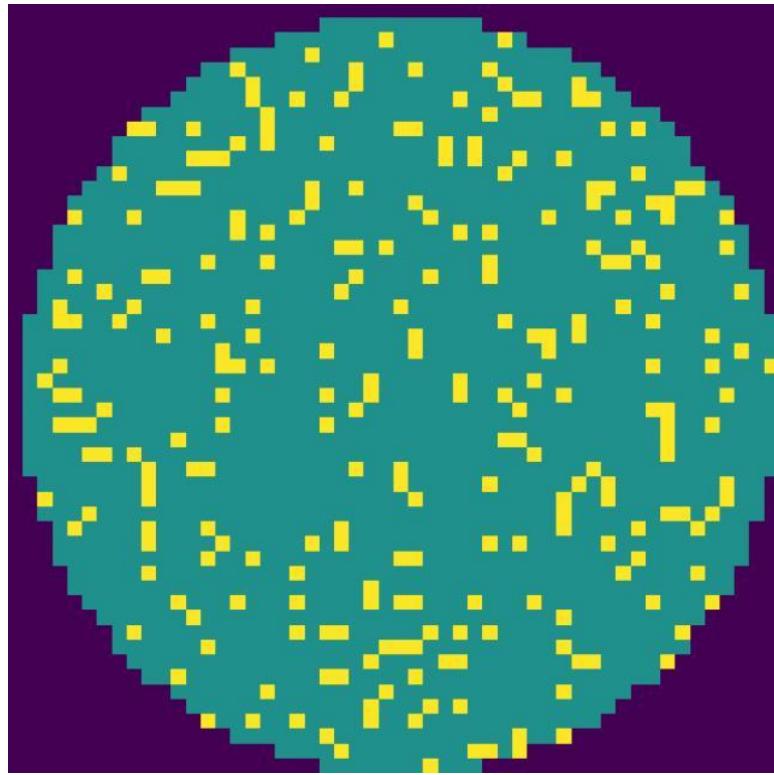
Defect Class: Normal

Confidence Score: 0.9998

Defect Percentage: 38.11%

Reason: Defect Percentage: 38.11% (<=40% threshold), Defect Class: Normal, Confidence: 99.98%

Wafer Defect Image:



Wafer 159 Inspection Decision

Wafer ID: Mechanical_MECH_01_W0027

Decision: FAIL

Machine Type: Mechanical

Machine ID: MECH_01

Timestamp: 2025-12-27T12:07:39.704952

Simulation Date: 2025-12-27

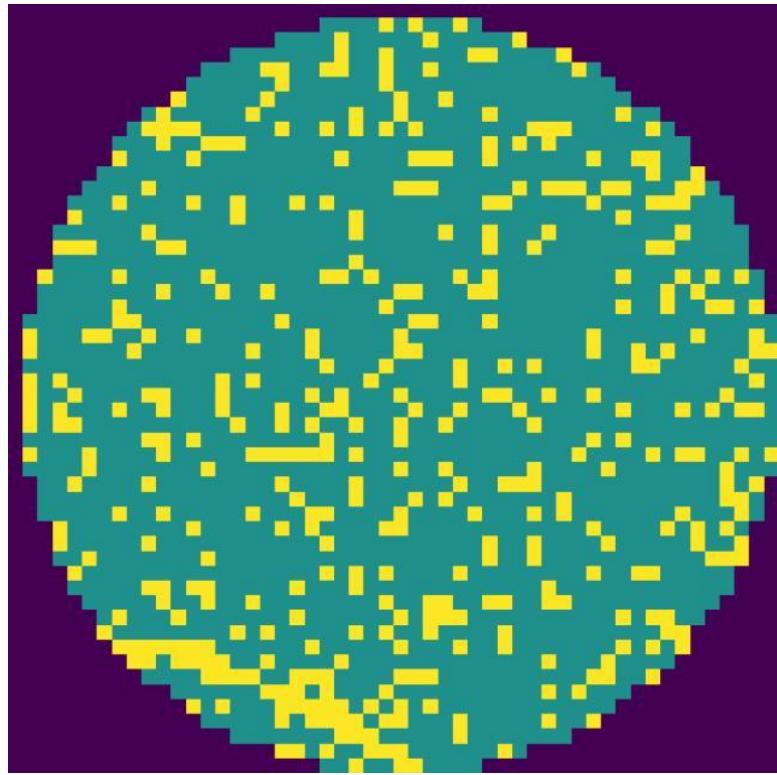
Defect Class: Scratch

Confidence Score: 0.9999

Defect Percentage: 43.89%

Reason: Defect Percentage: 43.89% (>40% threshold), Defect Class: Scratch, Confidence: 99.99%

Wafer Defect Image:



Wafer 160 Inspection Decision

Wafer ID: Mechanical_MECH_02_W0028

Decision: FAIL

Machine Type: Mechanical

Machine ID: MECH_02

Timestamp: 2025-12-27T12:07:40.414450

Simulation Date: 2025-12-27

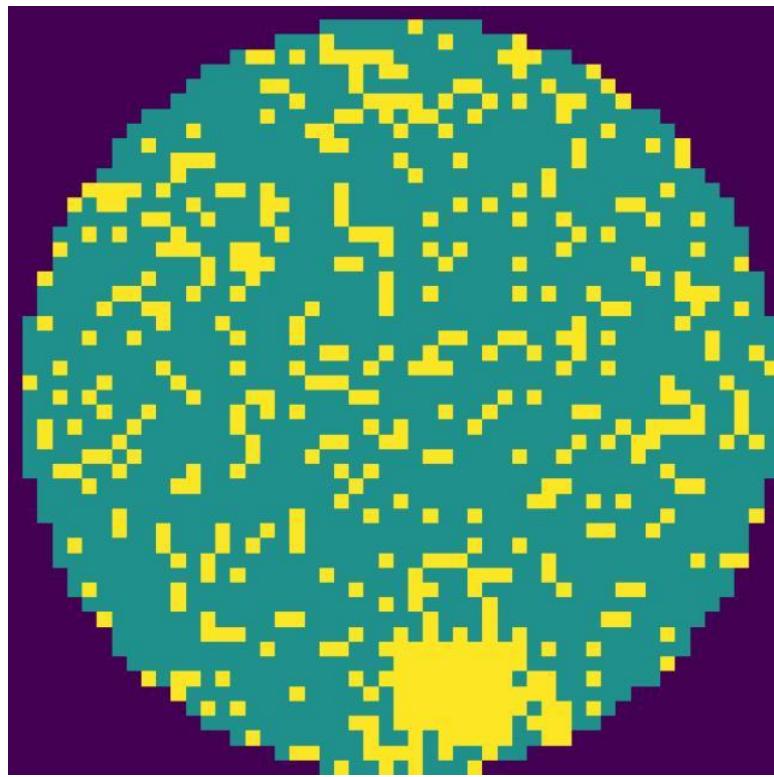
Defect Class: Local

Confidence Score: 0.9998

Defect Percentage: 47.63%

Reason: Defect Percentage: 47.63% (>40% threshold), Defect Class: Local, Confidence: 99.98%

Wafer Defect Image:



Wafer 161 Inspection Decision

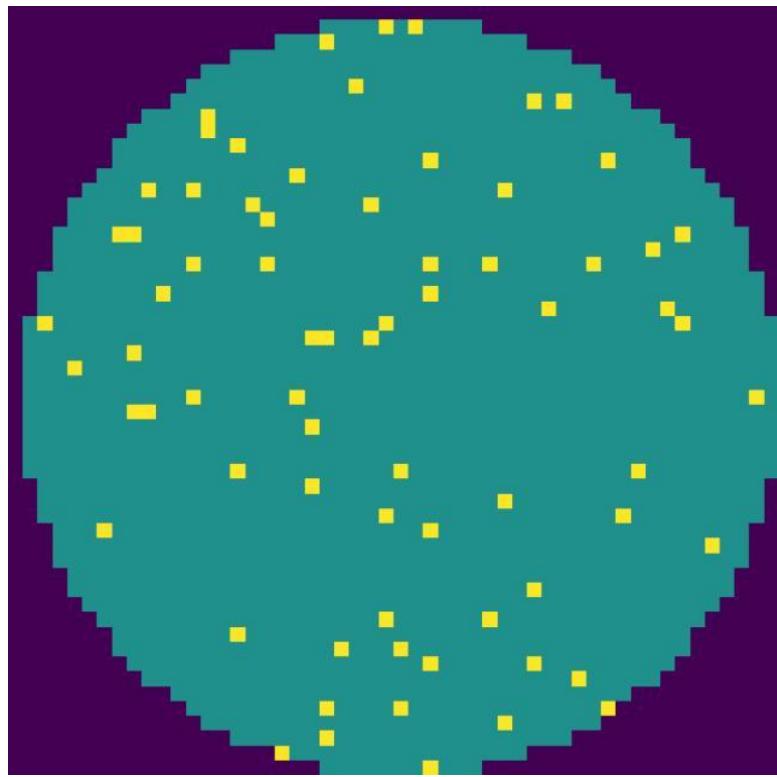
Wafer ID: Thermal_THERM_02_W0019
Decision: PASS

Machine Type: Thermal
Machine ID: THERM_02
Timestamp: 2025-12-27T12:07:41.513978
Simulation Date: 2025-12-27

Defect Class: Normal
Confidence Score: 0.9997
Defect Percentage: 32.51%

Reason: Defect Percentage: 32.51% (<=40% threshold), Defect Class: Normal, Confidence: 99.97%

Wafer Defect Image:



Wafer 162 Inspection Decision

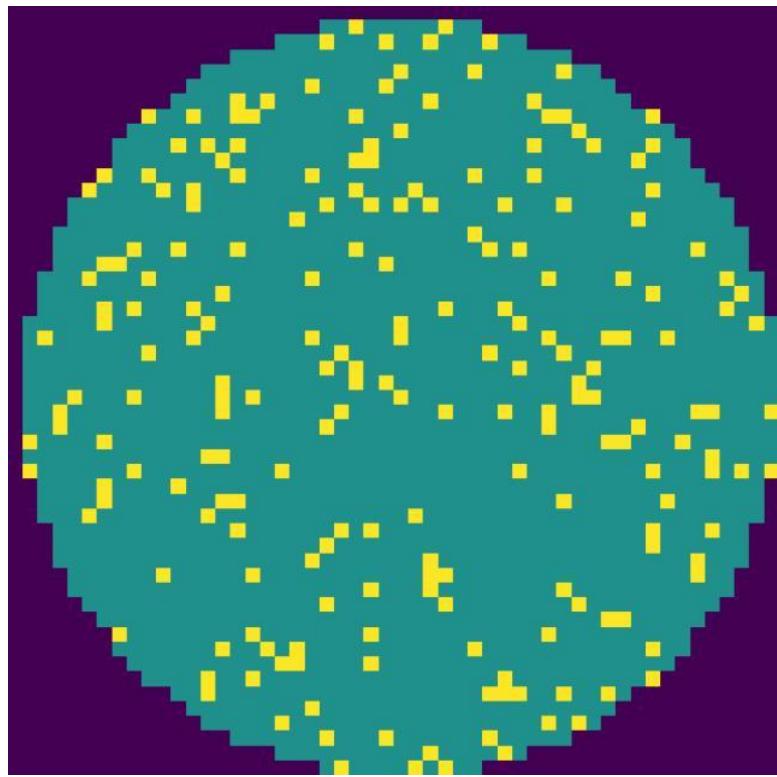
Wafer ID: Electrical_ELEC_02_W0033
Decision: PASS

Machine Type: Electrical
Machine ID: ELEC_02
Timestamp: 2025-12-27T12:07:43.120392
Simulation Date: 2025-12-27

Defect Class: Normal
Confidence Score: 0.9997
Defect Percentage: 35.74%

Reason: Defect Percentage: 35.74% (<=40% threshold), Defect Class: Normal, Confidence: 99.97%

Wafer Defect Image:



Wafer 163 Inspection Decision

Wafer ID: Electrical_ELEC_01_W0033

Decision: PASS

Machine Type: Electrical

Machine ID: ELEC_01

Timestamp: 2025-12-27T12:07:44.406012

Simulation Date: 2025-12-27

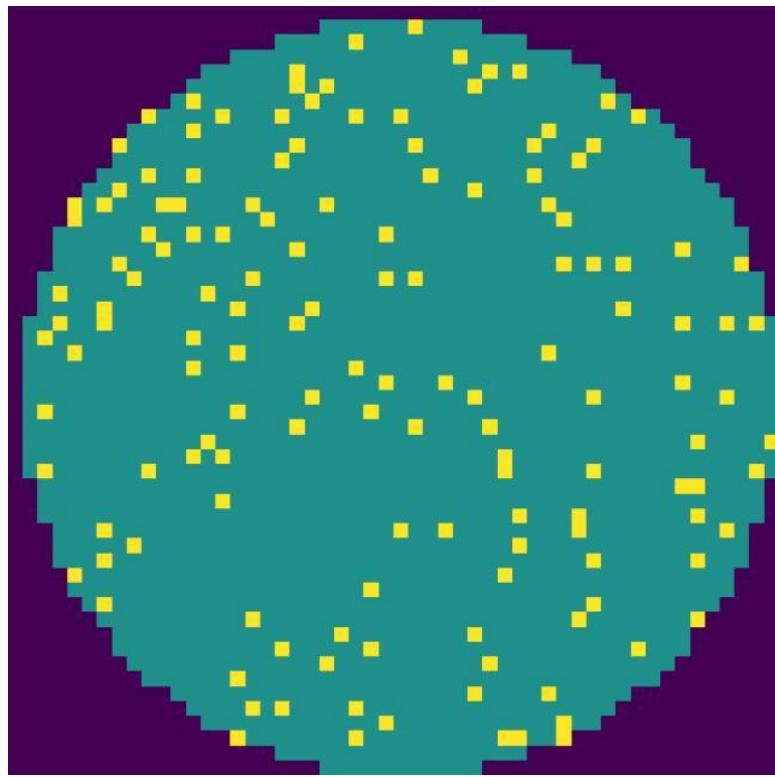
Defect Class: Normal

Confidence Score: 0.9998

Defect Percentage: 33.01%

Reason: Defect Percentage: 33.01% (<=40% threshold), Defect Class: Normal, Confidence: 99.98%

Wafer Defect Image:



Wafer 164 Inspection Decision

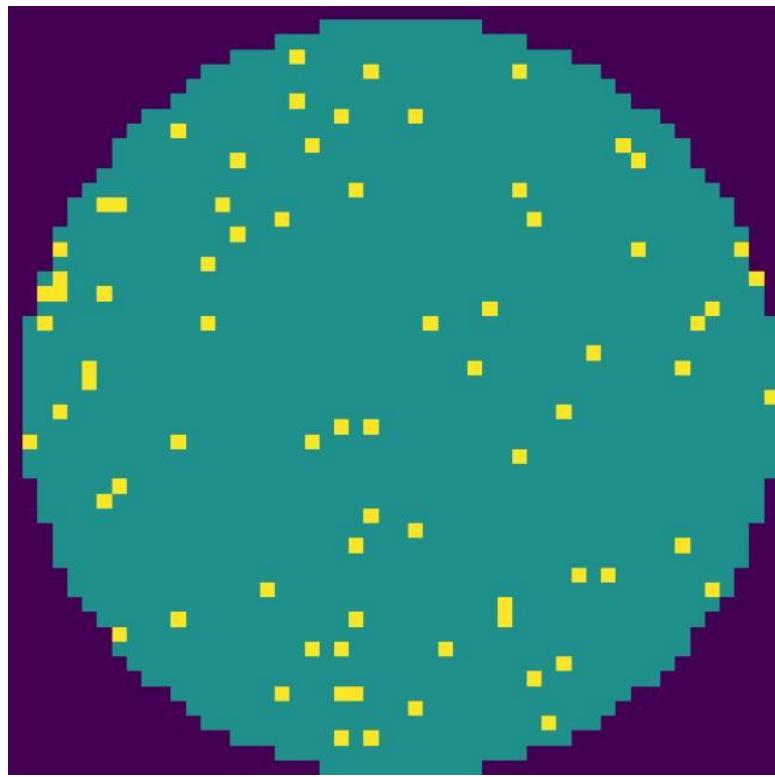
Wafer ID: Mechanical_MECH_01_W0028
Decision: PASS

Machine Type: Mechanical
Machine ID: MECH_01
Timestamp: 2025-12-27T12:07:46.257925
Simulation Date: 2025-12-27

Defect Class: Normal
Confidence Score: 0.9998
Defect Percentage: 32.88%

Reason: Defect Percentage: 32.88% (<=40% threshold), Defect Class: Normal, Confidence: 99.98%

Wafer Defect Image:



Wafer 165 Inspection Decision

Wafer ID: Mechanical_MECH_02_W0029

Decision: FAIL

Machine Type: Mechanical

Machine ID: MECH_02

Timestamp: 2025-12-27T12:07:47.784857

Simulation Date: 2025-12-27

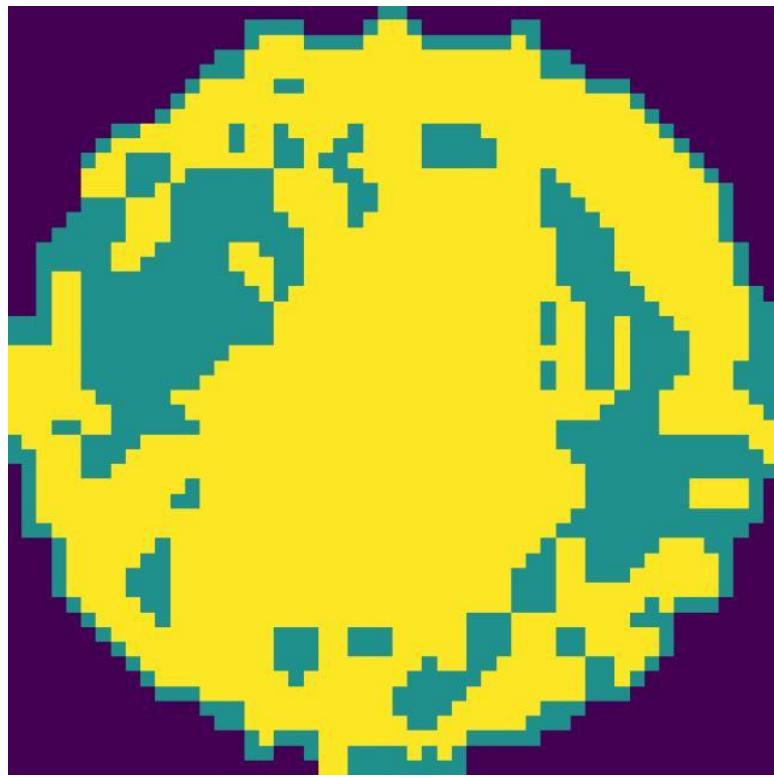
Defect Class: Near-Full

Confidence Score: 0.9993

Defect Percentage: 89.73%

Reason: Defect Percentage: 89.73% (>40% threshold), Defect Class: Near-Full, Confidence: 99.93%

Wafer Defect Image:



Wafer 166 Inspection Decision

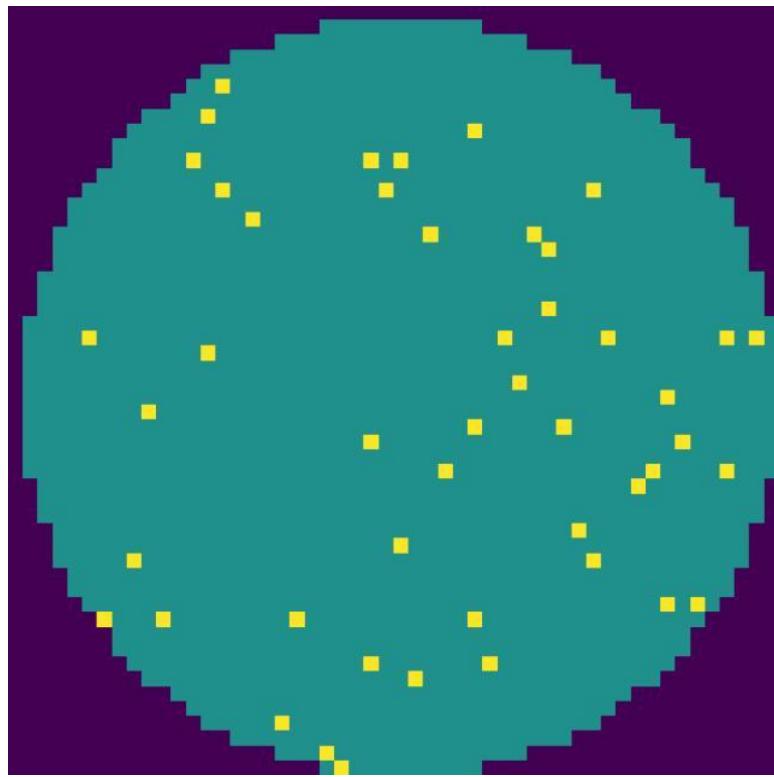
Wafer ID: Thermal_THERM_01_W0024
Decision: PASS

Machine Type: Thermal
Machine ID: THERM_01
Timestamp: 2025-12-27T12:07:47.876958
Simulation Date: 2025-12-27

Defect Class: Normal
Confidence Score: 0.9998
Defect Percentage: 30.04%

Reason: Defect Percentage: 30.04% (<=40% threshold), Defect Class: Normal, Confidence: 99.98%

Wafer Defect Image:



Wafer 167 Inspection Decision

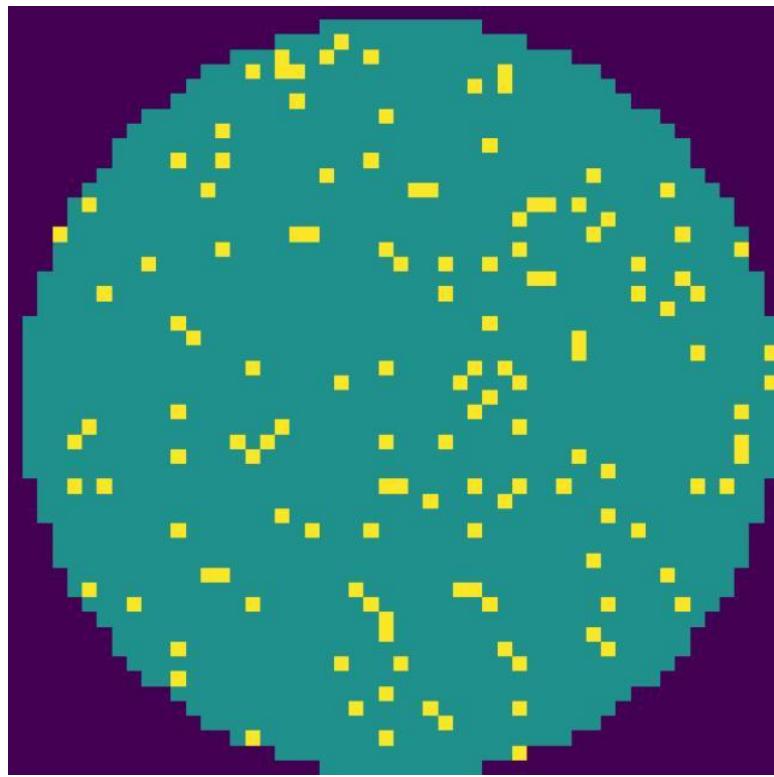
Wafer ID: Thermal_THERM_02_W0020
Decision: PASS

Machine Type: Thermal
Machine ID: THERM_02
Timestamp: 2025-12-27T12:07:48.493667
Simulation Date: 2025-12-27

Defect Class: Normal
Confidence Score: 0.9998
Defect Percentage: 33.52%

Reason: Defect Percentage: 33.52% (<=40% threshold), Defect Class: Normal, Confidence: 99.98%

Wafer Defect Image:



Wafer 168 Inspection Decision

Wafer ID: Electrical_ELEC_02_W0034

Decision: FAIL

Machine Type: Electrical

Machine ID: ELEC_02

Timestamp: 2025-12-27T12:07:48.993093

Simulation Date: 2025-12-27

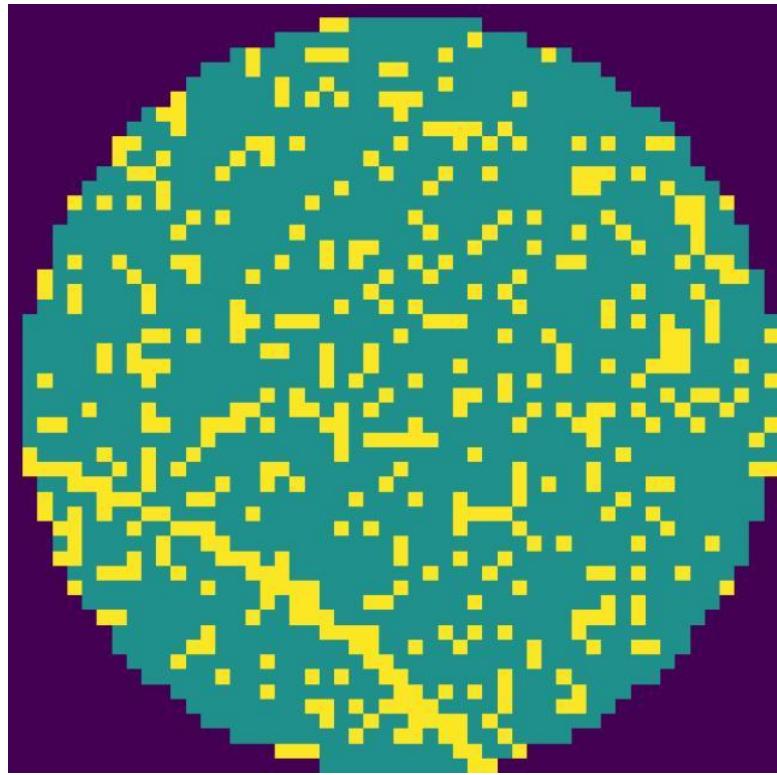
Defect Class: Scratch

Confidence Score: 1.0000

Defect Percentage: 45.04%

Reason: Defect Percentage: 45.04% (>40% threshold), Defect Class: Scratch, Confidence: 100.00%

Wafer Defect Image:



Wafer 169 Inspection Decision

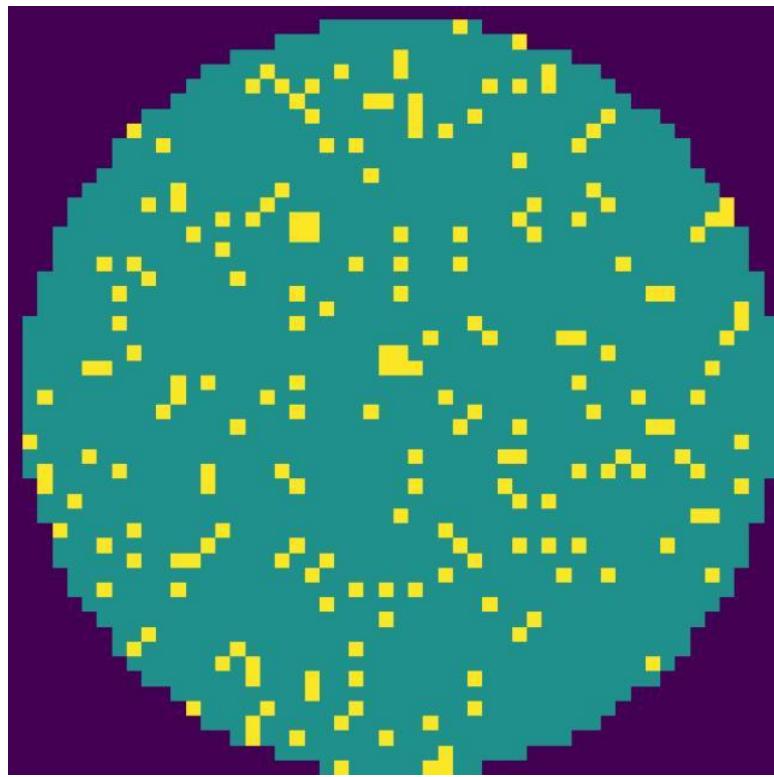
Wafer ID: Electrical_ELEC_01_W0034
Decision: PASS

Machine Type: Electrical
Machine ID: ELEC_01
Timestamp: 2025-12-27T12:07:50.257878
Simulation Date: 2025-12-27

Defect Class: Normal
Confidence Score: 0.9997
Defect Percentage: 36.26%

Reason: Defect Percentage: 36.26% (<=40% threshold), Defect Class: Normal, Confidence: 99.97%

Wafer Defect Image:



Wafer 170 Inspection Decision

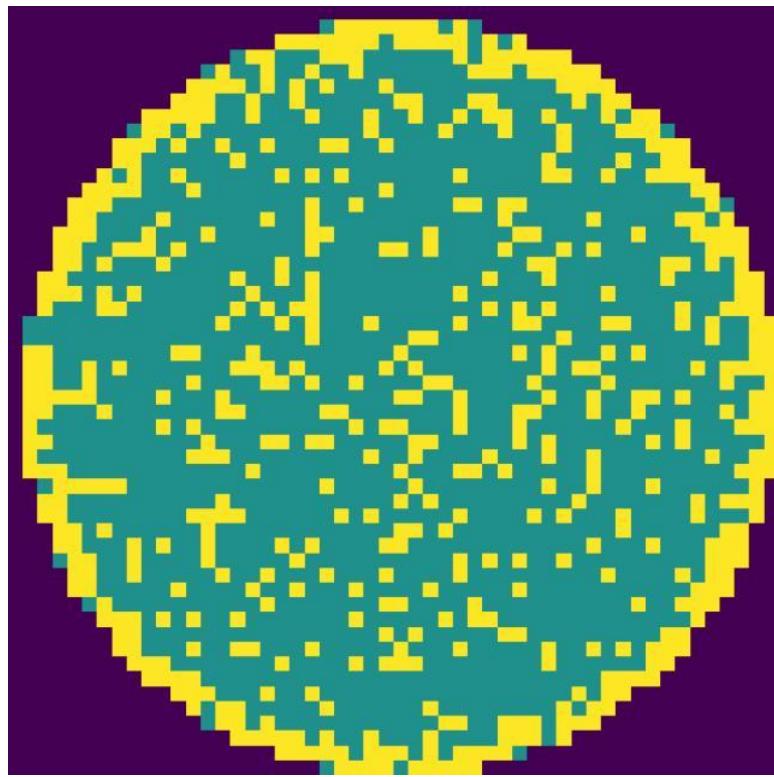
Wafer ID: Mechanical_MECH_01_W0029
Decision: FAIL

Machine Type: Mechanical
Machine ID: MECH_01
Timestamp: 2025-12-27T12:07:51.591608
Simulation Date: 2025-12-27

Defect Class: Edge-Ring
Confidence Score: 0.9973
Defect Percentage: 55.05%

Reason: Defect Percentage: 55.05% (>40% threshold), Defect Class: Edge-Ring, Confidence: 99.73%

Wafer Defect Image:



Wafer 171 Inspection Decision

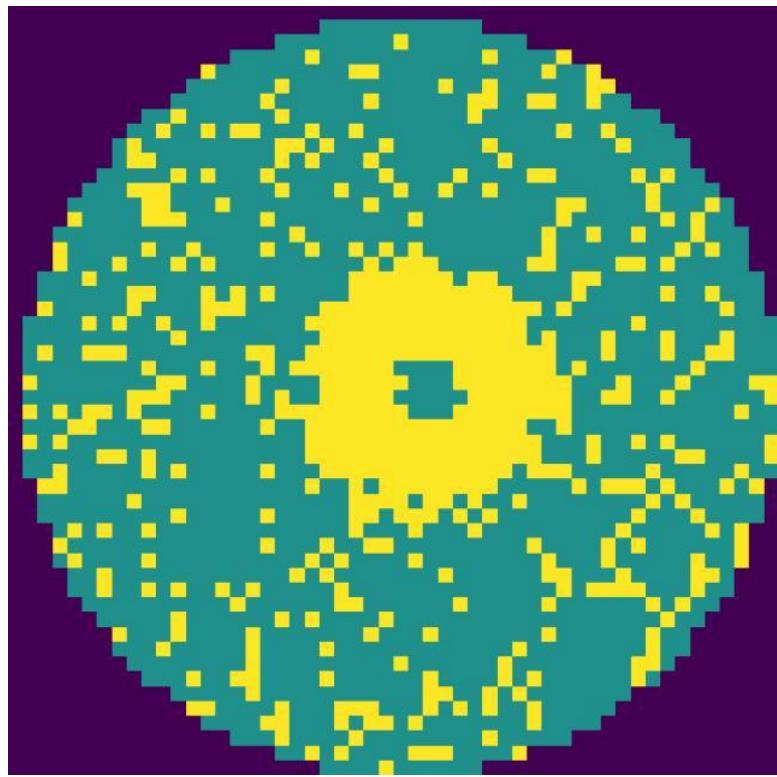
Wafer ID: Mechanical_MECH_02_W0030
Decision: FAIL

Machine Type: Mechanical
Machine ID: MECH_02
Timestamp: 2025-12-27T12:07:53.006021
Simulation Date: 2025-12-27

Defect Class: Donut
Confidence Score: 0.9989
Defect Percentage: 56.15%

Reason: Defect Percentage: 56.15% (>40% threshold), Defect Class: Donut, Confidence: 99.89%

Wafer Defect Image:



Wafer 172 Inspection Decision

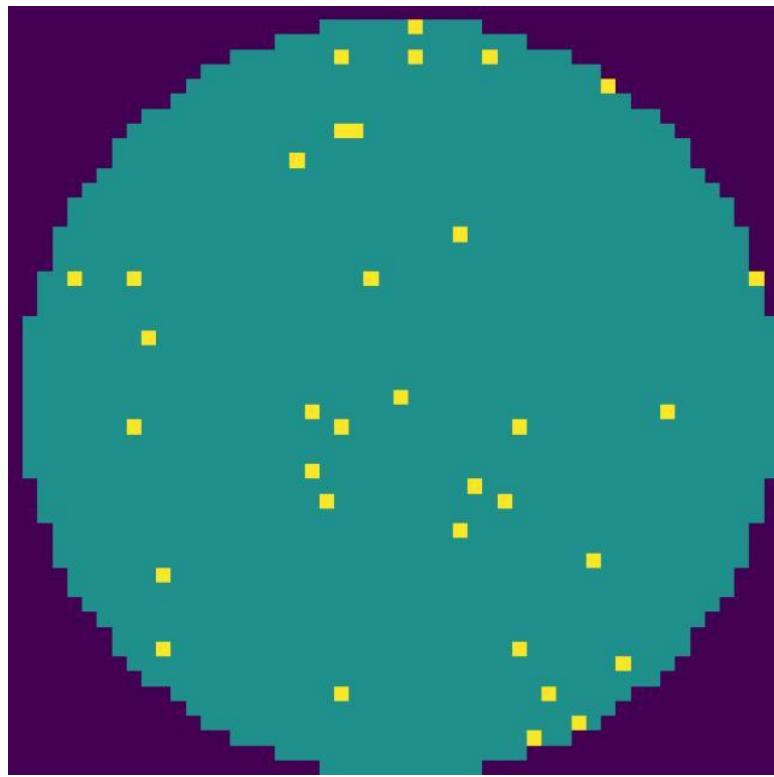
Wafer ID: Electrical_ELEC_02_W0035
Decision: PASS

Machine Type: Electrical
Machine ID: ELEC_02
Timestamp: 2025-12-27T12:07:54.933584
Simulation Date: 2025-12-27

Defect Class: Normal
Confidence Score: 0.9999
Defect Percentage: 33.22%

Reason: Defect Percentage: 33.22% (<=40% threshold), Defect Class: Normal, Confidence: 99.99%

Wafer Defect Image:



Wafer 173 Inspection Decision

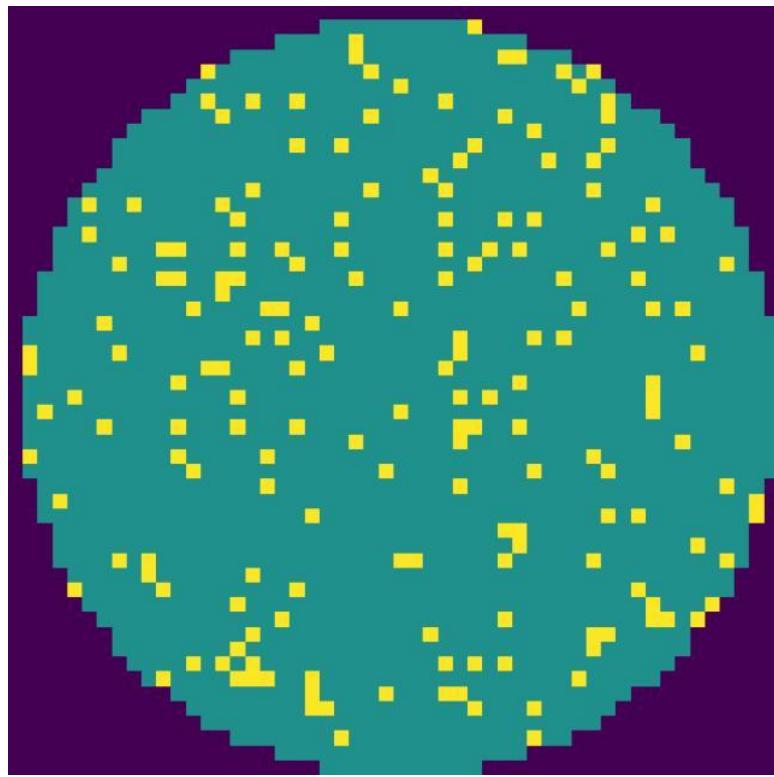
Wafer ID: Electrical_ELEC_01_W0035
Decision: PASS

Machine Type: Electrical
Machine ID: ELEC_01
Timestamp: 2025-12-27T12:07:55.926978
Simulation Date: 2025-12-27

Defect Class: Normal
Confidence Score: 0.9998
Defect Percentage: 35.70%

Reason: Defect Percentage: 35.7% (<=40% threshold), Defect Class: Normal, Confidence: 99.98%

Wafer Defect Image:



Wafer 174 Inspection Decision

Wafer ID: Thermal_THERM_02_W0021

Decision: PASS

Machine Type: Thermal

Machine ID: THERM_02

Timestamp: 2025-12-27T12:07:56.557852

Simulation Date: 2025-12-27

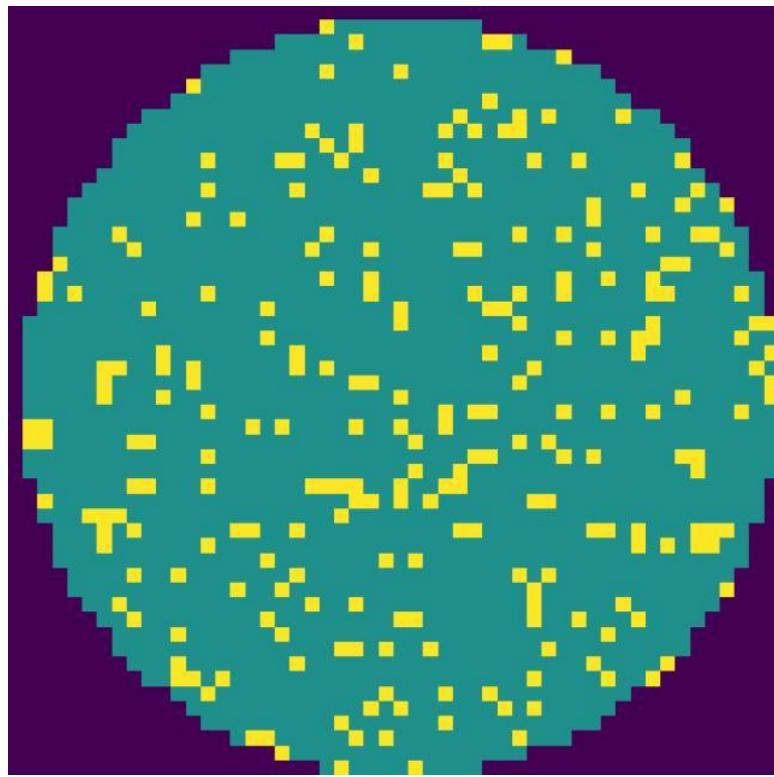
Defect Class: Normal

Confidence Score: 0.9999

Defect Percentage: 39.60%

Reason: Defect Percentage: 39.6% (<=40% threshold), Defect Class: Normal, Confidence: 99.99%

Wafer Defect Image:



Wafer 175 Inspection Decision

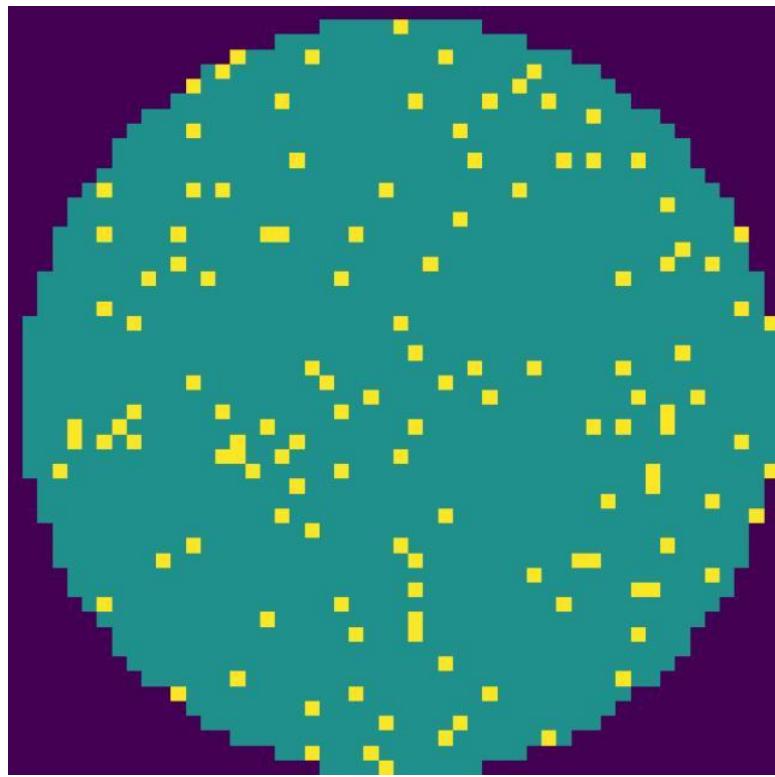
Wafer ID: Mechanical_MECH_01_W0030
Decision: PASS

Machine Type: Mechanical
Machine ID: MECH_01
Timestamp: 2025-12-27T12:07:56.800615
Simulation Date: 2025-12-27

Defect Class: Normal
Confidence Score: 0.9998
Defect Percentage: 33.33%

Reason: Defect Percentage: 33.33% (<=40% threshold), Defect Class: Normal, Confidence: 99.98%

Wafer Defect Image:



Wafer 176 Inspection Decision

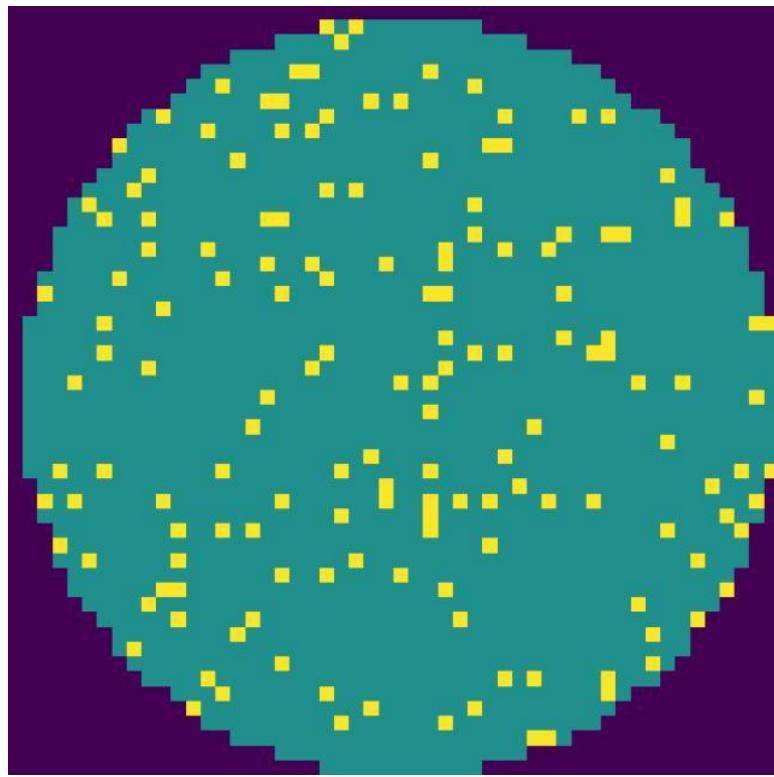
Wafer ID: Thermal_THERM_01_W0025
Decision: PASS

Machine Type: Thermal
Machine ID: THERM_01
Timestamp: 2025-12-27T12:07:56.907960
Simulation Date: 2025-12-27

Defect Class: Normal
Confidence Score: 0.9996
Defect Percentage: 34.12%

Reason: Defect Percentage: 34.12% (<=40% threshold), Defect Class: Normal, Confidence: 99.96%

Wafer Defect Image:



Wafer 177 Inspection Decision

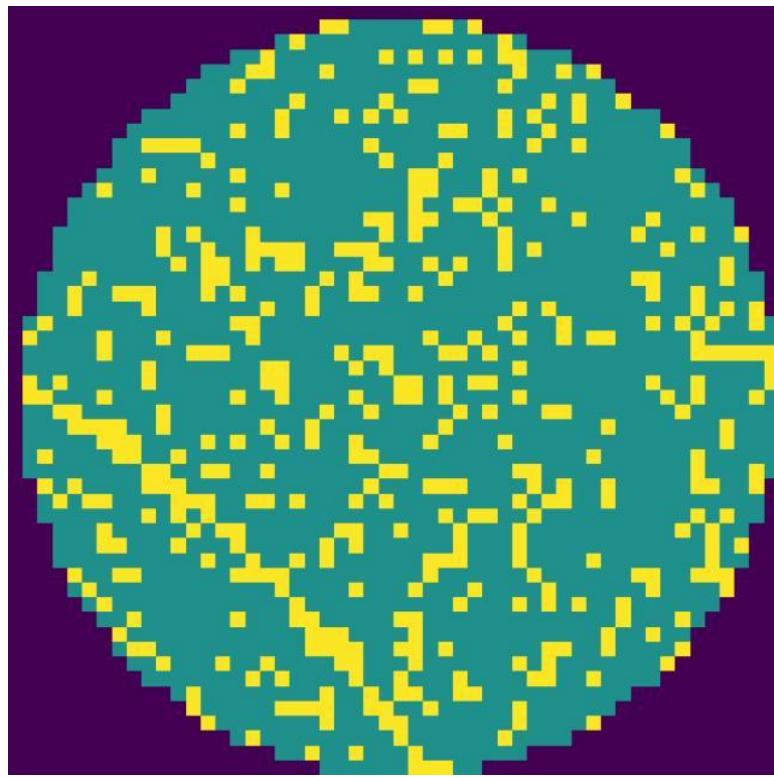
Wafer ID: Mechanical_MECH_02_W0031
Decision: FAIL

Machine Type: Mechanical
Machine ID: MECH_02
Timestamp: 2025-12-27T12:07:59.597338
Simulation Date: 2025-12-27

Defect Class: Scratch
Confidence Score: 0.9999
Defect Percentage: 45.11%

Reason: Defect Percentage: 45.11% (>40% threshold), Defect Class: Scratch, Confidence: 99.99%

Wafer Defect Image:



Wafer 178 Inspection Decision

Wafer ID: Electrical_ELEC_02_W0036

Decision: FAIL

Machine Type: Electrical

Machine ID: ELEC_02

Timestamp: 2025-12-27T12:08:00.086225

Simulation Date: 2025-12-27

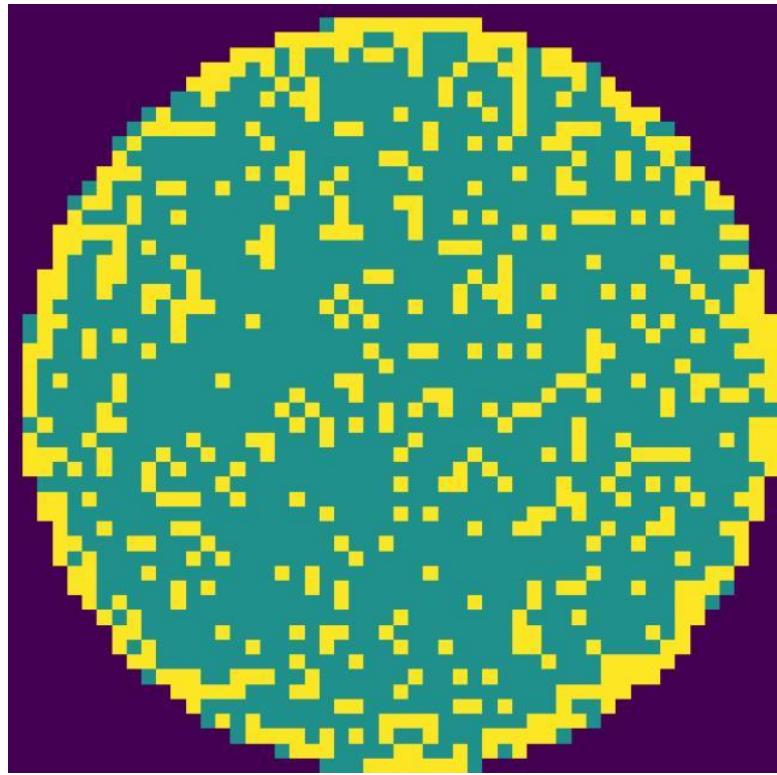
Defect Class: Edge-Ring

Confidence Score: 0.9981

Defect Percentage: 51.43%

Reason: Defect Percentage: 51.43% (>40% threshold), Defect Class: Edge-Ring, Confidence: 99.81%

Wafer Defect Image:



Wafer 179 Inspection Decision

Wafer ID: Electrical_ELEC_01_W0036

Decision: PASS

Machine Type: Electrical

Machine ID: ELEC_01

Timestamp: 2025-12-27T12:08:01.723669

Simulation Date: 2025-12-27

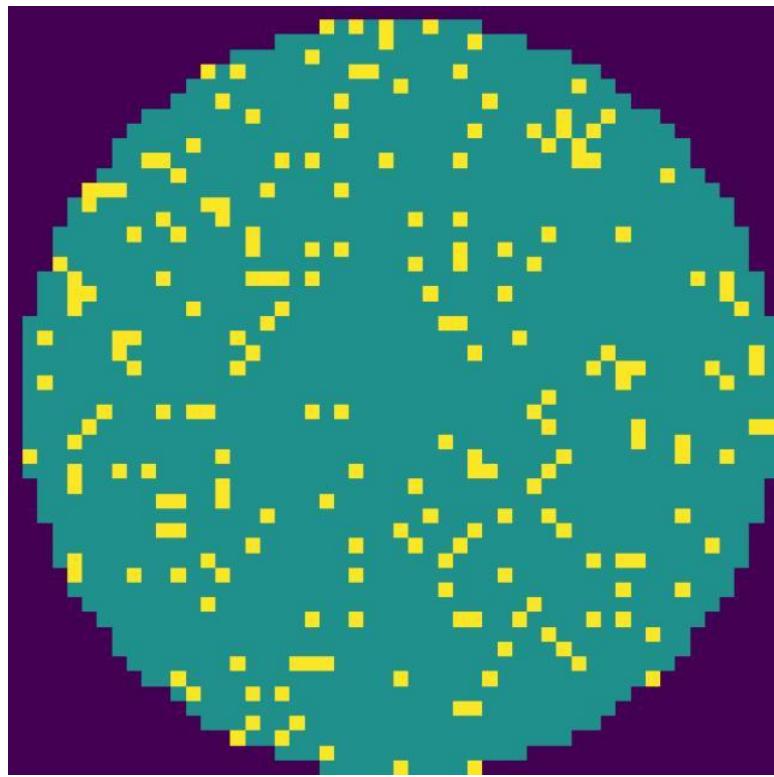
Defect Class: Normal

Confidence Score: 0.9993

Defect Percentage: 36.47%

Reason: Defect Percentage: 36.47% (<=40% threshold), Defect Class: Normal, Confidence: 99.93%

Wafer Defect Image:



Wafer 180 Inspection Decision

Wafer ID: Thermal_THERM_01_W0026

Decision: PASS

Machine Type: Thermal

Machine ID: THERM_01

Timestamp: 2025-12-27T12:08:02.595036

Simulation Date: 2025-12-27

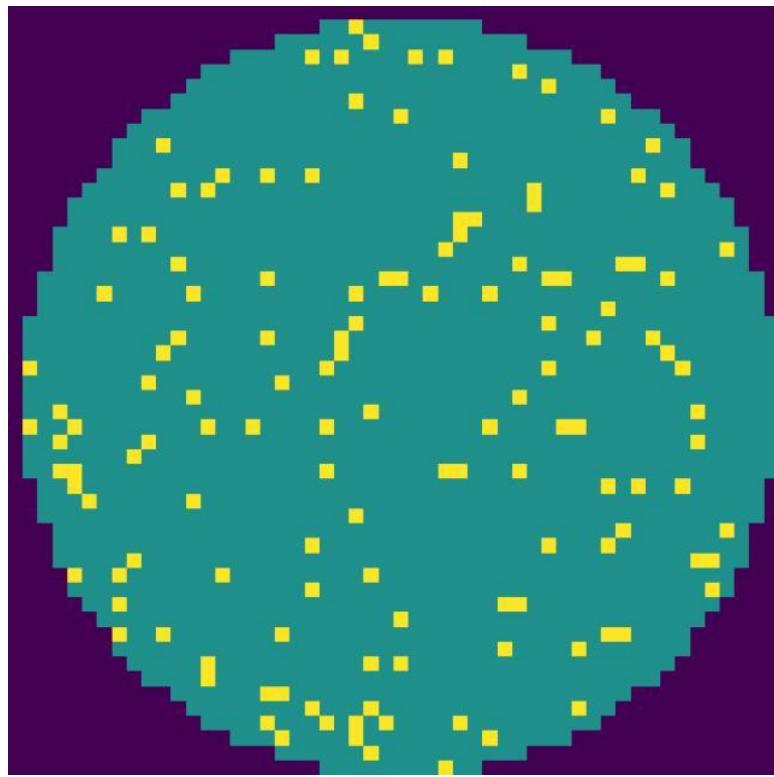
Defect Class: Normal

Confidence Score: 0.9996

Defect Percentage: 33.89%

Reason: Defect Percentage: 33.89% (<=40% threshold), Defect Class: Normal, Confidence: 99.96%

Wafer Defect Image:



Wafer 181 Inspection Decision

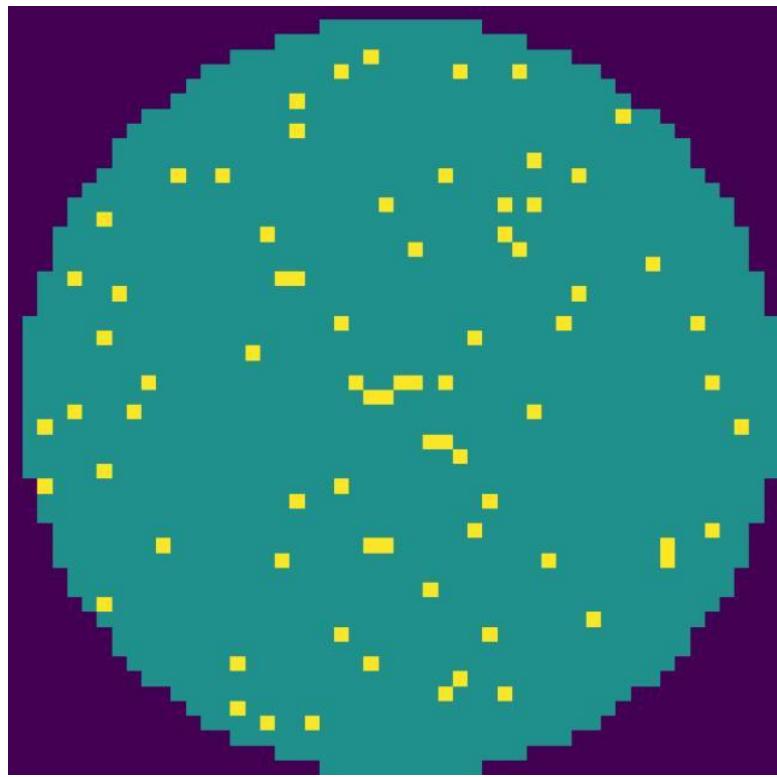
Wafer ID: Mechanical_MECH_01_W0031
Decision: PASS

Machine Type: Mechanical
Machine ID: MECH_01
Timestamp: 2025-12-27T12:08:02.796663
Simulation Date: 2025-12-27

Defect Class: Normal
Confidence Score: 0.9998
Defect Percentage: 31.73%

Reason: Defect Percentage: 31.73% (<=40% threshold), Defect Class: Normal, Confidence: 99.98%

Wafer Defect Image:



Wafer 182 Inspection Decision

Wafer ID: Electrical_ELEC_02_W0037

Decision: PASS

Machine Type: Electrical

Machine ID: ELEC_02

Timestamp: 2025-12-27T12:08:05.769858

Simulation Date: 2025-12-27

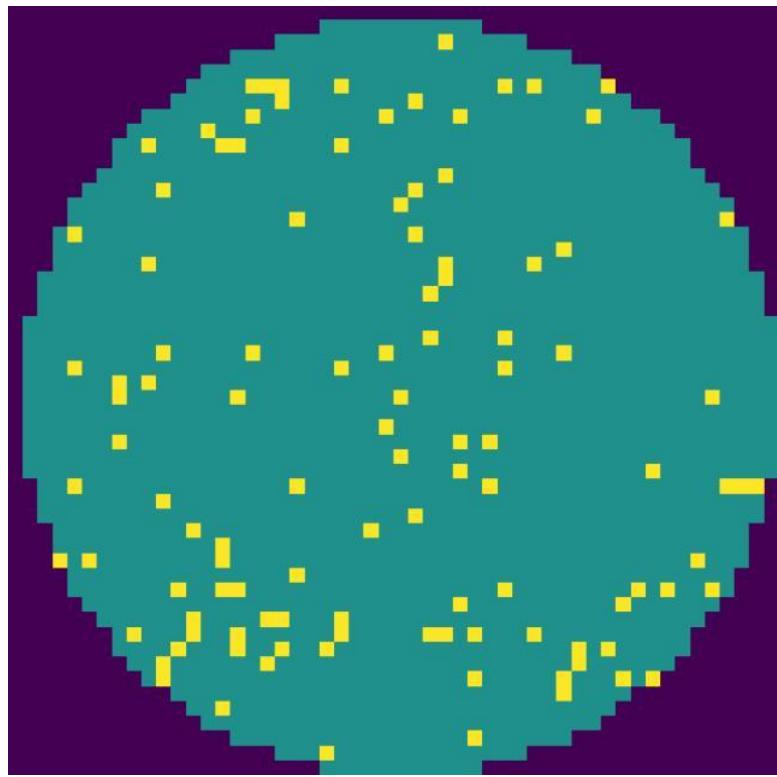
Defect Class: Normal

Confidence Score: 0.9997

Defect Percentage: 34.78%

Reason: Defect Percentage: 34.78% (<=40% threshold), Defect Class: Normal, Confidence: 99.97%

Wafer Defect Image:



Wafer 183 Inspection Decision

Wafer ID: Electrical_ELEC_01_W0037

Decision: PASS

Machine Type: Electrical

Machine ID: ELEC_01

Timestamp: 2025-12-27T12:08:06.819263

Simulation Date: 2025-12-27

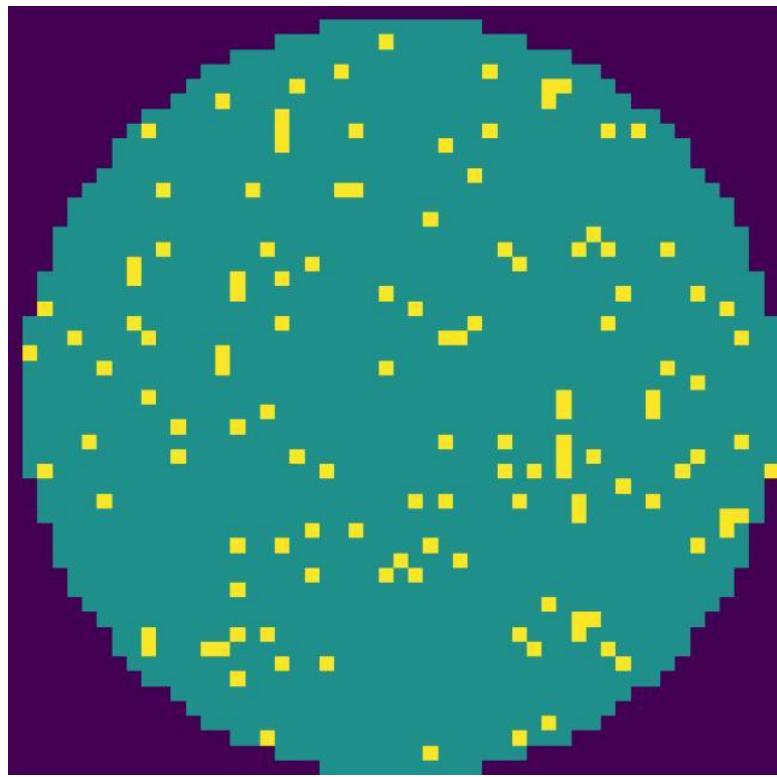
Defect Class: Normal

Confidence Score: 0.9998

Defect Percentage: 34.56%

Reason: Defect Percentage: 34.56% (<=40% threshold), Defect Class: Normal, Confidence: 99.98%

Wafer Defect Image:



Wafer 184 Inspection Decision

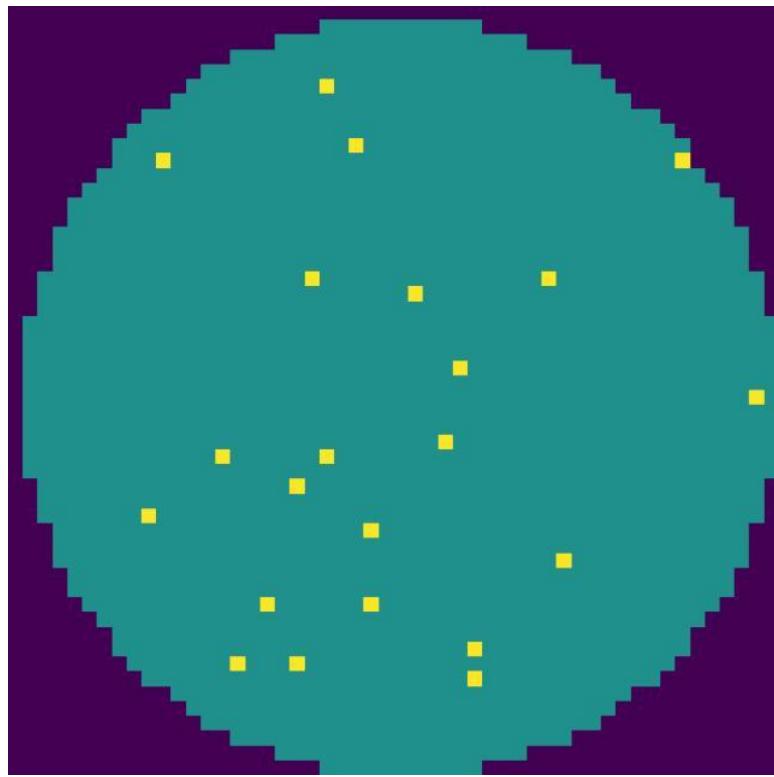
Wafer ID: Mechanical_MECH_02_W0032
Decision: PASS

Machine Type: Mechanical
Machine ID: MECH_02
Timestamp: 2025-12-27T12:08:06.960011
Simulation Date: 2025-12-27

Defect Class: Normal
Confidence Score: 0.9997
Defect Percentage: 29.05%

Reason: Defect Percentage: 29.05% (<=40% threshold), Defect Class: Normal, Confidence: 99.97%

Wafer Defect Image:



Wafer 185 Inspection Decision

Wafer ID: Thermal_THERM_02_W0022

Decision: FAIL

Machine Type: Thermal

Machine ID: THERM_02

Timestamp: 2025-12-27T12:08:08.277420

Simulation Date: 2025-12-27

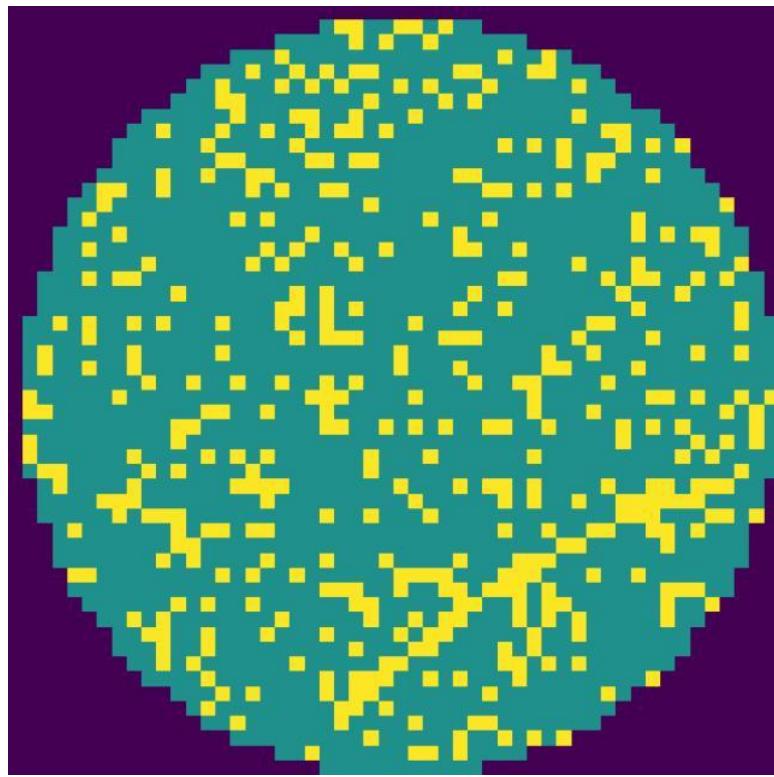
Defect Class: Scratch

Confidence Score: 1.0000

Defect Percentage: 43.14%

Reason: Defect Percentage: 43.14% (>40% threshold), Defect Class: Scratch, Confidence: 100.00%

Wafer Defect Image:



Wafer 186 Inspection Decision

Wafer ID: Mechanical_MECH_01_W0032

Decision: FAIL

Machine Type: Mechanical

Machine ID: MECH_01

Timestamp: 2025-12-27T12:08:08.450964

Simulation Date: 2025-12-27

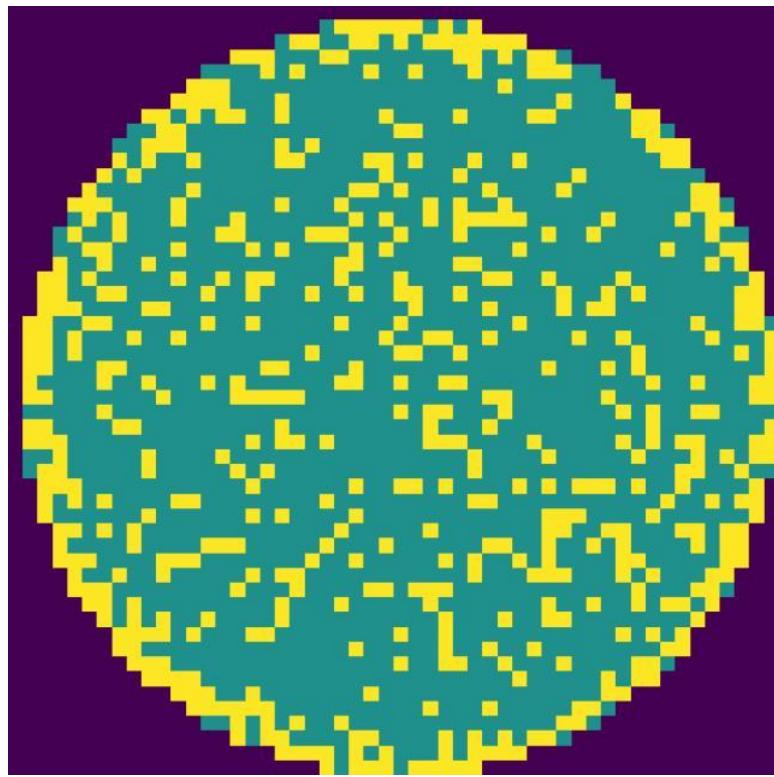
Defect Class: Edge-Ring

Confidence Score: 0.9641

Defect Percentage: 51.21%

Reason: Defect Percentage: 51.21% (>40% threshold), Defect Class: Edge-Ring, Confidence: 96.41%

Wafer Defect Image:



Wafer 187 Inspection Decision

Wafer ID: Electrical_ELEC_02_W0038

Decision: FAIL

Machine Type: Electrical

Machine ID: ELEC_02

Timestamp: 2025-12-27T12:08:11.137349

Simulation Date: 2025-12-27

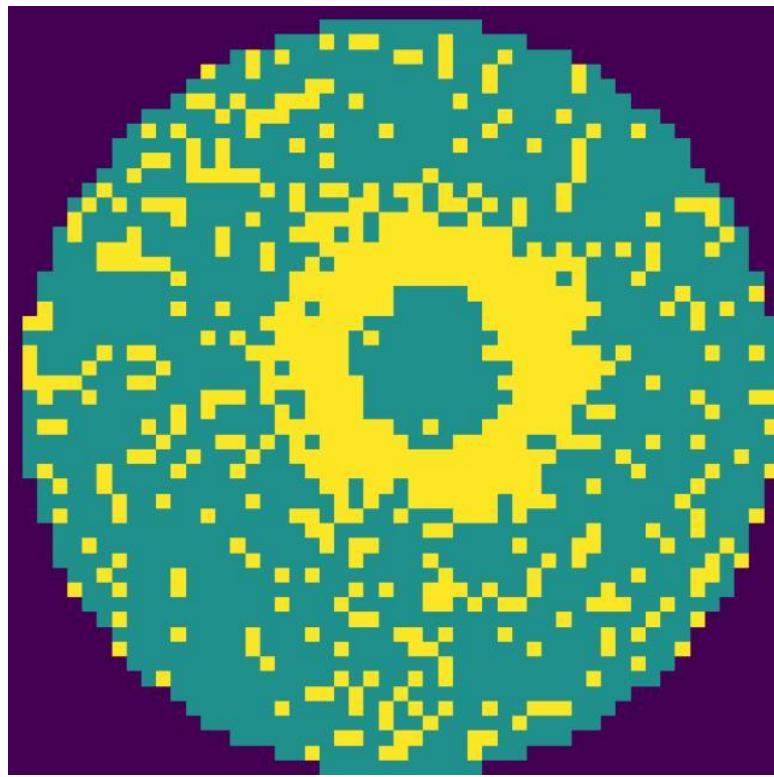
Defect Class: Donut

Confidence Score: 0.9999

Defect Percentage: 57.79%

Reason: Defect Percentage: 57.79% (>40% threshold), Defect Class: Donut, Confidence: 99.99%

Wafer Defect Image:



Wafer 188 Inspection Decision

Wafer ID: Thermal_THERM_01_W0027

Decision: FAIL

Machine Type: Thermal

Machine ID: THERM_01

Timestamp: 2025-12-27T12:08:12.554765

Simulation Date: 2025-12-27

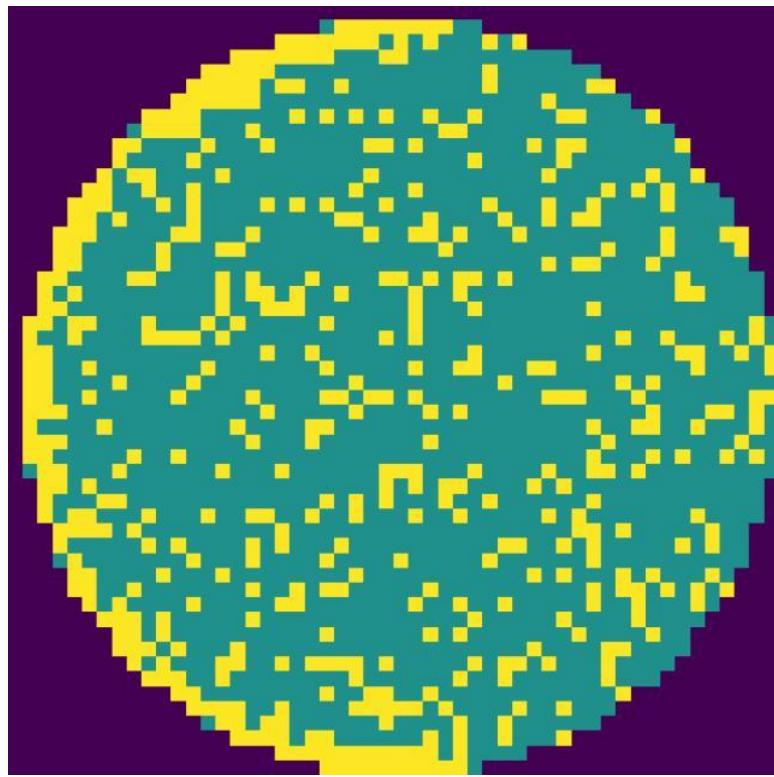
Defect Class: Edge-Loc

Confidence Score: 0.9979

Defect Percentage: 50.44%

Reason: Defect Percentage: 50.44% (>40% threshold), Defect Class: Edge-Loc, Confidence: 99.79%

Wafer Defect Image:



Wafer 189 Inspection Decision

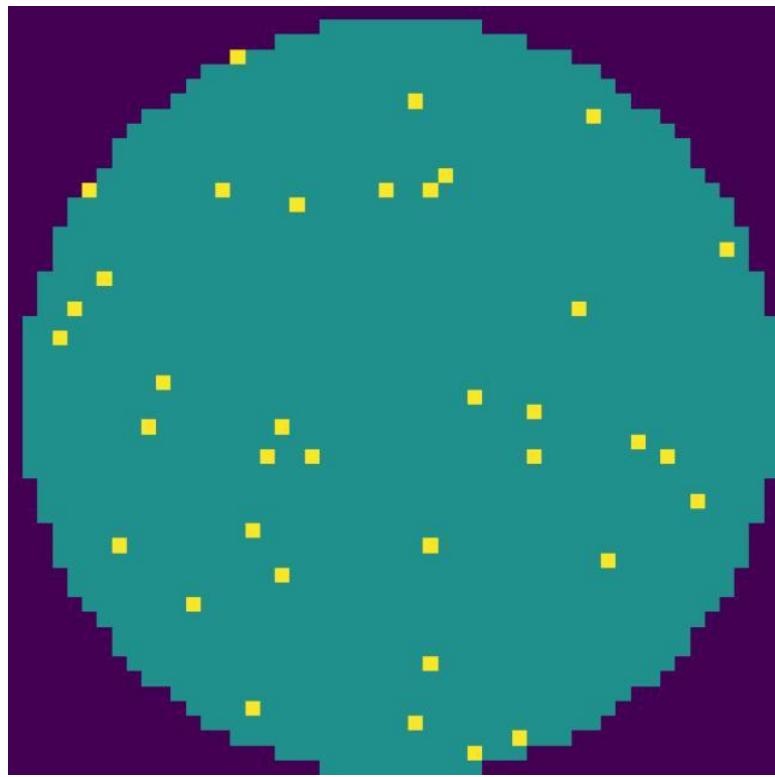
Wafer ID: Mechanical_MECH_02_W0033
Decision: PASS

Machine Type: Mechanical
Machine ID: MECH_02
Timestamp: 2025-12-27T12:08:12.600179
Simulation Date: 2025-12-27

Defect Class: Normal
Confidence Score: 0.9999
Defect Percentage: 31.11%

Reason: Defect Percentage: 31.11% (<=40% threshold), Defect Class: Normal, Confidence: 99.99%

Wafer Defect Image:



Wafer 190 Inspection Decision

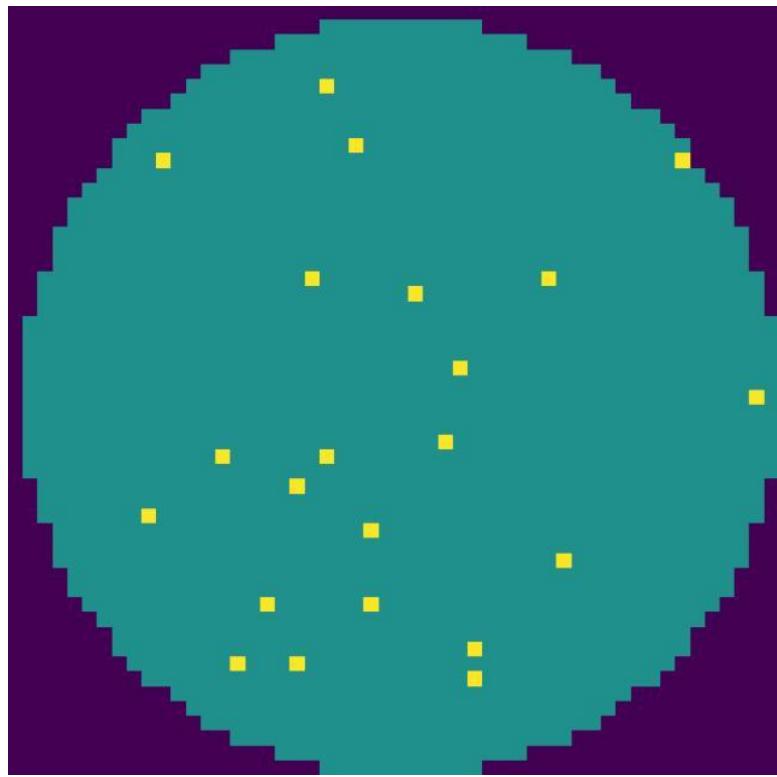
Wafer ID: Electrical_ELEC_01_W0038
Decision: PASS

Machine Type: Electrical
Machine ID: ELEC_01
Timestamp: 2025-12-27T12:08:12.805623
Simulation Date: 2025-12-27

Defect Class: Normal
Confidence Score: 0.9997
Defect Percentage: 29.05%

Reason: Defect Percentage: 29.05% (<=40% threshold), Defect Class: Normal, Confidence: 99.97%

Wafer Defect Image:



Wafer 191 Inspection Decision

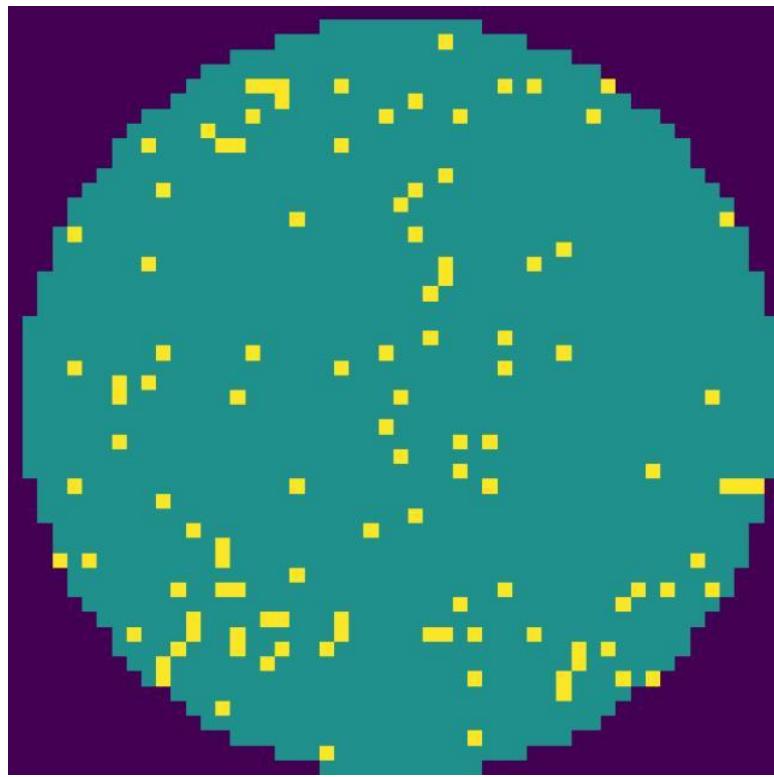
Wafer ID: Mechanical_MECH_01_W0033
Decision: PASS

Machine Type: Mechanical
Machine ID: MECH_01
Timestamp: 2025-12-27T12:08:15.142133
Simulation Date: 2025-12-27

Defect Class: Normal
Confidence Score: 0.9997
Defect Percentage: 34.78%

Reason: Defect Percentage: 34.78% (<=40% threshold), Defect Class: Normal, Confidence: 99.97%

Wafer Defect Image:



Wafer 192 Inspection Decision

Wafer ID: Electrical_ELEC_02_W0039

Decision: FAIL

Machine Type: Electrical

Machine ID: ELEC_02

Timestamp: 2025-12-27T12:08:16.966058

Simulation Date: 2025-12-27

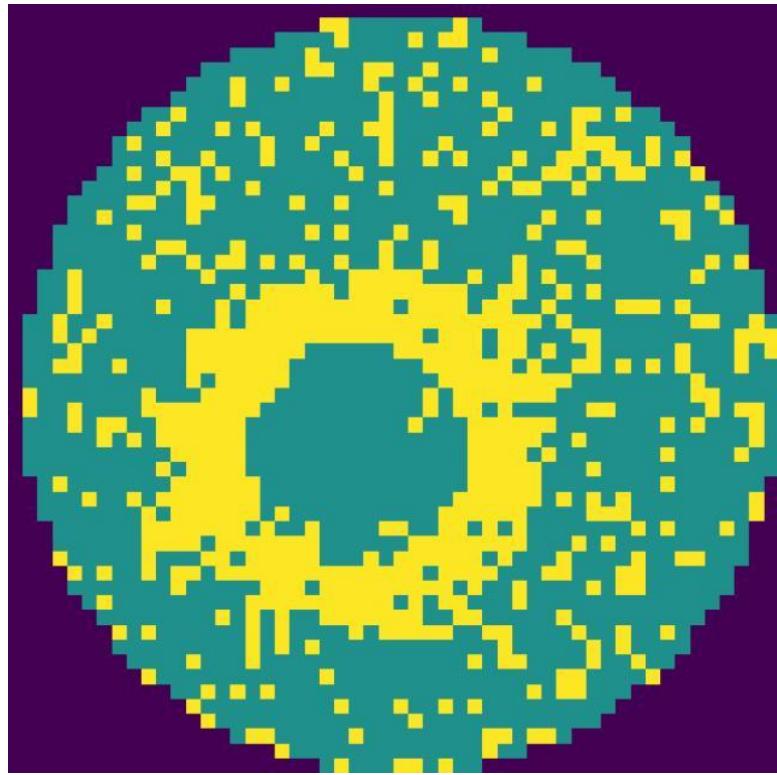
Defect Class: Donut

Confidence Score: 0.9999

Defect Percentage: 59.78%

Reason: Defect Percentage: 59.78% (>40% threshold), Defect Class: Donut, Confidence: 99.99%

Wafer Defect Image:



Wafer 193 Inspection Decision

Wafer ID: Electrical_ELEC_01_W0039

Decision: PASS

Machine Type: Electrical

Machine ID: ELEC_01

Timestamp: 2025-12-27T12:08:18.033811

Simulation Date: 2025-12-27

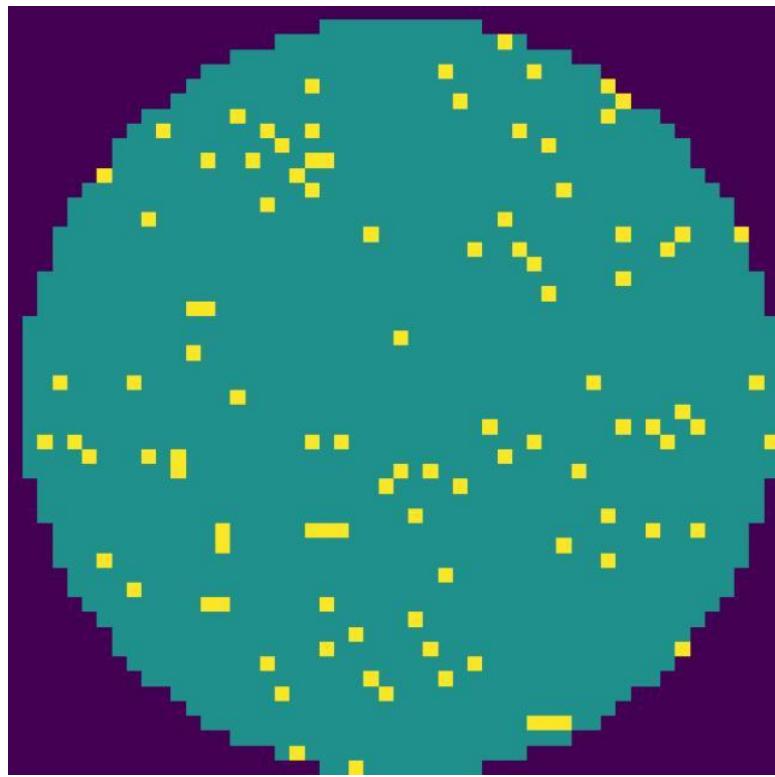
Defect Class: Normal

Confidence Score: 0.9998

Defect Percentage: 33.38%

Reason: Defect Percentage: 33.38% (<=40% threshold), Defect Class: Normal, Confidence: 99.98%

Wafer Defect Image:



Wafer 194 Inspection Decision

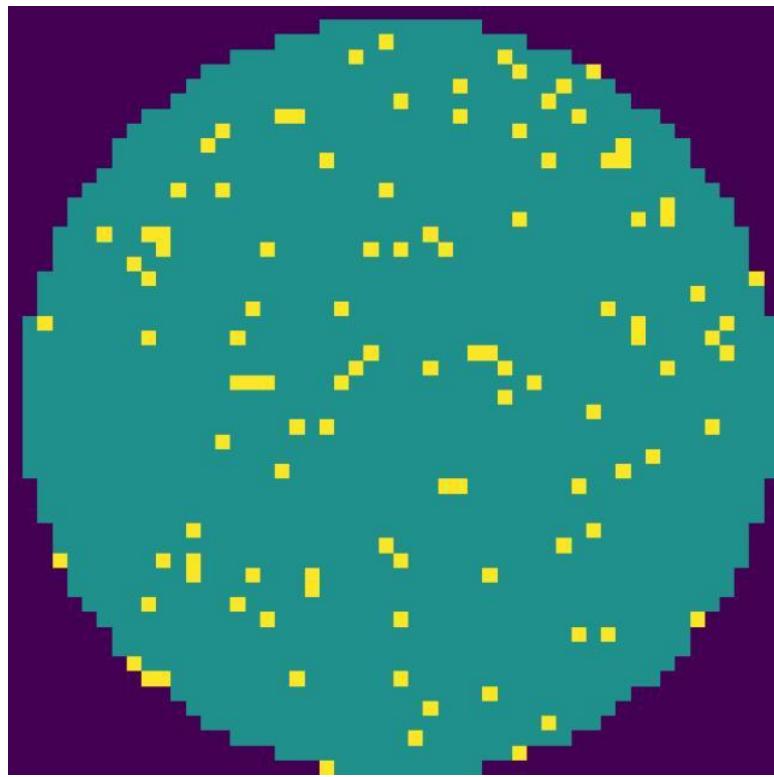
Wafer ID: Mechanical_MECH_02_W0034
Decision: PASS

Machine Type: Mechanical
Machine ID: MECH_02
Timestamp: 2025-12-27T12:08:18.267186
Simulation Date: 2025-12-27

Defect Class: Normal
Confidence Score: 0.9996
Defect Percentage: 35.18%

Reason: Defect Percentage: 35.18% (<=40% threshold), Defect Class: Normal, Confidence: 99.96%

Wafer Defect Image:



Wafer 195 Inspection Decision

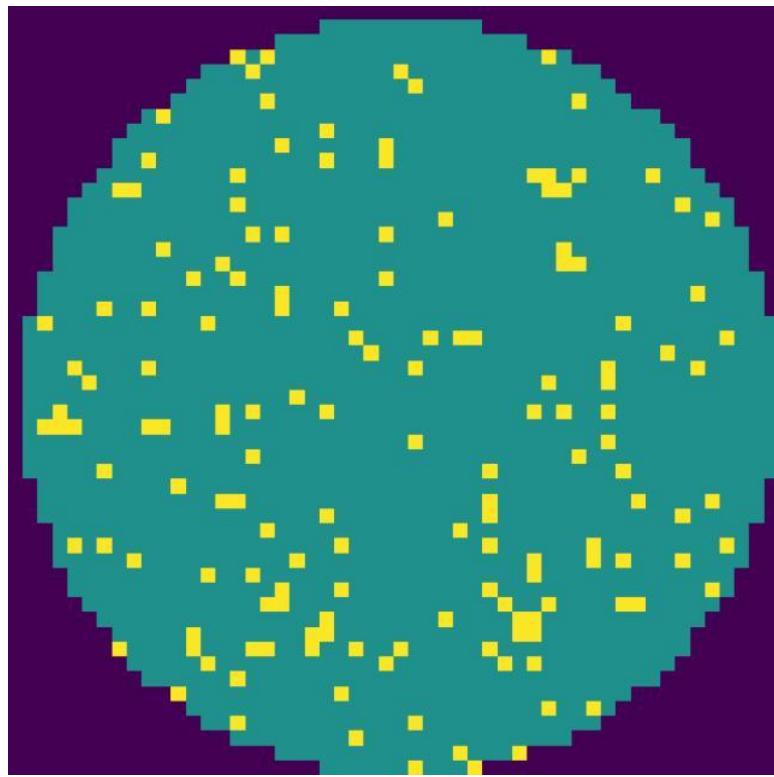
Wafer ID: Thermal_THERM_02_W0023
Decision: PASS

Machine Type: Thermal
Machine ID: THERM_02
Timestamp: 2025-12-27T12:08:19.662174
Simulation Date: 2025-12-27

Defect Class: Normal
Confidence Score: 0.9998
Defect Percentage: 35.83%

Reason: Defect Percentage: 35.83% (<=40% threshold), Defect Class: Normal, Confidence: 99.98%

Wafer Defect Image:



Wafer 196 Inspection Decision

Wafer ID: Mechanical_MECH_01_W0034

Decision: FAIL

Machine Type: Mechanical

Machine ID: MECH_01

Timestamp: 2025-12-27T12:08:20.730252

Simulation Date: 2025-12-27

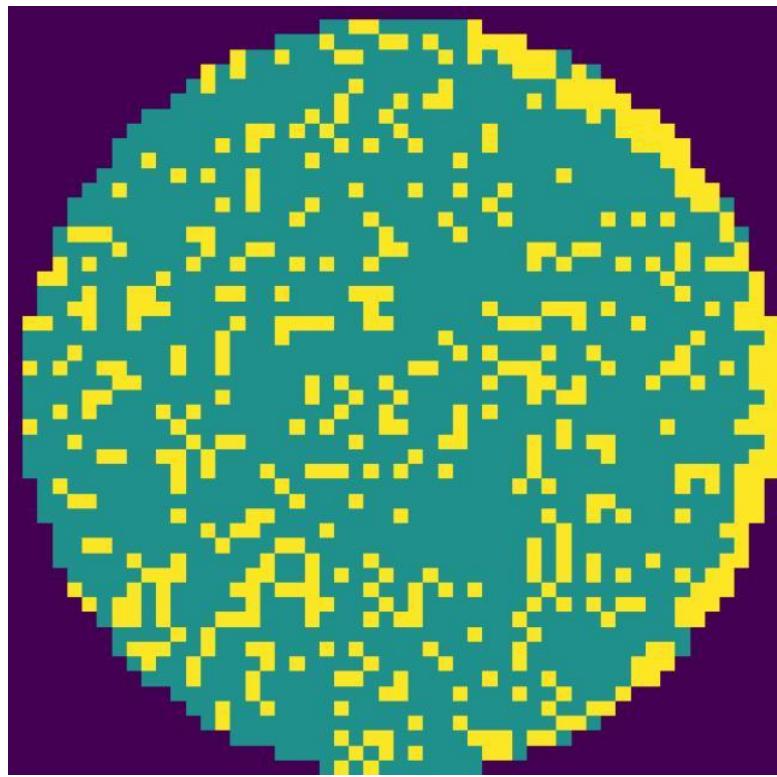
Defect Class: Edge-Loc

Confidence Score: 0.9617

Defect Percentage: 48.28%

Reason: Defect Percentage: 48.28% (>40% threshold), Defect Class: Edge-Loc, Confidence: 96.17%

Wafer Defect Image:



Wafer 197 Inspection Decision

Wafer ID: Electrical_ELEC_02_W0040

Decision: PASS

Machine Type: Electrical

Machine ID: ELEC_02

Timestamp: 2025-12-27T12:08:22.179691

Simulation Date: 2025-12-27

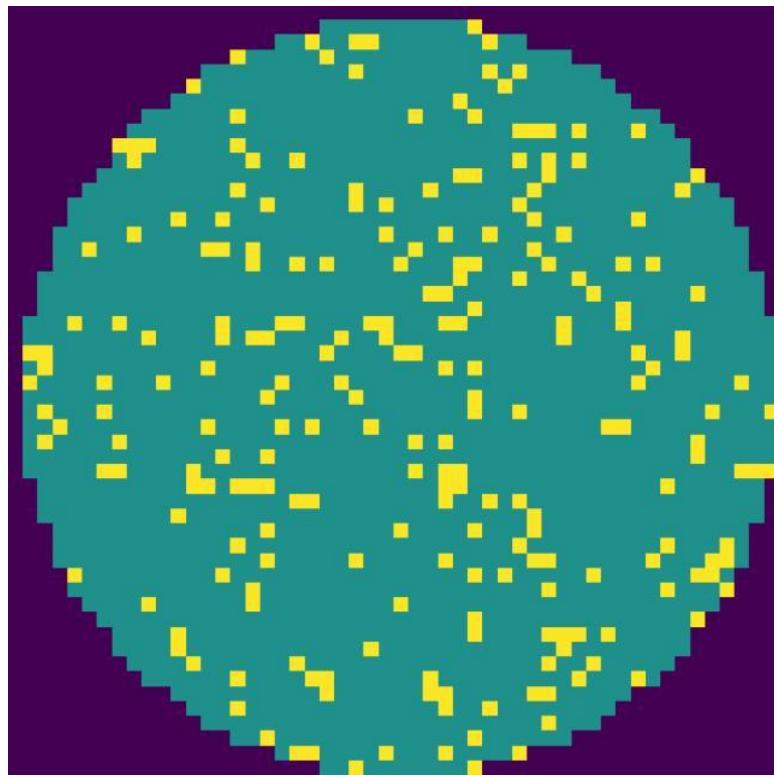
Defect Class: Normal

Confidence Score: 1.0000

Defect Percentage: 38.90%

Reason: Defect Percentage: 38.9% (<=40% threshold), Defect Class: Normal, Confidence: 100.00%

Wafer Defect Image:



Wafer 198 Inspection Decision

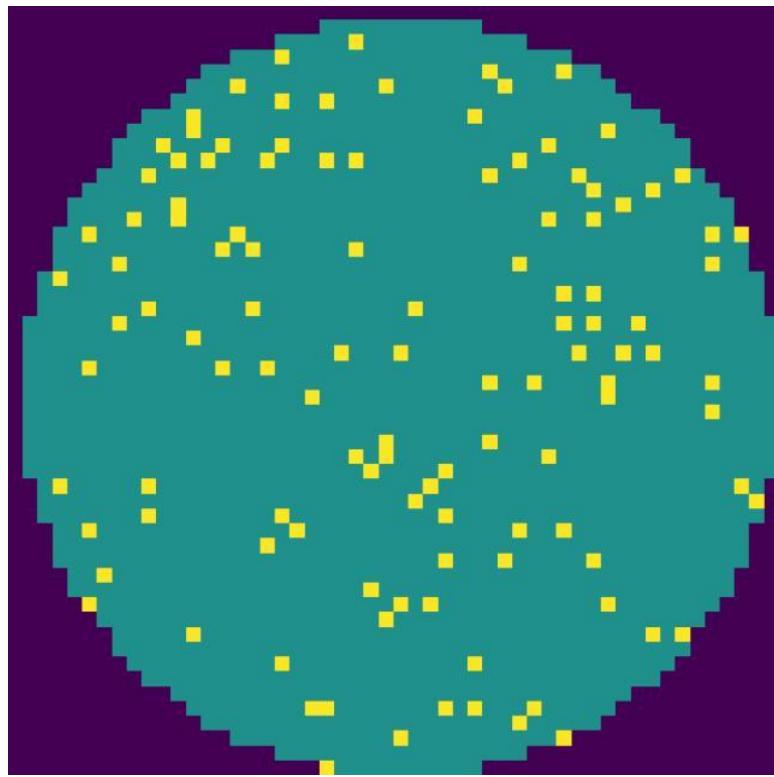
Wafer ID: Thermal_THERM_01_W0028
Decision: PASS

Machine Type: Thermal
Machine ID: THERM_01
Timestamp: 2025-12-27T12:08:22.835920
Simulation Date: 2025-12-27

Defect Class: Normal
Confidence Score: 0.9997
Defect Percentage: 32.36%

Reason: Defect Percentage: 32.36% (<=40% threshold), Defect Class: Normal, Confidence: 99.97%

Wafer Defect Image:



Wafer 199 Inspection Decision

Wafer ID: Electrical_ELEC_01_W0040

Decision: PASS

Machine Type: Electrical

Machine ID: ELEC_01

Timestamp: 2025-12-27T12:08:23.119402

Simulation Date: 2025-12-27

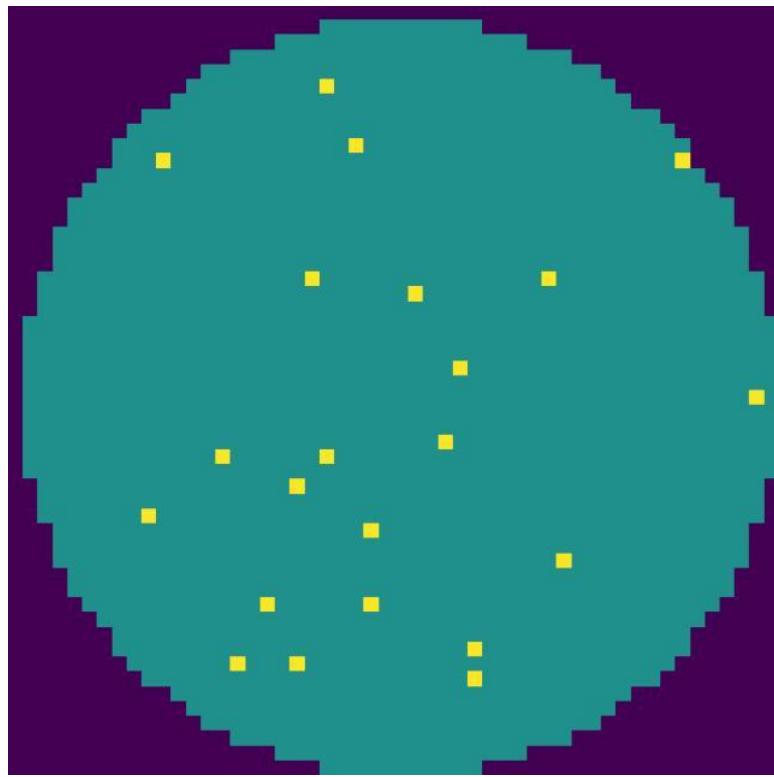
Defect Class: Normal

Confidence Score: 0.9997

Defect Percentage: 29.05%

Reason: Defect Percentage: 29.05% (<=40% threshold), Defect Class: Normal, Confidence: 99.97%

Wafer Defect Image:



Wafer 200 Inspection Decision

Wafer ID: Mechanical_MECH_02_W0035

Decision: FAIL

Machine Type: Mechanical

Machine ID: MECH_02

Timestamp: 2025-12-27T12:08:23.618790

Simulation Date: 2025-12-27

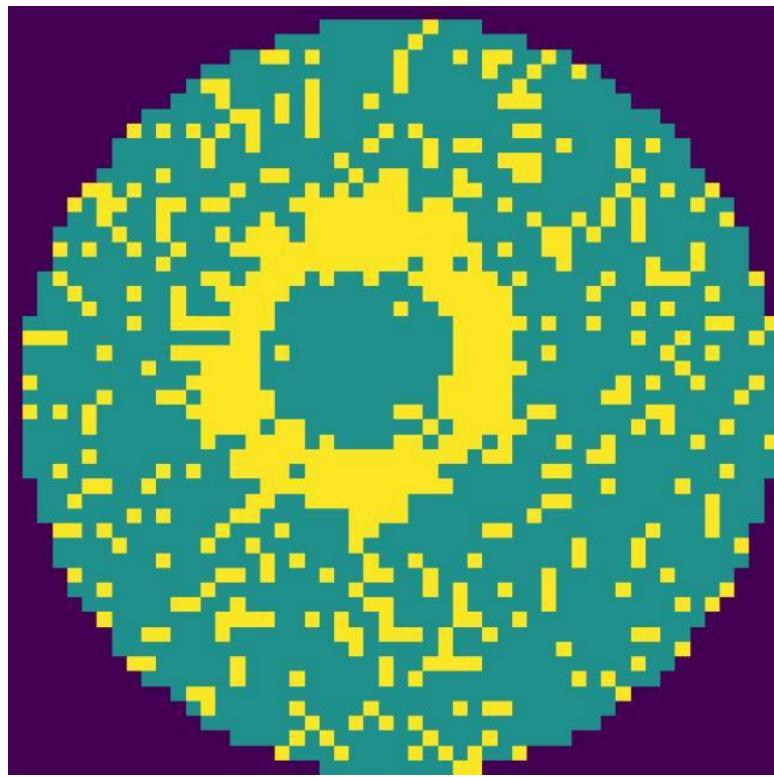
Defect Class: Donut

Confidence Score: 0.9999

Defect Percentage: 55.77%

Reason: Defect Percentage: 55.77% (>40% threshold), Defect Class: Donut, Confidence: 99.99%

Wafer Defect Image:



Wafer 201 Inspection Decision

Wafer ID: Mechanical_MECH_01_W0035

Decision: FAIL

Machine Type: Mechanical

Machine ID: MECH_01

Timestamp: 2025-12-27T12:08:26.396342

Simulation Date: 2025-12-27

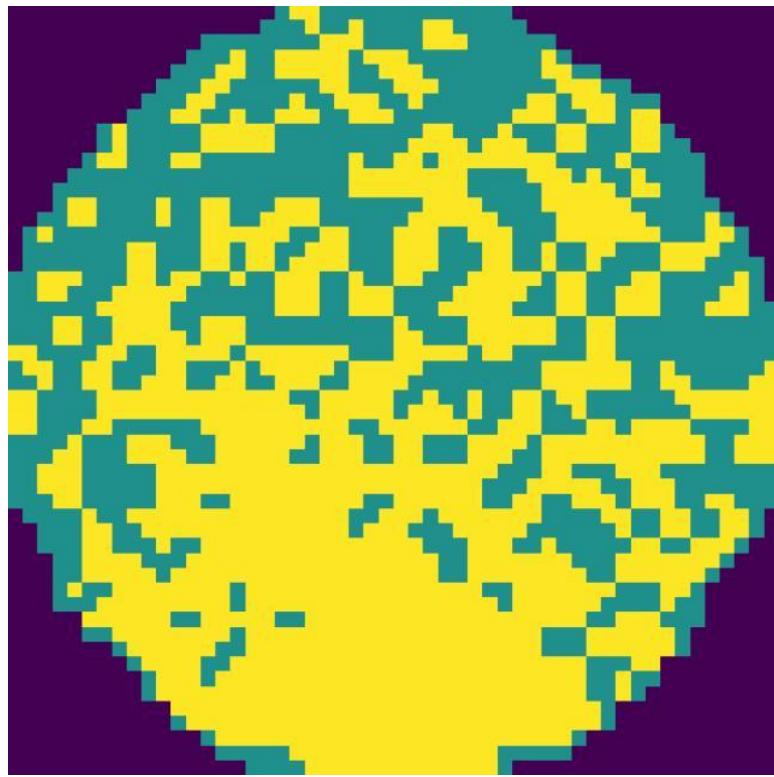
Defect Class: Random

Confidence Score: 0.9992

Defect Percentage: 79.16%

Reason: Defect Percentage: 79.16% (>40% threshold), Defect Class: Random, Confidence: 99.92%

Wafer Defect Image:



Wafer 202 Inspection Decision

Wafer ID: Electrical_ELEC_02_W0041

Decision: FAIL

Machine Type: Electrical

Machine ID: ELEC_02

Timestamp: 2025-12-27T12:08:28.171803

Simulation Date: 2025-12-27

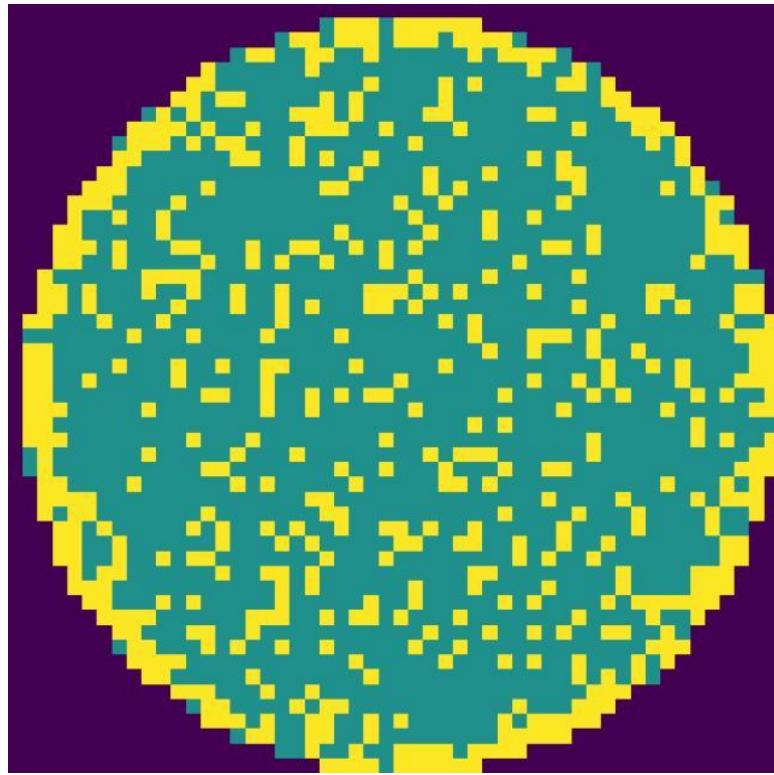
Defect Class: Edge-Ring

Confidence Score: 0.9966

Defect Percentage: 52.67%

Reason: Defect Percentage: 52.67% (>40% threshold), Defect Class: Edge-Ring, Confidence: 99.66%

Wafer Defect Image:



Wafer 203 Inspection Decision

Wafer ID: Thermal_THERM_02_W0024

Decision: FAIL

Machine Type: Thermal

Machine ID: THERM_02

Timestamp: 2025-12-27T12:08:28.368351

Simulation Date: 2025-12-27

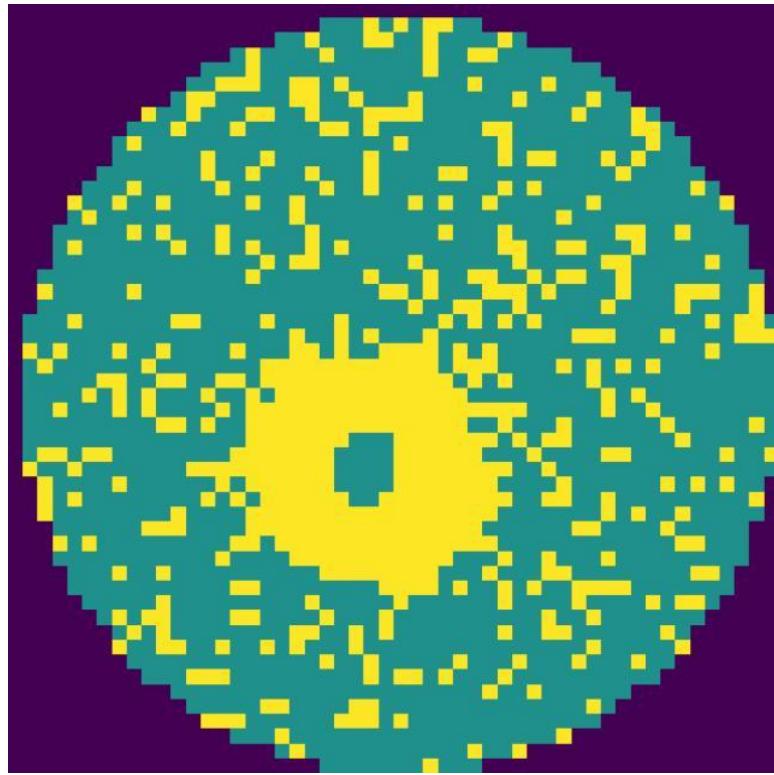
Defect Class: Donut

Confidence Score: 0.9991

Defect Percentage: 56.61%

Reason: Defect Percentage: 56.61% (>40% threshold), Defect Class: Donut, Confidence: 99.91%

Wafer Defect Image:



Wafer 204 Inspection Decision

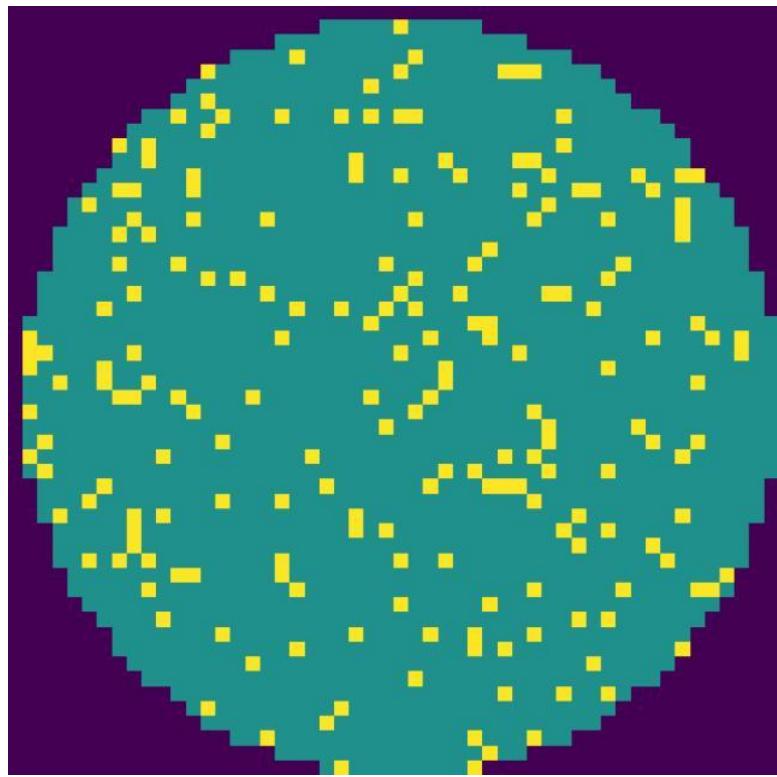
Wafer ID: Electrical_ELEC_01_W0041
Decision: PASS

Machine Type: Electrical
Machine ID: ELEC_01
Timestamp: 2025-12-27T12:08:29.028208
Simulation Date: 2025-12-27

Defect Class: Normal
Confidence Score: 0.9998
Defect Percentage: 35.92%

Reason: Defect Percentage: 35.92% (<=40% threshold), Defect Class: Normal, Confidence: 99.98%

Wafer Defect Image:



Wafer 205 Inspection Decision

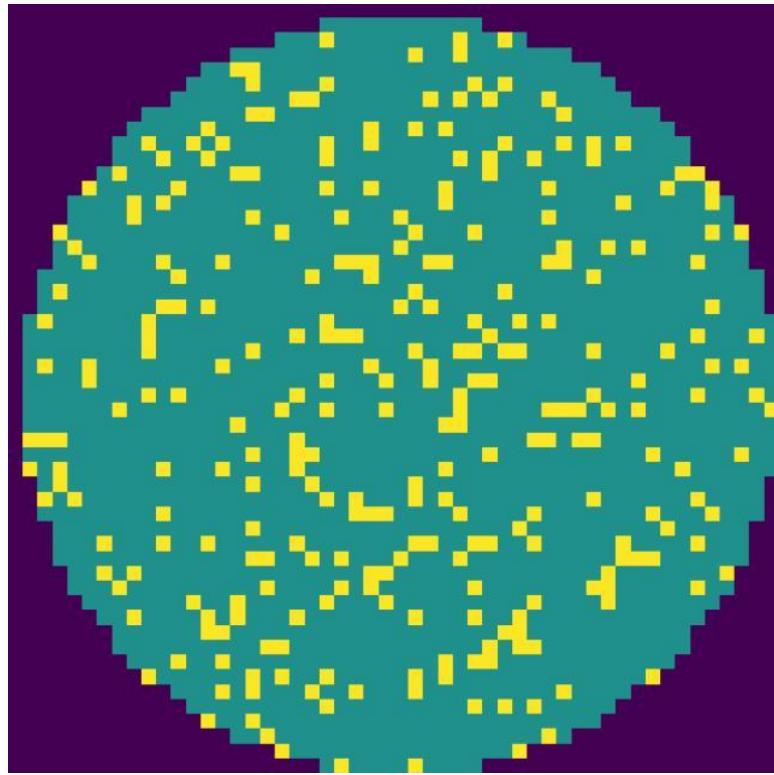
Wafer ID: Mechanical_MECH_02_W0036
Decision: PASS

Machine Type: Mechanical
Machine ID: MECH_02
Timestamp: 2025-12-27T12:08:29.448517
Simulation Date: 2025-12-27

Defect Class: Normal
Confidence Score: 0.9999
Defect Percentage: 38.27%

Reason: Defect Percentage: 38.27% (<=40% threshold), Defect Class: Normal, Confidence: 99.99%

Wafer Defect Image:



Wafer 206 Inspection Decision

Wafer ID: Thermal_THERM_01_W0029

Decision: FAIL

Machine Type: Thermal

Machine ID: THERM_01

Timestamp: 2025-12-27T12:08:30.028375

Simulation Date: 2025-12-27

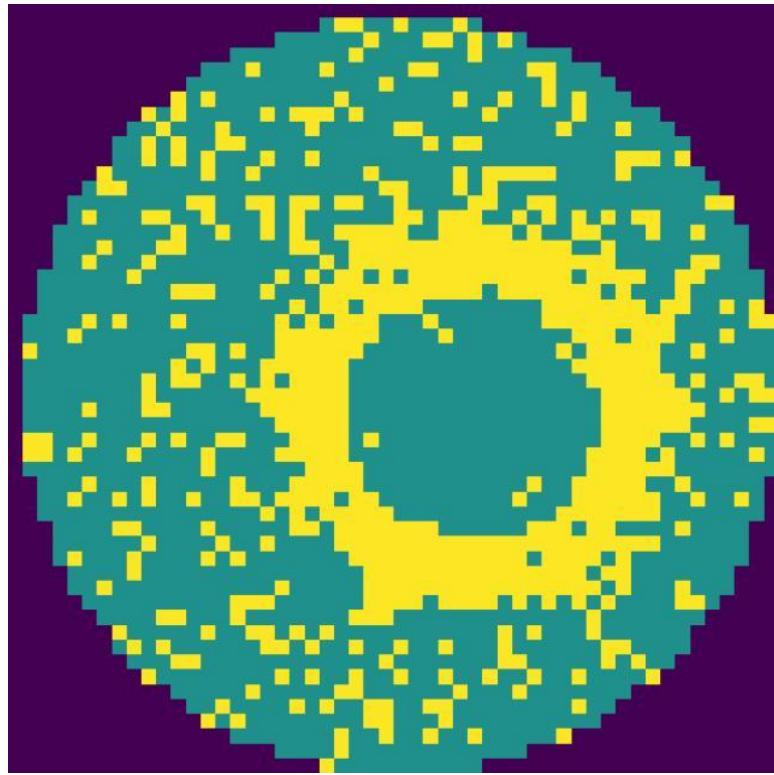
Defect Class: Donut

Confidence Score: 0.9998

Defect Percentage: 61.40%

Reason: Defect Percentage: 61.4% (>40% threshold), Defect Class: Donut, Confidence: 99.98%

Wafer Defect Image:



Wafer 207 Inspection Decision

Wafer ID: Mechanical_MECH_01_W0036

Decision: FAIL

Machine Type: Mechanical

Machine ID: MECH_01

Timestamp: 2025-12-27T12:08:34.040122

Simulation Date: 2025-12-27

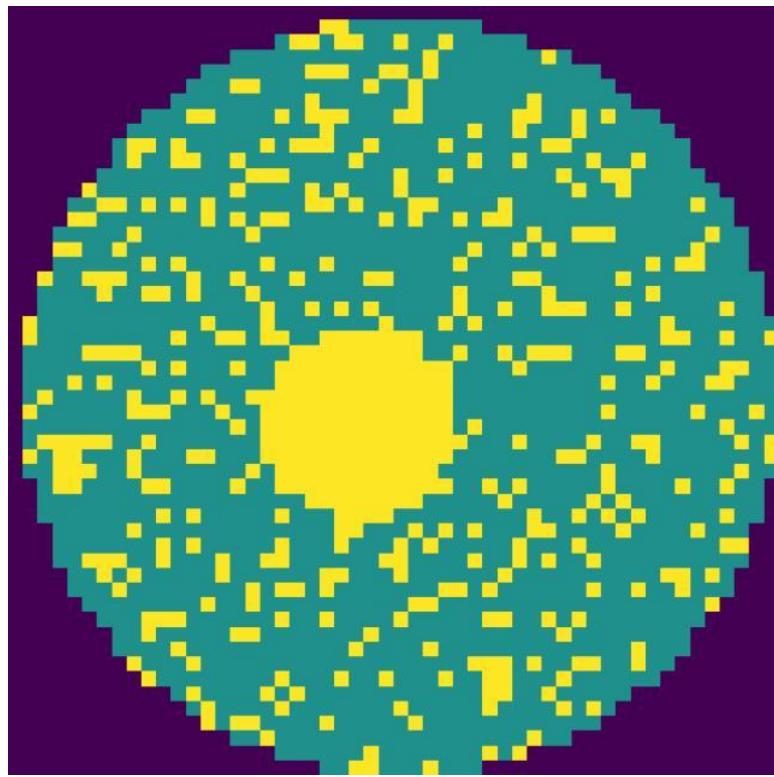
Defect Class: Center

Confidence Score: 0.9999

Defect Percentage: 51.84%

Reason: Defect Percentage: 51.84% (>40% threshold), Defect Class: Center, Confidence: 99.99%

Wafer Defect Image:



Wafer 208 Inspection Decision

Wafer ID: Electrical_ELEC_02_W0042

Decision: PASS

Machine Type: Electrical

Machine ID: ELEC_02

Timestamp: 2025-12-27T12:08:34.117900

Simulation Date: 2025-12-27

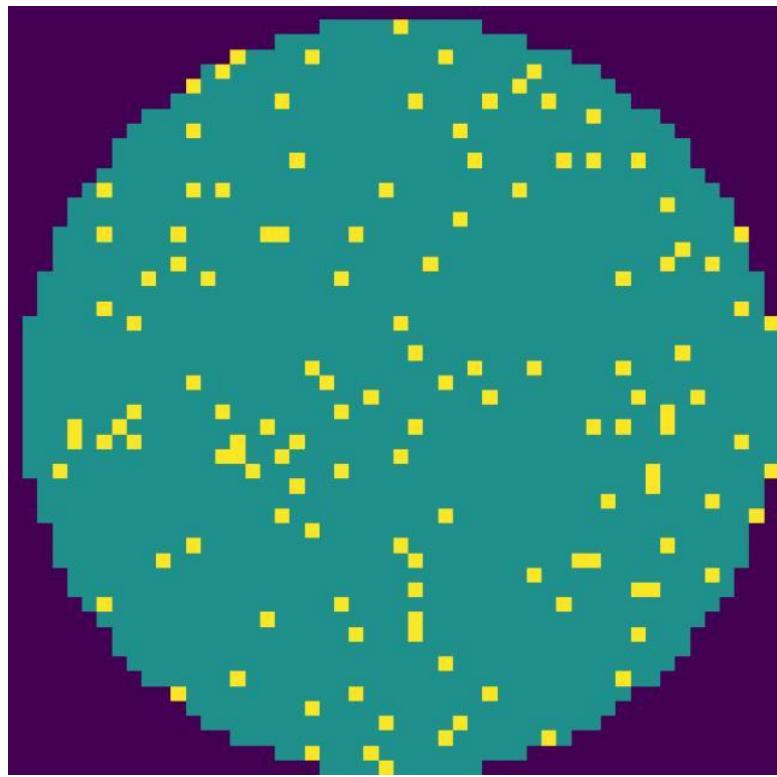
Defect Class: Normal

Confidence Score: 0.9998

Defect Percentage: 33.33%

Reason: Defect Percentage: 33.33% (<=40% threshold), Defect Class: Normal, Confidence: 99.98%

Wafer Defect Image:



Wafer 209 Inspection Decision

Wafer ID: Electrical_ELEC_01_W0042

Decision: PASS

Machine Type: Electrical

Machine ID: ELEC_01

Timestamp: 2025-12-27T12:08:34.460928

Simulation Date: 2025-12-27

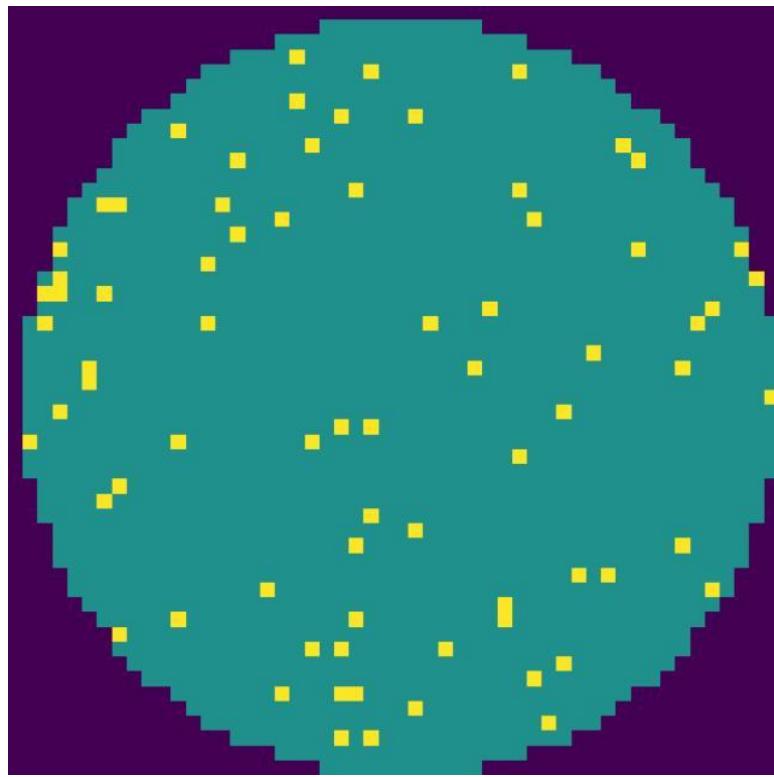
Defect Class: Normal

Confidence Score: 0.9998

Defect Percentage: 32.88%

Reason: Defect Percentage: 32.88% (<=40% threshold), Defect Class: Normal, Confidence: 99.98%

Wafer Defect Image:



Wafer 210 Inspection Decision

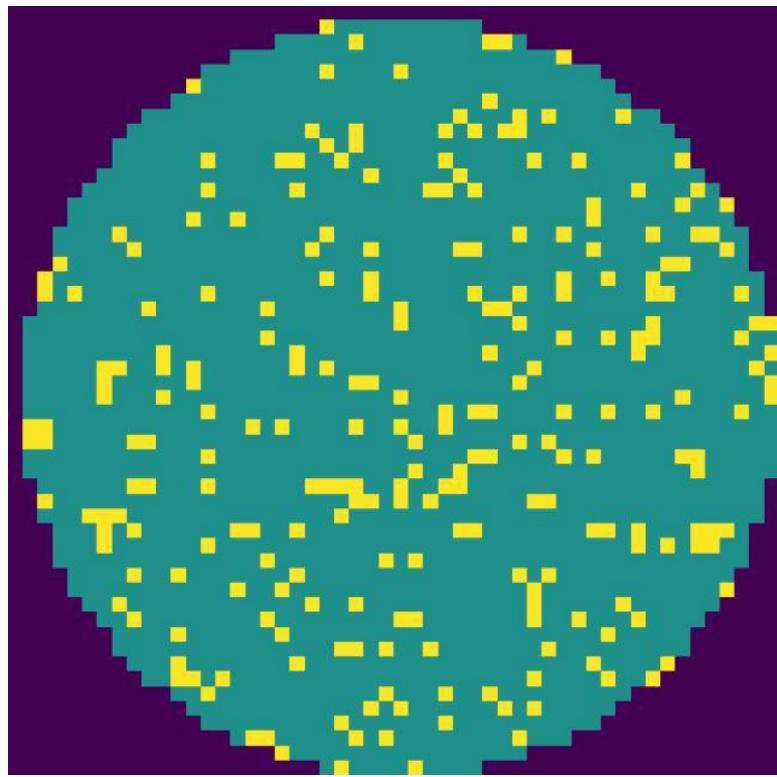
Wafer ID: Thermal_THERM_02_W0025
Decision: PASS

Machine Type: Thermal
Machine ID: THERM_02
Timestamp: 2025-12-27T12:08:35.151263
Simulation Date: 2025-12-27

Defect Class: Normal
Confidence Score: 0.9999
Defect Percentage: 39.60%

Reason: Defect Percentage: 39.6% (<=40% threshold), Defect Class: Normal, Confidence: 99.99%

Wafer Defect Image:



Wafer 211 Inspection Decision

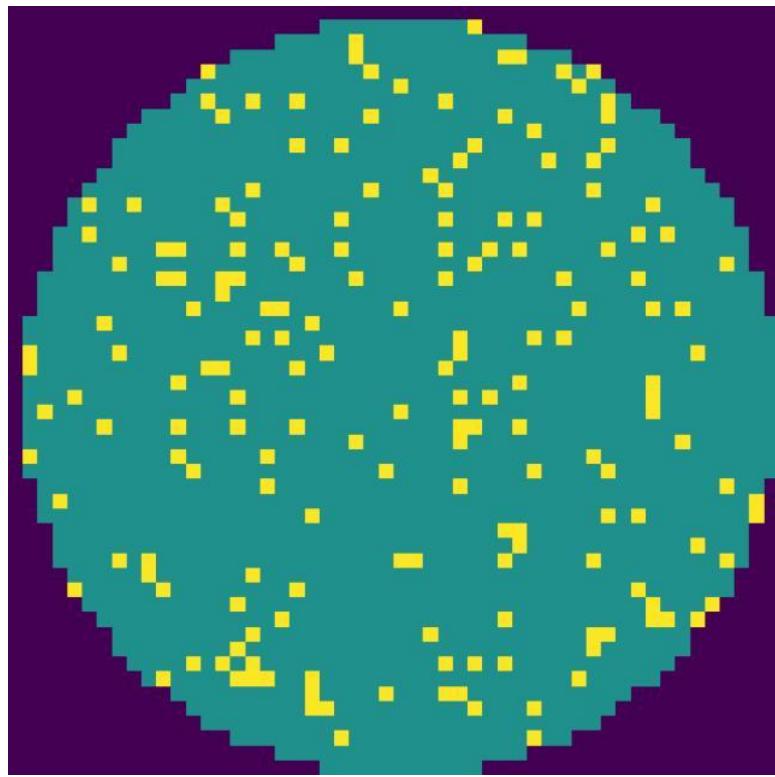
Wafer ID: Thermal_THERM_01_W0030
Decision: PASS

Machine Type: Thermal
Machine ID: THERM_01
Timestamp: 2025-12-27T12:08:35.909985
Simulation Date: 2025-12-27

Defect Class: Normal
Confidence Score: 0.9998
Defect Percentage: 35.70%

Reason: Defect Percentage: 35.7% (<=40% threshold), Defect Class: Normal, Confidence: 99.98%

Wafer Defect Image:



Wafer 212 Inspection Decision

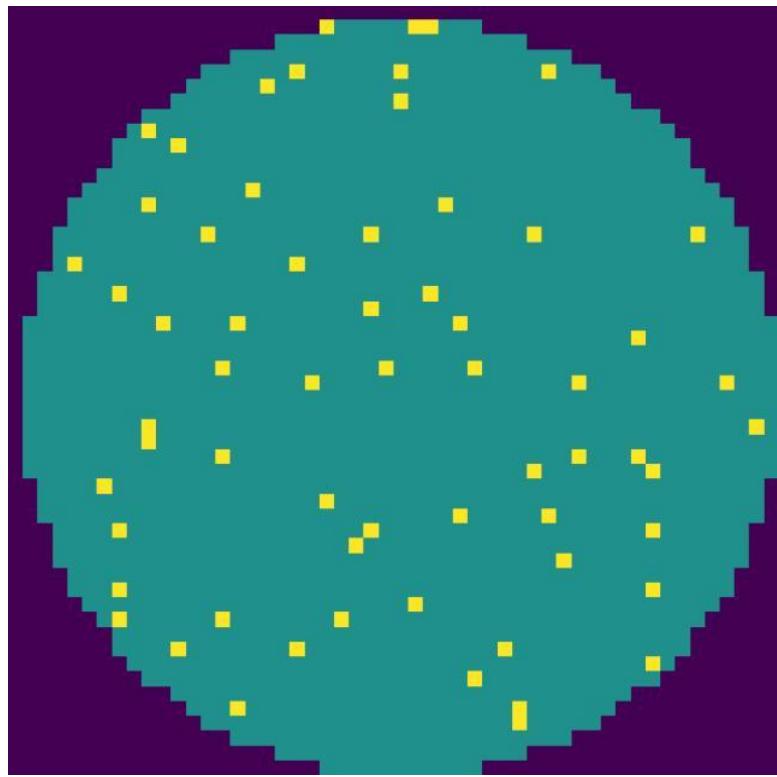
Wafer ID: Mechanical_MECH_02_W0037
Decision: PASS

Machine Type: Mechanical
Machine ID: MECH_02
Timestamp: 2025-12-27T12:08:37.428221
Simulation Date: 2025-12-27

Defect Class: Normal
Confidence Score: 0.9998
Defect Percentage: 32.51%

Reason: Defect Percentage: 32.51% (<=40% threshold), Defect Class: Normal, Confidence: 99.98%

Wafer Defect Image:



Wafer 213 Inspection Decision

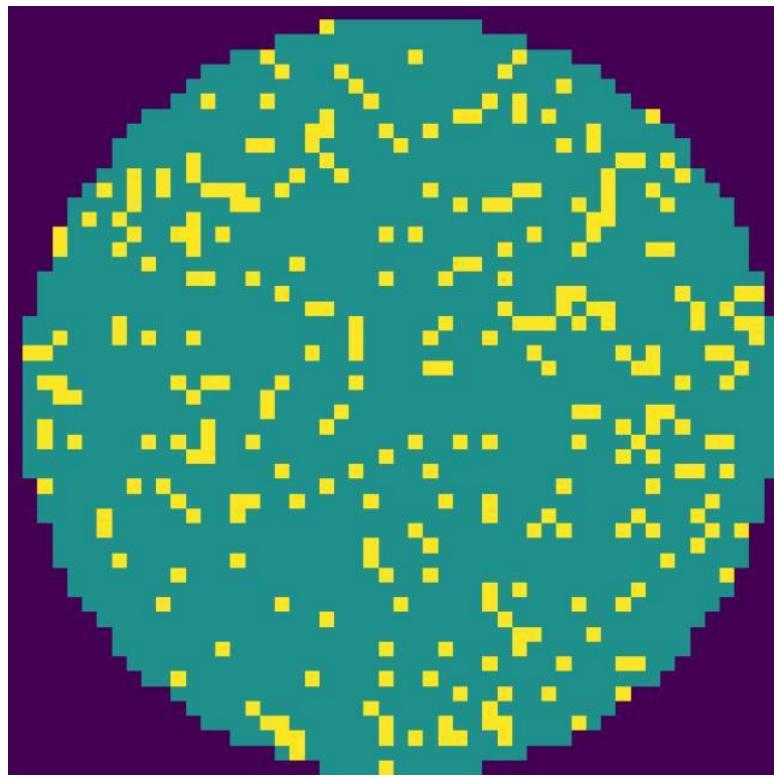
Wafer ID: Mechanical_MECH_01_W0037
Decision: PASS

Machine Type: Mechanical
Machine ID: MECH_01
Timestamp: 2025-12-27T12:08:39.261422
Simulation Date: 2025-12-27

Defect Class: Normal
Confidence Score: 0.9999
Defect Percentage: 38.85%

Reason: Defect Percentage: 38.85% (<=40% threshold), Defect Class: Normal, Confidence: 99.99%

Wafer Defect Image:



Wafer 214 Inspection Decision

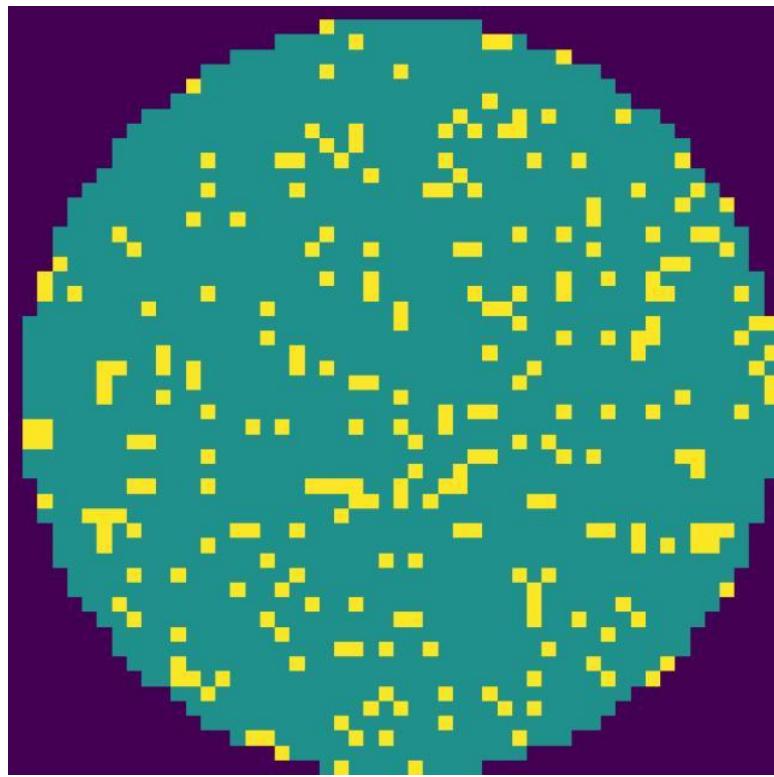
Wafer ID: Electrical_ELEC_02_W0043
Decision: PASS

Machine Type: Electrical
Machine ID: ELEC_02
Timestamp: 2025-12-27T12:08:39.420486
Simulation Date: 2025-12-27

Defect Class: Normal
Confidence Score: 0.9999
Defect Percentage: 39.60%

Reason: Defect Percentage: 39.6% (<=40% threshold), Defect Class: Normal, Confidence: 99.99%

Wafer Defect Image:



Wafer 215 Inspection Decision

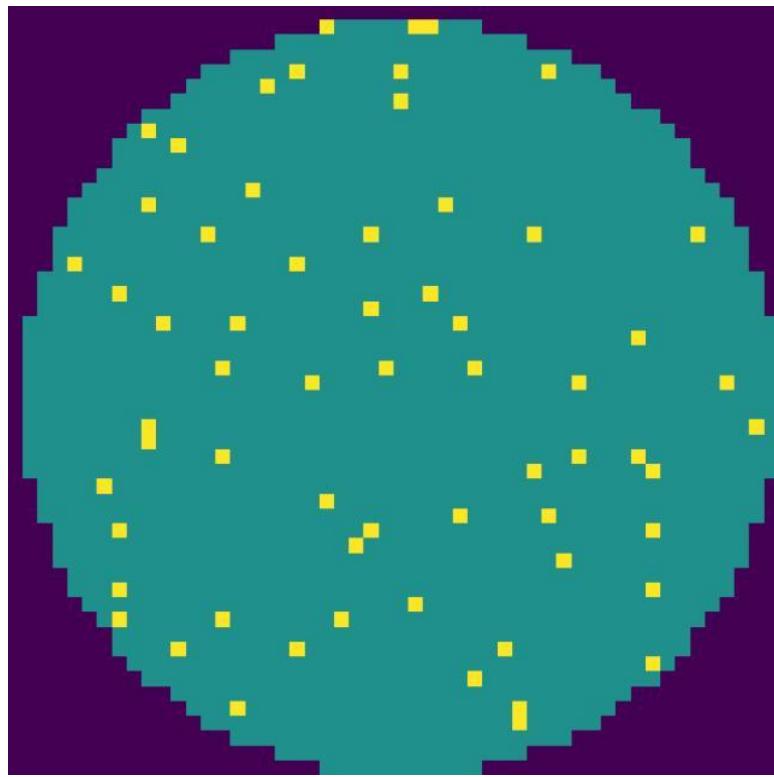
Wafer ID: Electrical_ELEC_01_W0043
Decision: PASS

Machine Type: Electrical
Machine ID: ELEC_01
Timestamp: 2025-12-27T12:08:40.112664
Simulation Date: 2025-12-27

Defect Class: Normal
Confidence Score: 0.9998
Defect Percentage: 32.51%

Reason: Defect Percentage: 32.51% (<=40% threshold), Defect Class: Normal, Confidence: 99.98%

Wafer Defect Image:



Wafer 216 Inspection Decision

Wafer ID: Thermal_THERM_02_W0026

Decision: FAIL

Machine Type: Thermal

Machine ID: THERM_02

Timestamp: 2025-12-27T12:08:42.894608

Simulation Date: 2025-12-27

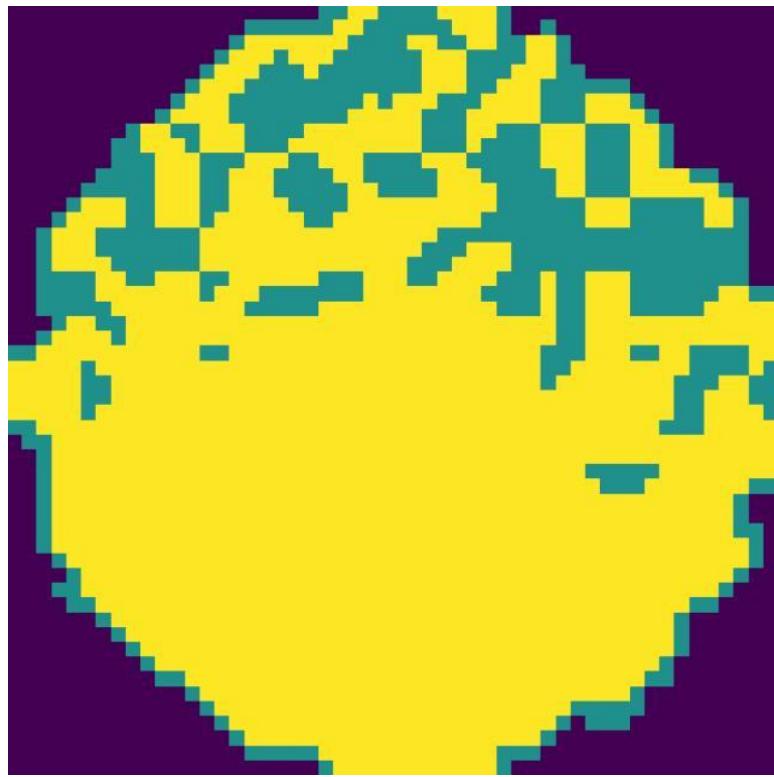
Defect Class: Near-Full

Confidence Score: 0.9979

Defect Percentage: 91.11%

Reason: Defect Percentage: 91.11% (>40% threshold), Defect Class: Near-Full, Confidence: 99.79%

Wafer Defect Image:



Wafer 217 Inspection Decision

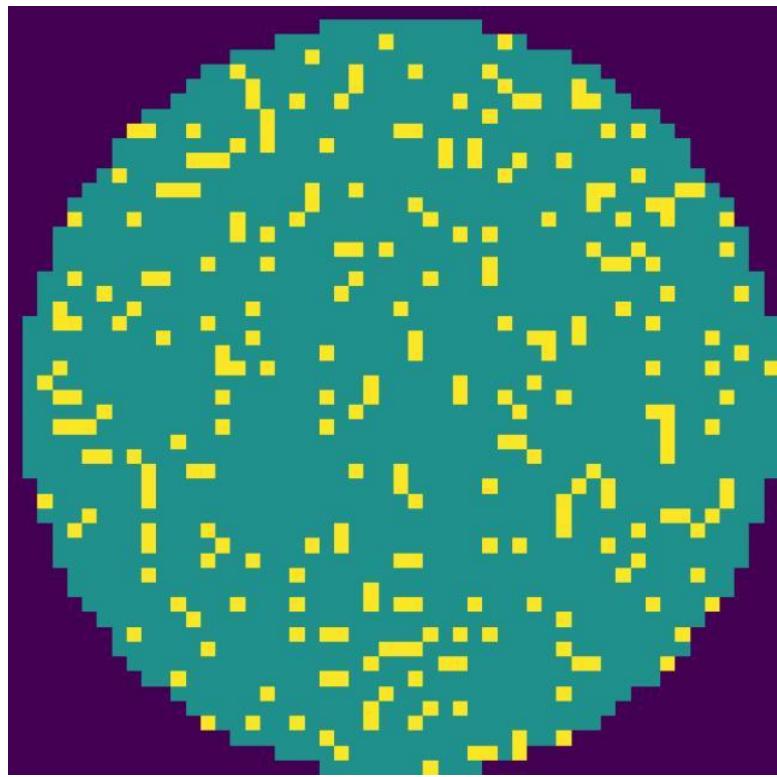
Wafer ID: Mechanical_MECH_01_W0038
Decision: PASS

Machine Type: Mechanical
Machine ID: MECH_01
Timestamp: 2025-12-27T12:08:44.472797
Simulation Date: 2025-12-27

Defect Class: Normal
Confidence Score: 0.9998
Defect Percentage: 38.11%

Reason: Defect Percentage: 38.11% (<=40% threshold), Defect Class: Normal, Confidence: 99.98%

Wafer Defect Image:



Wafer 218 Inspection Decision

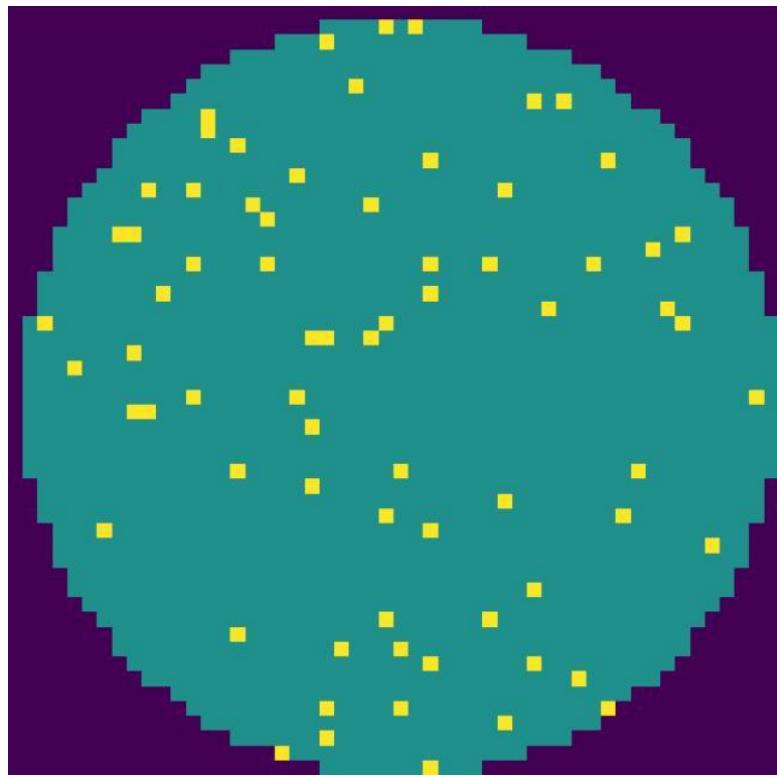
Wafer ID: Electrical_ELEC_02_W0044
Decision: PASS

Machine Type: Electrical
Machine ID: ELEC_02
Timestamp: 2025-12-27T12:08:44.552965
Simulation Date: 2025-12-27

Defect Class: Normal
Confidence Score: 0.9997
Defect Percentage: 32.51%

Reason: Defect Percentage: 32.51% (<=40% threshold), Defect Class: Normal, Confidence: 99.97%

Wafer Defect Image:



Wafer 219 Inspection Decision

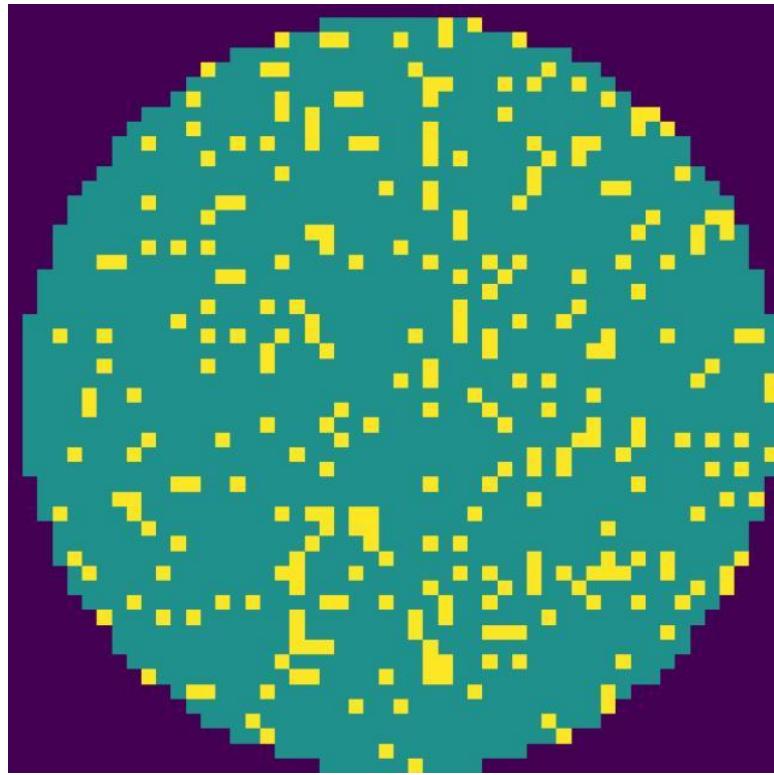
Wafer ID: Mechanical_MECH_02_W0038
Decision: PASS

Machine Type: Mechanical
Machine ID: MECH_02
Timestamp: 2025-12-27T12:08:44.608325
Simulation Date: 2025-12-27

Defect Class: Normal
Confidence Score: 0.9998
Defect Percentage: 39.16%

Reason: Defect Percentage: 39.16% (<=40% threshold), Defect Class: Normal, Confidence: 99.98%

Wafer Defect Image:



Wafer 220 Inspection Decision

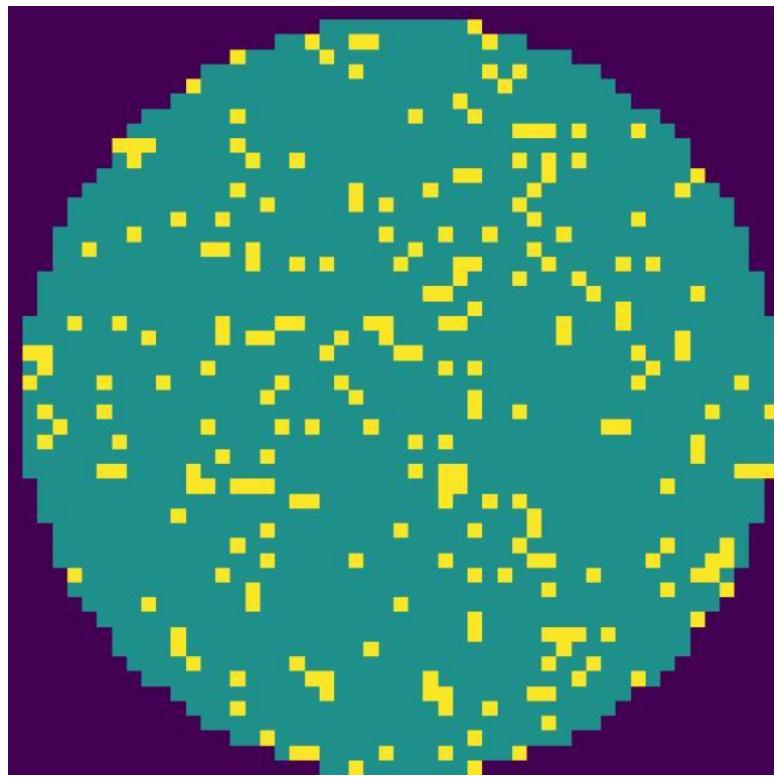
Wafer ID: Electrical_ELEC_01_W0044
Decision: PASS

Machine Type: Electrical
Machine ID: ELEC_01
Timestamp: 2025-12-27T12:08:45.352535
Simulation Date: 2025-12-27

Defect Class: Normal
Confidence Score: 1.0000
Defect Percentage: 38.90%

Reason: Defect Percentage: 38.9% (<=40% threshold), Defect Class: Normal, Confidence: 100.00%

Wafer Defect Image:



Wafer 221 Inspection Decision

Wafer ID: Thermal_THERM_01_W0031

Decision: FAIL

Machine Type: Thermal

Machine ID: THERM_01

Timestamp: 2025-12-27T12:08:46.877594

Simulation Date: 2025-12-27

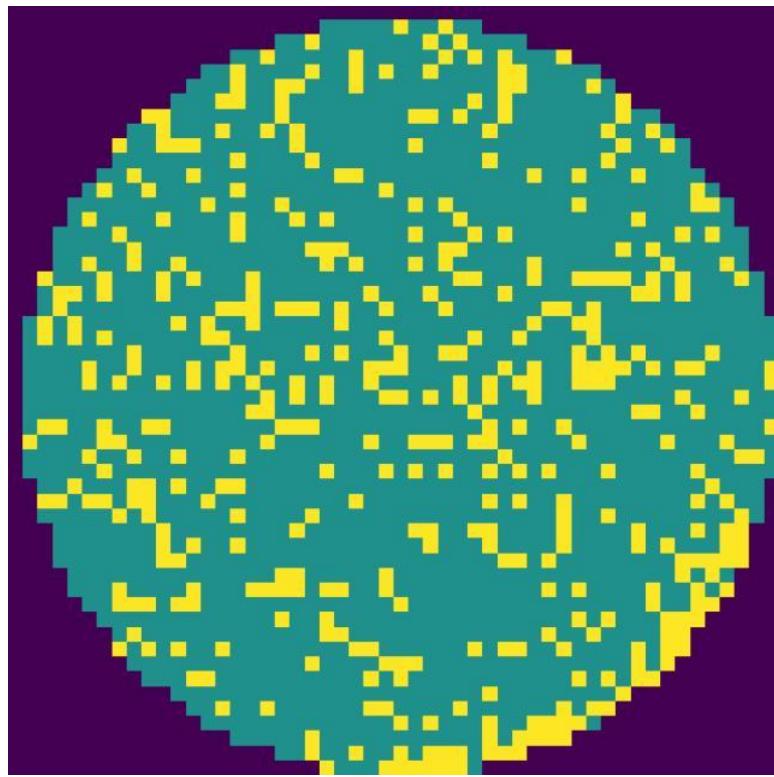
Defect Class: Edge-Loc

Confidence Score: 0.9930

Defect Percentage: 45.07%

Reason: Defect Percentage: 45.07% (>40% threshold), Defect Class: Edge-Loc, Confidence: 99.30%

Wafer Defect Image:



Wafer 222 Inspection Decision

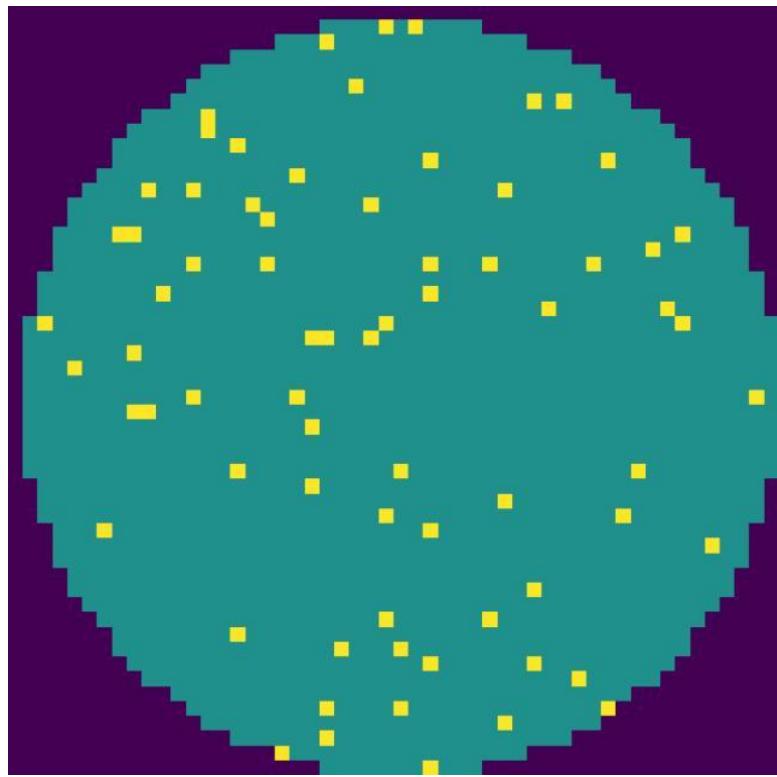
Wafer ID: Mechanical_MECH_01_W0039
Decision: PASS

Machine Type: Mechanical
Machine ID: MECH_01
Timestamp: 2025-12-27T12:08:50.122537
Simulation Date: 2025-12-27

Defect Class: Normal
Confidence Score: 0.9997
Defect Percentage: 32.51%

Reason: Defect Percentage: 32.51% (<=40% threshold), Defect Class: Normal, Confidence: 99.97%

Wafer Defect Image:



Wafer 223 Inspection Decision

Wafer ID: Electrical_ELEC_02_W0045

Decision: PASS

Machine Type: Electrical

Machine ID: ELEC_02

Timestamp: 2025-12-27T12:08:50.285765

Simulation Date: 2025-12-27

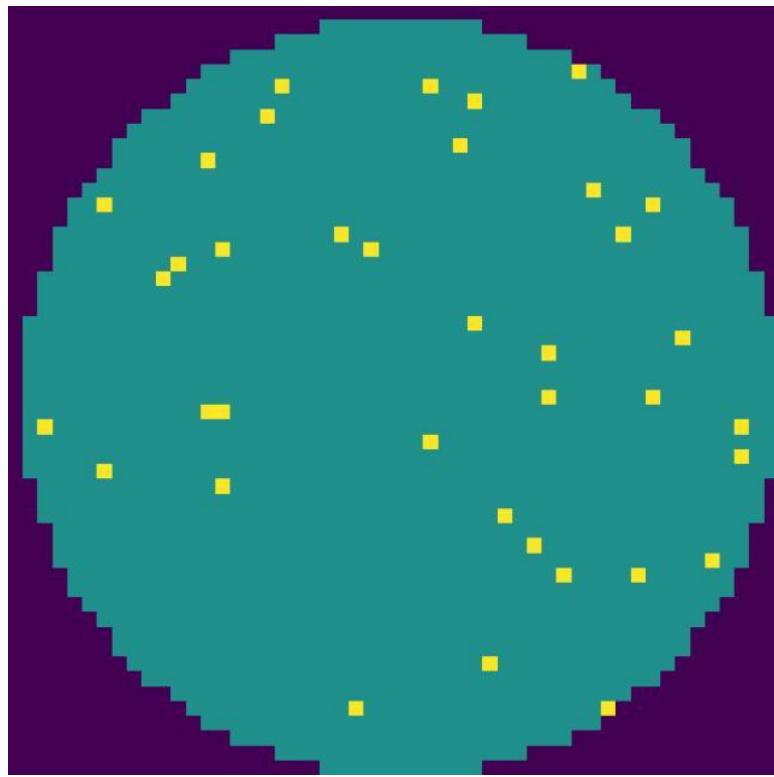
Defect Class: Normal

Confidence Score: 0.9999

Defect Percentage: 31.07%

Reason: Defect Percentage: 31.07% (<=40% threshold), Defect Class: Normal, Confidence: 99.99%

Wafer Defect Image:



Wafer 224 Inspection Decision

Wafer ID: Electrical_ELEC_01_W0045

Decision: PASS

Machine Type: Electrical

Machine ID: ELEC_01

Timestamp: 2025-12-27T12:08:51.090926

Simulation Date: 2025-12-27

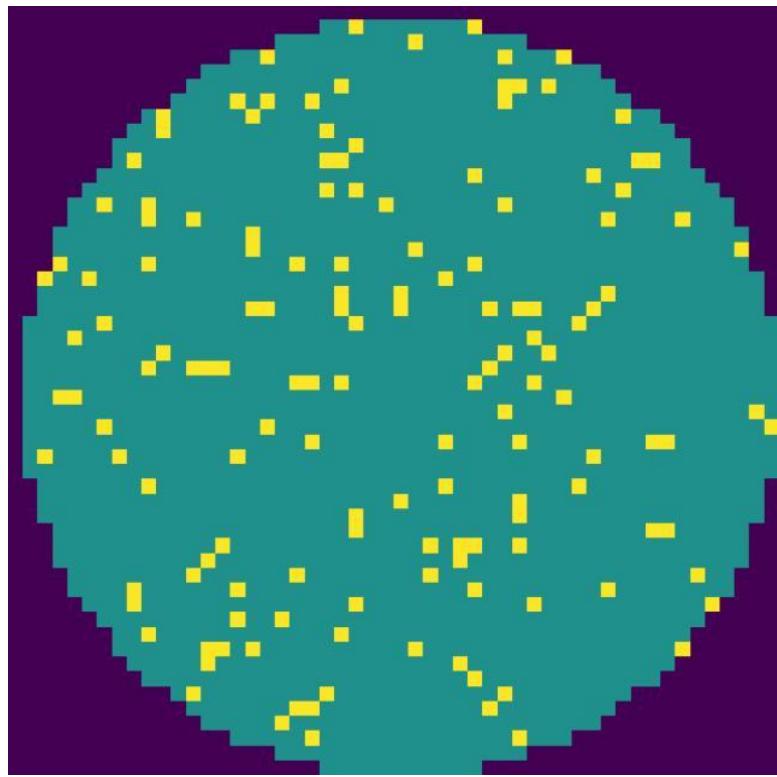
Defect Class: Normal

Confidence Score: 0.9998

Defect Percentage: 35.77%

Reason: Defect Percentage: 35.77% (<=40% threshold), Defect Class: Normal, Confidence: 99.98%

Wafer Defect Image:



Wafer 225 Inspection Decision

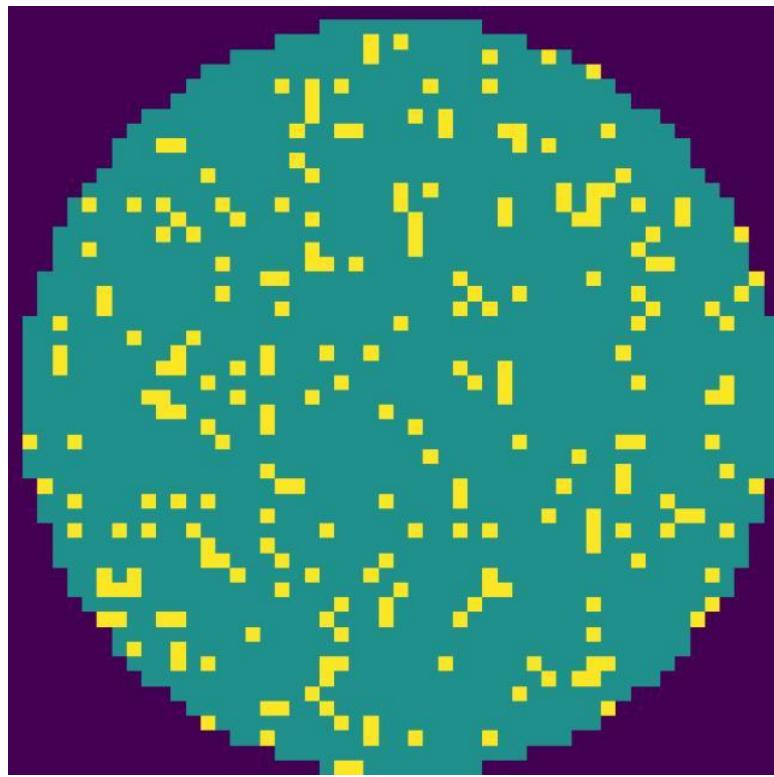
Wafer ID: Mechanical_MECH_02_W0039
Decision: PASS

Machine Type: Mechanical
Machine ID: MECH_02
Timestamp: 2025-12-27T12:08:52.153464
Simulation Date: 2025-12-27

Defect Class: Normal
Confidence Score: 0.9998
Defect Percentage: 38.44%

Reason: Defect Percentage: 38.44% (<=40% threshold), Defect Class: Normal, Confidence: 99.98%

Wafer Defect Image:



Wafer 226 Inspection Decision

Wafer ID: Thermal_THERM_01_W0032

Decision: FAIL

Machine Type: Thermal

Machine ID: THERM_01

Timestamp: 2025-12-27T12:08:52.562110

Simulation Date: 2025-12-27

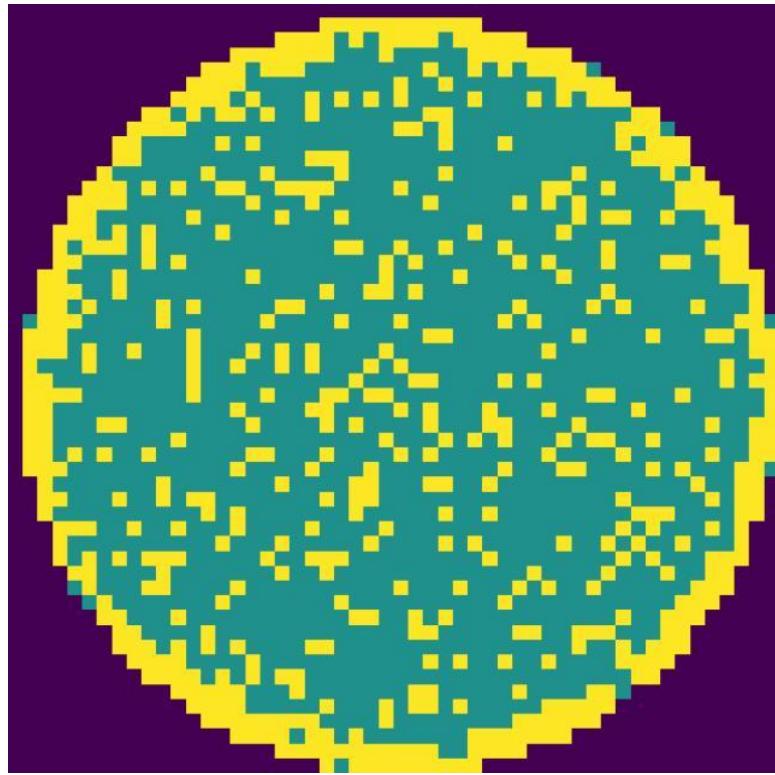
Defect Class: Edge-Ring

Confidence Score: 0.9832

Defect Percentage: 56.34%

Reason: Defect Percentage: 56.34% (>40% threshold), Defect Class: Edge-Ring, Confidence: 98.32%

Wafer Defect Image:



Wafer 227 Inspection Decision

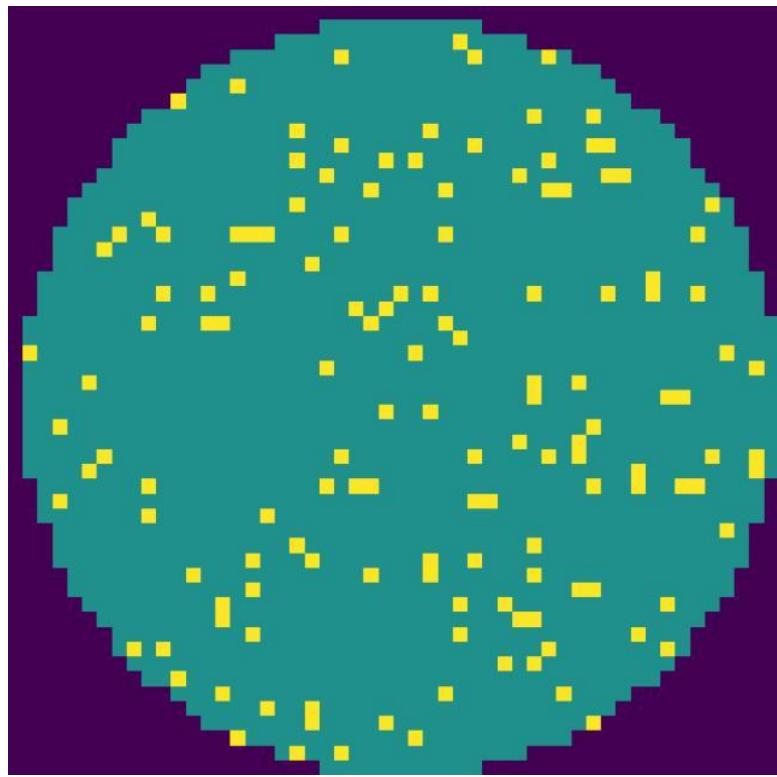
Wafer ID: Thermal_THERM_02_W0027
Decision: PASS

Machine Type: Thermal
Machine ID: THERM_02
Timestamp: 2025-12-27T12:08:52.990747
Simulation Date: 2025-12-27

Defect Class: Normal
Confidence Score: 0.9998
Defect Percentage: 34.76%

Reason: Defect Percentage: 34.76% (<=40% threshold), Defect Class: Normal, Confidence: 99.98%

Wafer Defect Image:



Wafer 228 Inspection Decision

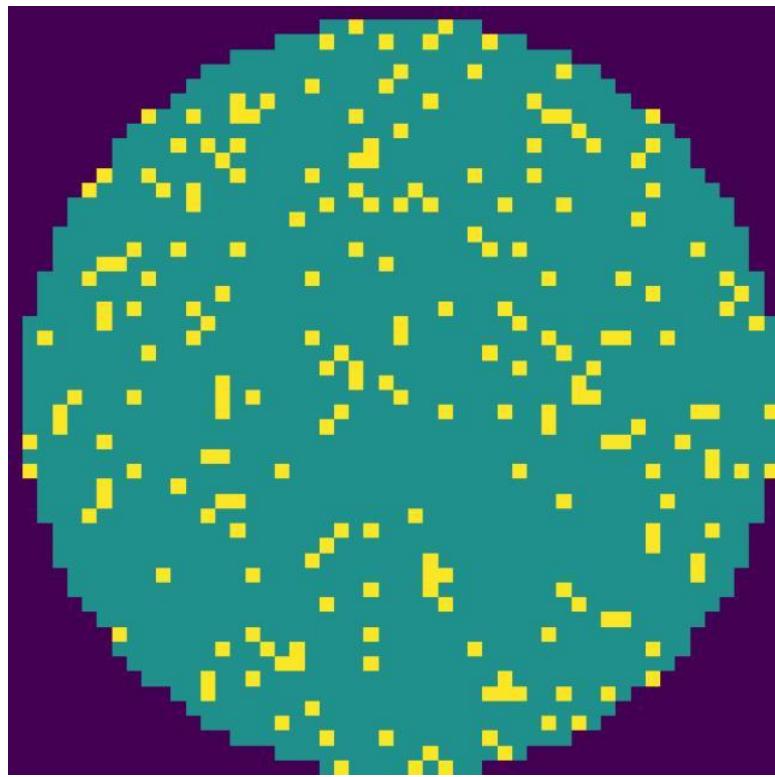
Wafer ID: Mechanical_MECH_01_W0040
Decision: PASS

Machine Type: Mechanical
Machine ID: MECH_01
Timestamp: 2025-12-27T12:08:55.887363
Simulation Date: 2025-12-27

Defect Class: Normal
Confidence Score: 0.9997
Defect Percentage: 35.74%

Reason: Defect Percentage: 35.74% (<=40% threshold), Defect Class: Normal, Confidence: 99.97%

Wafer Defect Image:



Wafer 229 Inspection Decision

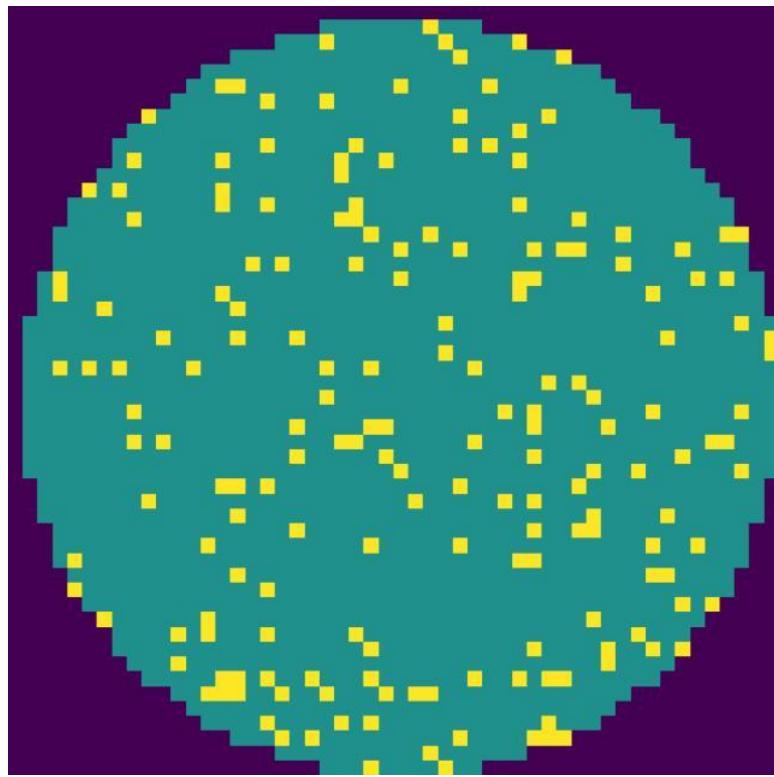
Wafer ID: Electrical_ELEC_02_W0046
Decision: PASS

Machine Type: Electrical
Machine ID: ELEC_02
Timestamp: 2025-12-27T12:08:56.022099
Simulation Date: 2025-12-27

Defect Class: Normal
Confidence Score: 0.9998
Defect Percentage: 36.69%

Reason: Defect Percentage: 36.69% (<=40% threshold), Defect Class: Normal, Confidence: 99.98%

Wafer Defect Image:



Wafer 230 Inspection Decision

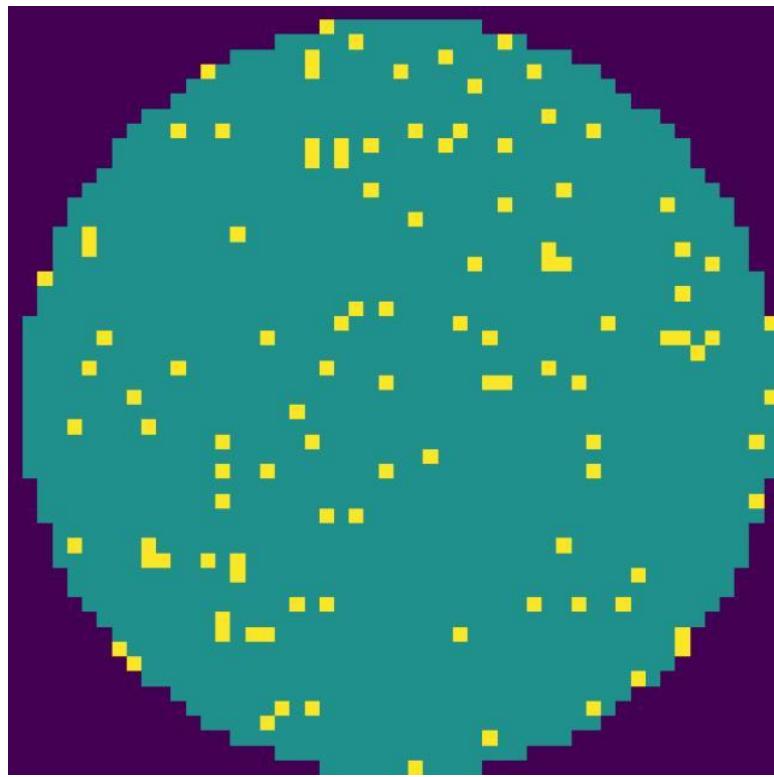
Wafer ID: Electrical_ELEC_01_W0046
Decision: PASS

Machine Type: Electrical
Machine ID: ELEC_01
Timestamp: 2025-12-27T12:08:56.661864
Simulation Date: 2025-12-27

Defect Class: Normal
Confidence Score: 0.9997
Defect Percentage: 35.66%

Reason: Defect Percentage: 35.66% (<=40% threshold), Defect Class: Normal, Confidence: 99.97%

Wafer Defect Image:



Wafer 231 Inspection Decision

Wafer ID: Mechanical_MECH_02_W0040

Decision: FAIL

Machine Type: Mechanical

Machine ID: MECH_02

Timestamp: 2025-12-27T12:08:58.337849

Simulation Date: 2025-12-27

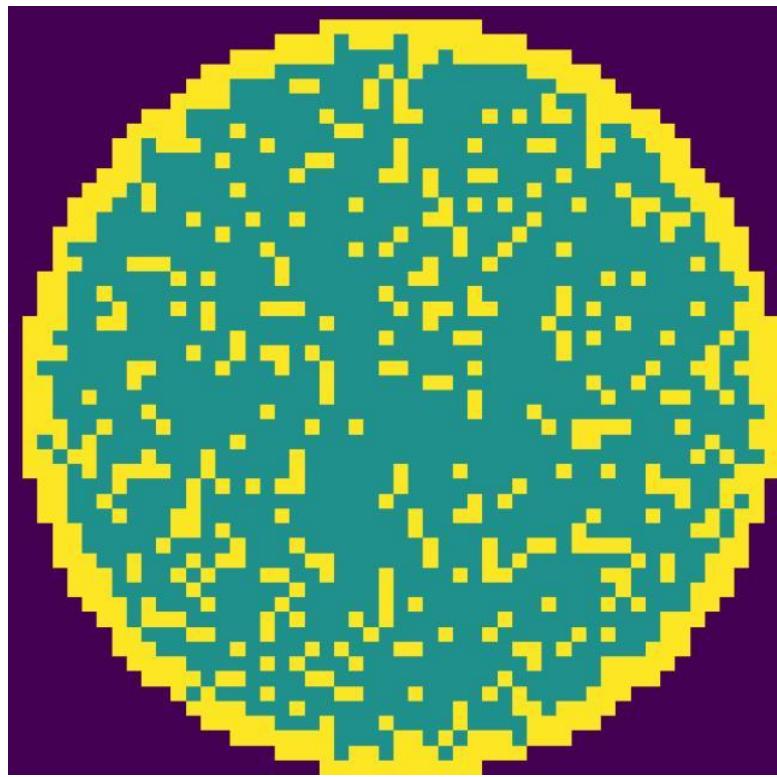
Defect Class: Edge-Ring

Confidence Score: 0.9825

Defect Percentage: 58.92%

Reason: Defect Percentage: 58.92% (>40% threshold), Defect Class: Edge-Ring, Confidence: 98.25%

Wafer Defect Image:



Wafer 232 Inspection Decision

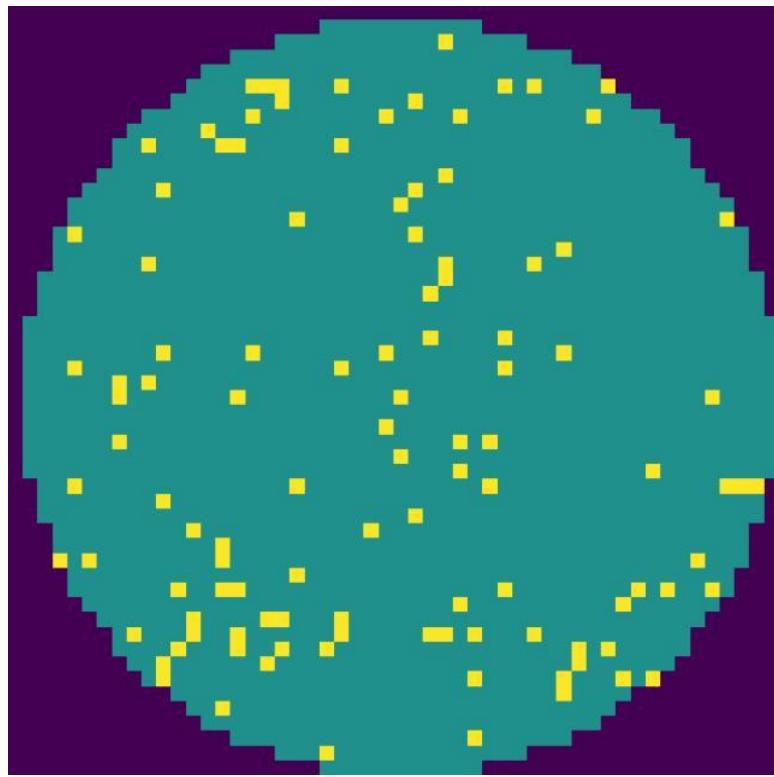
Wafer ID: Mechanical_MECH_01_W0041
Decision: PASS

Machine Type: Mechanical
Machine ID: MECH_01
Timestamp: 2025-12-27T12:09:01.428594
Simulation Date: 2025-12-27

Defect Class: Normal
Confidence Score: 0.9997
Defect Percentage: 34.78%

Reason: Defect Percentage: 34.78% (<=40% threshold), Defect Class: Normal, Confidence: 99.97%

Wafer Defect Image:



Wafer 233 Inspection Decision

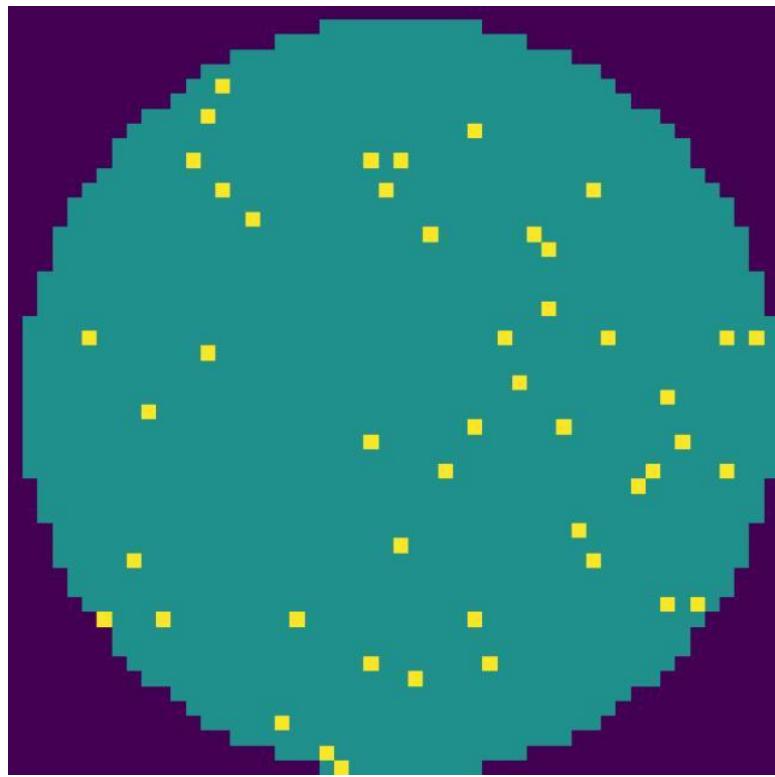
Wafer ID: Thermal_THERM_02_W0028
Decision: PASS

Machine Type: Thermal
Machine ID: THERM_02
Timestamp: 2025-12-27T12:09:01.501863
Simulation Date: 2025-12-27

Defect Class: Normal
Confidence Score: 0.9998
Defect Percentage: 30.04%

Reason: Defect Percentage: 30.04% (<=40% threshold), Defect Class: Normal, Confidence: 99.98%

Wafer Defect Image:



Wafer 234 Inspection Decision

Wafer ID: Electrical_ELEC_02_W0047

Decision: PASS

Machine Type: Electrical

Machine ID: ELEC_02

Timestamp: 2025-12-27T12:09:01.812549

Simulation Date: 2025-12-27

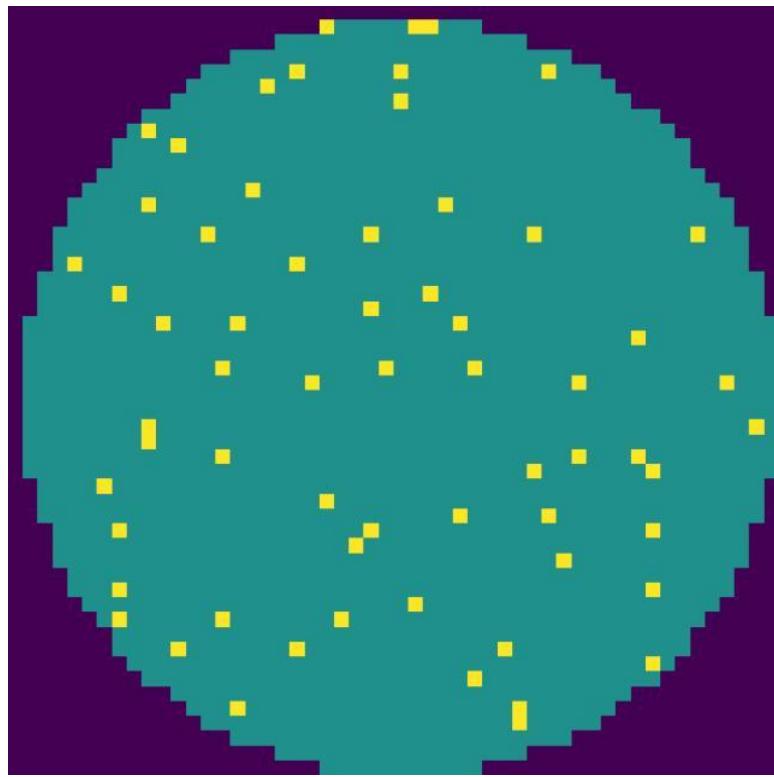
Defect Class: Normal

Confidence Score: 0.9998

Defect Percentage: 32.51%

Reason: Defect Percentage: 32.51% (<=40% threshold), Defect Class: Normal, Confidence: 99.98%

Wafer Defect Image:



Wafer 235 Inspection Decision

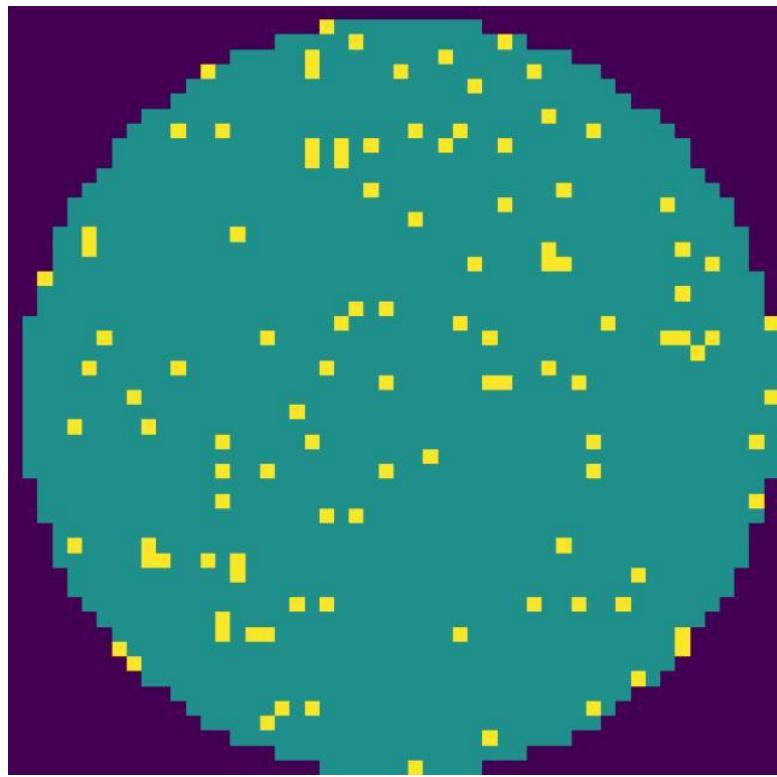
Wafer ID: Thermal_THERM_01_W0033
Decision: PASS

Machine Type: Thermal
Machine ID: THERM_01
Timestamp: 2025-12-27T12:09:01.910529
Simulation Date: 2025-12-27

Defect Class: Normal
Confidence Score: 0.9997
Defect Percentage: 35.66%

Reason: Defect Percentage: 35.66% (<=40% threshold), Defect Class: Normal, Confidence: 99.97%

Wafer Defect Image:



Wafer 236 Inspection Decision

Wafer ID: Electrical_ELEC_01_W0047

Decision: PASS

Machine Type: Electrical

Machine ID: ELEC_01

Timestamp: 2025-12-27T12:09:02.624133

Simulation Date: 2025-12-27

Defect Class: Normal

Confidence Score: 0.9998

Defect Percentage: 32.88%

Reason: Defect Percentage: 32.88% (<=40% threshold), Defect Class: Normal, Confidence: 99.98%

Wafer Defect Image:

